# Programmable Logic Handbook 

FOURTH EDITION

## Pa $2=-2$ <br> Rea No 64168807

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## The PAL® Concept

Monolithic Memories' family of PAL devices gives designers a powerful tool with unique capabilities for use in new and existing logic designs. The PAL circuit saves time and money by solving many of the system partitioning and interface problems brought about by increases in semiconductor device technology.

Rapid advances in large-scale integration technology have led to larger and larger standard logic functions; single I.C. s now perform functions that formerly required complete circuit cards. While LSI offers many advantages, advances have been made at the expense of device flexibility. Most LSI devices still require large numbers of SSI/MSI devices for interfacing with user systems. Designers are still forced to turn to random logic for many applications.


The designer is confronted with another problem when a product is designed. Often the function is well defined and could derive significant benefits from fabrication as an integrated circuit. However, the design cycle for a custom circuit is long and the costs can be very high. This makes the risk significant enough to deter most users. The technology to support maximum flexibility combined with fast turnaround on custom logic has simply not been available. Monolithic Memories offers the programmable solution.

The PAL device family offers a fresh approach to using fuse programmable logic. PAL circuits are a conceptually unified group of devices which combine programmable flexibility with high speed and an extensive selection of interface options. PAL devices can lower inventory, cut design cycles and provide high complexity with maximum flexibility. These features, combined with lower package count and high reliability, truly make the PAL circuit a designer's best friend.

## The PAL Circuit - Teaching Old PROMs New Tricks



Monolithic Memories developed the modern PROM and introduced many of the architectures and techniques now regarded as industry standards. As a major PROM manufacturer, Monolithic Memories has the proven technology and high volume production capability required to manufacture and support the PAL device.

The PAL circuit is an extension of the fusible link technology pioneered by Monolithic Memories for use in bipolar PROMs. The fusible link PROM first gave the digital systems designer the power to "write on silicon." In a few seconds he was able to transform a blank PROM from a general purpose device into one containing a custom algorithm, microprogram, or Boolean transfer function. This opened up new horizons for the use of PROMs in computer control stores, character generators, data storage tables and many other applications. The wide acceptance of this technology is clearly demonstrated by today's multimillion dollar PROM market.

The key to the PROM's success is that it allows the designer to quickly and easily customize the chip to fit his unique requirements. The PAL circuit extends this programmable flexibility by utilizing proven link technology to implement logic functions. Using PAL circuits the designer can quickly and effectively implement custom logic varying in complexity from random gates to complex arithmetic functions.

## ANDs and ORs

The PAL device implements the familiar sum of products logic by using a programmable AND array whose output terms feed a
fixed OR array. Since the sum of products form can express any Boolean transfer function, the PAL circuit uses are only limited by the number of terms available in the AND - OR arrays. PAL devices come in different sizes to allow for effective logic optimization.

Figure 1 shows the basic PAL circuit structure for a two-input, one-output logic segment. The general logic equation for this segment is:

$$
\begin{aligned}
\text { Output }= & \left(l_{1}+\bar{f}_{1}\right)\left(\overline{(1}_{1}+\bar{f}_{2}\right)\left(l_{2}+\overline{f_{3}}\right)\left(\overline{I_{2}}+\overline{f_{4}}\right)+ \\
& \left(l_{1}+\overline{f_{5}}\right)\left(\overline{I_{1}}+\overline{f_{6}}\right)\left(l_{2}+\overline{f_{7}}\right)\left(\overline{l_{2}}+\overline{f_{8}}\right)
\end{aligned}
$$

where the " 4 " terms represent the state of the fusible links in the PAL AND array. An unblown link represents a logic 1. Thus,
fuse blown, $f=0$
fuse intact, $f=1$
An unprogrammed PAL circuit has all fuses intact.






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## PAL Circuit Notation

Logic equations, while convenient for small functions, rapidly become cumbersome in large systems. To reduce possible confusion, complex logic networks are generally defined by logic diagrams and truth tables. Figure 2 shows the logic convention adopted to keep PAL logic easy to understand and use. In the figure, an " $x$ " represents an intact fuse used to perform the logic AND function. (Note: the input terms on the common line with the x's are not connected together.) The logic symbology shown in Figure 2 has been informally adopted by integrated circuit manufacturers because it clearly establishes a one-to-one correspondence between the chip layout and the logic diagram. It also allows the logic diagram and truth table to be combined into a compact and easy to read form, thereby serving as a convenient shorthand for PAL circuits. The two input - one output example from Figure 1 redrawn using the new logic convention is shown in Figure 3.


As a simple PAL logic example, consider the implementation of the transfer function:

$$
\text { Output }=I_{1} \bar{I}_{2}+\bar{I}_{1} I_{2}
$$

The normal combinatorial logic diagram for this function is shown in figure 4, with the PAL logic equivalent shown in figure 5 .

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Figure 5

Using this logic convention it is now possible to compare the PAL structure to the structure of the more familiar PROM and PLA. The basic logic structure of a PROM consists of a fixed AND array whose outputs feed a programmable OR array (figure 6). PROMs are low-cost, easy to program, and available in a variety of sizes and organizations. They are most commonly
used to store computer programs and data. In these applications the fixed input is a computer memory address; the output is the contents of that memory location.


Figure 6

The basic logic structure of the PLA consists of a programmable AND array whose outputs feed a programmable OR array (Figure 7). Since the designer has complete control over all inputs and outputs, the PLA provides the ultimate flexibility for implementing logic functions. They are used in a wide variety of applications. However, this generality makes PLAs expensive, quite formidable to understand, and costly to program (they require special programmers).

The basic logic structure of the PAL circuit, as mentioned earlier, consists of a programmable AND array whose outputs feed a fixed OR array (Figure 8). The PAL circuit combines much of the flexibility of the PLA with the low cost and easy programmability of the PROM. Table 1 summarizes the characteristics of the PROM, PLA and PAL logic families.


 (PROGRAMMABLE)

PAL Device 4 Ine4 Oute16 Products


Figure 7
Figure 8
8) pugel

| vishe PO elidsmmmgote | 40 | AND | OR | OUTPUT OPTIONS |
| :---: | :---: | :---: | :---: | :---: |
|  | PROM | Fixed | Prog | TS, OC |
| biw is ni beed ans | FPLA | Prog | Prog | TS, OC, Fusible Polarity |
| -rimoks A/19 atwiem vitater | FPGA | Prog | None | TS, OC, Fusible Polarity |
| [me7coth of vilson the id | FPLS | Prog | Prog | TS, Registered Feedback, I/O |
| mblerty of klaco phis io | PAL Circuit | Prog | Fixed | TS, Registered Feedback, I/O |

Table 1

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PAL Device Introduction
PAL Circuit Input/Output/Function/Performance Chart

| PART NO. | INPUT | OUTPUT | PROG. I/O'S | OUTPUT POLARITY | FEEDBACK REGISTER | FUNCTIONS | PERFORMANCE |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  | STD | A | -2 | A-2 | A-4 |
| 10H8 | 10 | 8 |  |  | AND-OR | AND-OR Gate Array | $x$ |  | $x$ |  |  |
| 12H6 | 12 | 6 |  |  | AND-OR | AND-OR Gate Array | X |  | X |  |  |
| 14H4 | 14 | 4 |  |  | AND-OR | AND-OR Gate Array | X |  | X |  |  |
| 16H2 | 16 | 2 |  |  | AND-OR | AND-OR Gate Array | X |  | X |  |  |
| 16C1 | 16 | 2 |  |  | BOTH ${ }^{1}$ | AND-OR/NOR Gate Array | X |  | X |  |  |
| 10L8 | 10 | 8 |  |  | AND-NOR | AND-OR Invert Gate Array | X |  | X |  |  |
| 12 L 6 | 12 | 6 |  |  | AND-NOR | AND-OR Invert Gate Array | X |  | X |  |  |
| 14L4 | 14 | 4 | (s) |  | AND-NOR | AND-OR Invert Gate Array | x |  | X |  |  |
| 16L2 | 16 | 2 |  |  | AND-NOR | AND-OR Invert Gate Array | X |  | X |  |  |
| 12 L 10 | 12 | 10 |  |  | AND-NOR | AND-OR Invert Gate Array | $x$ |  |  |  |  |
| 14L8 | 14 | 8 | प/ug |  | AND-NOR | AND-OR Invert Gate Array | X |  |  |  |  |
| 16L6 | 16 | 6 |  |  | AND-NOR | AND-OR Invert Gate Array | X |  |  |  |  |
| 18 L 4 | 18 | 4 |  |  | AND-NOR | AND-OR Invert Gate Array | X |  |  |  |  |
| 20 L 2 | 20 | 2 |  |  | AND-NOR | AND-OR Invert Gate Array | X |  |  |  |  |
| 20 C 1 | 20 | 2 |  |  | BOTH ${ }^{1}$ | AND-OR/NOR Gate Array | X |  |  |  |  |
| 16L8 | 10 | 2 | 6 |  | AND-NOR | AND-OR Invert Gate Array |  | $x$ |  | x | x |
| 20 L 8 | 14 | 2 | 6 |  | AND-NOR | AND-OR Invert Gate Array |  | X |  |  |  |
| 20 L 10 | 12 | 2 | 8 |  | AND-NOR | AND-OR Invert Gate Array | X |  |  |  |  |
| 16R8 | 8 | 8 |  | 8 | AND-NOR | AND-OR Invert Gate Array w/Regs |  | X |  | X | X |
| 16R6 | 8 | 6 | 2 | 6 | AND-NOR | AND-OR Invert Gate Array w/Regs |  | X |  | X | X |
| 16R4 | 8 | 4 | 4 | 4 | AND-NOR | AND-OR Invert Gate Array w/Regs |  | X |  | X | X |
| $20 \mathrm{R8}$ | 12 | 8 |  | 8 | AND-NOR | AND-OR Invert w/Regs |  | x |  |  |  |
| 20R6 | 12 | 6 | 2 | 6 | AND-NOR | AND-OR Invert w/Regs bi |  | x |  |  |  |
| 20R4 | 12 | 4 | 4 | 4 | AND-NOR | AND-OR Invert w/Regs |  | X |  |  |  |
| $20 \times 10$ | 10 | 10 |  | 10 | AND-NOR | AND-OR-XOR Invert w/Regs | $x$ |  |  |  |  |
| $20 \times 8$ | 10 | 8 | 2 | 8 | AND-NOR | AND-OR-XOR Invert w/Regs | x |  |  |  |  |
| $20 \times 4$ | 10 | 4 | 6 | 4 | AND-NOR | AND-OR-XOR Invert w/Regs | x |  |  |  |  |
| 16X4 | 8 | 4 | 4 | 4 | AND-NOR | AND-OR-XOR Invert w/Regs | X |  |  |  |  |
| 16A4 | 8 | 4 | 4 | 4 | AND-NOR | AND-CARRY-OR-XOR Invert w/Regs | X |  |  |  |  |
| 16P8 | 10 | 2 | 6 |  | PROG ${ }^{2}$ | AND-OR Gate Array |  | x |  |  |  |
| 16RP8 | 8 | 8 |  | 8 | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | x |  |  |  |
| 16RP6 | 8 | 6 | 2 | 6 | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | x |  |  |  |
| 16RP4 | 8 | 4 | 4 | 4 | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | x |  |  |  |
| 20RA10 | 10 |  | $10^{3}$ | $10^{3}$ | PROG ${ }^{2}$ | Asynchronous Gate Array |  | x |  |  |  |
| 20RS10 | 10 |  |  | 10 | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | X |  |  |  |
| 20RS8 | 10 |  | 2 | 8 | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | X |  |  |  |
| 20RS4 | 10 |  | 6 | 4 | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | x |  |  |  |
| 20S10 | 10 |  | 10 |  | $\mathrm{PROG}^{2}$ | AND-OR Gate Array |  | X |  |  |  |
| 32R16 | 16 | $16^{3}$ |  | $16^{3}$ | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | X |  |  |  |
| 64R32 | 32 | $32^{3}$ |  | $32^{3}$ | PROG ${ }^{2}$ | AND-OR Gate Array w/Regs |  | X |  |  |  |
| Table 2 <br> ${ }^{1}$ Simultaneous AND-OR and AND-NOR outputs <br> ${ }^{2}$ Programmable active high or active low. i.e. AND-OR or AND-NOR <br> ${ }^{3}$ Output can be registered or non-registered |  |  |  |  |  |  |  |  |  |  |  |

## PAL Circuits for Every Task

The members of the PAL family and their characteristics are summarized in Table 2. They are designed to cover the spectrum of logic functions at reduced cost and lower package count. This allows the designer to select the PAL circuit that best fits his application. PAL units come in the following basic configurations:

## Logic Arrays

PAL logic arrays are available in sizes from $12 \times 10$ ( 12 input terms, 10 output terms) to $20 \times 2$, with both active high and active low output configurations available (Figure 9). This wide variety of input/output formats allows the PAL device to replace many different sized blocks of combinatorial logic with single packages.


Figure 9

## Programmable I/O

A feature of the high-end members of the PAL family is programmable input/output. This allows the produt terms to directly control the outputs of the PAL circuit (Figure 10). One product term is used to enable the three-state buffer, which in turn gates the summation term to the output pin. The output is also fed back
into the PAL array as an input. Thus the PAL circuit drives the I/O pin when the three-state gate is enabled; the I/O pin is an input to the PAL array when the three-state gate is disabled. This feature can be used to allocate available pins for I/O functions or to provide bidirectional output pins for operations such as shifting and rotating serial data.


Figure 10

## Registered Outputs with Feedback

Another feature of the high end members of the PAL family is registered data outputs with registered feedback. Each product term is stored into a D-type output flip-flop on the rising edge of the system clock (Figure 11). The Q output of the flip-flop can then be gated to the output pin by enabling the active low threestate buffer.

In addition to being available for transmission, the Q output is fed back into the PAL array as an input term. This feedback allows the PAL circuit to "remember" the previous state, and it can alter its function based upon that state. This allows the designer to configure the PAL circuit as a state sequencer which can be programmed to execute such elementary functions as count up, count down, skip, shift, and branch. These functions can be executed by the registered PAL device at rates of up to 25 MHz .


Figure 11

## XOR PAL Circuits

These PAL devices feature an exclusive OR function. The sum of products is segmented into two sums which are then exclusive ORed (XOR) at the input of the D-type flip-flop (Figure 12). All of
the features of the Registered PAL circuits are included in the XOR PAL unit. The XOR function provides an easy implementation of the HOLD operation used in counters and other state sequencers.


Figure 12

## Programmable Output Polarity

The outputs can be programmed either active-low or activenigh. This is represented by the exclusive-or gates shown in Figure 13, PAL20RA10 Logic Diagram. When the output polarity fuse is blown, the lower input to the exclusive-or gate is high, so the output is active-high. Similarly, when the output polarity fuse is intact, the output is active-low. The programmable output polarity feature allows the user a higher degree of flexibility when writing equations.

## Programmable Clock

One of the product lines in each group is connected to the clock. This provides the user with the additional flexibility of a programmable clock, so each output can be clocked independently of all the others. (See Figure 13.)

## Programmable Set and Reset

Two product lines are dedicated to asynchronous set and reset. If the set product line is high, the register output becomes a logic 1. If the reset product line is high, the register output becomes a logic 0 . The operation of the programmable set and reset overrides the clock. (See Figure 13.)

## Individually Programmable Register Bypass

If both the set and reset product lines are high, the sum-ofproducts bypasses the register and appears immediately at the output, thus making the output combinatorial. This allows each output to be configured in the registered or combinatorial mode. (See Figure 13.)




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## Product Term Sharing

The basic configuration is sixteen product terms shared between two output cells. For a typical output pair, each product term can be used by either output; but, since product term sharing is
exclusive, a product term can be used by only one output, not both. If equations call for an output pair to use the same product term, two product terms are generated, one for each output. This should be taken into account when writing equations. PAL assemblers configure product terms automatically.


Figure 14

## Advanced PAL Circuit Features

For 1985, a number of new features have been incorporated into the PAL family, including:

- Programmable output polarity for active high or active low operation
- Register preload which allows complete functional testing
- Product term sharing ${ }^{\star}$, a feature making the number of product terms per output user-determinable
- Register bypass facilitating registered or combinatorial outputs
- Asynchronous clocks, sets, resets and output enables

A full description of each function is given on page 5-17.

## PAL Device Programming

PAL devices can be programmed in most standard PROM programmers with the addition of a PAL personality card. The PAL circuit appears to the programmer as a PROM. During programming half of the PAL device outputs are selected for programming while the other outputs and the inputs are used for addressing. The outputs are then switched to program the other locations. Verification uses the same procedure with the programming lines held in a low state.

## PALASM Software

 (PAL Device Assembler)PALASM software is used to define, simulate, build and test PAL device units. PALASM software accepts the PAL circuit Design Specification as an input file. It verifies the design against an optional function table and generates the fuse plot which is used to program the PAL devices. Presently, PALASM software is being replaced by its successor: PALASM2 software. PALASM2 software has added features that simplify the task of defining and simulating PAL Design Specifications.

## HAL® Device (Hard Array Logic)

The HAL family is the mask-programmed version of a PAL circuit. The HAL circuit is to a PAL circuit just as ROM is to a PROM. A standard wafer is fabricated to the 6 mask. Then a custom metal mask is used to fabricate aluminum links for a HAL circuit instead of the programmable Ti-W fuse array used in a PAL circuit.
The HAL device is a cost-effective solution for large quantities and is unique in that it is a gate array with a programmable prototype.

## ZHAL Device

## (Zero Power Hard Array Logic)

ZHAL devices are functionally identical to regular HAL devices but with the added feature of consuming zero standby power. This is highly desirable in portable digital equipment and lap-top computers.

## PAL Circuit Technology

PAL circuits are manufactured using the proven TTL Schottky bipolar Ti-W fuse process to make fusible-link PROMs. An NPN emitter follower array forms the programmable AND array. PNP inputs provide high impedance inputs ( 0.25 mA max) to the array. All outputs are standard TTL drivers with internal active pull-up transistors. Typical PAL circuit propagation delay time is less than 25 ns .

## PAL Device Data Security

The circuitry used for programming and logic verification can be used at any time to determine the logic pattern stored in the PAL array. For security, the PAL array has a "last fuse" which can be blown to disable the verification logic. This provides a significant deterrent to potential copiers, and it can be used to effectively protect proprietary designs.

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The PAL device part number is unique in that the part number code also defines the part's logic operation. The PAL device parts code system is shown below. For example, a PAL14L4CN would be a 14 input term, 4 output term, active-low PAL with a commercial temperature range packaged in a 20 -pin plastic dip.


## PAL Circuit Logic Symbols

The logic symbols for each of the individual PAL devices gives a concise functional description of the PAL logic function. This symbol makes a convenient reference when selecting the PAL device that best fits a specific application. Figure 18 shows the logic symbol for a PAL10H8 gate array.
volume, so it is essential that every possible production cost be minimized
The electronic dice game is simply constructed using a free running oscillator whose output is used to drive two asynchronous modulo six counters. When the user "rolls" the dice (presses a button), the current state of the counters is decoded and latched into a display resembling the pattern seen on an ordinary pair of dice.
A conventional logic diagram for the dice game is shown in Figure 15. (A detailed logic derivation is shown in the PAL device applications section of this handbook). It is implemented using standard TTL, SSI and MSI parts, with a total I.C. count of eight: six quad gate packages and two quad D-latches. Looks like a nice, clean logic design, right? Wrong!!

## A PAL Circuit Goes to the Casino

A brief examination of Figure 16 reveals two basic facts: first, the circuit contains mostly simple, combinatorial logic, and second, it uses a clocked state transition sequence. Remembering that the PAL device family contains ample provision for these features, the PAL device catalog is consulted. The PAL16R8 has all the required functions, and the entire logic content of the circuit can be programmed into a single PAL circuit shown in Figure 17.
In this example, the PAL circuit effected an eight-to-one package count reduction and a significant cost savings. This is typical of the power and cost-effective performance that the PAL family brings to logic design.

## A PAL Circuit Example

simple, high-volume consumer product: an electronic dice


Figure 17

## Advantages of Using PAL Circuits



The PAL device has a unique place in the world of logic design Not only does it offer many advantages over conventional logic, it also provides many features not found anywhere else. The PAL family:

- Programmable replacement for conventional TTL logic.
- Reduces IC inventories substantially and simplifies their control.
- Reduces chip count by at least 4 to 1 .
- Expedites and simplifies prototyping and board layout.
- Saves space with 20-pin and 24-pin SKINNYDIP® packages.
- High speed: 15 ns typical propagation delay.
- Programmed on standard PROM programmers.
- Programmable three-state outputs.
- Special feature eliminates possibility of copying by competitors.
All of these features combine together to lower product development costs and increase product cost effectiveness. The bottom line is that PAL units save money.


## Direct Logic Replacement



In both new and existing designs the PAL circuit can be used to replace various logic functions. This allows the designer to optimize a circuit in many ways never before possible. The PAL circuit is particularly effective when used to provide interfaces required by many LSI functions. PAL circuit flexibility combined with LSI function density makes a powerful team.

## Design Flexibility

The PAL circuit offers the systems logic designer a whole new world of options. Until now, the decision on logic system implementation was usually between SSI/MSI logic functions on one hand and microprocessors on the other. In many cases the function required is too awkward to implement the first way and too simple to justify the second. Now the PAL circuit offers the designer high functional density, high speed, and low cost. Even better, PAL devices come in a varity of sizes and functions, thereby further increasing the designer's options.

Space Efficiency


By allowing designers to replace many simple logic functions with single packages, the PAL device allows more compact P.C. board layouts. The PAL space-saving 20-pin and 24-pin "SKINNYDIP" package helps to further reduce board area while simplifying board layout and fabrication. This means that many multi-card systems can now be reduced to one or two cards, and that can make the difference between a profitable success or an expensive disaster.

## Smaller Inventory

The PAL device family can be used to replace up to $90 \%$ of the conventional TTL family. This considerably lowers both shelving and inventory cataloging requirements. Even better, small custom modifications to the standard functions are easy for PAL device users, not so easy for standard TTL users.


High Speed


The PAL device family runs faster or equal to the best of bipolar logic circuits. This makes the PAL circuit the ideal choice for most logical operations or control sequence which requires a medium complexity and high speed. Also, in many microcomputer systems, the PAL circuit can be used to handle highspeed data interfaces that are not feasible for the microprocessor alone. This can be used to significantly extend the capabilities of the low-cost, low-speed NMOS microprocessors into areas formerly requiring high-cost bipolar microprocessors.

## Easy Programming

The members of the PAL device family can be quickly and easily programmed using standard PROM programmers. This allows designers to use PAL circuits with a minimum investment in special equipment. Many types of programmable logic, such as the FPLA, require an expensive, dedicated programmer.

## Secure Data



The PAL device verification logic can be completely disabled by blowing out a special "last link." This prevents the unauthorized copying of valuable data, and makes the PAL circuit perfect for use in any application where data integrity must be carefully guarded.

## Summary

The PAL device family of logic devices offers designers new options in the implementation of sequential and combinatorial logic designs. The family is fast, compact, flexible, and easy to use in both new and existing designs. It promises to reduce costs in most areas of design and production with a corresponding increase in product profitability.

## A Great Performer!



PAL Device Introduction




strolignugitnos sic

## Contents Section 2



## 2-2

# PAL® Device-Programmable Array Logic HAL® Device-Hard Array Logic 

## Features/Benefits

- Reduces SSI/MSI chip count greater than 5 to 1
- Saves space with SKINNYDIP© packages
- Reduces IC Inventorles substantially
- Expedites and simplifies prototyping and board layout
- PALASM ${ }^{\text {™ }}$ silicon compiler provides auto routing and test vectors
- Security fuse reduces possibility of copying by competitors


## Description

The PAL device family utilizes an advanced Schottky TTL process and the Bipolar PROM fusible link technology to provide user programmable logic for replacing conventional SSI/MSI gates and flip-flops at reduced chip count.
The HAL device family utilizes standard Low-Power Schottky TTL process and automated mask pattern generation directly from logic equations to provide a semicustom gate array for replacing conventional SSI/MSI gates and flip-flops at reduced chip count.
There are four different speed/power families offered. Choose from either the standard, high-speed, half-power, or quarterpower family to maximize design performance.
The PAL/HAL device family lets the systems engineer "design his own chip" by blowing fusible links to configure AND and OR gates to perform his desired logic function. Complex interconnections which previously required time-consuming layout are thus "lifted" from PC board etch and placed on silicon where they can be easily modified during prototype check-out or production.

The PAL device transfer function is the familiar sum of products. Like the PROM, the PAL device has a single array of fusible links. Unlike the PROM, the PAL device is a programmable AND array driving a fixed OR array (the PROM is a fixed AND array driving a programmable OR array).
The PAL device transfer function is the familiar sum of products. Like the PROM, the PAL device has a single array of fusible links. Unlike the PROM, the PAL device is a programmable AND array driving a fixed OR array (the PROM is a fixed AND array driving a programmable OR array).

PAL*, HAL* and SKINNYDIP* are registered trademarks of Monolithic Memories. PMSI ${ }^{\text {rw }}$ and $\mathrm{HMSI}^{\text {rw }}$ are trademarks of Monolithic Memories.

In addition the PAL/HAL provides these options:

- Variable input/output pin ratio
- Programmable three-state outputs
- Registers with feedback
- Arithmetic capability
- Exclusive-OR gates
- Other options identified on page 5-17

Unused inputs are tied directly to $\mathrm{V}_{\mathrm{CC}}$ or GND. Product terms with all fuses blown assume the logical high state, and product terms connected to both true and complement of any single input assume the logical low state. Registers consist of D-type flip-flops which are loaded on the low-to-high transition of the clock. PAL/HAL Circuit Logic Diagrams are shown with all fuses blown, enabling the designer to use the diagrams as coding sheets.
The entire PAL device family is programmed using inexpensive conventional PROM programmers with appropriate personality and socket adapter cards. Once the PAL device is programmed and verified, two additional fuses may be blown to defeat verification. This feature gives the user a proprietary circuit which is very difficult to copy.
To design a HAL device, the user first programs and debugs a PAL circuit using PALASM software and the "PAL DESIGN SPECIFICATION" standard format. This specification is submitted to Monolithic Memories where it is computer processed and assigned a bit pattern number, e.g., P01234.
Monolithic Memories will provide a PAL device sample for customer qualification. The user then submits a purchase order for a HAL device of the specified bit pattern number, e.g., HAL18L4 P01234. See Ordering Information below.

## Ordering Information



## Register Bypass

Outputs within a bank must either be all registered or all combinatorial. Whether or not a bank of registers is bypassed depends on how the outputs are defined in the equations. A colon followed by an equal sign [;=] specifies a registered output with feedback which is updated after the low-to-high transition of the clock. An equal sign [=] defines a combinatorial output which bypasses the register. Registers are bypassed in banks of eight. Bypassing a bank of registers eliminates the feedback lines for those outputs.

## Output Polarity

Output polarity is defined by comparison of the pin list and the equations. If the logic sense of a specific output in the pin list is different from the logic sense of that output as defined by its equation, the output is inverted or active low polarity. If the logic sense of a specific output in the pin list is the same as the logic sense of that output as defined by its equation, the output is active high polarity.

## Product Term Sharing

The basic configuration is sixteen product terms shared between two output cells. For a typical output pair, each product term can be used by either output; but, since product term sharing is exclusive, a product term can be used by only one output, not both. If equations call for an output pair to use the same product term, two product terms are generated, one for each output. This should be taken into account when writing equations. PAL circuit assemblers configure product terms automatically.
This example uses the 84 -pin package. Four output equations are shown to demonstrate functionality. Pin names are arbitrary.

## Product Term Editing

A unique feature of product term sharing is the ability to edit the design after the device has been programmed. Without this feature, a new PAL device had to be programmed if the user needed to change his design. Product term editing allows the user to delete an unwanted product term and reprogram a previously unused product term to the desired fuse pattern. This feature is made possible by the product term sharing architecture. Since each product term can be routed to either output in a given pair by selecting one of two steering fuses, it is possible to blow both of the steering fuses thereby completely disabling that product term. Once disabled, that product term is powered down, saving typically 0.25 mA . The desired change may now be programmed into one of the previously unused product terms corresponding to that output pair. Additional edits can be made as long as there are unused product terms for the output in question.

## PRESET Feature (PAL64R32 device only)

Register banks of eight may be PRESET to all highs on the outputs by setting the PRESET pin (PS) to a Low level. Note from the Logic Diagram that when the state of an output is High, the state of the register is Low due to the inverting tri-state buffer.

## PAL Device Testability Features

Preload pins have been added to enable the testability of each state in state-machine design. Typically, for a modulo-n counter or a state machine there are many unreachable states for the registers. These states, and the logic which controls them are untestable without a way to "set-in" the desired starting state of the registers. In addition, long test sequences are sometimes needed to test a state machine simply to reach those starting states which are legal. Since complete logic verification is needed to ensure the proper exit from "illegal" or unused states, a way to enter these states must be provided. The ability to preluad a given bank of registers is provided in this device.
To use the preload feature, several steps must be followed. First, a high level on an assertive-low output enable pin disables the outputs for that bank of registers. Next, the data to be loaded is presented at the output pins. This data is then loaded into the register by placing a low level on the PRELOAD pin. PRELOAD is asynchronous with respect to the clock.


## Programmable Set and Reset (PAL20RA10 only)

In each SMAC, two product lines are dedicated to asynchronous set and reset. If the set product line is high, the register output becomes a logic 1 . If the reset product line is high, the register output becomes a logic 0 and the output pin a logic 1 due to output buffer inversion. The operation of the programmable set and reset overrides the clock.

## Individually Programmable Register Bypass (PAL20RA10 only)

If both the set and reset product lines are high, the sum-ofproducts bypasses the register and appears immediately at the output, thus making the output combinatorial. This allows each output to be configured in the registered or combinatorial mode.

## Programmable Clock (PAL20RA10 only)

One of the product lines in each group is connected to the clock. This provides the user with the additional flexibility of a programmable clock, so each output can be clocked independently of all the others.

| GENERIC LOGIC | PINS | PACKAGE | DESCRIPTION | PART NUMBER |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | STANDARD | HIGH SPEED | 1/2 POWER | 1/4 POWER |
| 10H8 | 20 | N,J,F,L,NL | Octal 10 Input And-Or Gate Array | $\begin{aligned} & \hline \text { PAL10H8 } \\ & \text { HAL10H8 } \\ & \hline \end{aligned}$ | $\begin{aligned} & \text { niou } \\ & \text { vsind } \end{aligned}$ | $\begin{aligned} & \hline \text { PAL10H8-2 } \\ & \text { HAL10H8-2 } \end{aligned}$ | ar |
| 12H6 | 20 | N,J,F,L,NL | Hex 12 Input And-Or Gate Array | $\begin{aligned} & \text { PAL12H6 } \\ & \text { HAL12H6 } \end{aligned}$ | $18500$ | $\begin{aligned} & \text { PAL12H6-2 } \\ & \text { HAL12H6-2 } \end{aligned}$ |  |
| 14H4 | 20 | N,J,F,L,NL | Quad 14 Input And-Or Gate Array | $\begin{aligned} & \text { PAL14H4 } \\ & \text { HAL14H4 } \end{aligned}$ | $10191 v$ | $\begin{aligned} & \text { PAL14H4-2 } \\ & \text { HAL14H4-2 } \end{aligned}$ |  |
| 16H2 | 20 | N,J,F,L,NL | Dual 16 Input And-Or Gate Array | $\begin{aligned} & \text { PAL16H2 } \\ & \text { HAL16H2 } \end{aligned}$ | 2-0. | $\begin{aligned} & \text { PAL16H2-2 } \\ & \text { HAL16H2-2 } \\ & \hline \end{aligned}$ | 19 I |
| 16C1 | 20 | N,J,F,L,NL | 16 Input And-Or/Nor Gate Array | $\begin{aligned} & \text { PAL16C1 } \\ & \text { HAL16C1 } \end{aligned}$ | Bata | $\begin{aligned} & \text { PAL16C1-2 } \\ & \text { HAL16C1-2 } \end{aligned}$ |  |
| 10L8 | 20 | N,J,F,L,NL | Octal 10 Input And-Or Invert Gate Array | $\begin{aligned} & \text { PAL10L8 } \\ & \text { HAL10L8 } \end{aligned}$ | 079 \% | $\begin{aligned} & \text { PAL10L8-2 } \\ & \text { HAL10L8-2 } \\ & \hline \end{aligned}$ |  |
| 12 L 6 | 20 | N,J,F,L,NL | Hex 12 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL12L6 } \\ & \text { HAL12L6 } \end{aligned}$ | 0791w | $\begin{aligned} & \text { PAL12L6-2 } \\ & \text { HAL12L6-2 } \\ & \hline \end{aligned}$ | WS oreos |
| 14L4 | 20 | N,J,F,L,NL | Quad 14 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL14L4 } \\ & \text { HAL14L4 } \end{aligned}$ | What | $\begin{aligned} & \text { PAL14L4-2 } \\ & \text { HAL14L4-2 } \end{aligned}$ | aremos |
| 16L2 | 20 | N,J,F,L,NL | Dual 16 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL16L2 } \\ & \text { HAL16L2 } \\ & \hline \end{aligned}$ | - | $\begin{aligned} & \text { PAL16L2-2 } \\ & \text { HAL16L2-2 } \\ & \hline \end{aligned}$ |  |
| 16L8 | 20 | N,J,F,L,NL | Octal 16 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL16L8 } \\ & \text { HAL16L8 } \end{aligned}$ | $\begin{aligned} & \text { PAL16L8A } \\ & \text { HAL16L8A } \\ & \hline \end{aligned}$ | PAL16L8A-2 HAL16L8A-2 | $\begin{aligned} & \hline \text { PAL16L8A-4 } \\ & \text { HAL16L8A-4 } \end{aligned}$ |
| 16R8 | 20 | N,J,F,L,NL | Octal 16 Input Registered And-Or Invert Gate Array | $\begin{aligned} & \text { PAL16R8 } \\ & \text { HAL16R8 } \end{aligned}$ | $\begin{aligned} & \text { PAL16R8A } \\ & \text { HAL16R8A } \end{aligned}$ | PAL16R8A-2 <br> HAL16R8A-2 | PAL16R8A-4 <br> HAL16R8A-4 |
| 16R6 | 20 | N,J,F,L,NL | Hex 16 Input Registered And-Or Invert Gate Array | $\begin{aligned} & \text { PAL16R6 } \\ & \text { HAL16R6 } \end{aligned}$ | PAL16R6A HAL16R6A | PAL16R6A-2 HAL16R6A-2 | PAL16R6A-4 HAL16R6A-4 |
| 16R4 | 20 | N,J,F,L,NL | Quad 16 Input Registered And-Or Invert Gate Array | $\begin{aligned} & \text { PAL16R4 } \\ & \text { HAL16R4 } \end{aligned}$ | $\begin{aligned} & \text { PAL16R4A } \\ & \text { HAL16R4A } \end{aligned}$ | PAL16R4A-2 HAL16R4A-2 | $\begin{aligned} & \text { PAL16R4A-4 } \\ & \text { HAL16R4A-4 } \end{aligned}$ |
| 16X4 | 20 | N,J,F,L,NL | Quad 16 Input Registered And-Or-Xor Invert Gate Array | $\begin{aligned} & \text { PAL16X4 } \\ & \text { HAL16X4 } \\ & \hline \end{aligned}$ | - ${ }^{\text {Hal }}$ |  |  |
| 16A4 | 20 | N,J,F,L,NL | Quad 16 Input Registered And-Carry-Or-Xor Invert Gate Array | PAL16A4 HAL16A4 |  | ), 1 | *) |
| 12L10 | 24 (28) | NS, JS,F,(L),(NL) | Deca 12 Input And-Or-Invert Gate Array | $\begin{aligned} & \hline \text { PAL12L10 } \\ & \text { HAL12L10 } \\ & \hline \end{aligned}$ |  |  |  |
| 14L8 | 24 (28) | NS,JS,F,(L),(NL) | Octal 14 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL14L8 } \\ & \text { HAL14L8 } \end{aligned}$ | 30030 |  |  |
| 16L6 | 24 (28) | NS,JS,F,(L),(NL) | Hex 16 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL16L6 } \\ & \text { HAL16L6 } \end{aligned}$ |  |  |  |
| 18L4 | 24 (28) | NS,JS,F,(L),(NL) | Quad 18 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL18L4 } \\ & \text { HAL18L4 } \end{aligned}$ |  |  |  |
| 20L2 | 24 (28) | NS,JS,F,(L), (NL) | Dual 20 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL20L2 } \\ & \text { HAL20L2 } \end{aligned}$ |  |  |  |
| $20 \mathrm{C1}$ | 24 (28) | NS,JS,F,(L), (NL) | 20 Input And-Or/Nor Gate Array | $\begin{aligned} & \text { PAL20C1 } \\ & \text { HAL20C1 } \end{aligned}$ |  |  |  |
| 20L10 | 24 (28) | NS,JS,F,(L),(NL) | Deca 20 Input And-Or-Invert Gate Array | $\begin{aligned} & \text { PAL20L10 } \\ & \text { HAL20L10 } \end{aligned}$ |  |  |  |
| 20×10 | 24 (28) | NS, JS,F,(L), (NL) | Deca 20 Input Registered And-Or-Xor Invert Gate Array | $\begin{aligned} & \text { PAL20×10 } \\ & \text { HAL20X10 } \end{aligned}$ |  |  |  |
| 20X8 | 24 (28) | NS, JS,F,(L), (NL) | Octal 20 Input Registered And-Or-Xor Inveri Gate Array | $\begin{aligned} & \text { PAL20X8 } \\ & \text { HAL20X8 } \end{aligned}$ |  |  |  |
| 20X4 | 24 (28) | NS,JS,F,(L), (NL) | Quad 20 Input Registered And-Or-Xor Invert Gate Array | $\begin{aligned} & \text { PAL20X4 } \\ & \text { HAL20X4 } \end{aligned}$ |  |  |  |
| 20L8 | 24 (28) | NS, JS,F,(L), (NL) | Octal 20 Input And-Or-Invert Gate Array |  | $\begin{aligned} & \text { PAL20L8A } \\ & \text { HAL20L8A } \\ & \hline \end{aligned}$ |  |  |
| 20R8 | 24 (28) | NS, JS,F,(L), (NL) | Octal 20 Input Registered And-Or Invert Gate Array |  | $\begin{aligned} & \text { PAL20R8A } \\ & \text { HAL20R8A } \end{aligned}$ |  |  |
| 20R6 | 24 (28) | NS, JS,F,(L), (NL) | Hex 20 Input Registered And-Or Invert Gate Array |  | $\begin{aligned} & \text { PAL20R6A } \\ & \text { HAL20R6A } \end{aligned}$ |  |  |
| 20R4 | 24 (28) | NS, JS,F,(L), (NL) | Quad 20 Input Registered And-Or Invert Gate Array |  | $\begin{aligned} & \text { PAL20R4A } \\ & \text { HAL20R4A } \end{aligned}$ |  |  |

[^1]PAL Device Input/Output/Function/Performance Chart

| GENERIC LOGIC | PINS | PACKAGE | DESCRIPTION | PART NUMBER |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | STANDARD | HIGH SPEED | 1/2 POWER |  | POWER |
| *16P8 | 20 | N,J,L,NL | Octal 16 Input And-Or Array w/Programmable Polarity |  | PAL16P8A HAL16P8A | $18,7,6,14$ |  | aH0 |
| *16RP8 | 20 | N, J, L, NL | Octal 16 Input Registered <br> And-Or Array <br> w/Programmable Polarity | A.jugat | PAL16RP8A HAL16RP8A | 3.76, 14 |  | 4 HP |
| * 16RP6 | 20 | N,J,L,NL | Hex 16 Input Registered And-Or Array w/Programmable Polarity | Dind ${ }^{\text {a }}$ | PAL16RP6A HAL16RP6A | 1,7, L, 14 |  | 3Har |
| *16RP4 | 20 | N,J,L,NL | Quad 16 Input Registered And-Or Array w/Programmable Polarity | ntatugn | PAL16RP4A HAL16RP4A | , J,7,4, W |  | 3101 |
| 20S10 | 24 (28) | N,J,W, (L), (NL) | Deca 20 Input And-Or Array w/Product Term Sharing | -bns tur | $\begin{aligned} & \text { PAL20S10 } \\ & \text { HAL20S10 } \end{aligned}$ | 1.7.6.61 |  | Q1St |
| 20RS10 | 24 (28) | N, J, W, (L), (NL) | Deca 20 Input Registered And-Or Array w/Product Term Sharing | bra tug | PAL20RS10 <br> HAL20RS10 | 1.7.6.14 |  | B.at |
| 20RS8 | 24 (28) | N,J,W, (L), (NL) | Octal 20 Input Registered And-Or Array w/Product Term Sharing | -bma fugnt | PAL20RS8 HAL20RS8 | 4,7,6,4 187.681 |  | $8.8 r^{\prime}$ |
| 20RS4 | 24 (28) | N, J, W, (L), (NL) | Quad 20 Input Registered And-Or Array w/Product Term Sharing | ugs | PAL20RS 4 HAL20RS4 | -1.7.6.19 |  | Bnar |
| 20RA10 | 24 (28) | N, J,W, (L), (NL) | Deca 20 Input Registered Asynchronous And-Or Array | 6) hevs | $\begin{aligned} & \text { PAL20RA10 } \\ & \text { HAL20RA10 } \end{aligned}$ |  |  | (0) |
| 32R16 | 40 (44) | N, J, (L), (NL) | 16 Output, 32 Input Registered And-Or Gate Array | alb 2 favai | PAL32R16 HAL32R16 |  |  | Wrot |
| 64R32 | 84 (88) | L,(P) | 32 Output, 64 Input Registered And-Or Gate Array | $x \rightarrow 0-x$ | PAL64R32 <br> HAL64R32 | 1,7,6,64 |  | MAOT |

* Contact Factory for Flat Pack

Die Configuration: PAL16L8


## PAL/HAL Device



Notes: Apply to electrical and switching characteristics
$\dagger \mathrm{I} / \mathrm{O}$ pin leakage is the worst case of $\mathrm{I}_{\mathrm{OZX}}$ or $\mathrm{I}_{\mathrm{IX}}$ e.g., $\mathrm{I}_{\mathrm{IL}}$ and ${ }^{\mathrm{I}}{ }_{\mathrm{OZH}}$.

* These are absolute voltages with respect to the ground pin on the device and includes all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.




2




2

20RA10



## Operating Conditions

| SYMBOL | 6Y\% yuts | WAH $5 Y$ PAR | TER |  | LITA |  |  | MERC | IAL | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SYMBOL |  |  |  | MIN |  | MAX |  |  |  |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage |  |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | $\checkmark$ |
| ${ }^{T}$ A | Operating free-air temperature |  |  | -55 |  |  | 0 |  | 75 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{T} \mathrm{C}$ | Operating case temperature |  |  |  |  | 125 |  | 4140 |  | ${ }^{\circ} \mathrm{C}$ |

Electrical Characteristics Over Operating Condilions

| SYMBOL | PARAMETER | TEST CONDITIONS |  |  | MIN | TYP | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{IL}}{ }^{*}$ | Low-level input voltage |  |  |  |  |  | 0.8 | V |
| $\mathrm{V}_{1 H^{*}}{ }^{*}$ | High-level input voltage |  |  |  | 2 |  |  | V |
| $V_{\text {IC }}$ | Input clamp voltage | $V_{C C}=$ MIN | $I_{1}=-18 \mathrm{~mA}$ |  |  | -0.8 | -1.5 | V |
| IIL | Low-level input current | $V_{C C}=$ MAX | $\mathrm{V}_{1}=0.4 \mathrm{~V}$ |  |  | -0.02 | $-0.25$ | mA |
| $\mathrm{IIH}^{\text {H }}$ | High-level input current | $V_{C C}=$ MAX | $\mathrm{V}_{1}=2.4 \mathrm{~V}$ |  |  |  | 25 | $\mu \mathrm{A}$ |
| II | Maximum input current | $V_{C C}=M A X$ | $\mathrm{V}_{1}=5.5 \mathrm{~V}$ |  |  |  | 1 | mA |
| 4 | Low-level output voltage | $\mathrm{v}_{\mathrm{CC}}=\mathrm{MIN}$ | MIL | $\mathrm{I}^{\mathrm{OL}}=8 \mathrm{~mA}$ | 0.3 |  | 0.5 | V |
| $\mathrm{V}_{\mathrm{OL}}$ |  |  |  |  |  |  |  |  |
|  |  |  | COM | ${ }^{\prime} \mathrm{OL}=8 \mathrm{~mA}$ |  |  |  |  |
| $\mathrm{V}_{\mathrm{OH}}$ | High-level output voltage | $\mathrm{V}_{\mathrm{CC}}=\mathrm{MIN}$ | MIL | ${ }^{1} \mathrm{OH}=-2 \mathrm{~mA}$ | 2.4 | 2.8 |  | V |
|  |  |  | COM | ${ }^{1} \mathrm{OH}=-3.2 \mathrm{~mA}$ |  |  |  |  |
| ${ }^{\text {IOS }}$ | Output short-circuit current** | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | $\mathrm{v}_{\mathrm{O}}=0 \mathrm{~V}$ | -30 | -70 | -130 | mA |
| Icc | Supply current | $\mathrm{V}_{\mathrm{CC}}=\mathrm{MAX}$ |  |  |  | 55 | 90 | mA |

## Switching Characteristics

| SYMBOL | Ler | PARAMETER | TEST CONDITIONS | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | 08 |  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| ${ }^{\text {t P }}$ | Input or feedback to output | Except 16C1 | $\begin{aligned} & R 1=560 \Omega \\ & R 2=1.1 \mathrm{k} \Omega \end{aligned}$ |  | 25 | 45 |  | 25 | 35 | ns |
|  |  | 16C1 |  |  | 25 | 45 |  | 25 | 40 |  |



## Operating Conditions

| SYMBOI |  |  |  | LITAP |  |  | MERC |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SYMBOL | 3ncmatue | ETER | MIN | TYP | Max | MIN | TYP | Max | UNIT |
| ${ }^{\text {CC }}$ | Supply voltage |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
|  | Width of clock | Low | 20 | 7 |  | 15 | 7 |  |  |
| tw | Width of clock | High | 20 | 7 |  | 15 | 7 |  | ns |
|  | Set up time from |  |  |  |  |  |  |  |  |
| ${ }^{\text {tsu}}$ | input or feedback to clock | 20R8A 20R6A 20R4A |  | 15 |  |  | 15 |  | ns |
| $t_{h}$ | Hold time |  |  | -10 |  |  | -10 |  | ns |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature |  | -55 |  |  | 0 | * | 75 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{T} \mathrm{C}$ | Operating case temperature |  |  |  | 125 |  |  |  | ${ }^{\circ} \mathrm{C}$ |

## Electrical Characteristics Over Operating Conditions



## Switching Characteristics Over Operating Conditions

| SYMBOL | PARAMETER |  | TEST | MILITARY |  |  |  | MMER | IAL | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | CONDITIONS | MIN | TYP | MAX | MIN | TYP | MAX |  |
| ${ }^{\text {tPD }}$ | Input or feedback to output | 20R6A 20R4A 20L8A | $\begin{aligned} & R_{1}=200 \Omega \\ & R_{2}=390 \Omega \end{aligned}$ |  | 15 | 30 |  | 15 | 25 | ns |
| ${ }^{\text {t CLK }}$ | Clock to output or feedback |  |  |  | 10 | 20 |  | 10 | 15 | ns |
| ${ }^{\text {tP }}$ PX | Pin 13 to output enable except 20L8A |  |  |  | 10 | 25 |  | 10 | 20 | ns |
| ${ }^{\text {tPXZ }}$ | Pin 13 to output disable except 20L8A |  |  |  | 11 | 25 |  | 11 | 20 | ns |
| ${ }^{\text {t P }}$ PX | Input to output enable | 20R6A 20R4A 20L8A |  |  | 10 | 30 |  | 10 | 25 | ns |
| ${ }^{\text {t P P }}$ Z | Input to output disable | 20R6A 20R4A 20L8A |  |  | 13 | 30 |  | 13 | 25 | ns |
| ${ }^{\text {f MAX }}$ | Maximum frequency | 20R8A 20R6A 20R4A |  | 20 | 40 |  | 28.5 | 40 |  | MHz |

## Operating Conditions

| SYMBOL | PARAMETER | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | $\checkmark$ |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature | -55 |  |  | 0 |  | 75 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{T} \mathrm{C}$ | Operating case temperature |  |  | 125 |  |  |  | ${ }^{\circ} \mathrm{C}$ |

## Electrical Characteristics Over Operating Conditions



Switching Characteristics Over Operating Conditions

| SYMBOL |  | TEST CONDITIONS | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | CQ PARAMETER |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| ${ }^{\text {t PD }}$ | Input or feedback to output | $\begin{aligned} & \mathrm{R} 1=560 \Omega \\ & \mathrm{R} 2=1.1 \mathrm{k} \Omega \end{aligned}$ | 25 |  | 45 | 25 |  | 40 | ns |

Standard PAL/HAL Device Series 20

| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ${ }^{\text {tw }}$ | Width of clock | Low | 25 | 10 |  | 25 | 10 |  | ns |
|  |  | High | 25 | 10 |  | 25 | 10 |  |  |
| $\mathrm{t}_{\text {su }}$ | Set up time from input or feedback to clock | 16R8 16R6 16R4 | 45 | 25 | 183 | 35 | 25 |  | ns |
|  |  | 16X4 16A4 | 55 | 30 |  | 45 | 30 |  |  |
| $t_{\text {h }}$ | Hold time |  | 0 | -15 |  | 0 | -15 |  | ns |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature |  | -55 |  |  | 0 |  | 75 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{T} \mathrm{C}$ | Operating case temperature |  |  |  | 125 |  |  |  | ${ }^{\circ} \mathrm{C}$ |

## Electrical Characteristics Over Operating Conditions

| SYMBOL | PARAMETER |  | TEST CONDITIONS | MIN | TVP | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IL }}{ }^{*}$ | Low-level input voltage |  |  |  |  | 0.8 | V |
| $\mathrm{V}_{\text {IH }}{ }^{*}$ | High-level input voltage |  | thr | 2 | - |  | V |
| VIC | Input clamp voitage | $\mathrm{V}_{\mathrm{CC}}=\mathrm{MIN}$ | $I_{1}=-18 \mathrm{~mA}$ |  | -0.8 | -1.5 | V |
| IIL | Low-level input current $\dagger$ | $V_{C C}=$ MAX | $\mathrm{V}_{1}=0.4 \mathrm{~V}$ |  | -0.02 | -0.25 | mA |
| ${ }^{1} \mathrm{H}$ | High-level input current $\dagger$ | $V_{C C}=$ MAX | $V_{1}=2.4 \mathrm{~V}$ |  |  | 25 | $\mu \mathrm{A}$ |
| I | Maximum input current | $\mathrm{V}_{C C}=\mathrm{MAX}$ | $\mathrm{V}_{1}=5.5 \mathrm{~V}$ |  |  | 1 | mA |
| $\mathrm{V}_{\mathrm{OL}}$ | Low-level output voltage | $V_{C C}=\mathrm{MIN}$ | MIL ${ }^{\text {I }} \mathrm{OL}=12 \mathrm{~mA}$ |  | 0.3 | 0.5 | V |
|  |  |  | $\mathrm{COM} \quad \mathrm{IOL}=24 \mathrm{~mA}$ |  |  |  |  |
| VOH | High-level output voltage | $V_{C C}=$ MIN | MIL $\quad 1 \mathrm{OH}=-2 \mathrm{~mA}$ | 2.4 | 2.8 |  | V |
|  |  |  | $\mathrm{COM} \quad \mathrm{I}^{\prime} \mathrm{OH}=-3.2 \mathrm{~mA}$ |  |  |  |  |
| IOZL | Off-state output current $\dagger$ | $V_{C C}=M A X$ | $\mathrm{V}_{\mathrm{O}}=0.4 \mathrm{~V}$ |  |  | -100 | $\mu \mathrm{A}$ |
| ${ }^{1} \mathrm{OZH}$ |  |  | $\mathrm{V}_{\mathrm{O}}=2.4 \mathrm{~V}$ |  |  | 100 | $\mu \mathrm{A}$ |
| 'OS | Output short-circuit current** | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | -30 | -70 | -130 | mA |
| ${ }^{1} \mathrm{CC}$ | Supply current | $V_{C C}=M A X$ | 16R4 16R6 16R8 16L8 |  | 120 | 180 | mA |
|  |  |  | 16X4 |  | 160 | 225 |  |
|  |  |  | 16A4 |  | 170 | 240 |  |

## Switching Characteristics Over Operating Conditions

| SYMBOL | PARAMETER |  |  |  | TEST CONDITIONS | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| ${ }^{\text {P P }}$ P | Input or feed- 16R6 16R4 16L8 |  |  |  |  | $\begin{aligned} & R_{1}=200 \Omega \\ & R_{2}=390 \Omega \end{aligned}$ |  | 25 | 45 |  | 25 | 35 | ns |
|  | Input or feed- back to output | 16X4 | 16A4 |  |  |  | 30 | 45 |  | 30 | 40 | ns |
| ${ }^{\text {t CLK }}$ | Clock to output or feedback |  |  |  |  |  | 15 | 25 |  | 15 | 25 | ns |
| ${ }^{\text {tp }}$ PX | Pin 11 to output enable except 16L8 |  |  |  |  |  | 15 | 25 |  | 15 | 25 | ns |
| $t_{\text {tPXZ }}$ | Pin 11 to output disable except 16L8 |  |  |  |  |  | 15 | 25 |  | 15 | 25 | ns |
| ${ }^{\text {t }}$ PZX | Input to output enable | 16R6 | 16R4 | 16L8 |  |  | 25 | 45 |  | 25 | 35 | ns |
|  |  | 16X4 | 16A4 |  |  |  | 30 | 45 |  | 30 | 40 | ns |
| ${ }^{\text {t P P }}$ ( | Input to output disable | 16R6 | 16R4 | 16L8 |  |  | 25 | 45 |  | 25 | 35 | ns |
|  |  | 16X4 | 16A4 |  |  |  | 30 | 45 |  | 30 | 40 | ns |
| ${ }^{\text {f M M }}$ ( | Maximum frequency | 16R8 | 16R6 | 16R4 | 14 |  | 25 |  | 16 | 25 |  | MHz |
|  |  | 16X4 | 16A4 |  | 12 |  | 22 |  | 14 | 22 |  |  |

## Standard PAL/HAL Device Series 24

20X10, 20X8, 20X4, 20 L 10

## Operating Conditions



## Electrical Characteristics Over Operating Conditions

| SYMBOL | 4 PARAMETER | 2hartionce TEST CONDITIONS |  | H2 | MIN | TYP | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IL }}{ }^{*}$ | Low-level input voltage |  |  | 9 gas | Ight | -Wor | 0.8 | V |
| $\mathrm{V}_{\text {IH }}{ }^{*}$ | High-level input voltage |  |  | egadiov | 2 |  |  | V |
| $V_{\text {IC }}$ | Input clamp voltage | $V_{C C}=M I N$ | $I_{1}=-18 \mathrm{~mA}$ | 98 | $\checkmark$ V10 | -0.8 | -1.5 | V |
| IIL | Low-level input current $\dagger$ | $V_{C C}=$ MAX | $\mathrm{V}_{1}=0.4 \mathrm{~V}$ | lather | 401 | -0.02 | -0.25 | mA |
| $\mathrm{I}_{1} \mathrm{H}$ | High-level input current $\dagger$ | $V_{C C}=$ MAX | $V_{1}=2.4 \mathrm{~V}$ | nerua | $4{ }^{\text {a }}$ | dobl | 25 | $\mu \mathrm{A}$ |
| 1 | Maximum input current | $\mathrm{V}_{\mathrm{CC}}=\mathrm{MAX}$ | $\mathrm{V}_{1}=5.5 \mathrm{~V}$ |  |  |  | 1 | mA |
| VOL | Low-level output voltage | $\mathrm{V}_{C C}=\mathrm{MIN}$ | MIL | $\mathrm{I}^{\mathrm{OL}}=12 \mathrm{~mA}$ |  | 0.3 | 0.5 | V |
|  |  |  | COM | ${ }^{\prime} \mathrm{OL}=24 \mathrm{~mA}$ |  |  |  |  |
| $\mathrm{V}^{\mathrm{OH}}$ | High-level output voltage | $\mathrm{V}_{\mathrm{CC}}=\mathrm{MIN}$ | MIL | ${ }^{\prime} \mathrm{OH}=-2 \mathrm{~mA}$ | $2.4 \quad 2.8$ |  |  | $v$ |
|  |  |  | COM | ${ }^{1} \mathrm{OH}=-3.2 \mathrm{~mA}$ |  |  |  |  |
| ${ }^{\prime} \mathrm{OZL}$ | Off-state output current $\dagger$ | $V_{C C}=M A X$ |  | $\mathrm{V}_{\mathrm{O}}=0.4 \mathrm{~V}$ |  |  | -100 | $\mu \mathrm{A}$ |
| ${ }^{1} \mathrm{OZH}$ |  |  |  | $\mathrm{V}_{\mathrm{O}}=2.4 \mathrm{~V}$ |  |  | 100 | $\mu \mathrm{A}$ |
| ${ }^{\text {I O }}$ | Output short-circuit current** | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  | $\mathrm{V}_{\mathrm{O}}=0 \mathrm{~V}$ | -30 | -70 | -130 | mA |
| ${ }^{\text {I CC }}$ | Supply current | $V_{C C}=M A X$ | $20 \times 10$ 20×8 | 20X4 | Mup | 120 | 180 | mA |
| ${ }^{1} \mathrm{CC}$ | Supply current | $\mathrm{V}_{\text {CC }}=\mathrm{MAX}$ | 20 L 10 |  |  | 90 | 165 | mA |

## Switching Characteristics Over Operating Conditions

| SYMBOL | PARAMETER | TEST | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | CONDITIONS | MIN | TYP | MAX | MIN |  | MAX |  |
| ${ }^{\text {t P }}$ | Input or feedback to output | $\begin{aligned} & R_{1}=200 \Omega \\ & R_{2}=390 \Omega \end{aligned}$ |  | 35 | 60 |  | 35 | 50 | ns |
| ${ }^{\text {t CLK }}$ | Clock to output or feedback |  |  | 20 | 35 |  | 20 | 30 | ns |
|  | Pin 13 to output disable/enable except 20L10 |  |  | 20 | 45 |  | 20 | 35 | ns |
| ${ }^{\text {t P P X }}$ | Input to output enable except $20 \times 10$ |  |  | 35 | 55 |  | 35 | 45 | ns |
| ${ }^{\text {tPXZ }}$ | Input to output disable except $20 \times 10$ |  |  | 35 | 55 |  | 35 | 45 | ns |
| ${ }^{\text {f MAX }}$ | Maximum frequency |  | 10.5 | 16 |  | 12.5 | 16 |  | MHz |

Fast PAL/HAL Device Series 20A, 20AP
16L8A, 16R8A, 16R6A, 16R4A, 16P8A, 16RP8A, 16RP6A, 16RP4A
Operating Conditions

| SYMBOL | Xami w PARAMETER |  | Military |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX | MIN |  | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
| ${ }^{\text {t }}$ w | Width of clock | Low | 20 | 10 |  | 15 |  |  | ns |
|  |  | High | 20 | 10 |  | 15 | 10 |  |  |
| ${ }^{\text {tsu }}$ | Set up time from input or feedback to clock | 16R8A 16R6A 16R4A 16RP8A 16RP6A 16RP4A | 30 | 15 |  | 25 | 15 |  | ns |
| $t_{h}$ | Hold time |  | 0 | -10 |  | 0 | -10 |  | ns |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature |  | -55 |  |  | 0 |  | 75 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{T} \mathrm{C}$ | Operating case temperature |  |  |  | 125 |  |  |  | ${ }^{\circ} \mathrm{C}$ |

Electrical Characteristics Over Operating Conditions


Switching Characteristics Over Operating Conditions

|  | PARAMETER |  | TEST CONDITIONS | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX | MIN |  | MAX |  |
|  | Input or feed- | 16R6A 16R4A 16L8A |  | Tithos |  |  |  |  |  |  |  |
|  | back to output | 16RP6A 16RP4A 16P8A |  |  | 15 | 30 |  |  | 25 | ns |
| ${ }^{\text {t CLK }}$ | Clock to output or feedback |  |  |  | 10 | 20 |  | 10 | 15 | ns |
| ${ }^{\text {tP }}$ PX | Pin 11 to output | nable except 16L8A 16P8A |  |  | 10 | 25 |  | 10 | 20 | ns |
| tPXZ | Pin 11 to output | sable except 16L8A 16P8A |  |  | 11 | 25 |  | 11 | 20 | ns |
| ${ }^{\text {t }} \mathrm{PZX}$ | Input to output enable | 16R6A 16R4A 16L8A 16RP6A 16RP4A 16P8A |  |  | 10 | 30 |  | 10 | 25 | ns |
| ${ }^{\text {t PXX }}$ | Input to output disable | 16R6A 16R4A 16L8A 16RP6A 16RP4A 16P8A |  |  | 13 | 30 |  | 13 | 25 | ns |
| $f_{\text {IMAX }}$ | Maximum frequency | 16R8A 16R6A 16R4A 16RP8A 16RP6A 16RP4A | 20 |  | 40 | रon | 28.5 | 40 |  | MHz |

## Operating Conditions

| SYMBOL | 5 Fr |  | WCal PARAMETER |  |  | MILITARY |  |  | COMMERCIAL |  |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  | MIN | TYP | MAX |  | MIN | TYP | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage |  |  |  |  | 4.5 | 5 | 5.5 |  | 4.75 | 5 | 5.25 | $\checkmark$ |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature |  |  |  |  | -55 |  | 125 |  | 0 |  | 75 | ${ }^{\circ} \mathrm{C}$ |

## Electrical Characteristics Over Operating Condilions



## Switching Characteristics Over Operating Condilions

| SYMBOL | 15- OE- PARAMETER |  |  | LITAP |  |  | MER |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SYMBOL | - Parameter | TEST | MIN | TYP | MAX | MIN |  | MAX | UNIT |
| ${ }^{t} P D$ | Input or feedback to output | $\begin{aligned} & \mathrm{R} 1=1.12 \mathrm{k} \Omega \\ & \mathrm{R} 2=2.2 \mathrm{k} \Omega \end{aligned}$ | 45 |  | 80 | 45 |  | 60 | ns |

$\square$

Half-Power Series 20A-2
16L8A-2, 16 R8A-2, 16 R6A-2, 16R4A-2
Operating Conditions

|  |  |  |  |  |  | LITAR |  | CO | MER | IAL | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SYMBOL |  | ETER |  |  | MIN | TYP | MAX | MIN | TVP | MAX | UNIT |
| $\mathrm{v}_{\mathrm{CC}}$ | Supply voltage |  |  |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
|  | Width of clock | Low |  |  | 25 | 10 |  | 25 | 10 |  |  |
| w | Widt of clock | High |  |  | 25 | 10 |  | 25 | 10 |  |  |
| ${ }^{\text {t }}$ su | Set up time from input or feedback to clock | 16R6A-2 | 16R4A-2 | 16R8A-2 | 50 | 25 |  | 35 | 25 |  | ns |
| $t_{h}$ | Hold time |  |  |  |  |  | 125 | 0 0 |  | 75 | $\begin{array}{\|l} \mathrm{ns} \\ \hline{ }^{\circ} \mathrm{C} \\ \hline \end{array}$ |
| ${ }^{\text {T }}$ A | Operating free-air temperature |  |  |  | -55 |  |  |  |  |  |  |

## Electrical Characteristics Over Operating Condilions



Switching Characteristics Over Operating Condilions

|  | PARAMETER |  | TEST | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SYMBOL |  |  | CONDITIONS | MIN | TYP | MAX | MIN | TYP | MAX |  |
| ${ }^{\text {t PD }}$ | Input or feedback to output | 16L8A-2 16R6A-2 16R4A-2 | $\mathrm{R}_{1}=200 \Omega$ |  | 25 | 50 |  | 25 | 35 | ns |
| ${ }^{\text {t CLK }}$ | Clock to output or feedback |  |  |  | 15 | 25 |  | 15 | 25 | ns |
| tpxz/ZX | Pin 11 to output disable/enable except 16L8A-2 |  |  |  | 15 | 25 |  | 15 | 25 | ns |
| ${ }^{\text {tPZX }}$ | Input to output enable | 16L8A-2 16R6A-2 16R4A-2 | $R_{2}=390 \Omega$ |  | 25 | 45 |  | 25 | 35 | ns |
| ${ }^{\text {tPXZ }}$ | Input to output disable | 16R8A-2' 16R6A-2 16R4A-2 |  |  | 25 | 45 |  | 25 | 35 | ns |
| ${ }^{\text {f MAX }}$ | Maximum frequency | 16R8A-2 16R6A-2 16R4A-2 |  | 14 | 25 |  | 16 | 25 |  | MHz |

## Operating Conditions

| SYMBOL | AISM What ysh PARAMETER |  |  | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage |  |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
| ${ }^{\text {t }}$ w | Width of clock | 16R8A-4 16R6A-4 16R4A-4 | Low | 40 | 20 |  | 30 | 20 |  | ns |
|  |  |  | High | 40 | 20 |  | 30 | 20 |  |  |
| ${ }^{\text {t }}$ su | Set up time from input or feedback to clock | 16R8A-4 16R6A-4 16R4A-4 |  | 90 | 45 | frowe |  | 45 |  | ns |
| $t^{\prime}$ | Hold time | 18. |  | 0 | -15 |  | 0 | -15 |  | ns |
| $\mathrm{T}_{\text {A }}$ | Operating free-air tempera |  |  | -55 |  | 125 | 0 |  | 75 | ${ }^{\circ} \mathrm{C}$ |

Electrical Characteristics Over Operating Conditions


Switching Characteristics Over Operating Condillons

| SYMBOL | PARAMETER |  | TEST | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| ${ }^{\text {tPD }}$ | Input or feedback to output | 16R6A-4 16R4A-4 16L8A-4 |  | $\begin{aligned} & R_{1}=800 \Omega \\ & R_{2}=1.56 \mathrm{k} \Omega \end{aligned}$ |  | 35 | 75 | no | 35 | 55 | ns |
| ${ }^{\text {t CLK }}$ | Clock to output or feedback |  |  |  | 20 | 45 |  | 20 | 35 | ns |
| ${ }^{\text {t PXXZ/ZX }}$ | Pin 11 tooutput disable/enable-except 16L8A-4 |  |  |  | 15 | 40 |  | 15 | 30 | ns |
| ${ }^{\text {t }}$ PZX | Input to output enable | 16R6A-4 16R4A-4 16L8A-4 |  |  | 30 | 65 | 4 | 30 | 50 | ns |
| ${ }^{\text {tP }}$ PXZ | Input to output disable | 16R6A-4 16R4A-4 16L8A-4 |  |  | 30 | 65 |  | 30 | 50 | ns |
| ${ }^{\text {f MAX }}$ | Maximum frequency | 16R8A-4 16R6A-4 16R4A-4 | 8 |  | 18. | Fre | 111 | 18 |  | MHz |



## Electrical Characteristics Over Operating Conditions

| SYMBOL | PARAMETER | TEST CONDITION |  |  | MIN | TYP | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $V_{\text {IL }}{ }^{\text {* }}$ | Low-level input voltage | Vea $=1 \mathrm{~V}$ | $0 \times 4=0+1$ |  |  |  | 0.8 | V |
| $\mathrm{V}_{\text {IH }}{ }^{\text {* }}$ | High-level input voltage |  |  |  | 2 |  |  | V |
| $V_{\text {IC }}$ | Input clamp voltage | $\mathrm{V}_{\text {CC }}=\mathrm{MIN}$ | $\mathrm{I}_{1}=-18 \mathrm{~mA}$ |  |  | -0.8 | -1.5 | V |
| IIL | Low-level input current | $V_{C C}=$ MAX | $\mathrm{V}_{1}=0.4 \mathrm{~V}$ |  |  | -0.02 | -0.25 | mA |
| $\mathrm{IIH}^{\text {H }}$ | High-level input current | $\mathrm{V}_{\text {CC }}=$ MAX | $\mathrm{V}_{1}=2.4 \mathrm{~V}$ |  |  |  | 25 | $\mu \mathrm{A}$ |
| II | Maximum input current | $V_{C C}=M A X$ | $\mathrm{V}_{1}=5.5 \mathrm{~V}$ |  |  |  | 1 | mA |
| $\mathrm{V}_{\mathrm{OL}}$ | Low-level output voltage | $\mathrm{V}_{\text {CC }}=\mathrm{MIN}$ | $\mathrm{I}_{\mathrm{OL}}=8 \mathrm{~mA}$ |  |  | 0.3 | 0.5 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | High-level output voltage | $V_{C C}=\mathrm{MIN}$ | $\mathrm{I}^{\mathrm{OH}}$ : Mil-2 mA | 2 mA | 2.4 | 2.8 |  | V |
| ${ }^{\text {IOZ }}$ | Off-state output current | $\mathrm{V}_{\mathrm{CC}}=\mathrm{MAX}$ | $\mathrm{V}_{\mathrm{O}}=2.4 \mathrm{~V} / \mathrm{V}_{\mathrm{O}}$ |  | -100 |  | 100 | $\mu \mathrm{A}$ |
| Ios | Output short-circuit current** | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ |  |  | -30 | -70 | -130 | mA |
| ${ }^{\text {I CC }}$ | Supply current | $\mathrm{V}_{\text {CC }}=\mathrm{MAX}$ |  |  |  | 155 | 200 | mA |

Switching Characteristics Over Operating Conditions

| SYMBOL | PARAMETER |  | TEST CONDITIONS | MILITARY MIN TYP MAX |  | COMMERCIAL MIN TYP MAX |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ${ }^{\text {t PD }}$ | Input or feedback to output | Polarity fuse intact | $\begin{aligned} & R_{1}=560 \Omega \\ & R_{2}=1.1 \mathrm{~K} \Omega \end{aligned}$ | 20 | 35 |  | 20 | 30 | ns |
|  |  | Polarity fuse blown |  | 25 | 40 |  | 25 | 35 |  |
| ${ }^{\text {t CLK }}$ | Clock to output or feedback |  |  | $10 \quad 17$ | 35 | 10 | 17 | 30 | ns |
| ${ }^{\text {ts }}$ | Input to asynchronous set |  |  | 22 | 40 |  | 22 | 35 | ns |
| ${ }^{\text {t }}$ R | Input to asynchronous reset |  |  | 27 | 45 |  | 27 | 40 | ns |
| ${ }^{\text {t P P X }}$ | Pin 13 to output enable |  |  | 10 | 25 |  | 10 | 20 | ns |
| ${ }^{\text {tPXZ }}$ | Pin 13 to output disable |  |  | 10 | 25 |  | 10 | 20 | ns |
| ${ }^{\text {t P }}$ PX | Input to output enable |  |  | 18 | 35 |  | 18 | 30 | ns |
| ${ }^{\text {t PXZ }}$ | Input to output disable |  |  | 15 | 35 |  | 15 | 30 | ns |
| ${ }^{\text {f MAX }}$ | Maximum frequency |  |  | $16 \quad 35$ |  | 20 | 35 |  | MHz |

SERIES 24RS, 20S10, 20RS10, 20RS8, 20RS4

## Operating Conditions

|  | Whan yur yaly PARAMETER | yaly PARAMETER |  | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SYMBOL |  |  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage | N |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
| ${ }^{\text {tw }}$ | Width of clock | Low |  | 20 | 10 |  |  | 10 |  | ns |
|  |  | High | (18) | 20 | 10 |  | 15 | 10 |  |  |
|  | Setup time from input or feedback to clock | 20RS10 |  |  |  | Winw | What | - |  | r |
| ${ }^{\text {tsu }}$ |  | $\begin{aligned} & \text { 2RRS8 } \\ & \text { 20RS4 } \end{aligned}$ | hashleatiy |  | 25 |  | $35$ |  |  | ns |
| $t_{h}$ | Hold time |  |  | 0 | -10 |  | 0 |  |  | ns |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature |  |  | -55 |  |  |  |  | 75 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{\text {T }}$ C | Operating case temperature |  |  |  |  | 125 |  |  |  | ${ }^{\circ} \mathrm{C}$ |

## Electrical Characteristics Over Operating Condititons



## Switching Characteristics Over Operating Conditions



PAL 32R16 HAL 32R16

Operating Conditions

| SYMBOL | TIOREMALSOS 4gyo yive | PARAMETER |  | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| $\mathrm{V}_{\mathrm{CC}}$ | Supply voltage |  |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
| $t_{w}$ | Width of cloc | T | Low | 25 |  |  | 20 |  |  | ns |
|  |  |  | High | 25 |  |  | 20 |  |  |  |
| ${ }_{\text {twp }}$ | Preload pulse width |  |  | 45 |  |  | 35 |  |  | ns |
| $t_{s u}$ | Setup time for input to clock |  | Polarity fuse intact | 50 |  | Houl | 40 |  |  | ns |
|  |  |  | Polarity fuse blown | 50 |  |  | 40 |  |  |  |
| $\mathrm{t}_{\text {sup }}$ | Preload setup |  |  | 30 |  |  | 25 |  |  | ns |
| $t_{h}$ | Hold time |  |  | 0 | -10 |  | 0 | -10 |  | ns |
| thp | Preload hold |  |  | 10 |  |  | 5 |  |  | ns |
| $\mathrm{T}_{\text {A }}$ | Operating fre | perature | ancilban | -55 |  | 3148 | 0 | Sris | 185 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{T} C$ | Operating ca | rature | 10, |  |  | 125 | 48 |  |  | ${ }^{\circ} \mathrm{C}$ |

Electrical Characteristics Over Operating Conditions

| SYMBOL | PARAMETER |  | TEST CONDITION | MIN TYP MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {IL }}{ }^{\text {* }}$ | Low-level input voltage |  |  | 0.8 | V |
| $\mathrm{V}_{1 \mathrm{IH}^{*}}$ | High-level input voltage |  | VAM年 | 2 | V |
| $V_{\text {IC }}$ | Input clamp voltage | $\mathrm{V}_{\mathrm{CC}}=\mathrm{MIN}$ | $I_{1}=-18 \mathrm{~mA}$ | -0.8-1.5 | $\checkmark$ |
| IIL | Low-level input current | $V_{C C}=M A X$ | $\mathrm{V}_{1}=0.4 \mathrm{~V}$ | -0.02-0.25 | mA |
| $\mathrm{IIH}^{\text {H }}$ | High-level input current | $V_{C C}=M A X$ | $\mathrm{V}_{1}=2.4 \mathrm{~V}$ | 25 | $\mu \mathrm{A}$ |
| 1 | Maximum input current | $V_{C C}=M A X$ | $\mathrm{V}_{1}=5.5 \mathrm{~V}$ | alaval trit 1 | mA |
|  | Low-level output voltage |  | MIL IOL | 0.30 .5 | V |
| OL | Low-level output voltage | $\checkmark$ | COM IO | $0.3-0.5$ |  |
| $v$ | High-leve |  | MIL I | 8 |  |
| OH |  |  | COM I | 2.8 |  |
| IOZL | tate output current |  |  | -100 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{OZH}}$ | c | CC $=$ MAX | damogo | (5) 100 | $\mu \mathrm{A}$ |
| Ios | Output short-circuit current** | $V_{C C}=M A X$ |  | $\begin{array}{lll}-30 & -70 & -130\end{array}$ | mA |
| ${ }^{1} \mathrm{CC}$ | Supply current | $V_{C C}=M A X$ |  | 200280 | mA |

Switching Characteristics over Operatling Condlltons


## PAL/HAL64R32

## Operating Conditions

| SYMBOL | Whatamas Parameter |  | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| SYMBOL |  |  | MIN |  | MAX |  | TYP | MAX |  |
| $\mathrm{v}_{\mathrm{CC}}$ | Supply voltage |  | 4.5 | 5 | 5.5 | 4.75 | 5 | 5.25 | V |
| ${ }^{t}$ w | Width of clock | Low | 25 |  | 9 mit |  | sola |  | ns |
|  |  | High |  |  |  |  | scla |  | ns |
| ${ }^{\text {tsu }}$ | Setup time for input to clock | Polarity fuse intact | 50 |  |  |  | 989 |  | ns |
|  |  | Polarity fuse blown |  |  | amif |  | - |  | col |
| th | Hold time |  | 0 | -10 |  | 0 | -10 |  | ns |
| $\mathrm{T}_{\text {A }}$ | Operating free-air temperature |  | -55 |  |  | 0 |  | 75 | ${ }^{\circ} \mathrm{C}$ |
| ${ }^{T} \mathrm{C}$ | Operating case temperature |  |  |  | 125 |  |  |  | ${ }^{\circ} \mathrm{C}$ |

Electrical Characteristics Over Operating Conditions

| SYMBOL | PARAMETER | TEST CONDITION |  |  | MIN | TYP M | MAX | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $V_{\text {IL }}$ * | Low-level input voltage |  |  |  |  |  | 0.8 | V |
| $\mathrm{V}_{1 \mathrm{H}^{*}}$ | High-level input voltage |  |  |  | 2 |  |  | V |
| $\mathrm{V}_{\text {IC }}$ | Input clamp voltage | $\mathrm{V}_{\text {CC }}=\mathrm{MIN}$ | $\mathrm{I}_{1}=-$ | mA |  | -0.8 | -1.5 | V |
| IIL | Low-level input current | $V_{C C}=M A X$ | $V_{1}=0$ |  |  | -0.02- | -0.25 | mA |
| ${ }^{1} \mathrm{IH}$ | High-level input current | $V_{C C}=M A X$ | $V_{1}=2$ |  |  |  | 25 | $\mu \mathrm{A}$ |
| 1 | Maximum input current | $V_{C C}=M A X$ | $\mathrm{V}_{1}=5.5$ |  |  |  | 1 | mA |
|  |  |  | MIL | $\mathrm{I}^{\mathrm{OL}}=8 \mathrm{~mA}$ |  | 03 | 5 | V |
| V | Low-level output voltage | ${ }^{\text {CC }}$ | COM | $\mathrm{I}_{\mathrm{OL}}=8 \mathrm{~mA}$ |  |  |  | $\checkmark$ |
|  | High-level output voltage |  | MIL | ${ }^{\mathrm{I}} \mathrm{OH}=-0.4 \mathrm{~mA}$ | 2.4 | 28 |  | v |
| V | High-ievel output voltage | ${ }^{\text {CC }}=\mathrm{MIN}$ | COM | $\mathrm{I}^{\mathrm{OH}}=-0.4 \mathrm{~mA}$ | 2.4 | 2.8 |  | $v$ |
| IOZL | Off-state output current | $V_{C C}=$ MAX |  | $\mathrm{V}_{\mathrm{O}}=0.4 \mathrm{~V}$ |  |  | -100 | $\mu \mathrm{A}$ |
| ${ }^{1} \mathrm{OZH}$ | Or-state output current | $\mathrm{VCC}^{\text {- MAX }}$ |  | $\mathrm{V}_{\mathrm{O}}=2.4 \mathrm{~V}$ |  |  | 100 | $\mu \mathrm{A}$ |
| los | Output short-circuit current** | $V_{C C}=M A X$ |  | $\mathrm{V}_{\mathrm{O}}=0 \mathrm{~V}$ | -10 | -40 | -60 | mA |
| ${ }^{1} \mathrm{CC}$ | Supply current | $V_{C C}=$ MAX |  |  |  | 400 | 640 | mA |

Switching Characteristics Over Operating Conditions

| SYMBOL | PARAMETER |  | TEST CONDITIONS | MILITARY |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ${ }^{\text {t }} \mathrm{PD}$ | Input to output | Polarity fuse intact | $\begin{gathered} R_{1}=560 \Omega \\ R_{2}=1.1 \mathrm{~K} \Omega \end{gathered}$ |  | 55 |  |  | 50 | ns |
|  |  | Polarity fuse blown |  |  | 60 |  |  | 55 |  |
| ${ }^{\text {t }}$ CLK | Clock to output or feedback |  |  |  | 30 |  |  | 22 | ns |
| tpZX | Output enable |  |  |  | 35 |  |  | 30 | ns |
| tpxZ | Output disable |  |  |  | 35 |  |  | 30 | ns |
| ${ }_{\text {t PR }}$ | Preset to output |  |  |  | 40 |  |  | 35 | ns |
| ${ }^{\text {f MAX }}$ | Maximum frequency |  |  | 12.5 |  | 16 | 20 |  | MHz |

## Testing Conditions

| SYMBOL |  | PARAMETER |  | MILITARY |  |  | COMMERCIAL |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | MIN | TYP | MAX | MIN | TYP | MAX |  |
| ${ }_{\text {t }}^{\text {wp }}$ | Preload pulse width |  |  | 45 |  |  | 35 | 109 |  | ns |
| $t_{\text {sup }}$ | Preload setup time |  | 10 | 60 |  |  | 50 |  |  | ns |
| $t_{\text {thp }}$ | Preload hold time |  |  | 10 |  |  | 5 |  |  | ns |
| tPRW | Preset pulse width |  | loskh maut virsitit | 30 |  |  | 25 |  |  | ns |
| tPRR | Preset recovery time |  | nurame sum | 40 |  |  | 35 |  |  | ns |



Switching Waveforms


## Output Register PRELOAD Series 20AP

The PRELOAD function allows the register to be loaded from data placed on the output pins. This feature aids functional testing which would otherwise require a state sequencer for test coverage. The procedure for PRELOAD is as follows:
1 Raise $\mathrm{V}_{\mathrm{CC}}$ to 4.5 V .
2 Disable output registers by setting pin 11 to $\mathrm{V}_{\mathrm{IH}}$.
3 Apply $\mathrm{V}_{\mathrm{IL}} / \mathrm{V}_{\mathrm{IH}}$ to all output registers.
4 Pulse pin 8 to $V_{p}$. Then back to 0 V .
5 Remove $\mathrm{V}_{I L} / \mathrm{V}_{\mathrm{IH}}$ from all output registers.
6 Lower pin 11 to $V_{\text {IL }}$ to enable the output registers.
7 Verify for $\mathrm{V}_{\mathrm{OL}} / \mathrm{V}_{\mathrm{OH}}$ at all output registers.

## Output Register PRELOAD Series 24RS

The PRELOAD function allows the register to be loaded from data placed on the output pins. This feature aids functional testing which would otherwise require a state sequencer for test coverage. The procedure for PRELOAD is as follows:
1 Raise $\mathrm{V}_{\mathrm{CC}}$ to 4.5 V .
2 Disable output registers by setting pin 13 to $\mathrm{V}_{\mathrm{IH}}$.
3 Apply $\mathrm{V}_{\mathrm{IL}} / \mathrm{V}_{\mathrm{IH}}$ to all cutput registers.
4 Pulse pin 10 to $V_{p}$. Then back to 0 V .
5 Remove $\mathrm{V}_{I L} / \mathrm{V}_{1 \mathrm{H}}$ from all output registers.
6 Lower pin 13 to $\mathrm{V}_{\text {IL }}$ to enable the output registers.
7 Verify for $\mathrm{V}_{\mathrm{OL}} / \mathrm{V}_{\mathrm{OH}}$ at all output registers.



PAL/HAL Device Logic Diagram




PAL/HAL Device Logic Diagram


10L8


$16 \mathrm{L8}$
1








PAL/HAL Device Logic Diagram

$2-42$





12 L 10







1

$20 L 8$


2-54



PAL/HAL Device Logic Diagram
20R4


$20 \times 8$



20RA10


2
$20 S 10$





PAL/HAL Logic Circuit Diagram 32R16

## Logic Diagram and Pinout for 84-Pin PLCC and 88-Pin-Grid-Array



PAL/HAL Logic Circuit Diagram 64R32

Logic Diagram and Pinout for 84-Pin PLCC and 88-Pin-Grid-Array 84 PIN PLCC


| VENDOR | MegaPAL'* | PAL20RA10 | PAL24RS | PAL20 | PAL24 | PAL24A |
| :--- | :---: | :---: | :---: | :--- | :--- | :--- |
| Data I/O | -Logic PAK <br> (32R16 only) | -Logic PAK | -Logic PAK | -Logic PAK | -Logic PAK | -Logic PAK |
| Kontron | - | - | - | -EEP 80* <br> PAL Adapter | -EEP 80 <br> PAL Adapter | -EEP 80 <br> PAL Adapter |
| Structured <br> Design | - | - | - | -SD 1000 | -SD 1000 | -SD 1000 |
| Stag | - | - | - | - ZL30 | -ZL30 | -ZL30 |
| Varix | Omni <br> Programmer | - | - | -Omni* <br> Programmer | -Omni <br> Programmer | -Omni <br> Programmer |
| Valley Data <br> Sciences | - | - | - | -Model 160 | -Model 160 | -Model 160 |
| Storey Systems | - | - | - | -P240* | -P240 | -P240 |
| Digelec | - | - | - | -UP803** | -UP803 | -UP803 |

* Except 16P8A, 16RP8A, 16RP6A, 16RP4A

MegaPAL ${ }^{\text {T }}$ is a trademark of Monolithic Memories.

The above chart represents those units which, at the time of printing, have been submitted to Monolithic Memories for evaluation and have demonstrated the capability to satisfactorily program the indicated devices.

## Die Configuration

PAL20RA10


Die Configuration

PAL32R16


2

PAL64R32




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## ****************** <br> FALASM Version 2.0 <br> ******************

Please wait, PALASM2 Syntax Checking.
PALASM FRONTEND, VZ. 06 - BETA RELEASE (C) - COPYRIGHT MONOLITHIC MEMORIES INC, 1984

Source file name [default: specs.dat] : BGATESP.RDS Frocessing BGATESF. FDS
Create error file [default: No]?
No error file created
Echo Palasm Design File to terminal [default: No]? Flease wait, XPLOT \& JEDEC File Generation.

PALASM XPLUT, VZ.06 - BETA RELEASE
(C) - COPYRIGHT MONOLITHIC MEMORIES INC., 1984

Equation being processed is for output $=\Rightarrow \ggg>$ Equation being processed is for output $==\gg \mathrm{E}$ Equation being processed is for output $==\gg \mathrm{H}$ Equation being processed is for output $==\gg \mathrm{L}$ Equation being processed is for output $==\ggg \gg$ Equation being processed is for output $=\Rightarrow>\mathrm{R}$
The fuseplot is stored in $====$ BGATESP. . xpt
The jedec is stored in $===>$ BGATESP. jed
All done!




ENTER A HIGHLIGHTED CHARACTER $>F$




ENTER MENU COMMAND $>L$
ENTER MENU COMMAND $>Q$

PAL Device Design Specification


## SImulation

TRACE ON A B C DEFGHIJKLMNPQRS
SETFACDFGJKMNPO
SETF /A $/ \mathrm{C} / \mathrm{F} / \mathrm{J} / \mathrm{M} / \mathrm{F}$
$\operatorname{SETF} / \mathrm{D} / \mathrm{G} / \mathrm{K} / \mathrm{N} / \mathrm{Q}$

Simulation Results
Page: 1
Gggg
A HLLL
B LHHH
C
DLLH
D HHLL
E HLLL
F HLLH
G HHLL
H HHLH
I XXXX
J HLLH
K HHLL
L LHHH
M HLLH
N HHLL
P HLLH
Q HHLL
R LHLH
S LLHL

## XPLOT Output

Title : Basic Gates (Negative Logic)
Pattern :
Revision : A
Author : A G Gilbert
Date : Monolis
PAL12P6
BASIC_GATES
$123 \quad 111111111122222222 \quad 2233$
000000000000000000000000000000000 100000000000000000000000000000000 00000000000000000000000000000000 000000000000000000000000000000000 400000000000000000000000000000000
 700000000000000000000000000000000

8 ---- --x- --00 --00 --00 --00 $----\quad---$ XXXX XxxX XXOO XXOO XXOO XXOO XXXX XXXX 1 XXXX XXXX XXOO XxOO XXOO XXOO XXXX XXXX $\begin{array}{llllll}11 & \text { xxxx } \\ 120000 & 0000 & 0000 & 0000 & 0000 & 0000 \\ 00000 & 0000\end{array}$ 13000000000000000000000000000000000 1400000000000000000000000000000000


16 ---x ---- --0 --00 --00 $--\infty 0$-.-- --| 17 | $-\mathrm{X}--$ | $-\overline{-1}$ | -000 | -000 | -00 | --00 | $-0-0$ |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| 18 | 0000 | 0000 | 0000 | 0000 | 0000 | 0000 | 0000 |
| 0000 |  |  |  |  |  |  |  | 1900000000000000000000000000000000 2000000000000000000000000000000000 2100000000000000000000000000000000 2200000000000000000000000000000000 2300000000000000000000000000000000

 $\begin{array}{lllllll}25 & \text { XXXX XXXX } & \text { XXOO } \\ 26 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 \\ 00000 & 0000\end{array}$
 $\begin{array}{llllllllll}27 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 \\ 28 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000\end{array}$ 2900000000000000000000000000000000 3000000000000000000000000000000000 3100000000000000000000000000000000
32 ---- ---- --00 x-00 --00 --00 ---- ----
$\begin{array}{llllll}33 & -1-- & -0-0 & -00 & --00 & x-00 \\ 34 & -0000 & -000 & ---0\end{array}$ 3500000000000000000000000000000000
 $\begin{array}{llllllllll}36 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 \\ 37 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000\end{array}$ 3800000000000000000000000000000000 3900000000000000000000000000000000

40 - $\qquad$ ---- --0 --00 --00 x-00 x--
 4200000000000000000000000000000000 4300000000000000000000000000000000 4400000000000000000000000000000000 $\begin{array}{lllllllll}45 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 \\ 46 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000\end{array}$ $\begin{array}{lllllllll}46 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000 & 0000\end{array}$


PAL Device Design Specification
Title
Pattern
Revision
Author
Compan
Date
4-16DEC. PDS
Mehrnaz Hada
Monolithic Memories, Santa Clara, CA
CHIP Decoder PAL6Ll6

EQUATIONS

|  | , |  |
| :---: | :---: | :---: |
| Q1 | /D*/C*/B* | En |
| Q2 | /D*/C* B*/A* | EN |
| 123 | $=/ D * / C * B * A *$ | EN |
| Q4 | $=/ D * C * / B * / A$ | ENI* |
| 1Q5 | $=/ D * C * / B * A *$ | EN |
| 186 | /D* C* B*/A* | EN |
| 187 | $=/ D^{*} C^{*} B^{*} A^{*}$ | EN |
| Q8 | D*/C*/B*/A* | EN |
| 189 | $\mathrm{D} * / \mathrm{C} * / \mathrm{B} *$ | EN |
| 1810 | D / / $\mathrm{C}^{*} \mathrm{~B}$ / / A * | ENI |
| 1 Q11 | $\mathrm{D} * / \mathrm{C*} \mathrm{~B}^{*} \mathrm{~A}$ * | EN1 |
| /Q12 | D* C*/B* |  |
| Q13 | D* C*/B* | EN2 |
| 14 | D* C* B */A* | EN1 |
|  | D* C* B* |  |

Q15 = D* C* B*A* EN1* EN2
simulation



The 4 to 16 decoder, decodes four binary decoded inputs into one of 16 mutually exclusive outputs, whenever the itwo enable lines EN1 and EN2 are high. When one or both ;of the enable lines are low the outputs are all set to ;high values.

## Simulation Results meisoct osival 1 an

Page : 1

|  | gggggggggg gg |
| :---: | :---: |
| D | LLLLHLLLLL LL |
| B | LLHHHHHLLL LL |
| c | LLLHHHLLLL LL |
| A | LHHHHHHHLL LL |
| Q 0 | LHHHHHHHLL HH |
| Q1 | HL-HHHHHLTH HH |
| Q2 | HHHHHHHHHH HH |
| Q3 | HHLHHHLHHH HH |
| Q 4 | HHHHHHHHHH HH |
| Q5 | ННННННнHHH HH |
| Q6 | HHHHHHHHHH HH |
| Q7 | HHHLHLHHHH HH |
| Q8 | нннннннннн нН $^{\text {H }}$ |
| Q9 | ННННННHHHH HH |
| Q10 | HHHHHHHHHH HH |
| Q11 | HHHHHHHHHH HH |
| Q12 | HHHHHHHHHH HH |
| Q13 |  |
| Q14 | нНнНННННН ${ }^{\text {HH }}$ |
| Q15 | HHHHLHHHHH HH |

## XPLOT Output



## Logic Symbol

## $\begin{array}{ll}\text { Fitle } & \text { PC I/O Mappe } \\ \text { Pattern MemIO.pds }\end{array}$ <br> Revision M A IO.pds Author A

Author A G Gilbert
Company Monolithic Memories Inc., Santa Clara, $C A$
Date
Personal computers which are hardware compatible with the ubiquitous IBM PC share this I/O map.
CHIP PC IO PALSL14
NC NC A9 A8 A7 AG A5 A4 A3 AEN /CSMONOCHRMAD GND /CSRS232AD/CSNMIMKR
/CSGMMEIOAD /CSCOLORAD /CSPRINTERAD /CS5FLOPPYAD / CSSDMAPGRG /CSPPICHIP /CSTIMERCHIP /CSINTCCHIP / CSDMACCHIP VCC

| Equations |  |
| :---: | :---: |
| CSDMACCHIP | $\begin{aligned} & =/ \mathrm{A} 9 * / \mathrm{AB} * / \mathrm{A} 7 * / \mathrm{A} 6 * / \mathrm{A} 5 \\ & * / \mathrm{A} 4 / \mathrm{AEN} \end{aligned}$ |
| CSINTCCHIP | $\begin{aligned} & =/ \mathrm{A} 9 \star / \mathrm{A} 8 * / \mathrm{A} 7 * / \mathrm{A} 6 * \mathrm{~A} 5 \\ & * / \mathrm{A} 4 * / \mathrm{A} 3 * / \mathrm{AEN} \end{aligned}$ |
| CSTIMERCHIP | $\begin{aligned} & =/ \mathrm{A} 9 * / \mathrm{A} 8 * / \mathrm{A} 7 * \mathrm{~A} 6 * / \mathrm{A} 5 \\ & * / \mathrm{A} 4 * / \mathrm{A} 3 * / \mathrm{AEN} \end{aligned}$ |
| CSPPICHIP $=$ | $\begin{aligned} & =/ \mathrm{A} 9 * / \mathrm{A} 8 * / \mathrm{A} 7 * \mathrm{~A} 6 * \mathrm{~A} 5 \\ & * / \mathrm{A} 4 * / \mathrm{A} 3 * / \mathrm{AEN} \end{aligned}$ |
| CSDMAPGRG $=$ | $=/ \mathrm{A} 9 * / \mathrm{A} 8 \star \mathrm{~A} 7 * / \mathrm{A} 6 * / \mathrm{A} 5$ <br> */A4*/A3*/AEN |
| CSMMIMKRG $=$ | $=/ \mathrm{A} 9 * / \mathrm{A} 8 * \mathrm{~A} 7 * / \mathrm{A} 6 * \mathrm{~A} 5$ |
| CSRS232AD $=$ | $\begin{aligned} & =\mathrm{A} 9 \star \mathrm{~A} 8 * \mathrm{~A} 7 \star \mathrm{~A} 6 * \mathrm{~A} 5 \\ & * \mathrm{~A} 4 * \mathrm{~A} 3 * / \mathrm{AEN} \end{aligned}$ |
| CS5FLOPPYAD | $\begin{aligned} D & =A 9 \star A 8 \star A 7 \star A 6 \star A 5 \\ & * A 4 * / A 3 * / A E N \end{aligned}$ |
| SPRINTERAD | $\begin{array}{rl} \mathrm{D} & =\mathrm{A} 9 \star / \mathrm{A} 8 * / \mathrm{A} 7 * \mathrm{~A} 6 * \mathrm{~A} 5 \\ * & \mathrm{~A} 4 * \mathrm{~A} 3 \star / \mathrm{AEN} \end{array}$ |
| CSCOLORAD $=$ | $\begin{aligned} & =\mathrm{A} 9 * \mathrm{AB} 8 \mathrm{~A} 7 * \mathrm{~A} 6 * / \mathrm{A} 5 \\ & * \mathrm{~A} 4 * / \mathrm{AEN} \end{aligned}$ |
| CSGAMEIOAD | $\begin{aligned} & =\mathrm{A} 9 * / \mathrm{AB} \% / \mathrm{A} 7 * / \mathrm{A} * / \mathrm{A} 5 \\ & * / \mathrm{A} 4 * / \mathrm{AEN} \end{aligned}$ |
| CSMONOCHRMA | AD $=$ A9*A8*A7*/A6*A5 |

;DMA controller
Chip select
Interupt controller
Chip select
HEX address 020-021
Timer
Chip select
HEX address 040-043
Parallel peripheral interface
; HEX address 060-063
DMA page register
;Chp select
;HEX address 080-083
NMI mask register
Chip select oAX
RS 232 module
HEX address 3 F8-3FF
; 5.25 floppy disk module ; Device select
;parallel printer module
Device select
Color graphics video module ; Device select
,Game I/O module Device select
HEX address $200-20$ ;Monochrome video module Device select

## simulation

TRACE_ON A9 AB A7 A6 AS A4 A3 AEN /CSMONOCHRMAD
/CSGMEIOAD/CSCOLORAD /CSPRTNTERAD /CS onochrmad CSRS232AD CSNMTMIRG /CSDMAPGRG /CSPPICHIP

SETF
SETF
SETF
SETF
SETF
SETF
SETF
SETF
SETF

SETF | 6 |  |
| :---: | :---: |
| 5 | A7 |
|  | /A6 |

```
A8 A7 A6 A5 A4 A3
```

/A6 /A7 /A8


## XPLOT Output

Title $:$ PC I/O Mapper
Pattern
Revision
RemIO.pds
Author
Company
A Gilbert
Date
Dotilithic Memories Inc

## PALBL14 PC_IO

$012345678901 \begin{array}{ll}11 & 1111 \\ 2345\end{array}$


$\qquad$ $\begin{array}{llll}5 & -x-x & -x x & x-x-x \\ 5 & -x-x \\ 5 & -x-x & x-x & -x-x \\ 7 & -x-x & x-x-x & x-x\end{array}$
$\qquad$
$\begin{array}{ll}11 & x-x-x-x-x-x- \\ 12 & x-x-x-x \\ 13 & x-x\end{array}$
total fuses blown: 101

## Logic Symbol



## PAL Device Design Specification



## PAL Device Design Specification



```
CHIP MUX4A PAL18P4 
Equations
OUTPUT[m=0..3] =OR [n=0..3] (INPUT[m,n] * BIN[n] ( SELECT[0] SELECT[1]
simulation
TRACE_ON INPUT[0..3,0..3] SELECT[0..1] OUTPUT[0..3]
```



```
    BEGIN SETF BIN[n](SELECT[1] SELECT(0))
        SETF
        SETF INPUT[0,.,3,0..3)
    END
    ; SELECT ADDRESS 
    SET ALL INPUTS
```

        4:1 MUX
    MUX4A. PDS
REVISION A A
AUTHOR Birkner
John
COMPANY
DATE
Monolithic Memories Inc. Santa Clara, CA
I/8/85
The four to one multiplexor routes one of four 4-bit nibbles,
his example illustrates the use of high level macros to
save typing and improve accuracy.

Simulation Results
Page : 1
INPUTOO XGLHHLLLLHH HLLHHLLHH
INPUT01 XLLHHHLHHL LLLHHHLLHH
INPUTO2 XLLHHHLLHH HLHHLLLLHM
INPUT03
XLLHHHLLHH
HLLHHHLHHI
INPUT10 XLLHHLLLLHH HLHEHHHLHEHH
INPUT10 XLHHLLLLHH HLLHHHLLHH
INPUT12 XLLIHHHLLHL LLILH HLHHLLLLH
INPUT13 XLLHHHLTHH HLLHHHLHHI
INPUT20 XLHHLLLLHH HLLHHHLLHH
INPUT21 XLLHHHLHHL LLLHHHLLHH
NPUT22 XLLHHHLLHH HLHHLLLLHH
INPUT23 $\times$ xLLHHHLLHH HLHHLLLLLHH
INPUT30 XLLHHLLLLLHH HLLLHHHLLLHH
INPUT31 XLLHHHLLHHL LLLHHHHLLHH
INPUT31 2 XLLLHHHLLHLH LLLHHHLLAH
INPUT33 XLLHHHLLHH HLLHHMLAHI
SELECT1 LLLLLLLLLL HHHHHHHHH
SELECTO LLLLLHHHH LLELLLHHHH
OUTPUT1 XLHHLHLHHL HLHHLHLHHL
OUTPUT2 XLHHLLHLHL HL HLHLLHLHHL
HHLHLHHL HLHHLHLHHL

## PAL Device Design Specification



SIMULATION

; Function Table for PALASM1


## Simulation Results

Page : 1

6 LHLLLLLLLLL LLLLLLLHHI
A5 LLHLLLLLLL LLLLLLLHLH
A4 LLLHLLLLLL LLLLLLLHHI A3 LLLLHLLLLL LLLLLLLLHLH A2 LLLLLHLLLL LLLLLLLHHL A1 LLLLLLLHLLL LLLLLLLLHLH AO LLLLLLLHLL LLLLLLLHEL
 B6 LLLLLLLEH LLLLH B5 LLLLLLLLLL HLLLLLLHLH B5 LLLLLLLLLL HLLLLLLHLH B4 LLLLLLLLLLL LHLLLLLLH B3 LLLLLLLLLL LLHLLLLHLH B2 LLLLLLLLLL LLLHLLLHHL B1 LLLLLLLLLLL LLLLLHLHHL


CHIP 3to8Dmux PALI6R8
$\begin{array}{lllllllll}\text { CLK } & \text { /CLR } & \text { /PR } & \text { A } & \text { B } & \text { C } & \text { /LD } & \text { POL TOG GND } \\ \text { /OC } & \text { Q7 } & \text { Q6 } & \text { Q5 } & \text { Q4 } & \text { Q3 } & \text { Q2 } & \text { Q1 } & \text { QO } \\ \text { VCC }\end{array}$ EQUATIONS

|  | ; Clear QO <br> ; Decode 000 <br> ; Load true <br> ; Load true <br> ;Load true <br> ;Hold <br> ;Toggle polarity |
| :---: | :---: |
|  | ; Clear Q1 <br> ; Decode 001 <br> ; Load true <br> ; Load true <br> ;Load true <br> ;Hold <br> ;Toggle polarity |
|  | ; Clear Q2 <br> ; Decode 010 <br> ; Load true <br> ; Load true <br> ;Load true <br> ;Hold <br> ;Toggle polarity |
|  | ; Clear Q3 <br> ;Decode 011 <br> ; Load true <br> ;Load true <br> iload true <br> ;Hold <br> ;Toggle polarity |
|  | ; Clear 24 <br> ; Decode 100 <br> ; Load true <br> ;Load true <br> ;Load true <br> ;Hold <br> ;Toggle polarity |
|  | ; Clear Q5 <br> ; Decode 101 <br> ; load true <br> ; Load true <br> ;Load true <br> ;Hold <br> ;Toggle polarity |
|  | ; Clear Q6 <br> ; Decode 110 <br> ; Load true <br> ; Load true <br> ; Load true <br> ;Hold <br> ;Toggle polarity |
|  | ; Clear Q7 <br> ; Decode 111 <br> ; Load true <br> ; Load true <br> ;Load true <br> ;Hold <br> ;Toggle polarity |

TRACE_ON /OC /CLR /PR /LD POL TOG C B A
Q7 Q6 Q5 Q4 Q3 Q2 Q1 QO

;Function Table for PALASM1
;/OC CLK /CLR /PR /LD POL TOG C B A Q7 Q6 Q5 Q4 Q3 Q2 Q1 QO


## Simulation Results

|  |  |  |  |
| :---: | :---: | :---: | :---: |
| /0C | LLLLLLLLLL | LLLLLLLLLL | LLHHHHH |
| $/ \mathrm{CLR}$ | LLLLHHHHHH | ННннННнНнН | нннннНн |
| /PR | LLLLLLHHHH | нннннннннн | нннНннн |
| /LD | LLLLLLLLLL | LLLLHHHHLL | LLLLLLL |
| POL | нНннннHHHH | HHHHHHHHLL | LLLLLLL |
| TOG | llllllllll | LLLLHHHHHH | HHHHHHH |
| c | XXXXXXLLLL | Llllllllll | Lllllll |
| B | xxxxxxLLLL | HHHHHHHHLL | LLLLLLL |
| A | xxxxxxLLHH | LLHHHHHHLL | нНнHHHH |
| Q7 | xxXLLHHLLL | LLLLLHHLLH | HHHZZZZ |
| Q6 | XxXLLHHLLL | LLLLLHHLLH | HHHzZzZ |
| Q5 | xxxLLHHLLL | LLLLLHHLLH | HHHzzzZ |
| Q4 | xxxLLHHLLL | LLLLLHHLLH | HHHzzzz |
| Q3 | XXXLLHHLLL | LLLHHLLHHH | HHHzzzz |
| Q2 | XXXLLHHLLL | LHHLLHHLLH | HHHzZzZ |
| Q1 | xxxLLHHLLH | HLLLLHHLLH | HLLzZzz |
| QO | xxxLLHHHL | LLLLLHHLLL | LHHzzzz |

## PAL Device Design Specification

Title octal Latch
Pattern 8latch.pds
Pattern 81atch.pds
Author Mehrnaz Hada
Company Monolithic Memories Inc. Santa Clara, CA Date $\quad 1 / 15 / 85$
CHIP octallatch PAL2OP8E
/LATCHO D1 DO QO O1 VCC1 Q2 Q3 D3 D2 CLRO GND
/LATCH1 D6 D7 Q7 Q6 VCC2 Q5 Q4 D4 D5 CLR1 VCC3
EQUATIONS


## Logic Symbol



## PAL Device Design Specification




## Simulation Results

 CLR HHHHLLLLLL LLLLLLLLLLL LLLLLLLLLL LHHHLLLLLL
 JKT XXXXLLLLLLL LLLHHHHHHH HLLLLHHLLLL HHHLLLLHHHH T $\begin{array}{lllll}\text { TT } & \text { XXXLLLXXXXX } & \text { XXXXXXXXXX } & \text { XXXXHHHXXX } & \text { XXXLLLLLLH } \\ \text { D } & \text { XXXXXXXXXX } & \text { XXXXXXXXXX } & \text { XXXXXXXXXX } & \text { XXXXXXXXXX }\end{array}$ $\begin{array}{lllll}\text { D } & \text { XXXXXXXXXX } & \text { XXXXXXXXXX } & \text { XXXXXXXXXXX } & \text { XXXXXXXXXX } \\ \text { DT } & \text { XXXLLLXXXX } & \text { XXXXXXXXXX } & \text { XXXXHHHXXX } & \text { XXXLLLXXXXX }\end{array}$


Page : ${ }^{2} \mathrm{cg} \mathrm{cg} \mathrm{cg}$ cg cgcg o g cg cgcg
CR LR LLLLLHHHHHH HHHHHHHLLL LLLLLLLLLL
CLR LLLHHHHHHH HHHHHHHLLL LLLLLLLLLL

JKT HHHHHLLLLL LLLLLLLLLLH HHHHHHHHZ
T LLLLLLLLLL LLLLLLLLLLL LLLLLLLLLL
T T LLLLLLLLLL LLLLLLLLLL LLLLLLLLLI
D XXXXXXLLLH HHLLLLLLLLL LLLLLLLLLLI
TT XXXXXLLLLL LLLLLLLLLLL LLLLLLLLLZ
XXXXXXXXXX XXXXXXXLLL HHHLLLLLLL


Logic Symbol


## PAL Device Design Specification




## Simulation Results



Page : 1
C c cgcgcga gcgagcgcg c CLK XXHLHLHLHL HLHLHLLLHLH HHH /LD LLLLHHLLHH LLHHL工HHHH HHH D8 LLLLLLLHHH LLLLHHHHHH HHH 6 LLLLLLHHHH HHHHLLLLLL LLL LLLLLLLHHH LLLLHHHHHH HHH LLLLLLLHHH HHHHLLLLLL LLI LLLLLLHHHH HHHHLLLLLL LLI LLLLLLHHHH LLLLHHHHHH HHH LLLLLLHHHH HHHHLILLLL LLI LLLLLLHHHH LLLLHHHHHH HHH XXXLLLLHHH HLLLLHHHHZ ZZZ XXXLLLLHHH HHHHHLLLLZ ZZZ XXXLLLLHHH HLLLLHHHHZ ZZZ XXXLLLLLHHH HLLLLHHHHZ ZZZ XXXLLLLLHH
XXXHELLLHHH
HLLLLHLHLZ
ZZZ XXXLLLLLHHH
XXLLLLHHHHZ
ZZZ $\begin{array}{lll}\text { XXXXLLLLLHHH } & \text { HLLLLLHHHEZ } \\ \text { ZZZ } \\ \text { XXXLLLLHHH } & \text { HHHHHLLLLZ } \\ \text { ZZZ }\end{array}$ XXXLLLLLHH HHHHHLLLLZ ZZZ XXXLLLLLHH HLLLLHHHHZ ZZ



CHIP 10BitReg PAL20X10
$\begin{array}{llllllllllll}\text { CLK } & \text { DO } & \text { D1 } & \text { D2 } & \text { D3 } & \text { D4 } & \text { D5 } & \text { D6 } & \text { D7 } & \text { D8 } & \text { D9 } & \text { GND } \\ \text { /OC } & \text { Q9 } & \text { Q8 } & \text { Q7 } & \text { Q6 } & \text { Q5 } & \text { Q4 } & \text { Q3 } & \text { Q2 } & \text { Q1 } & \text { QO } & \text { VCC }\end{array}$ EQUATIONS

| $/ Q 0:=/ D 0$ | iLoad D0 |
| :--- | :--- |
| $/ Q 1:=/ D 1$ | iLoad D1 |
| $/ Q 2:=/ D 2$ | ;Load D2 |
| $/ Q 3:=/ D 3$ | iLoad D3 |
| $/ Q 4:=/ D 4$ | iLoad D4 |
| $/ Q 5:=/ D 5$ | iLoad D5 |
| $/ Q 6:=/ D 6$ | iLoad D6 |
| $/ Q 7:=/ D 7$ | ;Load D7 |
| $/ Q 8:=/ D 8$ | ;Load D8 |
| $/ Q 9:=/ D 9$ | ;Load D9 |

SIMULATION


SETF OC /D9 /D8 /D7 /D6 /D5 /D4 /D3 /D2 /D1 /DO
CLOCKF CLK
SETF D9 D8 D7 D6 D5 D4 D3 D2 D1 DO
CLOCKF CLK ;Load all ones

SETF D9 /D8 D7 /D6 D5 /D4 D3 /D2 D1 /D0
SETF /D9 D8 /D7 D6 /D5 D4 /D3 D2 /D1 D0 CLOCKF CLK

SETF 10 OC
; Test HI-Z
;Function Table for PALASM1
; $10 C$ CLK D9 D8 D7 D6 D5 D4 D3 D2 D1 D0 ;Q9 Q8 Q7 Q6 Q5 Q4 Q3 Q2 Q1 QO


|  | $\begin{aligned} & \mathrm{g} \quad \mathrm{cg} \mathrm{cg} \\ & \text { LLLLLLLLLL } \end{aligned}$ | $\underset{\text { LLLLLHHHHH }}{\mathrm{cg} \mathrm{cg}}$ |
| :---: | :---: | :---: |
| CLK | XXHHLLHLLH | HLLHLLLHHL |
| Q9 | XXXLLLLLHH | HHHHLLZZZZ |
| Q8 | XXXLLLLLHHH | LLLLHHZZZZ |
| Q7 | XXXLLLLLHHH | HHHHLLZZZZ |
| Q6 | XXXLLLLLHH | LLLLHHZZZZ |
| Q5 | XXXLLLLLHH | HHHHLLZZZZ |
| Q 4 | XXXLLLLLHHH | LLLLHHZZZZ |
| Q3 | XXXLLLLLHHH | HHHHLLZZZZ |
| Q2 | xxxLLLLHHM | LLLI |
| Q1 | XXXLLLLLHH | HHHHLLZZZZ |
| Q 0 | XXXLLLLHHH | LLLLHHZZZZ |
| D9 | LLLLLHHHHH | HHLLLLLLLL |
| D8 | LLLLLHHHLL | LLHHHHHHHH |
| D7 | LLLLLHHHHH | HHLLLLLLLL |
| D6 | LLLLLHHHLL | LLHHHHHHHH |
| D5 | LLLLLHHHHH | HHLLLLLLLL |
| D4 | LLLLLHHHLL | LLHHHHHHHH |
| D3 | LLLLLHHHHH | HHLLLLLLLL |
| D2 | LLLLLHHHLL | LLHHHHHHHH |
| D1 | LLLLLHHHHH | HH |
|  |  |  |





```
\(+/ \mathrm{S3}\) * S 2 * \(/ \mathrm{S} 1\) * \(/ \mathrm{SO} \mathrm{S}^{*} \mathrm{D} 3\) \(+1 \mathrm{S3}\) * S2 * \(/ \mathrm{S} 1\) * S0 * D4
```



``` * / S2 * /S1 * /SO * D7
* /S2 * /S1 * S0 * D8
```



``` S2 * /S1 * /S0 * D11
S2 * /S1 * S0 * D12
S2 * S1 */S0 * D13 S3 * S2 * S1 * 1 S0 * D13
S3 * S2 * S1 * SO * D1 Shift 4 spaces
Shift 5 spaces
Shift 6 spaces
Shift 7 spaces
Shift 8 spaces
Shift 9 spaces
Shift 10 spaces
Shift 11 spaces
Shift 12 spaces
Shift 13 spaces
Shift 14 spaces SIMULATION
TRACE_ON CLKI CLK2 CLK3 CLK4 OC1 OC2 OC3 OC4 PL1 S1 2 PL3 PL4 PS1 PS2 PS3 PS4 S3 D9 D10 D11 D12 D13 D14 D15 Q0 Q1 Q2 Q3 Q4 Q5 Q6 Q7 Q8 Q9 Q10 Q11 Q12 Q13 Q14 Q15
SETF OC1 OC2 OC3 OC4 /PS1/PS2 /PS3 /PS4
/PL1 /PL2 /PL3 /PL4 /S3 /S2 /S1 /S0 D0
D1 /D2 /D3 /D4 /D5 /D6 /D7 /D8 /D9 /D10
CLOCKF CLK1 CLK2 CLK3 CLK4
; Clock
\(\begin{array}{lll}\text { SETF /S3 /S2 /S1 } & \text { SO } \\ \text { CLOCKF CLK1 CLK2 CLK3 CLK4 }\end{array}\) SETF /S3 /S2 S1/SO SETF /S3 /S2 S1 SO
CLOCKF CLK1 CLK2 CLK3 CLK4 SETF / S3 S2 / S1/So LLCKF CLK1 CLK2 CLK3 CLK4 CLOCKF CLKI CLK2 CLK3 CLK4 SETF / S3 S2 S1/SO LLOCKF CLKI CLK2 CLK3 CLK 4
SETF /S3 S2 S1 So CLOCKF CLKI CLK2 CLK3 CLK4
\(\begin{array}{lll}\text { SETF S3 } & \text { /S2 } & \text { Sl } \\ \text { CLOCKF } & \text { SLK } \\ \text { CLK } & \text { CLK3 } \\ \text { CLK } 4\end{array}\)
```

shift

Shift 2
;Shift 3
;Shift 4
;Shift 5
;Shift
;Shift 7

Shift 8

```
;The l6-bit barrel shifter will shift 16 bits of data (Dl5-DO) a number of locations into the output pins, as specifled by the binary encoded input. A compacted gn. It can be specified as following:
QR \(J=0.15]:=\)
OR \(=0.15]\{D[(J+K)-((J+K) / 16) * 16] * \operatorname{BIN}[K, I=3 \ldots 0] S(I)\}\)
;Inputs are shown by D. Si are shift amount inputs and QJ are outputs. 16 product terms in each output pair are directed to one output; thus only 16 out of 32 output pins are used
```


## Simulation Results



PAL Device Design Specification

 EqUATIONS


## 3setho Touegx


simulation

SETF E1 E2/DATA/PRLD1 /PRLD2
SETF /AO /A1 /A2 /A3
CLOCKF CLK1 CLK2
SETF AO /A1 /A2 /A3
CLOCKF CLK1 CLK2
SETF /AO A1 /A2 /A3
CLOCKF CLKI CLK2

SETF /AO /A1 A2
CLOCKF CLKI CLK2
SETF AO /A1 A2 $/$ A3
CLOCKF CLK1 CLK2
SETF /AO A1 A2
CLOCKF
CLK1
CLK2
SETF AO A1 A2
CLOCKF
CLK
CLK
SETF /AO /A1 /A2 A3
CLOCKF CLK1 CLK2
SETF AO /A1 /A2 A3
CLOCKF CLK1 CLK2
SETF /AO A1 /A2 A3
CLOCKF CLK1 CLK2.
SETF AO A1 /A2
CLOCKF CLK1 CLK2

SETF AO /A1 A2 A3
CLOCKF CLK1 CLK2
SETF /AO A1 A2 A
CLOCKF CLK1 CLK2
SETF AO A1 A2 A3
CLOCKF CLK1 CLK2
setf data
SETF /AO /A1 /A2 /A3

## Simulation Results


(C) - COPYRIGHT MONLITHIC MEMORIES INC., 1984
$\begin{array}{l:l}\text { Title } & \\ \text { Pattern } & \text { 16-BIT Addressable Register } \\ \text { Revision } & \text { ADREI6.PDS }\end{array}$
$\begin{array}{l:l}\text { Ruthor } & \text { John Birkner } \\ \text { Company } & \text { Monolithnic Memories Inc } \\ \text { Date } & 2 / 11 / 85\end{array}$
${ }_{\text {ADREG16 }}^{\text {PAL3 } 2 R 16}$
$\begin{array}{lllllllllll}11111 & 1112222 & 22222233 & 33333333 & 44444444 & 44555555 & 55556 \\ 01234567 & 89012345 & 67890123 & 45678901 & 23 \times 56789 & 01234567 & 89012345 & 67890\end{array}$



$$
\begin{aligned}
& \text { OUTPUT PINS: } \begin{array}{r}
111222223334 \\
\text { OLARITY FUSE: } \\
\hline
\end{array} .
\end{aligned}
$$

$\begin{array}{lrrr}\text { OUTPUT } & \text { BANK: } & \text { 4-40 } & \text { 17-24 } \\ \text { FLUSH FUSE: } & \mathrm{X} & \mathrm{X}\end{array}$
TOTAL FUSES BLOWN: 5008


Figure 1 illustrates a simple traffic intersection consisting of two one-way streets, direction 1 and direction 2. Each direction has a signal consisting of red, yellow, and green lamps which are activated with appropriately named active high signals. Also each
direction has a sensor which provides an active high direction has a sensor which provides an active high
signal indicating the presence of an oncoming vehicle. signal indicating the presence of an oncoming vehicle. sensors as inputs and the lamps as outputs, as shown in Figure 2.


Figure 1. Traffic Intersection

Figure 2 also includes the system clock and an initialize (or reset) signal, which drives the controller to a predefined initial state. This raises two important issues in designing sequential logic with PAL devices. First, all circuit implementations of sequential logic with PAL devices are totally synchronous. This implies that all state variables (flip-flops) change at the same time, PAL sequential logic designs should include a means for initialization to implement test programs and ensure reliable circuit operation. The specifics of the controller operations are detailed with a state diagram shown in Figure 3.


Figure 2. Traffic Signal Controller


3

Each circle in Figure 3 represents a stable state, i.e. an output configuration lasting at least one clock cycle. Inside the circles is the name of the state (S0-S7) and the outputs associated with that state. For the sake of simplicity in the state diagram, the transitions involving INIT are omitted; INIT simply drives the circuit to so from any state, regardless of other inputs

Since RED1 = / RED2, RED1 is implemented with one flip-flop and RED2 with an external inverter.

## PAL Device Design Specification



ITLE
PATTERN
AUTHOR
COMPANY
DATE

TRAFFIC SIGNAL CONTROLLER
A
KELVIN CHOW
MONOLITHIC MEMORIES INC., SANTA CLARA
L16RP8
CLK SEN1 SEN2 INIT NC NC NC NC NC GND
STRING I1 / SEN1*/SEN2*/INIT
STRING I2 , /SEN1*SEN2*/INIT
$\begin{array}{ll}\text { STRING I3: } & \text { SEN1*/SEN2*/INIT } \\ \text { STRING I4, } \\ \text { SEN1*SEN2*/INIT }\end{array}$
STRING I5 , INIT
STATE
SO $\quad=\operatorname{BIN}[4](R 1, Y 1, G 1, Y 2, G 2)$
S2 $=\operatorname{BIN}[4](\mathrm{R} 1, \mathrm{Y} 1, \mathrm{G1}, \mathrm{Y} 2, \mathrm{G} 2$
$\begin{aligned} \mathrm{S} 4 & =\text { BIN[8](R1,Y1,G1,Y2,G2) } \\ & =\text { BIN[17](R1,Y1,G1,Y2,G2 }\end{aligned}$
= BTN 6 (R1,Y1,G1,Y2,G2
$\mathrm{S} 7=\mathrm{BIN}[18](\mathrm{R1}, \mathrm{Y} 1, \mathrm{G} 1, \mathrm{Y} 2, \mathrm{G} 2)$
$S_{S 1}=I 1 * S 2+I 2 * S 2+I 3 * S 2+I 4 * S 2+I 5 * S 0$
$\begin{array}{ll}S 3 & =I 1 * S 4+I 2 * S 4+I 3 * S 4+I 4 * S 4+I 5 * S 0 \\ S 4 & =I 1 * S 5+I 2 * S 4+I 3 * S 6+I 4 * S 5+I 5 * S 0\end{array}$
S5 $\quad=I 1 * S 6+I 2 * S 6+I 3 * S 6+I 4 * S 6+I 5 * S 0$
$57=11 * S 7+I 2 * S 7+I 3 * S 7+I 4 * S 7+I 5 * S 0$
SIMULATION
RACE ON CLK INIT SEN1 SEN2 R1 Y1 G1 Y2 G2

CLOCKF
CHECK /R1 /Y1 G1 /Y2 /G2
SEIF /INIT /SEN1 /SEN2

SETF SEN1 /SEN2
CHECK /RI /Y1 G1/Y2 /G2
SETF /SEN1 SEN2
CHECK /R1 /Y1 G1 /Y2 /G2
SETF SEN1 SEN2
CHECK /R1 Y1 /G1 /Y2 /G2
SETF /SEN1 /SEN2
CHECK R1 /Y1 /G1 /Y2 G2
SETF /SEN1 SEN2
CHECK
CLOCKF
CLOCKF
CHECK R1/Y1/G1 Y2/G2

CHECK
CLOCKF
CLOCKF
CLOCKF
; This simulation was done using the alpha release version of Palasm2 software.

## Simulation Results


INIT HHHHHHHLLL LLLLLLLLLL LLLLLLLLLL LLLLLLLL
SEN1 XXXXXXXLLL HHHLLLHHHL LLLLLLLLLL
SEN2 XXXXXXXLLL LLLHHHHHHL LLHHHHHHHH HHHHHHHH
R1 XXXXXLLLLL LLLLLLLLLL LHHHHHHHHH LLLLLLHH
Y1 XXXXXLLLLL LLLLLLLLLH HLLLLLLLLL LLLLHHLI
G1 XxxxxhHHHH HHHHHHHHLL LLLLLLLLLLL HHHHLLLL
G2 XXXXXILLLL LLLLLLLLLL LHHHHHHHLL LLLLLLHH

## Logic Symbol



## State Machine Design Example

A typical control logic problem is the memory-to-processor handshake on memory transfer used in many computer architectures. The processor makes a transfer request by activating a request line (REQ) and specifies a read or write operation on a Read/Write line (R/W).
During a read operation, the processor waits for a Data Available signal at which time the data bus is sampled and the request line lowered, thus completing the cycle. During a write operation, the processor places data on the bus and waits for a Write Complete signal after the write cycle is finished. Upon write complete, the


Figure 1. State Diagram - Memory Handshake Logic

| STATE | DOUT | DA | WE | WC | C0 | C1 |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: |
| WAIT | 0 | 0 | 0 | 0 | 0 | 0 |
| READ1 | 1 | 0 | 0 | 0 | 0 | 0 |
| READ2 | 1 | 1 | 0 | 0 | 0 | 0 |
| READ3 | 0 | 0 | 0 | 0 | 0 | 0 |
| COUNT1 | 0 | 0 | 1 | 0 | 1 | 0 |
| COUNT2 | 0 | 0 | 1 | 0 | 0 | 1 |
| COUNT3 | 0 | 0 | 1 | 0 | 1 | 1 |
| WRITE1 | 0 | 0 | 1 | 0 | 0 | 0 |
| WRITE2 | 0 | 0 | 1 | 1 | 0 | 0 |
| WRITE3 | 0 | 0 | 0 | 1 | 0 | 0 |

request line is lowered, hence completing the cycle. Table 1 shows the state assignments and the appropriate outputs. The state diagram is shown in Figure 1. Also the handshaking operation is illustrated in the timing diagram of Figure 2.
The memory-board logic to implement this function may be designed with gates and edge-triggered flip-flops as shown in Figure 3. This particular design would require about five SSI/MSI packages, but the same design can be implemented by a single PAL16RP6. The PAL design specification using state equations is shown on the next page.


Figure 2. Memory Handshake Timing


Figure 3. Memory Handshake Logic
hemuky hanidhake logic MEMORY1.PDS

CHIP MEMORY PALI6RPG
CLK ADDR1 ADDR2 ADDR3 ADDR4 REQ RW INIT NC GND /OE NC/WC Cl CO/WE/DA/DOUT NC VCC
STRING II: REQ*RW*ADDR1*ADDR2*ADDR3*ADDR4*/INIT

STRING I3
STRING I4
(/REQ $+/$ (ADDR1
STRING 15 , INIT
state
WAIT $=$ BIN [0] (DOUT, DA, WE,WC, CO,C1)
WAIT
READ2
READ 3
WRITE1 $=$ BIN[0](DOUT,DA,WE,WC,C0,C1)
COUNT1 $=$ BIN[8](DOUT,DA,WE,WC,CO,C1)
COUNT2 $=$ BIN[10] (DOUT, DA,WE,WC, CO, C1)
COUNT3 $=$ BTN [9] (DOUT, DA, WE, WC, CO, C1)
WRITE2 $=$ BIN [12] (DOUT,DA,WE,WC,CO,C1)

EQUATIONS

READ1 := I4*READ2 + I3*READ2 + I2*READ2 + I1*READ2
READ2 : = I4*READ3 + I3*READ3 + I2*READ3 + I1*READ
READ3 := I1*READ3 + I4*WAIT
TTE1 $:=$ I5*WAIT $14 *$ COUNT1 + I3*COUNT1 + I2*COUNT1 + I1*COUNT1
COUNT1 $:=I 4 *$ COUNT2 $+I 3 *$ COUNT2 $+I 2 *$ COUNT2 $+I 1 *$ COUNT2
COUNT2 + I5*WAIT
$:=14 *$ COUN
$+\quad 15 *$ WAIT
COUNT3 $:=I 4 *$ WRITE2 $+I 3 *$ WRITE2 $+I 2 *$ WRITE2 + I1*WRITE2
WRITE2 := I4*WRITE3 + I3*WRITE3 + I2*WRITE3 + I1*WRITE3
HRTTE3 +15 *WAIT

+ I5*WAIT
SIMULATION
TRACE_ON REQ RW CLK /DOUT /DA /WE /WC
SETF INIT /REQ OE RW ADDR1 ADDR2 ADDR3 ADDR4 CHECK / DOUT

SETF REQ /INIT
CLOCKF
CLOCKF
CLOCKF
CHECK DOUT DA
SETF / REC
CLOCKF
CHECK /DOUT /DA
SETF REQ /RW
CLOCKF
CLOCKF
CLOCKF
CLOCKF
SETF /REQ
CLOCKF
CLOCKF
CLOCKF
; This simulation was done using the alpha release version of Palasm2 software

|  | g cg | c c cg cg | HHLHLHLHLH | $\mathrm{ccgcc}^{\text {c }}$ |
| :---: | :---: | :---: | :---: | :---: |
| CLK | XXHLLHHLHH | LHLHLLHHLL | HHLHLHLHLH | LHLLHLHL |
| REQ | LLLLHHHHHH | HHHHHLLLLLH | HHHHHHHHHH | HHHLLLLL |
| RW | нНнH\%HHHHH | HHHHHHHHHL | LLLLLLLLLL | LI |
| /DOUT | XXXHHHLLLL | LLLLLLLHHH | HHHHHHHHHH | HHH |
| /DA | XххунHHHHL | LLLLLLLHHH | нННННнНнH | HH |
| /WE | ХХхунннннН | HHHHHHHHHH | HLLLLLLLLL | LLHHHHHH |
| /WC | XXXXXXXHH | HHHHHH | HH | LLHHH |

## Logic Symbol



## PAL Device Design Specification

| Title | 4Bit_Counter |
| :--- | :--- |
| Pattern | 4cnt.pds |
| Revision | A |
| Author | Mehrnaz Hada |
| Company | Monolithic Memories Inc. Santa Clara, CA |
| Date | $1 / 14 / 85$ |
| CHIP | 4 BitCounter PALl6RP4 |

CIK UP AI BI CI DI CLR LOAD NC GND
EQUATIONS


SIMULATION
TRACE_ON AI BI CI DI LOAD CLR UP A B C D
SETF LOAD /CLR AI BI CI DI OC ;Load all registers
SETF CLR ;Clear all registers

SETF /CLR UP /LOAD
; Start counting up
FOR I:= 1 TO 16 DO
Count up 16 clock cycles
CLOCKF CLK
END
SETF LOAD /CLR /UP AI BI CI DI CLOCKF
SETF/LOAD
FOR I:= 1 TO 16 DO
BEGIN
CLOCKF CLK

SETF LOAD CLR AI /BI CI /DI
CLOCKF CLK
setf /OC
;The 4-bit counter counts up or down and has the clear and
;load capability. The clear operation overrides count and iload capability. The clear operation overrides count and ;UP=high. It counts down whenever CLR=10w, LOAD=10w, and

## Simulation Results

|  | g cgegc c |  | cooco | c cocge |
| :---: | :---: | :---: | :---: | :---: |
| AI | HHHHHHHHHH | НННННННННН | НННННННННН | НННННННHH |
| BI | HHHHHHHHHH | НННННННННН | ННННННННHH | НННHHHHHHH |
| CI | ННННННННHH | НННННННННН | НННННнHHHH | НННННННH\% |
| DI | НННННННННН | нннннннннн | HHH | HHH1 |
| LOA | HHHHHHLLLL | LLLLLLLLL | LLLLLLLL | LLLLL |
| CLR | LLLLHHLLLL | LLLLLLLLLL | LLLLLLLLL | LLLLLL |
| UP | XXXXXXXHнH | HННHHHHHHH | ННнНнHнHH | HHHHHHHHI |
| A | XXXAHHLLLLL | LLLLLLLLLL | LHHHHHHHHH | HHHHHLLHHH |
| B | XXXHHLLLLL | LLLHHHHHHH | HLLLLLLLLH | HHHHHHHL |
| c | XXXHHLLLLL | HHHLLLLLHH | HLLLLHHHHL | LLI |
| D | XXXHHLLHH | LHHLLHHL | LHHLI | LHHLLHHI |

## Logic Symbol



## PAL Device Design Specification

| Title | 8Count |  |  |
| :--- | :--- | :--- | :--- |
| Pattern | 8count.pds |  |  |
| Revision | A |  |  |
| Author | Mehrnaz Hada |  |  |
| Company | Monolithic Memories Inc. Santa Clara, CA |  |  |
| Date | $1 / 15 / 85$ |  |  |

;This 8 -bit up/down counter has the hold and load ;capabilities. It sets all the outputs high if SET=high.
;it loads new value when $S E T=10 w$ and LOAD=high. Else it ; counts up if UP=high and counts down if UP=low.
CHIP 8Bitcounter PAL20X8
CLK UP DO D1 D2 D3 D4 D5 D6 D7 LD GND
IOC SET Q7 $25 \quad$ Q5 54 Q3 22 Q1 QO CIN VCC

## EqUATIONS


molhosilloeq3 erglaoti ashrect 3 AC

SETF LD /D7 D6 /D5 D4 /D3 D2 /D1 D0 CHECK /Q7 Q6/Q5 Q4/Q3 Q2/Q1 QO SETF /LD UP FOR I:=1 TO 5 DO
BEGIN
CLOCKF CLK
IF $\mathrm{I}=3$ THE
BEGIN
SETF /UP

## END

;Loading some data ;Checking the output ; for the loaded data ; Counting up after ,removing HOLD, count iup 3 cycles, count ; down for 2 cycles.

## Simulation Results



## Logic Symbol



## PAL Device Design Specification



CLOCKF CLK
SETF $/ L D$
CLOCKF CLK
;Function Table


| control | Data | In |  | Data |
| :---: | :---: | :---: | :---: | :--- |
| DDDDDDDD | Out |  |  |  |
| QQQQQQQQ |  |  |  |  |

## Simulation Results



## Logic Symbol



Revision
Author Company Date

Mehrnaz Hada
Monolithic Memories Inc. Santa Clara, CA 1/15/85
;The 10 -bit counter increments on the rising edge of the Clock input (CLK), if CNT input is high. The outputs are ; when the enable line (/OE) is low. The counter is ;cleared (all lows) if CLR=HIGH.
CHIP 10BitCount PAL2ORS10
CLK / SET NC CNT NC /CLR NC NC NC NC NC GND IOE Q5 Q3 25 Q2 27 Q1 $88 \quad 20 \quad 29 \quad 24 \mathrm{VCC}$

## EQUATIONS

| 180 | $\begin{aligned} & :=/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * Q 0 \\ & +/ \mathrm{SET} * / \mathrm{CNT} * / \mathrm{CLR} * / 80 \\ & +\operatorname{CLR} \end{aligned}$ | ;Toggle <br> ;Hold <br> ;CLR |
| :---: | :---: | :---: |
| 181 | $\begin{aligned} & :=/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * \mathrm{QO} * Q 1 \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{QO} * / \mathrm{Q1} \\ & +/ \mathrm{SET} * / \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q1} \\ & +\quad \mathrm{CLR} \end{aligned}$ | ;Toggle <br> ;Toggle <br> ;Hold <br> ;CLR |
| /Q2 | $\begin{aligned} & :=/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * Q 0 * Q 1 * \\ & \mathrm{Q} 2 \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{QO} * / \mathrm{Q} 2 \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q1} * / \mathrm{Q2} \\ & +/ \mathrm{SET} * / \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{QL}^{2} \\ & +\mathrm{CLR} \end{aligned}$ | ;Toggle <br> ;Toggle <br> ; Toggle <br> ;Hold <br> ;CLR |
| 183 | $\begin{aligned} & :=/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * \mathrm{QO} * \mathrm{Q1} * \\ & +/ \mathrm{SET} * \mathrm{Q} 2 \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{QO} * / \mathrm{Q3} \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q1} * / \mathrm{Q} 3 \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q2} * / \mathrm{Q} 3 \\ & +/ \mathrm{SET} * / \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q3} \\ & +\mathrm{CLR} \end{aligned}$ | ;Toggle <br> ;Toggle <br> ; Toggle <br> ;Toggle <br> ;Hold <br> ;CLR |
| /24 | $\begin{aligned} & :=/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * \mathrm{QO} * \mathrm{Q1} * \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{QO} * / \mathrm{Q4} \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q1} * / \mathrm{Q4} \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{QL}^{*} / \mathrm{Q4} \\ & +/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q3} * / 24 \\ & +/ \mathrm{SET} * / \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q4} \end{aligned}$ | ;Toggle <br> ;Toggle <br> ; Toggle <br> ;Toggle <br> ; Toggle <br> ;Hold <br> ; CLR |
| 185 |  | ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Hold <br> ; CLR |
| /86 |  | ;Toggle <br> ;Toggle <br> ; Toggle <br> ;Toggle <br> ;Toggle <br> ; Toggle <br> ; Toggle <br> ;Hold <br> ;CLR |
| 187 |  | ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle <br> ; Toggle <br> ;Toggle <br> ;Toggle <br> ; Hold <br> ;CLR |
| /Q8 |  | ;Toggle <br> ;Toggle <br> ;Toggle <br> ; Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle <br> ;Toggle |

Q9 : $=$ /SET * CNT * /CLR * Q0 * Q1 * Q 2
Q 8

* Q3 * Q 9 $\mathrm{Q}^{*} \mathrm{Q5}$ * Q6 * Q7 * $+/ \operatorname{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{QO}$ */R9 /SET * CNT * /CLR * /Q1 * /O9 ;Togg1e /SET * CNT */CLR */Q1 */R9 ;Toggle
$+/ \mathrm{SET}$ * CNT */CLR */Q2 */Q9 ;Toggle +/SET * CNT * /CLR */Q3*/Q9 ;Toggle /SET * CNT * /CLR * $1 \mathrm{Q4}$ */R9 ;Toggle
$+/ \mathrm{SET}$ * CNT * /CLR */Q5 */09 ;Togle +/SET * CNT * /CLR * /Q5 */R9 ;Toggle + /SET * CNT * /CLR * /Q6 * /Q9 ;Toggle
$+/ \mathrm{SET}$ * CNT * /CLR * /Q7 */Q9 ;Toggle $+/ \mathrm{SET} * \mathrm{CNT} * / \mathrm{CLR} * / \mathrm{Q7} * / \mathrm{Q9}$;Toggle
 + CLR ; CLR
SIMULATION
TRACE_ON OE CLK SET CLR CNT QO Q1 Q2 Q3 Q4 Q5 Q6 Q7 Q8 Q9
SETF OE /CLR SET
CLOCKF CLK
SETF CLR
CLOCKF CLK
SETF /SET CNT /CLR
FOR I:= 1 TO 5 DO
BEGIN
CLOCKF CLK
IF I=4 THEN
BEGIN
CHECK /QO /Q1 Q2
END
END

SETF / CNT

## Simulation Results


CE HHHHHHHHHH HHHHHHHHHH H
SET HHHHHHHLLL LLLLLLLLLL I
CLR LLLLHHHLLL LLLLLLLLLL I
CNT XXXXXXXHHH HHHHHHHHLL L
QO XXXHHHLLLH HLLHHLLHHH F
Q1 XXXHHHLLLL LHHHHLLLLL I
Q3 XXXHHHLLLL LLLLLLLLLL
Q4 XXXHHHLLLL LLLLLLLLLL
Q5 XXXHHHLLLL LLLLLLLLLLI I
Q6 XXXHHHLLLL LLLLLLLLLLL
Q7

Q8 | XXXHHHLLLL |
| :--- |
| Q 9 |
| XXXHHHLLLL |
| LLLLLLLLLLLL |

## Logic Symbol



## runcional עescription

Shown below is a schematic of two PAL devices implementing a 5-bit up asynchronous ring counter with programmable rollover, asynchronous load, and reset. Initial count point can be loaded by asserting /LD low. Rollover point is loaded by asserting /LR

Iow. Q4...Q0 and R4...R0 are compared in the PAL16C1 which is implemented as a comparator. The result of the comparison is fed back from the PAL16C1 to the PAL20RA10 device through the /RST line. Note that a Master Reset must be executed first before an initial count point can be loaded.

Block Diagram


## PAL Device Design Specification

## PALI6C

ROLLO2
COMPARATOR
MONOLITHIC MEMORIES INC., SANTA CLARA, CA

EQUATIONS
/RST


FUNCTION TABLE
Q4 Q3 Q2 Q1 Q0 R4 R3 R2 R1 R0/MR /RST


DESCRIPTION
PAL16CI DESIGN SPECIFICATION
-BIT COMPARATOR WITH MASTER RESET OVERRIDE
(SECOND OF THE TWO PALS SOLUTION ON THE 5-BIT COUNTER WITH PROGRAMMABLE ROLLOVER, ASYNCHRONOUS LOAD
BILL KARKULA $7 / 19 / 84$
THIS DEVICE COMPARES 5 BITS OF DATA (R4...RO) WITH Q4...QO
AND ASSERTS /RST IF THEY ARE EQUAL. THEREFORE/RST
GOES LOW WHEN PROGRAMMED ROLLOVER POINT RA. . RO GOES LOW, INDICATING A MASTER RESET.

NOTE: THIS PAL DESIGN SPEC WAS ASSEMBLED ON PALASM V1.7.

## PAL Device Design Specification


/PL D4 D3 D2 D1 DO CK NC /LD /LR /RST GND
EQUATIONS

TRACE_ON PL OE CK QO Q1 Q2 Q3 Q4 SETF RST /LD ; of registers on reg. output ; Deassert SET funct

SETF D0 D1 D2 D3 D4 LD
CHECK SETF /OE Q4 Q3 Q2 Q1/Q0/LD

Disable RESET (LD=0) ; HHHHL (Q4..QQ)

SETF PL
SETF OE/PL
Load reg 's W/ data ;on output bus. ;TRISTATE funct.
SETF CK
SETF $/ \mathrm{CK}$
$\begin{array}{ll}\text { SETF CK } \\ \text { SETF } & \text { /CK }\end{array}$
SETF CK
$\mathrm{SETF} / \mathrm{CK}$
$\begin{array}{ll}\text { SETF } & \text { CK } \\ \text { SETF }\end{array}$

## Simulation Results

$\qquad$
PL XXXXXXXHLL LLLLLLLLLL LLL OE XXXXXLLLHH HHHHHHHHHH HHH CK XXXXXXXXXXH HHLHHLHHHH LHH QO HHHLLZZLHH LLLLHHHLLL LLH Q2 HHHLLZZHLL LLLLLLLLLLH HHH Q3 HHHLLZZZHLL LLLLLLLLLLL LLL

## Functional Description

Shown below is a schematic of two PAL devices implementing a 5-bit up asynchronous ring counter with programmable rollover, asynchronous load, and reset. Initial count point can be loaded by asserting /LD low. Rollover point is loaded by asserting /LR
low. Q4 ..Q0 and R4...R0 are compared in the PAL16C1 device which is implemented as a comparator. The result of the comparison is fed back from the PAL16C1 logic circuit to the PAL20RA10 device through the /RST line. Note that a Master Reset must be executed first before an initial "countdown" point can be loaded.

## Block Diagram



PAL Device Design Specification

PAL16C1
ROLLO2
ROLIO2
COMPARATOR
MONOLITHIC MEMORIES INC., SANTA CLARA, CA $\begin{array}{lllllll}\text { Q4 } & \text { Q3 } & \text { Q2 } 21 & \text { Q0 } \\ \text { RO } & \text { R3 } & \text { R2 R1 } & \text { GND } \\ \text { NC } & \end{array}$

EQUATIONS
/RST
$=\mathrm{Q} 4 * / \mathrm{R} 4 * / \mathrm{MR}+1 \mathrm{Q} 4 * \mathrm{R} 4 * / \mathrm{MR}$ $+\mathrm{Q} 3 * / \mathrm{R} 3 * / \mathrm{MR}+/ \mathrm{Q} 3 * \mathrm{R} 3 * / \mathrm{MR}$ $+\mathrm{Q} 2 * / \mathrm{R} 2 * / \mathrm{MR}+/ \mathrm{Q} 2 * \mathrm{R} 2 * / \mathrm{MR}$ $+\mathrm{Q1*} / \mathrm{Rl} / / \mathrm{MR}+/ \mathrm{Q1*R1*/MR}$
$+\mathrm{QO} / \mathrm{RO} / \mathrm{MR}+/ \mathrm{QO} \mathrm{RO} / \mathrm{MR}$
;COMPARE Q4 \& R4 MSB ; COMPARE Q3 \& R3 ; COMPARE Q2 \& R2 ; COMPARE Q1 \& RI
; COMPARE QO \& RO LSB
FUNCTION TABLE
Q4 Q3 Q2 Q1 Q0 R4 R3 R2 R1 R0/MR /RST

;43210 43210 R
HLLLL LLLLL H
LHLLL LLLLL H
LLLLHL LLLLLL H
LLLLH LLLLL H
LLLLL HLLLL H
LLLLLL LHLLL H
LLLLL LLLHL H
LLLLL LLLLH H
LLLLL LLLLL H
HHHH HHHHH H
LHLHL LHLHL H
HLHLH HLHLH H
HHHHH LLLLLI
14 TEST ODD CHECKERBOARD
16 TEST MASTER RESET

## DESCRIPTION

PALIGCI DESIGN SPECIFICATION
5-BIT COMPARATOR WITH MASTER RESET OVERRIDE
(SECOND OF THE TWO PALS SOLUTION ON THE 5-BIT COUNTER WITH PROGRAMMABLE ROLLOVER, ASYNCHRONOUS LOAD AND RESET.) MONOLITHIC MEMORIES INC., SANTA CLARA, CA

7/19/84
THIS DEVICE COMPARES 5 BITS OF DATA (R4...RO) WITH Q4... 0 AND ASSERTS /RST IF THEY ARE EQUAL. THEREFORE/RST
GOES LOW WHEN PROGRAMMED ROLLOVER POINT R4...RO MATCHES COUNT Q4...Q0./RST ALSO GOES LOW WHEN /MR goes Low, INDICATING A MASTER RESET.
NJTE: THIS PAL DESIGN SPEC WAS ASSEMBLED ON PALASM V1.7


9 99 g g9g 9g gg gig gg gg gg g OE XXXXXLLLHH HHHHHHHHHH HHHHHHHHHH HHHHHHH CK XXXXXXXXXH HHLHHLHHHH LHHLHHHLHH LHHHHHL QO LLLHHZZHLL HHHHLLLHHH HHLLLHHHHL LLHHHHH
Q2 LLLHHZZLHH HHHHHHHHHL LLLLLLLLLLL LLLLHHH
Q3 LLLHHZZLHH HHHHHHHHHH HHHHHHHHHH HHHHHLI


CHIP DN_COUNTER PAL2ORA1O
OE RO R1 R2 R3 R4 QO Q1 O2 O3 R4 VCC GN
simulation
PL OE CK QO Q1 Q2 Q3 Q4

CHECK /QO /Q1 /Q2 /Q3 /Q4

SETF /D0 /D1 /D2 /D3 /D4 LD SETF /OE/Q4/Q3/Q2/Q1 QO/LD
4.

FOR I:=1 TO 7 DO
SETF
$\mathrm{SETF} / \mathrm{CK}$
$\mathrm{IF} \mathrm{I}=2$
THEN
CHECK Q4 Q3 Q2/Q1/QO
IF $I=6$ THEN
CHECK Q4 $\mathrm{QB}^{2} / \mathrm{Q2} / \mathrm{Q1} / \mathrm{QO}$
END
CHECK Q4/Q3 Q2 Q1 QO
END
;Test SET function ; of registers register outputs ;Test RESET funct.

Disable RESET, load tristate registers lload regs w/ dat Disatput bus.
;TRISTATE function. w/ LlLLH \& clocked
; 7 times.
; Rollover at $\mathrm{I}=2$
; count goes LLLLL
to HHHHH.
Check rollover pt.

This application is for a seven-bit register with handshake logic. The chip can be used for interfacing between a microprocessor and its peripheral I/O. The on-chip flag flip-flop provides the handshaking capability required in typical demand-responsebased data transfer. Both the register and the flag flip-flops are asynchronously cleared by CLR signal.

## Block Diagram


and at the same time, the event is signified by asserting DRDY signal. The DRDY signal indicates that the data is available in the register. By monitoring the DRDY signal when it is high, the stored input data can be transferred to Q output port by asserting /OE three-state control signal. After moving the data, DACK signal should be applied to clear the flag flip-flop.

## Handshake Operation



Seven-Bit I/O Port with Handshake Logic
DACK

## PAL Device Design Specification

Title Pattern
Revision
Author Company Sadahiro Horiko / Kelvin Chow
Company Monolithic Memories Inc., Santa Clara, Ca
Date
$3 / 1 / 85$
CHIP IOPORT PAL2ORA1O
PL D0 D1 D2 D3 D4 D5 D6 CE DCLK CLR GND
OE DACK DRDY NC $86 \quad 85 \quad 84 \quad 83 \quad 22 \quad 81 \quad 80 \quad$ VCC
EQUATIONS

| Q0 | : $=$ D0 | ; LSB of 7-bit regs |
| :---: | :---: | :---: |
| QO. CLKF | = DCLK | ; External clock |
| QO. SETF | = CLR | ; Clear register |
| QO.TRST | $=\mathrm{CE}$ | ;Tristate control |
| 21 | := D1 | ; Data 1 |
| Q1. CLKF | = DCLK | ; External clock |
| Q1. SETF | = CLR | ; Clear register |
| Q1.tRST | $=C E$ | ;Tristate control |
| Q2 | := D2 | ; Data 2 |
| Q2. CLKF | $=\mathrm{DCLK}$ | ; External clock |
| Q2. SETF | = CLR | ; Clear register |
| Q2.TRST | $=\mathrm{CE}$ | ;Tristate control |
| Q3 | := D3 | ; Data 3 |
| Q3. CLKF | $=$ DCLK | ; External clock |
| Q3. SETF | = CLR | ; Clear register |
| Q3.TRST | $=C E$ | ;Tristate control |
| Q4 | := D4 | ; Data 4 |
| Q4.CLLKF | = DCLK | ;External clock |
| Q4.SETF | = CLR | ; Clear register |
| Q4.TRST | $=\mathrm{CE}$ | ;Tristate control |
| Q5 | : $=$ D5 | ; Data 5 |
| Q5.CLKF | = DCLK | ;External clock |
| Q5.SETF | = CLR | ; Clear register |
| Q5.TRST | $=C E$ | ;Tristate control |
| Q6 | := D6 | ;Data 6 |
| Q6.CLKF | $=$ DCLK | ; External clock |
| Q6.SETF | = CLR | ; Clear register |
| Q6.tRST | CE | ; Tristate control |
| DRDY | := GND | ;Handshake logic |
| DRDY. CLKF | = DACK | ; Cleared by DAck |
| DRDY.RSTF | = DCLK | ; Clear |
| DRDY.SETF | = CLR | ;Asserted by DCLK |
| DRDY.TRST | = vcc | ; (External clock) |

TRACE ON CLR QO Q1 Q2 Q3 Q4 Q5 Q6 DCLK DRDY DACK
SETF PL /CE /OE /DO D1 /D2 D3 /D4 D5 /D6 CLR /DCLK /DACK iset input values
;Remove the tri-
istates on the ;outputs and clear ;registers

SETF CLR
SETF /CLR
SETF DCLK
SETF DCLK
SETF /DCLK
; Clock the data $\&$ ;set DRDY register

SETF DACK
SETF DACK
SETF /DACK
SETF /DACK
;Remove the clock
;Assert DACK
;Lower DACK

Simulation Results


## Functional Description

Original application was developed by LTT, Conflans Ste. Honorine, FRANCE. Part of the schematics, reprinted with courtesy of LTT, is used to control a serial data link based upon a specialized LSI chip.
Originally designed with six standard SSI/MSI circuits, this same function can now be implemented, not only into a single PAL20RA10 device, but with even more features and better performance. The function can be divided into three subfunctions:

1. Address Decoding
2. Control Flags
3. Transmission Speed Selection

Up to four address lines are allowed (eight were actually used), plus two extra lines which are special decoding controls (MEM/IO selection, Enable Control . . .). Two flip-flop load flag conditions, from the address bus (A1 and A2), providing handshake between the 6850 UART and the communication lines. They have a common clock which also serves as Chip Select (CSO) for the UART.

The UART Transmit clock (TXCLK) can be directly connected to the Receive Clock (CK or RXCLK) or represents the Receive Clock value divided by sixteen. This function was performed by four D-type Flip-Flops connected as a 4-stage Asynchronous Divider. Since each basic cell, used in a PAL20RA10 device has four Product Terms available, this function could be implemented either asynchronously or synchronously. In the PAL Design Specification example, a 4-bit synchronous divider was used instead of the asynchronous circuit shown in the schematic.

## Pin Description

1. TEST ............ Allows preload function for testing
2. SYSRESET ........ Reset line from microprocessor.

A2 ................. Address line from address bus.
4. A1 ............. Address line from address bus

HDSHAKE ........ Handshake line (CTS/RTS).
CK External clock
7. E ................................. Enable line from microprocessor
AUXDECOD . . ..... Extra decoding line (e.g. board level decoding)
9. A3 . . . . . . . . . . . . . . Address line from address bus
10. A4 ............... Address line from address bus.
11. A5 .............. Address line from address bus.
12. GND .............. Reference power supply ground
13. /OE ............... Output enable line.
14. A6 ............... Address line from address bus
15. SPEEDSEL . . . . . . . . Speed selection line.
16. DIV4 ............ MSB 4-bit synchronous counter.
17. DIV3 .............. 3rd stage synchronous counter.
18. DIV2 ............ 2nd stage synchronous counter.
19. DIV1 ............. LSB 4-bit synchronous counter.
20. CSO ............... UART chip select line (CSO)
11. BLOCREC ........ Bloc receive line.
22. DIR DIV ............ Direct or divided clock.
23. /TPH .............. External use flag
24. VCC

5 V power supply



Figure 6.
After


Figure 7.

## PAL Device Design Specification



## Simulation Results

|  |  | gg gg gg g | g9 | gg gg gg |
| :---: | :---: | :---: | :---: | :---: |
| Al | ХхнннннНнH | НННННННННН | HHHHHHHHHH | HHHHHHHHHH |
| A2 | Ххнннннннн | нНнннннННн | нННННННHHH | HННННнHHH |
| A3 | ХхнннннннН | нннннНнНнН | нНнННнНнHH | НННННННННН |
| A 4 | ХхнННННННН | нНнННННнНН | НННННННННН | НННННННННН |
| A5 | ХхнннннннН | нннннннннн | нНнНнннннН | НННННННННН |
| A6 | XXLLLLLLLLL | LLLLLLLLLL | LLLLLLLL | Llllllllll |
| E | ХХННнНнНнH | нHHHHHHHHH | HHHHHHHHHH | HHHHHHHHHH |
| AUXDECOD | XXHHHHHHHH | HHHHHHHHHH | HHHHHHHHHH | HНННННнHHH |
| SYSRESET | HHLLLLLLLL | LLLLLLLLLL | LLLLLLLLLL | LLLLLLLLLL |
| /TPH | LLLLHHHHHH | нНннHHHHHH | HHHHHHHHHH | HHHHHHHHH |
| HDSHAKE | LLHHHHHHHH | HHHHHHHHHH | нНнННннннн | HHHHHHHHHH |
| Cso | ХХНHHHHHHH | HНННННнНнH | HHHHHHHHHH | нННнНННННН |
| SPEEDSEL | LLLLLLLLLLL | LLLLLLLLLL | LLLLLLLLLL | LLLLLLLLLL |
| DIRDIV | LLLLHHHHHH | нннннннннн | ННННHHHHHH | нннннннннн |
| CK | XXXXXHHLLHH | LHHLHHLHHL | HHLHHLHHLH | HLHHLHHLHH |
| DIV1 | XLLLLLHHHL | LLHHHLLLHH | HLLLHHHLLL | HHHLLLHHHL |
| DIV2 | XLLLLLLLLH | HHHHHLLLLL | LHHHHHHLLL | LLLHHHHHHL |
| DIV3 | XLLLLLLLLL | LLLLLHHHHH | HHHHHHHLLL | LLLLLLLLLH |
| DIV4 | xLLLLLLLLL | LLLLLLLLLL | LLLLLLLHH | HHHHHHHHHH |

Page : 2

| A1 | HHH |
| :--- | :--- |
| A2 | HH |
| A3 | HHH |
| A4 | HHH |
| A5 | HH |
| A6 | LLI |
| E | HH |
| AUXDECOD | HHH |

3

| DIV3 | HHHHHHHHHH |
| :--- | :--- |
| DIV4 | HHHHHHHHHH |



## Functional Description

One of the more widely used computer families is the Digital Equipment Corp.'s PDP-11 series. This family of computers uses the DEC unibus to communicate between cards. A specific protocol is required to interface a card to the unibus. This protocol is described in the available DEC literature.
Since the unibus is an asynchronous bus, much of the interface circuitry consists of combinational logic to generate specific signals and flip-flops which are set and reset as flags. This tends to use a lot of SSI and MSI logic packages. Using Monolithic Memories' PAL devices, much of this logic can be condensed into a few packages. Figure 2 is the schematic diagram for an interrupt Controller to be used on the unibus. (p. 6-30 of the 1976 DEC PDP-11 Peripherals Handbook.)

Many cards communicate over the bus by taking control of the unibus with an interrupt request, and then do whatever they require before releasing control. As can be seen, this interrupt controller takes six special interface ICs, ( 380 and 8881 bus
drivers and receivers) eight MSI, SSI ICs, (7400, 7402 nad 7474s) along with some transistors and discrete parts. This parts count can be considerably reduced by using PAL20RA10 and PAL20L10 devices.

Figure 1 shows how the circuit with the PAL devices would look. The two PAL devices allow almost all of the 7400,7402 and 7474 packages to be removed. (Almost a $4-1$ saving in chip count.) In addition the preload pin (PRLD) on the 20RA10 allows the flipflops to be easily set to a known state on power up, or when re-initializing. So the PAL devices reduce the logic package count from eight chips to three.
This shows that by using PAL devices substantial space and circuit savings can be realized when interfacing to the unibus. In the schematic shown, thre are three VLSI devices, three MSIs and two SSIs. Using a PAL20RA10 logic circuit, it is possible to replace three MSIs and one SSI device, thereby reducing the chip count by a factor of two. The ICs inside the enclosed loop were replaced.



## PAL Design Specification

|  |  |  |
| :---: | :---: | :---: |
|  |  |  |
| INTERRUPT LOGIC |  |  |
| MONOLITHIC MEMORIES INC., SANTA CLARA, CA |  |  |
| INTRAH INTRAHEN MCLEARAH INTRBH INTRBHEN MCLEARB |  |  |
|  |  |  |
| STARTINTRBL FF3RESET ENINTRB INTRDONEBH INTRDONEAH EN8881 |  |  |
| SSYN NBGINBH FFIRESET ENINTRA NBGINAH VCC |  |  |
| EQUATIONS |  |  |
| /NBGINAH | BGINAH | ;FFI CLK CONTROL |
|  |  | ; block A |
| /FF1RESET | = MCLEARAH+ENINTRA | ; SET FFI CONTROL |
|  |  | ; BLOCK A |
| /ENINTRA | $=$ INTRAHEN*INTRAH | ; ENABLE INTERRUPT |
| /NBGINBH | $=$ BGINBH | ; FF3 CLOCK CONTROL |
|  |  | ; block b |
| /SSYN | = BUSSSYNL*BUSBBSYL |  |
| /EN8881 $=$ STARTINTRAL*STARTINTRBL |  |  |
|  |  |  |
| / INTRDONEAH | BUSSSYNL+STARTINTRAL | ; INTERRUPT BUS <br> ;SIGNAL INTERRUPT |
|  |  | ; DONE |
| /ENINTRB | $=$ INTRBH*INTRBHEN | ; ENABLE INTERRUPT |
| /FF3RESET | = MCLEARBH+ENINTRB | ; SET FF3 CONTROL |
| /INTRDONEBH | +STARTINTRBL | ; BLOCK B |
| finrdonedr | BUSSSYNL+STARITNIRBL | ; DONE |

PAL20L10
INTRPO1
INTERRUPT LOGIC
INTRAH INTRAHEN MCLEARAH INTRBH INTRBHEN MCLEARBH BGINBH BGINAH BUSSSYNL BUSBBSYL STARTINTRAL GND
IARTINTRBL FF3RESET ENINTRB INTRDONEBH INTRDONEAH EN8881
EQUATIONS

DESCRTPTION
COMBINATORIAL LOGIC FOR PAL2ORAIO INTERRUPT CONTROLLER
(IST PART OF THE TWO PALS SOLUTION: PAL2OLIO \& PAL2ORA10) MONOLITHIC MEMORIES INC., SANTA CLARA, CA DAN KINSELLA 7/19/84
NOTE: THIS PAL DESIGN SPEC WAS ASSEMBLED ON PALASM V1.7.


Figure 2.




High performance Programmable Array Logic devices are powerful building blocks for video system applications. In this paper a tutorial approach is taken to describe the synthesis of a personal computer-based video digitizer peripheral. The design exercise features typical video frame buffer functional modules such as a time base generator, memory address generator and
memory control logic which are integrated into a single MegaPAL ${ }^{\text {Tu }}$ device. To maximize the information transfer from this tutorial the reader should be moderately familiar with general PAL design concepts, however, a minimal amount of video knowledge is required to grasp the design implementation.



## HOW TO GET LUCKY IN CALIFORNIA

Hello my name is Alfie Gilbert. That is me on the right with my supervisor, John Birkner. John co-invented the PAL logic circuit back in 1977 and has championed these remarkable devices ever since. As a token of MMI's appreciation of John's effort, he drives a PORSCHE CARRERA which is quite a beautiful car. Not bad John, not bad at all!

If you take the time to ask John how one might be so lucky as to be handed the keys to a turbo, he will answer you in one word, INNOVATE. So how do I innovate my way into a Porsche you are probably wondering? If you are a mature electronic engineer, you no doubt have some strong ideas and some direct innovative work experiences to serve as guidelines. Students and recent graduates however face a little different challenge. Although these individuals typically have few preconceptions about what is feasible, which is quite an asset, they often have not experienced the design process.
保 the tradeoffs and "tricks-of-the-trade" involved with logic design. If you are a student, I hope this application will help focus your creativity into something rewarding like John's car. GO FOR IT!

As you probably noticed by now, this application note is written in the literary first person which is very unusual for technical subjects. I chose this style because I wanted to relate to you directly, designer to designer. Although I am presently employed as an applications specialist, I enjoy teaching electronics as a second career, which over the years has put me in direct contact with many students who seem to share one thing in common, the desire to invent something. PAL devices from the student perspective, are ideal vehicles for creative design because they directiy realize digital logic equations in silicon. If a design can be described with Boolean algebra or state equations, it can be built with PAL devices. All this magic is made possible by systematically burning out a fuse array, the height of simplicity in ASIC design.

## SOME PERSPECTIVE

PAL logic circuits participate in a segment of the semiconductor marketplace known as ASICs, which is an acronym for Application Specific Integrated circuits. Programmable Array Logic, Gate Array, Standard Cell, and Full custom technologies compete for market share in the ASIC arena. Typically, ASICs implement the functionality that would occupy a whole circuit board of standard MSI logic onto a single chip. Of the four ASIC technologies, PAL devices are by far the simplest to use. PAL-based designs typically can be implemented in a far shorter timeframe than with the other three alternatives. Development systems for PAL designs are less expensive as well. A typical PAL development system consists of a personal computer and a programming unit. This FRAME GRABBER design exercise, for example, was done using a COMPAQ computer, a VARIX programmer, and a TEKTRONIX scope. The pearl of wisdom which I would like to pass on to the reader is simple: No matter what you are designing or what technology (ASIC or standard logic) you use to design, it is easier to prototype the design with PAL devices. Any designer will tell you that pals are great building blocks. Pros also know that true artists SHIP thier product FIRST. This is known as opening the window of opportunity and it is very crucial to the success of a product. The following is an excerpt from the Macintosh Design Case History article which appeared in IEEE SPECTRUM DECEMBER 1984. If you have a chance, read the entire article.


#### Abstract

The computer's circuit density was one bottleneck. Mr. Smith had trouble paring enough circuitry off his first two prototype to squeeze them onto one logic board... Another problem with the Macintosh display was its limited dot density... Mr. Smith could think of but one alternative: combine the video and other miscellaneous circuitry on a single custom $n$-channel MOS chip. Mr. Smith began designing such a chip in February 1982. During the next six months the size of the hypothetical chip kept growing... After thinking about the problem for three months, Mr. Smith concluded in July 1982 that "the difference in size between this chip and the state of Rhode Island is not very great." He then set out to design the circuitry with higher-speed programmable array logic--as he had started to do six months earlier. He had assumed that higher resolution in the horizontal video required a faster clock speed. But he realized that he could achieve the same effect with clever use of faster bipolar-logic chips that had become available only a few months earlier. By adding several high speed logic circuits and a few ordinary circuits, he pushed the resolution to 512 dots. Another advantage was that the PALs were a mature technology and their electrical parameters could tolerate large variations from the specified values, making the Macintosh more stable and more reliable-important characteristics for a so-called appliance product.

\section*{WHAT WIZARDS KNOW}

The fellow referred to as Mr. Smith in the excerpt from SPECTRUM is Burrell Smith. It is amusing that Burrell's business card really does read "HARDWARE WIZARD" which is a fairly accurate title considering his handiwork. He and Andy Hertzfeld (computer cult heroes out here in Silicon valley) wrote a great technical description of the Macintosh System Architecture and System Software for BYTE Magazine, February 1984 (Volume 9, Number 2). I encourage you to reference that issue to get some insight into how creatively PALs may be employed in system design. The six PAL devices which are designed into the Macintosh are a lot more than "glue logic". They form the core of the video graphics/bus management hardware. I can not elaborate too much more on the functionality of the Macintosh PAL set without touching on some proprietary subjects, so I won't, other than to mention that the MAC PAL devices are all from the " 20 pin " family, PALl6R8-type parts. As you probably guessed, I own a MAC (as well as several other computers which I keep for historical reasons) really like it, and respect its designers. NICE WORK FOLKS!


## OLD PAL DEVICES, NEW PAL DEVICES

Technology has a way of marching on, with us or without us, therefore a substantial part of the design challange is often in picking the technological alternative which is most in league with the future. When Burrell Smith designed the MAC's PAL set (back in 1982) the industry "workhorse" was the PALI6R8/PAL16L8 family of parts. The big advances at that time were in the speed area, fast (A) PAL devices which featured a propagation delay of only 25 ns were novel. Of course today in 1985 we have even faster (B) PAL logic circuits which save yet another 10 ns of the propagation delay resulting in a blazing fast TPD of only 15 ns . Over the past few years, we have also seen the power consumption of MMI PAL devices decrease by a factor of two ( -2 ) and a factor of four ( -4 parts). Most of these improvements and variations in speed and power for the 20 -pin family have resulted from changes in our semiconductor process. All of these changes are certainly noteworthy, however, I think ARCHITECTURE is the area where MMI has really advanced by leaps and bounds. In 1984, MMI brought to market the first parts of our megaPAL family, the PAL64R32 and the PAL32R16 devices. MMI was flattered to be given the PRODUCT of the YEAR award (Electronic Products Magizine) for the PAL64R32 logic circuits. I chose it for the heart of this design exercise. Our megaPAL devices feature several significant architectural improvements over previous PAL devices most notably, product term sharing, programmable output polarity, and register bypass. The PAL64R32 device has 32 input pins, 32 output pins, and 256 product terms to relate the inputs to outputs. The PAL64R32 logic circuit is four times as dense as the PALl6R8 device, one of which is also included in this design exercise, because it will soon be fabricated in CMOS.

## DIFFERENT STROKES FOR DIFFERENT FOLKS

Equally significant to the megaPAL, in terms of architecture, is another new PAL from MMI, the PAL2ORAlO logic circuit (the RA in the designator stands for Registered Asynchronous). Each of the 10 identical macrocells of the 20RAlo features a 7474 type D flip-flop which may be asynchronously set or reset (via a product term). The clock to the macrocell register is also derived from a product term which is a somewhat radical departure from traditional PAL architectures. Other features of the 20RAlo include macrocell register bypass (this is accomplished by simultaneously asserting set and reset, which of course is an illegal condition for a 7474 register), and programable output polarity. The PAL2ORAlO device is an extremely flexible and unstructured device. It is ideal for interfacing dissimilar signals, or interfacing to an asynchronous system bus. Needless to say, I have also chosen to include the PAL2ORAlo device in this design exercise. MegapAL devices are highly structured logic elements which make them ideal for synchronous logic. The

PAL2ORAlO logic circuits are just the opposite, they are flexible and most effective in asynchronous environments. Because most applications have elements of structured and random logic, I am very enthusiastic about designing with megapal devices and PAL2ORAlo logic circuits in tandem. The "trick", of course, is to partition the system so that synchronous logic is realized in the highly structured megaPAL device while the random logic is implemented by the more flexible RA PAL.

THE IBM (INVERSE BURRELL MACHINE) CHIP SET
As I am sure you have noticed, computer coupled raster graphics video systems have abounded in recent years. In just the consumer electronic sector we have witnessed the video game, the personal computer, and most recently digital television. This explosive growth, in part, has been fueled by the decreasing cost of memory, specifically RAM. RAM memory is important in modern raster video systems because it retains the luminance and chrominance information required by the display monitor to generate an image. This RAM memory is often refered to as the bit map of the video raster. A video controller is a device which facilitates a one-to-one pairing between each bit of the video RAM array and a specific location (coordinate) on the monitor's display tube. If you did investigate the Macintosh's video design, you no doubt realize the power and flexibity of PAL devices in implementing video controllers. What I propose we do together at this point, is invent a widget that does the INVERSE operation of a video controller, specifically a video digitizer/frame buffer. Video controllers typically pull information out of RAM to form an output signal known as "composite video", our unit accepts composite video as input and stores that information in a RAM array. We will call it a FRAME GRABBER because that is exactly what it does. The host environment for our FRAME GRABBER will be a personal computer. This environment will provide a debug monitor during development and allow us to "reconstruct" our digital image thru the PC graphics mode for display. The FRAME GRABBER will interface thru the I/O channel of ubiquitous IBM-PC compatible computers. Application support software to simulate "gray scale" will be writen in a higher level language (turbo Pascal), rather than Assembly language, in the hopes of being self explanatory.

Before beginning our design exercise, let us review some video principles and get familiar with the signals which we will be dealing with. If you have no idea how a television works, Milt Wilcox wrote a good application note titled A Color TV Primer for the E.E. Which may be found in National Semiconductor Linear Applications Handbook. It is worth reading, as is the video section of Donald Finke's classic Electronic Engineering Handbook.

## A BRIEF OVERVIEW OF VIDEO

Suppose we focus a typical consumer video camera (VHS or Beta format) on a target such as the one depicted in FIGURE ONE. The output signals of these types of video cameras were standardized several years ago by the EIA and formalized in a document known as RS-170A. This type of video signal is often referred to as "NTSC composite video" because it contains four distinct signal components which are merged together (for better or worse if you are a videophile). These four signals are luminance(brigthness) chrominance (color), audio (sound), and synchronization. This type of signal is sufficient to directly drive most monitors, and is also the basis for television broadcast as well. The output signal of most video sources (VCRs, Videodisks,etc.) that are sold in North America are also composite video, thus making them identical to this video camera example. That fact is handy to know, because it insures that our FRAME GRABBER widget will be compatible with most contemporary video sources (compatibility is a very important issue and should always be carefully considered by the designer as early as possible in a product design cycle).


Let's investigate the video output signal generated by the camera aimed at the "gray bar" target depicted in FIGURE ONE. The camera signal illustrated in FIGURE TWO is for the "scan" from point A to point B. The important thing for the reader to notice is that the camera output signal is proportional to the brightness (luminous intensity) of the target during the scan fron A to B. This process of scanning from right to left happens 262.5 times as the target is traversed from top to bottom. In between each scan is a time interval known as horizontal retrace (or H sync). During this time the target scan is blanked as the raster retraces its path to get into position just slightly below point $A$. The scan process then repeats. The horizontal retrace time interval may be seen in the camera output signal of FIGURE TWO as the "pulse" which is labeled SYNC. It takes about 64 ms for a scan and retrace to occur. A collection of 262.5 consecutive

At this point, the scan blanks for a rather long time (the interval is known as vertical retrace and lasts for a period equal to 20 horizontal scans) as the raster moves vertically to the top of the target again. The whole field is then traced out again, however, the scans of the second field are offset by half a horizontal line. Two consecutive fields of video are known as a VIDEO FRAME. It is precisely this amount of information, a frame, which our widget will digitize and store in RAM, because this is the minimum information required to reconstruct an image. The total number of horizontal scans in one video frame is 262.5 scans/field times 2 fields/frame or 525 scans/frame (NTSC composite video is often referred to as a 525 line system). Incidentally, the reason why the two consecutive video fields are offset by half a horizontal scan is a "trick" called interlacing and it is helpful in reducing display tube flicker.


## TIMING IS EVERYTHING

In video systems, even more than in life, timing is critical. Video is a highly repetitive process and every event in that process happens in synchronous with a clock. The "clock" for composite video is usually an integer multiple (harmonic) of the NTSC "color burst" frequency. Color burst frequency is defined by the EIA to be 3.579545 MHz ( a copy of the RS-170A signal standard is included as an appendix to this design exercise). The horizontal scan rate of composite video approximately $15,750 \mathrm{~Hz}$ (one scan period ( H ) $=$ 63.556 ms ). The field rate is $525 / 2$ times the horizontal scan rate (about 60 Hz ) which then makes the frame rate 30 Hz .

## SOME QUICK NUMBERS

On the bus expansion slots of personal computers which are hardware compatible with the IBM-PC is a signal called OSC which has a frequency of 14.318 MHz (fourth harmonic of color burst). Since our FRAME GRABBER widget will be hosted by a PC, it is natural to use OSC as our system clock. The flash A/D conversion rate was chosen to be equal to color burst for this exercise. Some quick calculations on the FRAME GRABBER timing will reveal the following facts: If 30 Hz is the video frame rate and 14.3 MHz is the system clock, 476190 system clock periods will elapse in one video frame. Since a nineteen bit counter is required to count to 476190 , the heart of the FRAME BUFFER will indeed be a counter of this length. If the video signal is digitized to two bits of accuracy per flash conversion and the flash conversion rate is 3.58 MHz ll9050 samples or 238100 bits (roughly 32 k bytes of RAM) will be required to retain the information content of $a$ video frame in memory.


Since the FRAME GRABBER system clock rate is 14.3 MHz and the A/D flash conversion rate is 3.58 MHz four system clock cycles ( 280 nsec ) elapse between conversions. The memory organization is 8 bits wide and the $A / D$ accuracy is 2 bits wide therefore 4 sucessive flash conversions will have to be "packed" into each byte of RAM. Four sucessive flashes will require 16 system clock cycles ( 1.12 ms ) to complete. A 4-bit counter obviously increments to 16 , therfore it is natural to segment our requisite 19-bit counter into a 4-bit counter (which will be implemented as the time base module of the megaPAL design specification) and a 15-bit counter (address generation module). A 15-bit counter increments to 32 k which is the required memory address range to store a video frame at our particular

A/D conversion rates and resolution. The reader can crosscheck these rough numbers by remembering that a memory write occurs every 1.12 ms ( 16 cycles of the system clock) and a horizontal scan takes about 64 ms , therfore 58 bytes are required to store a line of video. There are 525 lines in a video frame, so the address counter will increment to 30,450 over the duration of a video frame in we allow it to "free run". The outputs of the FRAME GRABBER time base module are illustrated in FIGURE THREE, as well as the write enable signal, to the static RAMs (/WRITE), the flash A/D bus output enable (/FLOE) and address counter increment signal (INCADR). This should give some idea of the basic system timing.

## CLAMP PLEASE

In most video cameras, the RS-170 output signal is usually AC coupled at the source for isolation purposes. This situation presents a small problem for the FRAME GRABBER because the input video signal is "floating", i.e., it lacks DC integrity. In order for an AC-coupled signal to be digitized, it must be "clamped" (DC restored) before it can be compared against a series of voltage thresholds. A traditional circuit to accomplish this technique of flash A/D conversion usually involves a series of linear comparators and an accurate resistor network to divide down a precision voltage reference. DC restoration is generally accomplished by "dumping" one side of a coupling capacitor with a transistor during the back porch interval of horizontal retrace. For low-resolution applications, however, a much simpler PAL-based circuit can perform the same function.


The FRAME GRABBER video clamp/flash converter circuit is shown in FIGURE FOUR. Let's investigate how this circuit operates from an analog point of view. The DC voltage at node A (VA) is about 2.1 volts if one assumes each of the three silicon diodes has a forward voltage drop of .7 volt when driven hard (RS must be on the order of 500 ohms). The voltage VB will then be 1.4 volts or one diode drop below VA. If the Thevenin equivalent impedance to ground at node $B$ was infinite, the most negative part of the AC coupled video input signal ( H sync) would be clamped at 1.4 volts by the action of the diodes and capacitor. In reality the circuit is not a perfect clamp because other currents do indeed enter and leave node $B$, but it does work reasonably well if $C$ is large (on the order of 100 microfarads for our $z$ Thevenin of 5 k ohms). The clamped video signal will be diminished at the input nodes $\mathrm{T} 2, \mathrm{Tl}$, and TO by the ratio dictated by the voltage divider formed by R1, R2, R3, and R4. The voltages at nodes T3, T2, T1, and TO implicitly are "compared" against the internal threshold (about 1.4 volts) of the PAL device input structure which causes a logic level discrimination or conversion. This simple flash A/D converter implemented by a PALl6R8 and a few passives performs surprisingly well if the PAL digital noise is mostly common mode with the input (avoid ground loops at all cost). This scheme may easily be extended to 3 bits of resolution which requires 8 thresholds to be encoded, if 1\% resistors are used in the ladder. For higher resolution applications, the design may include comparators to front end the PAL device. Above 3 bits of resolution, a bipolar technology imposed limitation on this A/D technique occurs because the input structure of a TTL PAL device will both source and sink current depending on the voltage magnitude at the input. This leakage current obviously increases with the number of thresholds and has a cumulative negative effect in the resistor string. Future CMOS PAL logic circuits will be ideal for these applications however, because of the high input impedance of CMOS devices.

## THE FRAME GRABBER SYSTEM OPERATION

The FRAME GRABBER system diagram is illustrated in FIGURE FIVE. Three PAL devices form the core of the system. The megapAl device handles most of the timing, address, and control logic. The PALl6R8 handles A/D conversion and local bus interface, while the PAL2ORAIO serves to interface the local bus to the host PC I/O channel bus. To complete the system four 8 k byte static RAMs form the buffer memory and an octal transceiver (74LS245) provides sufficent drive for the I/O channel. The FRAME GRABBER has two modes of operation. When the MODE control bit is high, the unit is in the capture mode. Video input will continuously be digitized and stored in RAM. When the MODE bit is low, or read mode, the PC I/O channel takes over memory control. The byte of buffer memory pointed to by the address counter value can be accessed by an I/O reference to location 100 HEX.


REVISION A
A.G.GILBERT

COMPANY
MMI SANTA CLARA, CA.
DATE

## CHIP FLASH PALI6R8 DEVICE

```
CLK /CLR Q358 Q716 NC T3 T2 T1 TO GND
/OE D0 D1 D2 D3 D4 D5 D6 D7 VCC
;
```

; This design specification module implements a low resolution
; Flash A/D converter. Four input thresholds (T3 thru TO) are
synchronously encoded into two bit groupings, then "packed"
four times to form an output byte. This packing operation is
accomplished by two parallel four bit shift registers which
are functionally implemented in this PAL device. One shift register
operates on even bits while the other on odd bits (e.g.
D0 - D2 - D4 - D6). These CONVERSION/SHIFT operations occurs
on the rising edge of the 14.3818 MHz system clock when time
base input clocks are in the proper state. Four periods of the
system clock elapse between sucessive Flash conversions for an
effective Flash rate of 3.58 MHz . If the clamped video input signal
has sufficent magnitude to cross the upper three thresholds (white)
the two bit encoding would be ll. If none of the four thresholds
(Hsync) were crossed, the encoding would be 00 . The first encoding
in a sequence of four flashes will end up registered in D7 and D6.
The last encoding will be registered in DI and DO. A monotonically
increasing video signal from Hsync to black to gray to white
would be represented by 00011011 after packing. Get the idea?
One final comment, the PALI6R8 device does not have an output
polarity fuse, therefore, this design specification module
is implemented in negative logic.
;
EQUATIONS





| REVISION | A |
| :--- | :--- |
| AUTHOR | ALFIE / KELVIN |
| COMPANY | MMI, SANTA CLARA, CA |
| DATE | $12 / 20 / 84$ |

CHIP INTERFACE PAL2ORAIO DEVICE

```
NC AEN /IOW BA9 BA8 BA7 BA6 BA5 BA4 DO Dl GND
/OE D2 /FBRRD /FBRWE INC /CLRADR MODE Q3 /IOR /245EN D3 VCC
This design specification module implements a nibble wide (four bit)
control register for the FRAME GRABBER unit. The outputs of this
module respond to the address, data, and control lines of the host
Personal computer which must be hardware compatible with the IBM PC.
Some of the outputs are combinatorial while others are registered for
obvious reasons. This module is implemented in mixed logic and
demonstrates the superior flexibity of this new PAL device.
EQUATIONS
FRAME GRABBER CONTROL REGISTER MODULE
```

```
CONTROL REGISTER "INC" BIT
```

CONTROL REGISTER "INC" BIT
OUTPUT IS DERIVED FROM HOST COMPUTER DATA BUS LINE DO
IF AN I/O WRITE OCCURS AT LOCATION llO THRU llF HEX
;
INC
:= DO
INC.CLKF =/AEN*IOW*/BA9*BA8*/BA7*/BA6*/BA5*BA4

```
; CONTROL REGISTER "/CLRADR" BIT
; CONTROL REGISTER "/CLRADR" BIT
IF AN I/O WRITE OCCURS AT LOCATION llo THRU llF HEX
;
/CLRADR \(:=/ D 1\)
/CLRADR.CLKF \(=/\) AEN*IOW*/BA9*BA8*/BA7*/BA6*/BA5*BA4
CONTROL REGISTER "MODE" BIT
OUTPUT IS DERIVED FROM HOST COMPUTER DATA BUS LINE D2
IF AN I/O WRITE OCCURS AT LOCATION 110 THRU 11F HEX
;
MODE \(\quad:=\mathrm{D} 2\)
MODE.CLKF \(\quad=/ A E N * I O W * / B A 9 * B A 8 * / B A 7 * / B A 6 * / B A 5 * B A 4\)
; UNUSED CONTROL REGISTER BIT
; ALSO RESPONDS TO AN I/O WRITE TO 11X HEX
;
Q3 := D3
Q3.CLKF \(\quad=/ \mathrm{AEN} * I O W * / B A 9 * B A 8 * / B A 7 * / B A 6 * / B A 5 * B A 4\)
; HOST SYSTEM I/O DECODER
```

; THIS COMBINATORIAL OUTPUT IS USED TO ENABLE THE BUS BUFFER
74LS245 IF THE HOST REFERENCES I/O LOCATIONS 100 THRU IIF HEX
;
245EN =/AEN*/BA9*BA8*/BA7*/BA6*/BA5
; THIS COMBINATORIAL OUTPUT IS USED TO FILL THE FRAME BUFFER
; RAM LOCATION POINTED TO BY THE ADDRESS GENERATOR WHEN
; THE HOST COMPUTER WRITES TO I/O LOCATION IOX HEX
FBRWE =/AEN*IOW*/BA9*BA8*/BA7*/BA6*/BA5*/BA4
; THIS COMBINATORIAL OUTPUT IS USED TO READ THE FRAME BUFFER
; RAM LOCATION POINTED TO BY THE ADDRESS GENERATOR WHEN
; THE HOST COMPUTER READS I/O LOCATION lOX HEX
FBRRD =/AEN*IOR*/BA9*BA8*/BA7*/BA6*/BA5*/BA4
SIMULATION
TRACE_ON AEN /IOR /IOW BA9 BA8 BA7 BA6 BA5 BA4 D3 D2 D1 DO
SETF OE /AEN /IOR IOW /BA9 BA8 /BA7 /BA6 /BA5 BA4 D3 D2 D1 D0
SETF /IOW /DO
SETF IOW /D2 ;CLOCK CONTROL REG
SETF /IOW /D3 /DI
SETF IOW D2 DO
SETF OE /AEN /IOR IOW /BA9 BA8 /BA7 /BA6 /BA5 BA4 /D3 /D2 /D1 /D0
SETF /IOR IOW /BA4
SETF IOR/IOW /BA4
SETF /IOR /IOW /BA9 BA8 /BA7 /BA6 BA5
SETF BA6/BA5
SETF BA7 /BA6
SETF /BA8 /BA7
SETF BA9 BA8
SETF AEN /BA9

```
;ASSERT /FBRWE
;ASSERT /FBRRD
;ASSERT /245EN
;UNASSERT ;ACTIVE ADDRESS ; RANGE

Video Frame Grabber





```

;This equation implements a 2 TO l DATA MULTIPLEXER. The output
;signal (/RAMWE) may be thought of as the write enable line for the
;static RAMs. This output is derived indirectly from either the
;time base generator (/WRI ,) or the host personal computer control
;bus (/FBRWE). This allows the PC to fill the FRAME GRABBER by doing
;an I/O write.
;
/RAMWE =/WRITE * MODE
+/FBRWE */MODE
;This equation also implements a 2-TO-1 MUX, again controlled by the
;mode signal. This signal is used to enable the address counter so it
; can increment (remember that the address counter is clocked by the
;14.3 MHz system clock). The output is derived from the time base
;generator if the FRAME GRABBER is in the capture mode, or from the
irising edge of the input signal INC if the unit is in the read mode.
;INCADR is positive polarity pulse with a duration equal to one system
;clock period which is }70\mathrm{ nsec.
;
INCADR :=/Q716MHZ * Q358MHZ * Q179MHZ * Q090MHZ * MODE */PWRUP
+/INCDLY * INC */MODE */PWRUP
;This bit of logic is used to synchronize the input signal INC with
; the 14.3 MHZ system clock. Notice that the condition of INCDLY low
;and INC high realizes a synchronous rising edge detector for the
;input signal INC (refer to the second product in the logic equation
; for INCADR).
;
HMCOLY := Inc
;
;
;This design specification module generates signals which enable the
;three-state outputs of the Flash A/D and the static RAMs. The Flash
;output enable (/FLOE) is derived from the time base generator and is
;qualified by the unit being in the capture mode. The memory output
;enable (/RAMOE) is derived from the host computer control bus if
; the frame buffer is in the read mode.
;
/RAMOE =/FBRRD */MODE + MODE
FLOE :=/Q716MHZ * Q358MHZ * Q179MHZ * Q09OMHZ * MODE */PWRUP
+ Q716MHZ */Q358MHZ * Q179MHZ * QO9OMHZ * MODE */PWRUP
;This design specification was assembled on an PC compatible ; computer using the beta release of PALASM2 SOFTWARE. The simulation ;was done on a VAX using the alpha release of the simulator. Slight ; variations in syntax may occur at production release. The ;FRAME GRABBER design has not been optimized in the hopes of ;being self explanitory! ...Alfie Gilbert

```

SIMULATION
```

TRACE_ON CLKI CLK2 CLK3 CLK4
/PWRUP MODE FLOE WRITE INCADR
Q716MHZ Q358MHZ Q179MHZ QO90MHZ
A0 Al A2 A3 A4 A5 A6 A7 A8 A9
AlO All Al2

```
\(\begin{array}{rllll}\text { SETF } & \text { OE1 } & \text { OE2 } & \text { OE3 } & \text { OE4 } \\ \text { PSI } & \text { PS2 } & \text { PS3 } & \text { PS4 } \\ & \text { PLI } & \text { PL2 } & \text { PL3 } & \text { PL4 }\end{array}\)
SETF PWRUP MODE
CLOCKF CLK1 CLK3 CLK4
SETF / PWRUP
FOR I:=1 TO 17 DO
    BEGIN
        CLOCKF CLKI CLK3 CLK4
    END
SETF CLRADR
CLOCKF CLK1 CLK3 CLK4
SETF /CLRADR
FOR I:=1 TO 32 DO
FOR I:
        CLOCKF CLKI CLK3 CLK4
    END
SETF AO Al /A2 /A3 /A4
            /A5 /A6 /A7 /A8 /A9
            /Al0 /All /Al2 /Al3 /Al4 ;TOGGLE A2
FOR I: \(=1\) TO 187 DO
    BEGIN
        CLOCKF CLKI CLK3 CLK4
        IF \(I=17\) THEN BEGIN SETF A2 END ;TOGGLE A3
        IF I=17 THEN BEGIN SETF A3 END ;TOGGLE A4
        \(\begin{array}{lll}I F & I=17 \\ I F & I=17 & \text { THEN BEGIN SETF A4 END BEGIN SETF A5 END ;TOGGLE A5 }\end{array}\)
        IF I=17 THEN BEGIN SETF A5 END ;TOGGLE A6
        IF I=17 THEN BEGIN SETF A6 END ;TOGGLE A7
        IF \(I=17\) THEN BEGIN SETF A7 END ;TOGGLE A8
        \(\begin{array}{llllll}\text { IF } & I=17 & \text { THEN BEGIN SETF A8 END } \\ \text { IF } & I=17 & \text { THEN BEGIN SETF A9 END } & \text { TOGGLE A9 }\end{array}\)
        \(\begin{array}{lllll}\text { IF } & I=17 & \text { THEN } & \text { BEGIN SETF A8 END } & \text { TOGGLE A9 } \\ \text { IF } I=17 & \text { THEN } & \text { BEGIN SETF A9 } & \text { END } & \text { TOGGLE A10 }\end{array}\)
        IF \(I=17 \quad\) THEN BEGIN SETF Al0 END \(\quad\) TOGGLE All
        IF I=17 THEN BEGIN SETF All END ;TOGGLE Al2
    END
SETF /A14 /Al3 ;EXERCISE RAM DECODER
\(\begin{array}{lrr}\text { SETF /Al4 } & \text { /Al3 } \\ \text { SETF /Al4 } & \text { Al3 } \\ \text { SETF Al4 } & \text { /Al3 }\end{array}\)
\(\begin{array}{lrr}\text { SETF /Al4 } & \text { /Al3 } \\ \text { SETF /Al4 } & \text { Al3 } \\ \text { SETF Al4 } & \text { /Al3 }\end{array}\)
SETF Al4 Al3
; CLOCK SIGNALS
; CONTROL SIGNALS
; TIME BASE SIGNALS
;ADDRESS SIGNALS
; ENABLE OUTPUTS
;UNASSERT SET
;UNASSERT PRELOAD
; CLEAR TIME BASE
; CLEAR ADDRESS COUNTER
;TOGGLE Al and AO


\section*{}


15－F56－1985 13．12

FRAMERGZ GRABSER
OR


PLL \(64 R 32\)
FRAME GRABBER

PALHBS1．TRF：1 15－FEB－1235 13：12

\section*{PALGLR 32
FRAME GRAGZER
Page E}


PWRUP LLLLLLLLLL LLLLLLLLL LLLLLLLLLL L MLALLLLLL

INCADR LLLLLLLLLL LLLLHALLLL LLLLLLLLLL LLLLLLLLLL
S30MAZ
\begin{tabular}{|c|c|c|c|c|}
\hline & & & & \\
\hline \[
41
\] & MHHHHHAHHH & Harnhrlicl & LLLLLLLLL & LLLLLLLLLLL \\
\hline 42 & & & LLLLLLLLL & LLLLLLLLL \\
\hline \({ }^{4} 3\) & Ll & LlLLLLLLLL & LlLLLLLLLL & LLLLLLLLL \\
\hline \({ }^{4} 5\) & LLLL & LLLLLLLLL & & \\
\hline 46 & LLLLL & L & & \\
\hline A 7 & にしくLlL &  & 以1LLLLLL & \\
\hline 48 & LLLL & 1LLLLLLL & Lllllill & \\
\hline \({ }_{4}{ }^{1} 10\) & LLLLLLL & L & LLLLLLLL & LLLLLL \\
\hline
\end{tabular}




ALO 4 R 32
Page 6

PALHB51．TRF：1
PALOLR 32
FRAME GRABSER
Page
\begin{tabular}{|c|c|c|c|c|}
\hline & \({ }_{\text {LHLSLH }}\) & & LHLHLHLHLH & LMLHLHLHLH \\
\hline CLK2 & LLLLLLLLLL & L & LLLLLLLLLL & LLLLLLLLL \\
\hline CLK3 & LHLHLHLHLH & － & LHLHLHLHLH & \\
\hline & & & & \\
\hline PWRUP & LLLLLLLLL & & LL & \\
\hline MODE & & & & \\
\hline & LLLLLLLLLLLL & LLLLLLLLLL & HHHHLLLLLLL & \\
\hline INCAD & LLLLLLLLLL & LLLLLLLLLL & LLHMLLLLLL & \\
\hline & L & & & \\
\hline 3MH2 & LHAHHLL & LLFHHHLLLL & & \\
\hline 6179 MHz & нННННhimil & LILLLLHHH & HhHHLLLLLL & LLHhHhathe \\
\hline CO90MHz & LLLLLLLLLH & НРН－Нниянн & HMHHLL & LLLLLLLLLL \\
\hline & H－HKHHHHHH & hamahmatha & hHHHLLLLLL & LLLLlllll \\
\hline \({ }_{4}{ }^{4}\) &  &  &  & सHAMHMOHH \\
\hline A3 & & & & LLLLLLL \\
\hline \({ }^{4} 4\) & & －lllillle & LLLLLLLLLL & LLLLLLLLLL \\
\hline \({ }^{4} 5\) & & L & & \\
\hline \({ }_{4}{ }^{\text {a }}\) & & & & \\
\hline \({ }^{4}\) & L & LLLLL & LILL & CLILLLLIL \\
\hline \[
48
\] & & & & \\
\hline A10 &  & Littili & LtLtttiti & KtLtitili \\
\hline \({ }^{\text {A } 11}\) & LLLLLLLLLL & & & \\
\hline
\end{tabular}

Page 4 PALHB51．TRF：1
PALGUR32
FRAMERGRABJER
PEge OB
\begin{tabular}{|c|c|c|c|c|}
\hline & & & & \\
\hline &  & 镯 & & \\
\hline  &  &  & thutlut & \\
\hline  &  &  &  & ram \\
\hline & Н－मutubut & & & \\
\hline \({ }^{4}\) & & & & \\
\hline  & & & & \\
\hline & & & & \\
\hline & & & & \\
\hline
\end{tabular}
\begin{tabular}{|c|c|c|c|c|}
\hline  &  &  &  &  \\
\hline &  & － & 等tuttut & thtuthtid \\
\hline  & LHtLL &  & \＃\＃\＃ctut & ¢¢ \\
\hline \％ & & & & \\
\hline  & \％ & &  & \\
\hline \({ }^{\frac{1}{4} \text { 根 }}\) & & & & \\
\hline  & & &  & \\
\hline & tu &  & &  \\
\hline
\end{tabular}

PALHBST．TRF：
15－FE5－1955 13：12 Page 10



PALHBS1．TRF：1
1う－Fピ－19を5 13：12 Page 12
PALGLRSZ
＝RAME GRABSER
Page 12



\section*{FOOD FOR THOUGHT}

The FRAME GRABBER which we just synthesized in our design exersise is actually half of a video Frame Buffer unit. Video frame buffers have become quite popular in recent years. The key elements of a video frame buffer are illustrated in FIGURE SIX. The concept behind a frame buffer is simpre. A frame buffer stores the incoming video information in a RAM array for future use, and the digitized image has been stored in a memory array, it is often processed by digital signal processing techniques. These techniques may be hardware or software based. Digital signal processing implemented in hardware tend to be very fast (even real time), but expensive, while software signal processing algorithms are slower, but more cost effective in most applications. The most basic type of digital signal processing usually performed on video is image enhancement. Video signals which have been corrupted by noise are likely candidates for image enhancement. In many types of applications image enhancement is often followed by a more complex type of signal processing, known as pattern recognition. This type of signal processing is usually a software algorithm which does not execute in real time and for that reason digital image frames must be buffered in memory.


The popularity of Video Frame Buffers has been both application and technology driven. The ever decreasing cost-per-bit of RAM has made the system designer the size of memory arrays required to store video images of acceptable resolution and gray scale content affordable ASIC technology such as the megapAL device which we just investigated, has streamlined the address, control, and timebase logic of video frame buffers as well. These technological advances have made many applications economically feasible. In the industrial sector these applications include robot control, collision
avoidance, quality control, quality assurance, incoming inspection, surveillance/security systems, and a host of others. If you are starting to get excited about the prospect of innovating something on your own, you are probably pondering what the future will be like. I think we will see vision applications abound in personal computer environments. The combination of an optical imager coupled to a personal computer is the silicon parity of a very familiar organic computer, namely, our eyes and brain. It is only a matter of time until personal computers can read and recognize for us. So my advice to designers is simple : Imagineer before you Engineer! When you get to the point of implementing your ideas, think about PAL devices, they are remarkable axels for the wheels of your mind. I hope you enjoyed reading this design exercise as much as I enjoyed creating it.
```

                                    ... Alfie Gilbert
    ```

Please feel free to send
comments or sugestions to
A. G. Gilbert

MMI 09-26
2175 Mission College Blvd.
Santa Clara, Ca. 95054-1592


```

Type
L = Array [0..239] of Integer;
Fash = Array [0..3] of Integer;
VAR
X1,X2,Y1,Y2,
X,Y,W,
AB,C,H,I,J,K,M,N,P,Num,
Hsync,NO,
remain,
P1,P2,
Byte,
color : INTEGER;
Ch : Char;
Line : L;
Q : Fash;
even,odd : Boolean;
Procedure Check; (* Check to start the program *)
Begin
Writeln('Do you want to display a picture or snap one?');
Write('Continue D/S');
Repeat
Read (kJod, ch)
Until (ch='D') OR (ch='S') OR (ch='d') OR (ch='s');
End;
(* If 's' capture a new frame *)
(* before begining *)
(* If 'd' display last frame *)
(* Upper \& Lower characters *)
(* are both accepted
*)
Procedure Binary(X:Integer; Var Q:Fash);
Var
PI,PJ : Integer;
A : Array[0..7] of Integer;
Flash : Integer;
Begin
PJ :=0;
For PI := }7\mathrm{ Downto 0 Do
(* Convert each value read
Begin
A[PI] := X Mod 2;
X := X Div 2;
End;
For Flash := 0 to 3 Do
Begin
PI := Flash;
If (A[PJ]=0) AND (A[PJ+1]=0) Then Q[PI]:=0;
If (A[PJ]=0) AND (A[PJ+1]=1) Then Q[PI]:=1;
If (A[PJ]=1) AND (A[PJ+1]=0) Then Q[PI]:=2;
If (A[PJ]=1) AND (A[PJ+1]=1) Then Q[PI]:=3;
PJ := PJ+2;
End;
(* Unpack each byte by
*)

```
```

End;
(* converting the 8-bit
(* value into 4 flash values*)
Begin
Check;
GraphMode;
Palette(l);
color := 1;
C := 0;
I := 0;
J := l;
N := 0;
Hsync := 0;
NO :=0;
AB := 0;
If (ch='S') OR (ch='s') Then
Begin
Port[272] := 4;
Port[272] := 6;
For I := 1 To 1l000 Do
AB := AB+1;
End;
Port[272] := 4;
While (C<>20) AND (NO<>22000) Do
Begin
Port[272] := 2;
Port[272]:= 3;
X := Port[256];
NO := NO+1;
If }\textrm{X}=0\mathrm{ Then C := C+1
Else C := 0;
End;
If (NO=20000) AND (C<>20) Then
Write('You need to adjust your light!!');
For I := 1 To 2000 Do
Begin
Port[272] := 2;
Port[272] := 3;
x := Port[256];
End;
For Y := 0 To 199 Do
Begin
(* Start the main program 1. *)
(* If snapping a new picture *)
(* Run the check procedure *)
(* Graphics mode *)
(* Use black color graphics *)
(* Set counter to zero *)
(* Set all initial condition*)
(* delay about 1/30 sec *)
(* to be able to capture the *)
(* video frame after reseting*)
(* the address counter and *)
(* setting the mode bit for *)
(* Reset address counter *)
(* Reset the mode bit for *)
(* Reset the mode bit for *)
(* the address counter *)

```

\section*{(1)}
 (* the address counter *)
```

```
Case remain of
```

```
Case remain of
    0: Even := True;
    0: Even := True;
    1: Odd := True;
    1: Odd := True;
End;
End;
While H<>1 Do (* Look for horizontal sync *)
While H<>1 Do (* Look for horizontal sync *)
    Begin
    Begin
        Port[272]:= 2;
        Port[272]:= 2;
        Port[272]:= 3;
        Port[272]:= 3;
        X:= Port[256];
        X:= Port[256];
        If X=0 Then
        If X=0 Then
            Begin
            Begin
                Binary (W,Q) ;
                Binary (W,Q) ;
                For I :=0 TO 3 Do
                For I :=0 TO 3 Do
                Line[I] := Q[I];
                Line[I] := Q[I];
                Binary (W,Q) ;
                Binary (W,Q) ;
                For I :=0 TO 3 Do
                For I :=0 TO 3 Do
                Line[I+4] := Q[I];
                Line[I+4] := Q[I];
                H:= = 1;
                H:= = 1;
            End
            End
        Else (* Else assign X to previous *)
        Else (* Else assign X to previous *)
        Wlse
        Wlse
    End;
    End;
K := = 7;
K := = 7;
For I := 1 To 55 Do (* At this point the first *)
For I := 1 To 55 Do (* At this point the first *)
    Begin smemonl bug
    Begin smemonl bug
        Port[272]:=2;
        Port[272]:=2;
        Port[272] := 3;
        Port[272] := 3;
        X := Port[256];
        X := Port[256];
        Binary (X,Q);
        Binary (X,Q);
        For J :=0 To 3 Do
        For J :=0 To 3 Do
            Begin
            Begin
                K := K+1;
                K := K+1;
                Line[K] := Q[J];
                Line[K] := Q[J];
            End;
            End;
    End;
    End;
While Hsync<>12 Do mor (* Look for the first *)
While Hsync<>12 Do mor (* Look for the first *)
    Begin
    Begin
        If Line[P]=0 Then
        If Line[P]=0 Then
            Hsync:= Hsync+1
            Hsync:= Hsync+1
        Else
        Else
            Hsync := 0;
            Hsync := 0;
        P := P+1;
        P := P+1;
    End;
    End;
Pl := P+29; (* Disgard the next 29 bytes *)
Pl := P+29; (* Disgard the next 29 bytes *)
P2 := Pl+160
P2 := Pl+160
(* Display the next l60 bytes*)
(* Display the next l60 bytes*)
(* of data the next 160 bytes*)
(* of data the next 160 bytes*)
For I := P1 TO P2 Do
For I := P1 TO P2 Do
    Begin
    Begin
        Yl := Y;
```

        Yl := Y;
    ```*)
                                    )
```

```
        X:= Port[256];
```

        X:= Port[256];
    (* two bytes of horizonta
(* two bytes of horizonta
(* line are stored. Read the *)
(* line are stored. Read the *)
(* next 55 bytes {[zaइ]3 (roc*)
(* next 55 bytes {[zaइ]3 (roc*)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
(* Look for the lst byte of *)
ct pmbsxevmos \&)
ct pmbsxevmos \&)
0tal sytgy *)
0tal sytgy *)
0.4nL 51815% *
0.4nL 51815% *
(* Look for horizontal sync *)
(* Look for horizontal sync *)
(* Look for horizontal sync *)
(* Look for horizontal sync *)
|
|
Int ifs dea *
Int ifs dea *
-, fcectut-09
*)
)

```
nlpese
50
; xoent
4bera


\section*{Video Frame Grabber}
```

        Y2 := Y;
        X2 := Xl+2;
        If Line[I]=2 Then
        Begin
            If even Then (* Place -X for even lines
                Plot((X1+1),Y1,color)
            Else Plot(Xl,Yl,color); (* Place X- for odd lines
        End;
            If Line[I]=3 Then Draw(X1,Y1,X2,Y2,color);
        Xl := Xl+2;
        End;
    End;
    gotoxy(1,25);
Write('Press ESC to stop.');
Read(Kbd, Ch);
If Ch=\#27 Then
TextMode;
End.

```



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\subsection*{1.1 The Language of Logic}

Although you may not be aware of it, you are already an expert at forming, simplifying and comprehending Boolean equations and expressions. Boolean algebra, in its most common application, is concerned with the truth or falsity of statements; and any time you describe what circumstances would make something true or false, you have made a Boolean equation.
For example, suppose \(A\) is true only if \(B\) and \(C\) are true. These three letters may represent anything you like - A may be whether or not you may become president, B may be whether or not you are elected, and C may be whether or not you are a citizen of the U.S.A. You may become president only if you are elected and you are a citizen of the United States. If we wrote that statement in equation form, it might look like this:
\[
A=B^{*} C
\]
where the * is a shorthand notation for the word 'and.' \(A, B\) and \(C\) are all Boolean variables, since they represent some value which may be either true or false. You either are a citizen of the United States, or you are not - there is no in between. Examining the relationship between these three variables, we find that:
1) if you are elected and you are citizen then you may become president;
2) if you are elected but you are not a citizen then you cannot become president;
3) if you are not elected, but you are a citizen, you still can't become president, and;
4) if you are neither elected nor a citizen, then you definately cannot become president.

This same relationship, which may be expressed in terms of an English sentence of a Boolean expression may also be represented by a table of all the possibilities, called a truth table. If we let ' 1 ' stand for true, and ' 0 ' stand for false, we can make the following table:
\begin{tabular}{|c|c|c|}
\hline B & C & A \\
\hline 0 & 0 & 0 \\
\hline 0 & 1 & 0 \\
\hline 1 & 0 & 0 \\
\hline 1 & 1 & 1 \\
\hline
\end{tabular} Table 1-1

The table above is a standard way of expressing logical relationships. Our truth table lists the possibilities one-by-one. If B and \(C\) are false, then \(A\) will be false, If \(B\) is true and \(C\) is false, then \(A\) will still be false. If \(B\) is false, and \(C\) is true then \(A\) will still be false. However, if B and C are both true, then A will be true.

\subsection*{1.2 AND, OR and NOT}

The fact is that every time you have an equation of the form:
\[
A=B^{*} C
\]
you will have a truth table of the form in section 1.2 because the table and the word 'and' are just two ways of expressing the same relationship between two Boolean variables.
true. This equation could be written:
\[
A=B+C
\]

Do not confuse the ' + ' with the addition sign of arithmetic; in Boolean algebra, it is shorthand notation for the word 'or'. A truth table for this equation would be:
\begin{tabular}{|c|c|c|}
\hline \(\mathbf{B}\) & \(\mathbf{C}\) & \(\mathbf{A}\) \\
\hline \hline 0 & 0 & 0 \\
\hline 0 & 1 & 1 \\
\hline 1 & 0 & 1 \\
\hline 1 & 1 & 1 \\
\hline
\end{tabular}

This table expresses a different relationship between the variables than AND does; AND requires that both of its operands be true for the expression to be true. OR only requires that one of its operands be true for the expression to be true. From the table above, we can see that:
1) if both \(B\) and \(C\) are false, then \(A\) is false:
2) if \(B\) is false, and \(C\) is true, then \(A\) is true:
3) if \(B\) is true and \(C\) is false, then \(A\) is true and:
4) if both \(B\) and \(C\) are true, then \(A\) is true.

Finally, let's look at the operator 'not'. If \(A\) equals not \(B\), then the value of \(A\) is the inverse of \(B\). This equation would be:
\[
A=/ B
\]

Again, the \(/ /\) ' should not be mistaken for the division sign of arithmetic. It is a shorthand notation for the Boolean operator, 'not'. The truth table for this equation would be:

which is to say that:
1) if \(B\) is false, then \(A\) is true and:
2) if \(B\) is true then \(A\) is false.

\subsection*{1.3 Precedence}

In arithmetic, the multiplication sign is always evaluated before the addition sign. For example:
\[
3+4 \times 7
\]
is 31 , not 49 . Similarly, the AND sign is always evaluated before the OR sign. Another way to say this is that AND has a higher precedence than OR.
Of course, in arithmetic, the precedence of operators may be changed with parentheses. If you wish the expression:
\[
3+4 \times 7
\]
to be evaluated as 49 , then you should write it as:
\[
(3+4) \times 7
\]

The parentheses enclose a subexpression that should be evaluated before the expression as a whole can be evaluated.
Of the three Boolean operators we have seen so far, NOT has the highest precedence, then AND, then OR.

\subsection*{1.4 Associativity and Commutativity}

Both the AND and OR operators have the property of associativity (in fact, all Boolean operators have this property, except for NOT). The property of associativity says that in an expression with more than one operator of the same kind, it does not matter which you evaluate first. In terms of equations, this would be:
\[
\begin{aligned}
B^{*}\left(C^{*} D\right) & =\left(B^{*} C\right)^{*} D \\
& \text { or } \\
B+(C+D) & =(B+C)+D
\end{aligned}
\]

All Boolean operators (except for NOT) are also commutative. This means that the order in which the operands appear is not important. In equations, that would be
\[
\begin{gathered}
\mathrm{B}^{*} \mathrm{C}=\mathrm{C}^{\star} \mathrm{B} \\
\text { or } \\
\mathrm{B}+\mathrm{C}=\mathrm{C}+\mathrm{B}
\end{gathered}
\]

\subsection*{1.5 Postulates and Theorems}

In 1854, the mathematician and philosopher George Boole published his book, 'An Investigation of The Laws of Thought', in which he demonstrated how classical logic could be defined with algebraic terminology and operations. Then, in 1938, C. E. Shannon published his paper "A Symbolic Analysis of Relay and Switching Circuits", which demonstrated a Boolean algebra of two values called "switching algebra", which could be used to represent the properties of bistable electric switching circuits. A minimal set of formal postulates is needed in order to define this Boolean algebra. Here we will define Boolean algebra to be an algebra defined over the set B, where B = (False, True) and over the operators AND ( \({ }^{*}\) ), OR ( + ) and NOT (/), such that:
1) All operators are closed (which means that it is impossible to create a Boolean expression that has a value other than True or False),
2) Postulates 1 through 4 in Table 1-6 are true, and
3) NOT is an operator which, when applied to a Boolean variable, \(x\), creates its complement such that, if \(x=\) True then /x = False, and if \(x=\) False then \(/ x=\) True.
Given this basic set of rules, it is possible to derive any of the theorems in Table 1-6, For example:
Theorem 1a) \(x+x=x\)
\[
\begin{aligned}
x+x & =(x+x)=\text { True } & & \text { by Postulate } 1 \mathrm{~b} \\
& =(x+x)(x+/ x) & & \text { by Postulate } 2 \mathrm{a} \\
& =x+(x * / x) & & \text { by Postulate } 4 b \\
& =x+\text { False } & & \text { by Postulate } 2 b \\
& =x & & \text { by Postulate 1a }
\end{aligned}
\]

\subsection*{1.5.1 Duality}

One of the most important properties of Boolean algebra is the duality principle. This principle states that any algebraic expression that may be deduced from the postulates of Boolean algebra has a dual which is also true. The dual of an expression is obtained by replacing all Trues with Falses, all Falses with Trues, all ANDs with ORs, and all ORs with ANDs. For example:
Theorem 2a \(\quad x+\) True \(=\) True
has the dual:
\(x^{*}\) False \(=\) False
which is also theorem 2 b . All postulates and theorems listed in Table 1-6 are listed as pairs of duals. Of course, any of these theorems could also be derived without using the duality principle. For example:
\begin{tabular}{rlrl} 
Theorem 2b & \(\quad x^{*}\) False \(=\) False & & \\
\(x^{*}\) False & \(=\) False \(+(x+\) False \()\) & & by Postulate \(1 a\) \\
& \(=\left(x^{*} / x\right)+(x+\) False \()\) & & by Postulate \(2 b\) \\
& \(=x^{*}(/ x+\) False \()\) & & by Postulate \(4 a\) \\
& \(=x^{*} / x\) & & by Postulate \(1 a\) \\
& \(=\) False & & by Postulate \(2 b\)
\end{tabular}

\subsection*{1.5.2 Using Truth Tables}

Finally, theorems may be demonstrated with truth tables. A theorem always holds true if it holds true for all cases; and since two variables can only have two values each, there are only four possible cases, so it is reasonable to look at a theorem on a case-by-case basis. For example, we can prove Theorem 5 a with the following truth table:
\begin{tabular}{|c|c|c|c|}
\hline\(x\) & \(y\) & \(/(x+y)\) & \(\left(/ x^{*} / y\right)\) \\
\hline\(F\) & \(F\) & \(T\) & \(T\) \\
\hline\(F\) & \(T\) & \(F\) & \(F\) \\
\hline\(T\) & \(F\) & \(F\) & \(F\) \\
\hline\(T\) & \(T\) & \(F\) & \(F\) \\
\hline
\end{tabular}

Table 1-7
It can be seen from Table 1-7 that, in every case, \(/(x+y)\) is equal to (/x*/y).

\subsection*{1.5.3 Complement of a Boolean Function}

A Boolean expression is some mixture of Boolean variables and operators that has a value. For example:
\[
x+y^{*} z^{*} / a
\]
is a Boolean expression. A Boolean function is a statement in which two expressions are equated. For example:
\[
\begin{aligned}
a & =b^{*} c \\
/\left(c^{*} d\right) & =/ c^{+} / d
\end{aligned}
\]
are Boolean functions. (The difference is the presence of an equal sign. It is worth noting that equals, or equivalence is also a Boolean function because two expressions are either equal or they aren't. However, in this book we will attempt to present only true equations, so the Boolean values of an equals sign may be ignored in functions.)
So far, we have talked about a Boolean expression's value as True or False. More frequently, these values are written as 1 and 0 , with 1 standing for True, and 0 standing for False. From now on, we will also adopt this standard.
The complement of an expression may be written easily by placing the NOT operator in front of the enclosed expression:
\[
/\left(x+y^{*} z^{*} / a\right)
\]
but it is also possible to complement a function. The complement of a function is obtained by complementing both sides of an equation. For example, given the equation:
\[
l a=b^{*} c+1
\]

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the complement would be:
\[\)\begin{tabular}{rl}
\(\qquad /^{*}(/ a)=/\left(b^{*} \mathrm{c}+1\right)\)
\end{tabular}
\]
which could be simplified:
\[\)\begin{tabular}{ll}
\(\mathrm{a}=/\left(\mathrm{b}^{*} \mathrm{c}+1\right)\) & \text { by Theorem 3 } \\
\(\mathrm{a}=/\left(\mathrm{b}^{*} \mathrm{c}\right)^{*} / 1\) & \text { by Theorem 5a } \\
\(\mathrm{a}=/\left(\mathrm{b}^{*} \mathrm{c}\right)^{*} 0\) & \text { def. of complement } \\
\(\mathrm{a}=0\) & \text { by Theorem 2b }
\end{tabular}
\]

Note the differences between obtaining the complement of a function, and obtaining the dual of a function. The complement is obtained by complementing the entire expression on both sides of the equation, and manipulating it from there with the given postulates and theorems. The dual of a function is obtained by replacing all 1 's with 0 's, all 0 's with 1 's, all ANDs with ORs, and all ORs with ANDs.
In fact, the easiest way in which to obtain the complement of a function is by taking the dual of the function and complementing each individual variable (called a literal). For example, the complement of:
\[
F=(x+/ y)^{*}\left[w^{*}(x+z)\right]
\]
can be found by
1) taking the dual:

Dual: \(F=\left(x^{*} / y\right)+\left[w+\left(x^{*} z\right)\right]\) and,
2) complementing each literal:

Complementing: \(/ F=\left(/ x^{*} y\right)+\left[/ w+\left(/ x^{*} / z\right)\right]\)

\subsection*{1.6 Algebraic Simplification}

Aliteral is a complemented (/x) or uncomplemented ( \(x\) ) variable. A term is a subexpression, often enclosed in parentheses. The equation:
\[
F=(x+/ y)^{*} / x
\]
has three literals and two terms. Simplifying a Boolean equation is an attempt to minimize the number of literals or the number of terms in an equation. Unfortunately, in many situations, one can only be minimized at the expense of the other, so it is important to decide from the outset whether you are minimizing literals or terms. Literals can be minimized by repeated applications of the postulates and theorems of Boolean algebra (Table 1-6), but there is no algorithm; it is a trial and error process. For example, the equation:
\[
F=\left(x^{*} / z\right)+\left[(x+y)^{*} / z\right]
\]
may be simplified through the following steps:
\[
\begin{array}{rlr}
F & =\left(x^{*} / z\right)+\left[(x+Y)^{*} / z\right] & \\
& =\left(/ z^{*} x\right)+\left[/ z^{*}(x+Y)\right] & \\
& =/ z^{*}[x+(x+y)] & \\
& =/ z^{*}[(x+x)+y] & \\
& =/ z^{*}(x+y) & \\
& \text { Theostulatate 3b 4a } \\
\text { Theorem 4a }
\end{array}
\]

The equation is now simplified because there are no postulates or theorems, which, when applied, will serve to further reduce the number of literals.

\subsection*{1.6.1 Sum of Products and Product of Sums}

When an equation is in the form:
\[
F=\left(a^{*} b\right)+\left(c^{*} / a\right)+e
\]
for example, it is said to be in sum of products form. This is because the equation is composed of a number of product terms (ANDs) that are summed (ORed) together. The subexpression result of two operands ANDed together is referred to as a product because of the resemblance of the AND operator to the multiplication operator of arithmetic; the result of OR is referred to as a sum because of the resemblance of the OR operator to the addition operator of arithmetic.
When an equation is in the form: assainaposembrasab a
\[
F=(a+b)^{*}(a+/ b)
\]
for example, it is said to be in product of sums form, because it is composed of a number of sum terms (OR) that are ANDed together. Both sum of products and product of sums forms are called standard form.

\subsection*{1.6.2 Canonical Forms}

If an equation has three variables that are complemented or uncomplemented, then there are a limited number of ways in which these variables can be ANDed or ORed together. Referring to Table 1-9, under the column 'Minterms', and the subcolumn 'Terms', there are seven different ways in which three variables could be ANDed together. Each combination has been given a name - the letter ' \(m\) ' and a number. For example, the expression:
\[
\left(/ x^{*} y^{*} z\right) \text { is } m_{3}
\]
while the expression:
\[
\left(x^{*} y^{*} / z\right) \text { is } m_{7}
\]

Using these shorthand notations for expressions, we can refer to the equation:
ent hasulay mos:
\[
\begin{gathered}
F=\left(/ x^{*} y^{*} / z\right)+\left(x^{*} / y^{*} / z\right)+\left(x^{*} / y^{*} z\right) \\
\text { as: } \\
F=m_{2}+m_{4}+m_{5}
\end{gathered}
\]
which is much more compact. When an equation is expressed in terms of these named AND subexpressions, or minterms it is said to be in sum of minterms form.
Similarly, there are seven ways in which three variables may be ORed together, each variable being primed or unprimed. A named OR subexpression is called a maxterm. The equation:
\[
F=(x+y+z)^{*}(x+/ y+/ z)^{*}(/ x+/ y+/ z)
\]
could also be written as:
\[
\mathrm{F}=\mathrm{m}_{0}{ }^{*} \mathrm{~m}_{3}{ }^{*} \mathrm{~m}_{7}
\]
since each OR subexpression has been given a name consisting of an ' \(M\) ' and a number. (See the column 'Maxterms' in Table 1-9.) An equation expressed in this way is said to be written in product of maxterms form. Both sum of minterms and product of maxterms forms are called canonical forms.

In many equations, not every variable is represented in every term, but it is still possible to write them in canonical form. A little algebraic manipulation will produce the missing terms that are needed. For example, the equation:
\[
F=\left(x^{*} y^{*} z\right)+\left(/ x^{*} y\right)
\]

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is missing a ' \(z\) ' in its second term. In order to write this equation in sum of minterms form, we must first take the following steps:
\begin{tabular}{rlrl}
\(F\) & \(=\left(x^{*} y^{*} z\right)+\left(/ x^{*} y^{*} 1\right)\) & Postulate 1b \\
& \(=\left(x^{*} y^{*} z\right)+\left[/ x^{*} y^{*}(z+/ z)\right]\) & Postulate 2a \\
& \(=\left(x^{*} y^{*} z\right)+\left(/ x^{*} y^{*} z\right)+\left(/ x^{*} y^{*} / z\right)\) & Postulate 4a \\
& \(=m_{7} m_{3}+m_{2}\) & &
\end{tabular}

To create a missing variable in a maxterm, use the duals of the postulates used above. To create more than one missing variable, expand the equation as many times as is needed by following the steps above.

\subsection*{1.6.3 Conversion Between Canonical Forms}

Canonical forms do not only exist because they are more compact; using canonical forms, it is possible to write any equation expressed in sum of products in terms of product of sums.
Given the equation:
\[
\begin{aligned}
F & =\left(/ a^{*} b^{*} / c\right)+\left(a^{*} / b^{*} c\right)+\left(a^{*} b^{*} c\right) \\
& =m_{2}+m_{5}+m_{7}
\end{aligned}
\]
we can take its complement by forming an equation from all the minterms that are NOT present in the equation:
\[
\begin{aligned}
\text { IF } & =m_{0}+m_{1}+m_{3}+m_{4}+m_{6} \\
& =\left(/ a^{*} / b^{*} / c\right)+\left(/ a^{*} / b^{*} c\right)+\left(/ a^{*} b^{*} c\right)+\left(a^{*} / b^{*} / c\right)+\left(a^{*} b^{*} / c\right)
\end{aligned}
\]

Finally, using the dual/complement method, we can take the complement again. Of course, by Theorem 3 (Table 1-9), anything that is complemented twice returns to its original value:
\[
F=(a+b+c)^{*}(a+b+/ c)^{*}(a+/ b+/ c)^{*}(/ a+b+c)^{*}(/ a+b+/ c)
\]

We have now expressed function \(F\), originally in sum of products, in product of sums form. Any Boolean equation can be written in either form.
An even quicker way of doing this conversion is to write a product of maxterms equations using the maxterm numbers which did not appear in the original equation. For example, in our equation \(F\), written in sum of minterms form, we used the numbers 2,5 and 7 . In our product of maxterms form, we would use the maxterms \(0,1,3,4\) and 6 .
\[
\begin{aligned}
F & =m_{0}+m_{1}+m_{3}+m_{4}+m_{6} \\
& =(a+b+c)^{*}(a+b+/ c)^{*}(a+/ b+/ c)^{*}(/ a+b+c)^{*}(/ a+/ b+c)
\end{aligned}
\]

This works because each maxterm is the dual of the minterm that has the same number.
Of course, any equation written in the canonical forms can likely be simplified; so after converting from standard form to canonical form, then converting from one canonical form to another, you may wish to simplify your equation.
\begin{tabular}{|c|c|}
\hline Postulate 1 & \begin{tabular}{l}
(a) \(x+\) False \(=x\) \\
(b) \(x\) True \(=x\)
\end{tabular} \\
\hline Postulate 2 & \begin{tabular}{l}
(a) \(x+1 x=\) True \\
(b) \(x^{*} / x=\) False
\end{tabular} \\
\hline Postulate 3 & \begin{tabular}{l}
(a) \(x+y=y+x\) \\
(b) \(x^{\prime} y=y^{*} x\)
\end{tabular} \\
\hline Postulate 4 & \begin{tabular}{l}
(a) \(x^{*}(y+z)=\left(x^{*} y\right)+\left(x^{*} z\right)\) \\
(b) \(x+\left(y^{\prime} z\right)=(x+y)^{2}(x+z)\)
\end{tabular} \\
\hline Theorem 1 & \begin{tabular}{l}
(a) \(x+x=x\) \\
(b) \(x \cdot x=x\)
\end{tabular} \\
\hline Theorem 2 & \begin{tabular}{l}
(a) \(x+\) True \(=\) True \\
(b) \(x^{*}\) False \(=\) False
\end{tabular} \\
\hline Theorem 3 & \(1(\mathrm{x})=\mathrm{x}\) \\
\hline Theorem 4 & \begin{tabular}{l}
(a) \(x+(y+z)=(x+y)+z\) \\
(b) \(x^{*}\left(y^{*} z\right)=\left(x^{*} y\right)^{*} z\)
\end{tabular} \\
\hline Theorem 5 & \begin{tabular}{l}
(a) \(/(x+y)=/ x^{*} / y\) \\
(b) \(/\left(x^{*} y\right)=/ x+/ y\)
\end{tabular} \\
\hline Theorem 6 & \begin{tabular}{l}
(a) \(x+\left(x^{*} y\right)=x\) \\
(b) \(x^{*}(x+y)=x\)
\end{tabular} \\
\hline
\end{tabular}

Table 1-6. Postulates and Theorems of Boolean Algebra

\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|}
\hline \(\mathrm{X} \mathbf{Y}\) & F1 & F2 & F3 & F4 & F5 & F6 & F7 & F8 & F9 & F10 & F11 & F12 & F13 & F14 & F15 & F16 \\
\hline \hline 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \\
\hline 0 & 1 & 0 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 0 & 0 & 0 & 0 & 1 & 1 & 1 & 1 \\
\hline 1 & 0 & 0 & 0 & 1 & 1 & 0 & 0 & 1 & 1 & 0 & 0 & 1 & 1 & 0 & 0 & 1 & 1 \\
\hline 1 & 1 & 0 & 1 & 0 & 1 & 0 & 1 & 0 & 1 & 0 & 1 & 0 & 1 & 0 & 1 & 0 & 1 \\
\hline & & \(*\) & & \(X\) & & Y & \(+:\) & + & & & Y & & \(1 X\) & & & \\
\hline
\end{tabular}

Table 1-7. Boolean Operators


Table 1-10. Logic Gates

\subsection*{2.0 Binary Systems}

Binary numbers utilize a base 2 number system that can only be in one of two logical states: \(a\) " 0 " or a " 1 ". This number system is used in current digital computer systems because the outputs of most switching circuits can only be in one of the two logical states. Also, when transistor circuits are operating in one of two modes only, greater reliability can be obtained.

\subsection*{2.1 Base Conversion}

Normally, decimal (base 10) numbers are written using a positional notation. In other words, the value of the number is determined by multiplying each digit to an appropriate power of 10 which is dependent on its relative position to the decimal point.

\section*{Example 2.1}
\[
714.02=7 \times 10^{2}+1 \times 10^{1}+4 \times 10^{0}+0 \times 10^{-1}+2 \times 10^{-2}
\]

\subsection*{2.1.1 Base 2 to Base 10 Conversion}

Similarly, binary (base 2) numbers are also position-dependent relative to the binary point; each binary digit is multiplied by an appropriate power of 2 in order to obtain the decimal equivalent. The following example shows the conversion from a base 2 number to a base 10 number.

\section*{Example 2.2}
\[
\begin{aligned}
101.01_{2} & =1 \times 2^{2}+0 \times 2^{1}+1 \times 2^{0}+0 \times 2^{-1}+1 \times 2^{-2} \\
& =4+0+1+0+1 / 4 \\
& =5.25_{10}
\end{aligned}
\]

Notice that the binary point separates the positive and the negative powers of 2 . This is similar to the case of the decimal point separating the positive and negative powers of 10 .

\subsection*{2.1.2 Base 10 to Base 2 Conversion}

Converting a base 10 integer to a base 2 integer requires utilizing the division method. To explain, let N represent the base 10 integer. Divide this integer, N, by 2 since base 2 is desired. As a result, there should be a quotient, \(Q_{0}\), and a remainder, \(R_{0}\). Then divide the previous quotient, \(\mathrm{Q}_{0}\), by 2 again and continue this process until the final quotient equals zero. The desired binary digits are the remainders resulting from each division step; the least significant bit starts with \(R_{0}\).

\section*{Example 2.3}

Converts \(61_{10}\) to binary:
\begin{tabular}{rlrl}
\(61 / 2\) & \(=30\) & remainder \(=1\) & LSB \\
\(30 / 2\) & \(=15\) & remainder \(=0\) & \\
\(15 / 2=7\) & remainder \(=1\) & \\
\(7 / 2=3\) & remainder \(=1\) & \\
\(3 / 2=1\) & remainder \(=1\) & \\
\(1 / 2=0\) & remainder \(=1\) & MSB \\
\(61_{10}\) & \(=111101_{2}\) & &
\end{tabular}

Converting decimal fractions to binary requires successive multiplications by 2. Let F be a decimal fraction. Multiply this number F by 2 and obtain an integer and a fraction result. Take this integer and multiply once again by 2 . Continue this process until it terminates or until a sufficient number of digits has been reached. The desired digits are the integer parts that were obtained at each multiplication step. The most significant digit is obtained first.

Example 2.4 inumolgmos at thew notiosvidue SSES
Convert \(0.375_{10}\) to binary
\begin{tabular}{rlrlll}
0.375 & 0.750 & 0.500 & 10 & \(=0\) & MSB \\
\(\times \quad 2\) \\
\hline 0.750 & \(\frac{x}{1.500}\) & \(\frac{x}{1.000}\) & \(1_{1}=1\) & \(1_{2}=1\) & LSB \\
\(0.375_{10}\) & \(=0.011\) & & & &
\end{tabular}

Note that if this procedure doesn't terminate, then the result must be a repeating fraction.

\subsection*{2.1.3 Base 2 to Base 8}

To convert binary to octal (base 8) or vice versa is very simple and can be done by inspection. Each octal digit corresponds to three binary digits since it can be in one of eight states ( 0 to 7 ). Therefore, the binary number should be divided into groups of three starting from the binary point. Each group on both sides of the binary point is replaced by an octal digit representation.

\section*{Example 2.5}
\(101110.011_{2}=101110.011\)
Similarly, binary to hexadecimal (base 16) and vice versa can also be done easily. This time, instead of three, the binary number is broken up into groups of four. The reason is because a hexadecimal digit can assume one of sixteen states ( 0 to \(9, A\), B, C, E and F). Again starting from the binary point, each group is replaced by its hexadecimal equivalent.

\section*{Example 2.6}
\begin{tabular}{rl}
\(11100101.0011_{2}\) & \(=1110\) \\
& \(0101 \cdot 0011\) \\
& \(=\) E \(\quad 5 \cdot 31^{2}\)
\end{tabular}

कौt zsciupen vectmun kernid a to themelamoa e's sit brit ot

\subsection*{2.2 Simplicity of Binary Arithmetic}

Due to the design of logic networks, it is much easier to do binary than decimal arithmetic in digital systems. Although binary arithmetic is implemented in about the same manner, the addition tables are much easier. Fortunately, numerical subtractions may be performed by addition operations between numbers. This property is of little use in the decimal system. However, much can be gained if used in the binary system. This is mainly due to the fact that in a binary system, complements of numbers are easily implemented, and the same hardware can be used for addition and subtraction operations. This allows for considerable savings in terms of system hardware design.

\subsection*{2.2.1 1's Complement}

To find the 1's complement of a binary number is easily done by inverting each digit (0 or 1) up to the most significant digit specified.
Example 2.7
The 1's complement of:
\(01011.1101=10100.0010\)

To subtract two positive binary numbers \(X\) and \(Y,(X-Y)\), the following procedures should be used:
1. Take the 1 's complement of \(Y\) and add it to \(X\).
2. Check results for overflow carry:
a. If there is an overflow carry, add it to the least significant digit of the result.
b. If there is no overflow carry, the result is negative. Then, complement this result and place a minus sign in front.

\section*{Example 2.8}
a) \(1010.11-1000.01=\) ?
1010.11
\(+0111.10-1\) 's complement of 1000.01
overflow \(1 \overline{0010.01}\)
\[
+\frac{1}{0010.10}-\text { add overflow carry }
\]
b) \(1001.10-1100.11=\) ?
\[
1001.10
\]
\(+\underline{0011.00}-1\) 's complement of 1100.11
no overflow \(\overline{1100.10} \rightarrow-0011.01\)
Since there is no overflow carry, take the 1's complement of 1100.10 and add a negative sign in front of it:

Answer is -0011.01

\subsection*{2.2.3 2's Complement}

The most widely used numbering manipulation technique in current digital computers is the 2's complement method. This method is easily implemented with any decent computer instruction set. Using the same hardware for addition and subtraction in 2's complement makes system design simpler and can lead to savings in cost.
To find the 2 's complement of a binary number requires the following:
1. Take the logical complement by inverting each digit of the binary number.
2. Add 1 to the least significant digit.


The 2's complement of 001100.01 is:
step \((1)+\frac{110011.10}{\text { step }(2)+\frac{1}{110011.11} \rightarrow \text { answer }}\) logical complement of 001100.01

This technique can also be done by visual inspection. Start with the least significant digit of the number and visually scan to the left. Leave all digits unchanged until the first " 1 " is encountered. Then invert all the remaining digits to the left. Note that the binary point has no effect on this procedure.

\subsection*{2.2.4 Subtraction with 2's Complement}

The steps for subtracting two binary numbers \(X\) and \(Y\), \((X-Y)\), are as follows:
1. Add \(X\) to the 2's complement of \(Y\).
2. Check result for overflow carry:
a. If there is an overflow carry, then throw it out. The result now represents ( \(X-Y\) ).
b. If there is no overflow carry, the number is negative. Take the 2's complement of the result and place a negative sign in front of it.

\section*{Example 2.10}
a) \(1110.11-1011.10=\) ?
\[
\begin{gathered}
\\
\underset{\text { overflow carry }}{\text { throw out } 1}
\end{gathered}+\underline{1110.11} \text { 00100.10 }-2 \text { 's complement of } 1011.10
\]
b) \(0001.11-1000.10=\) ?
\[
\begin{gathered}
\\
\text { no overflow } \\
\text { carry }
\end{gathered}+\underline{0001.11} \begin{aligned}
& \text { 0111.10 }-2 \text { 's complement of } 1000.10 \\
& 1001.01 \rightarrow-0110.11
\end{aligned}
\]

Since there is no overflow, this number is negative. Therefore, take the 2's complement of 1001.01 and add a minus sign in front: Answer is -0110.11



\subsection*{3.0 Karnaugh Map}

\subsection*{3.1 Karnaugh Map Technique}

There exists a technique that allows the logic designer to minimize Sum of Product terms by utilizing Karnaugh maps. The Karnaugh map (referred to as K-map) graphically displays the implicants (minterm) in any Sum of Product expression. It is derived directly from the truth table of this expression. K-maps are very useful for minimizing three, four, five and even six variable functions, but it gets too complicated beyond six. For expressions with more than six variables, the numerical manipulation should be done on a computer that uses the QuineMcCluskey method. This technique will not be discussed in this book.

\subsection*{3.1.1 K-Map Reading Procedure}

Each minterm cell in the K-map has a value of "1" as determined by the truth table. Circle those single minterm cells that will combine with its adjacent cells to form larger groups of \(1,2,4,8\), etc. If each single minterm cell is grouped individually, the map reading process should yield the original Sum of Product expression.
However, if two minterm cells are grouped together, at least one variable is dropped. This is because the theorem \(X^{*} Y+X^{*} / Y=X\) has been executed once. If a group of four adjacent minterm cells have been combined, then the theorem has been executed twice and two variables are dropped. Thus, a group of eight adjacent cells result in three variables being dropped. Therefore, the main objective is to minimize the number of minterm cell groupings while maximizing the number of minterm cells in each grouping. By minimizing the number of cell groupings, the number of inputs to the OR function is reduced. On the other hand, by maximizing the number of cells in each grouping, the number of inputs to the AND function is reduced.

\subsection*{3.1.2 K-Map Matrix Labels}

In labeling the K-map matrix, the following rule should be followed.
Top to bottom or left to right:
Two-variable Three-variable
Four-variable
\begin{tabular}{ccl} 
wo-variable & Three-variable & \multicolumn{1}{c}{ Four-variable } \\
00 & 000 & Add a 'O' MSB and use the \\
01 & 001 & three-variable chart for the first \\
11 & 011 & half. For the second half, add a \\
10 & 010 & '1' MSB and repeat the same \\
& 110 & chart in reverse order. \\
\hline & 111 & \\
& 101 & \\
& 100 &
\end{tabular}

Notice that the number of variables shown above is referring to one axis only ( X or Y ). However, this technique may be used for any number of variables that may be desired on each axis. For any axis greater than one variable, the second-half is a mirror image of the first-half with the MSB equal to a ' 1 '. This can be seen above when comparing the three-variable list to the twovariable list.

\subsection*{3.1.3 K-Map Examples}

Examples of three-and four-variables K -maps are shown below. The corresponding truth tables for the examples are also shown to illustrate the derivation of the K-maps.

Example 3.1
Three-Variables K-map:
\begin{tabular}{|c|c|c|c|}
\hline \(\mathbf{A}\) & \(\mathbf{B}\) & \(\mathbf{C}\) & \(\mathbf{F}\) \\
\hline \hline 0 & 0 & 0 & 0 \\
\hline 0 & 0 & 1 & 1 \\
\hline 0 & 1 & 0 & 1 \\
\hline 0 & 1 & 1 & 1 \\
\hline 1 & 0 & 0 & 0 \\
\hline 1 & 0 & 1 & 1 \\
\hline 1 & 1 & 0 & 1 \\
\hline 1 & 1 & 1 & 0 \\
\hline
\end{tabular}

product term \(1=\mathrm{B}^{*} / \mathrm{C}\) product term \(2=/ B^{*} C\) product term \(3=/ A^{*} C\) (SOP form)
\(F=B^{*} / C+/ B^{*} C+/ A * C\)
Karnaugh Map

\section*{Truth Table}

Example 3.2
Four-Variables K-map:
\begin{tabular}{|c|c|c|c|c|}
\hline \(\mathbf{A}\) & \(\mathbf{B}\) & \(\mathbf{C}\) & \(\mathbf{D}\) & \(\mathbf{F}\) \\
\hline \hline 0 & 0 & 0 & 0 & 1 \\
\hline 0 & 0 & 0 & 1 & 1 \\
\hline 0 & 0 & 1 & 0 & 1 \\
\hline 0 & 0 & 1 & 1 & 1 \\
\hline 0 & 1 & 0 & 0 & 1 \\
\hline 0 & 1 & 0 & 1 & 1 \\
\hline 0 & 1 & 1 & 0 & 0 \\
\hline 0 & 1 & 1 & 1 & 0 \\
\hline 0 & 1 & 1 & 1 & 0 \\
\hline 1 & 0 & 0 & 0 & 1 \\
\hline 1 & 0 & 0 & 1 & 1 \\
\hline 1 & 0 & 1 & 0 & 1 \\
\hline 1 & 0 & 1 & 1 & 0 \\
\hline 1 & 1 & 0 & 0 & 1 \\
\hline 1 & 1 & 0 & 1 & 1 \\
\hline 1 & 1 & 1 & 0 & 0 \\
\hline 1 & 1 & 1 & 1 & 0 \\
\hline
\end{tabular}
product term \(1=/ C\)
product term \(2=/ \mathrm{A}^{*} / \mathrm{B}\) product term \(3=/ \mathrm{B}^{*} \mathrm{C}^{*} / \mathrm{D}\) (SOP form) \(F=/ C+\left(/ A^{*} / B\right)+\left(/ B^{*} C^{*} / D\right)\)

Truth Table

\subsection*{4.0 Combinational Logic}

\subsection*{4.1 Logic Design Introduction}

Logic design is a combination of analysis, synthesis, minimization and implementation of Boolean functions. Boolean functions must originally come from worded statements. This is a very important part of logic design because the worded statement can be ambiguous and imprecise, while the Boolean equation must be unambiguous and exact. The conversion of words to equations is called synthesis. Engineers must be careful when synthesizing a problem because many times the originator of a problem is not a technical person. It is the responsibility of the logic designer to review the synthesis of the problem with the originator to make sure the solution is suitable.

\subsection*{4.2 Combinational Design}

Combinational logic is a network whose output is solely dependent upon its inputs. It has no feedback loops or memory elements.
The first step in combinational design is to analyze the problem and then define it in an exact manner. This will make synthesizing a Boolean equation much easier.
Synthesis usually takes several steps. Using truth tables and K-maps are common ways of specifying a problem and putting it in the minimal Boolean form.

\section*{Example 4.1}

A seven-segment decoder decodes a BCD number and turns on the appropriate segments of a seven-segment digit. Given the seven-segment digit in Figure 4-1 develop a minimal equation for each segment by using a truth table and K-maps.


Figure 4-1. Seven-Segment Decoder

Forming a truth table from Figure 4-1 is done by writing all ' 10 ' possible inputs down, then determining which segments should be activated for each input. For example, segment 'a' is activated whenever; \(2,3,5,7,8,9\) or 0 is input to the decoder. Once the table is formed, a K-map can be made for each segment. The K-maps are used to derive a Sum of Products logic equation for each segment.
K-maps are an excellent way of forming equations when three to six variables are involved in a problem. Two standard algebraic forms of the function can be derived - the standard Sum of Products - (minterm expansion) and the standard Product of Sums (maxterm expansion). A network of AND and OR gates is derived directly from either form.
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|c|c|}
\hline \multirow{2}{*}{ DECIMAL } & \multicolumn{4}{|c|}{ INPUTS } & \multicolumn{9}{c|}{ OUTPUTS } \\
\cline { 2 - 14 } & \(\mathbf{W}\) & \(\mathbf{X}\) & \(\mathbf{Y}\) & \(\mathbf{Z}\) & \(\mathbf{a}\) & \(\mathbf{b}\) & \(\mathbf{c}\) & \(\mathbf{d}\) & \(\mathbf{e}\) & \(\mathbf{f}\) & \(\mathbf{g}\) \\
\hline \hline 0 & 0 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 1 & 1 & 0 \\
\hline 1 & 0 & 0 & 0 & 1 & 0 & 1 & 1 & 0 & 0 & 0 & 0 \\
\hline 2 & 0 & 0 & 1 & 0 & 1 & 1 & 0 & 1 & 1 & 0 & 1 \\
\hline 3 & 0 & 0 & 1 & 1 & 1 & 1 & 1 & 1 & 0 & 0 & 1 \\
\hline 4 & 0 & 1 & 0 & 0 & 0 & 1 & 1 & 0 & 0 & 1 & 1 \\
\hline 5 & 0 & 1 & 0 & 1 & 1 & 0 & 1 & 1 & 0 & 1 & 1 \\
\hline 6 & 0 & 1 & 1 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 1 \\
\hline 7 & 0 & 1 & 1 & 1 & 1 & 1 & 1 & 0 & 0 & 0 & 0 \\
\hline 8 & 1 & 0 & 0 & 0 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \\
\hline 9 & 1 & 0 & 0 & 1 & 1 & 1 & 1 & 0 & 0 & 1 & 1 \\
\hline
\end{tabular}




\[
d=/ X^{*} / \mathbf{Z}+/ X^{*} Y^{*}+\mathbf{Y}^{*} / \mathbf{Z}+X^{*} / \mathbf{Y}^{*} \mathbf{Z}
\]

\[
\mathrm{w}, \mathrm{X} \begin{array}{c|c|c|c|c|}
\mathrm{Y}, \mathrm{Z} & 00 & 01 & 11 & 10 \\
\hline 00 & 1 & 0 & 0 & 0 \\
\hline 01 & 1 & 1 & 0 & 1 \\
\hline 11 & \mathrm{X} & \mathrm{x} & \mathrm{X} & \mathrm{x} \\
\hline 10 & 1 & 1 & \mathrm{x} & \mathrm{x} \\
\hline
\end{array}
\]
\[
e=/ X^{*} / Z+Y^{*} / Z
\]
\(\mathbf{g}=\mathbf{W}+\mathbf{X}^{*} / \mathbf{Y}+/ X^{*} \mathbf{Y}+\mathbf{Y}^{*} / \mathbf{Z}\)

\section*{Logic Tutorial}
\begin{tabular}{|c|c|c|c|c|l|}
\hline ROW & \(A\) & \(B\) & \(C\) & MINTERMS & MAXTERMS \\
\hline \hline 0 & 0 & 0 & 0 & \(/ A^{*} / B^{*} / C=m 0\) & \(A+B+C=M 0\) \\
\hline 1 & 0 & 0 & 1 & \(/ A^{*} / B^{*} C=m 1\) & \(A+B+/ C=M 1\) \\
\hline 2 & 0 & 1 & 0 & \(/ A^{*} B^{*} / C=m 2\) & \(A+/ B+C=M 2\) \\
\hline 3 & 0 & 1 & 1 & \(/ A^{*} B^{*} C=m 3\) & \(A+/ B+/ C=M 3\) \\
\hline 4 & 1 & 0 & 0 & \(A^{*} / B^{*} / C=m 4\) & \(/ A+B+C=M 4\) \\
\hline 5 & 1 & 0 & 1 & \(A^{*} / B^{*} C=m 5\) & \(/ A+B+/ C=M 5\) \\
\hline 6 & 1 & 1 & 0 & \(A^{*} B^{*} / C=m 6\) & \(/ A+/ B+C=M 6\) \\
\hline 7 & 1 & 1 & 1 & \(A^{*} B^{*} C=m 7\) & \(/ A+/ B+/ C=M 7\) \\
\hline
\end{tabular}

\section*{Table 4-1. Minterm and Maxterm Expansions}

Each minterm is a product term, so a Sum of Products expression may be written with minterms.

Example 4.2
Rewrite the Sum of Products equations from example 4.1 in minterm form.
\[
\begin{aligned}
& a=\operatorname{Im}(0,2,3,5,7,8,9,10,11,12,13,15) \\
& b=\operatorname{Im}(0,1,2,3,4,7,8,9,10,11,12,15) \\
& c=\operatorname{Im}(0,1,3,4,5,6,7,8,9,11,12,13,14,15) \\
& d=\operatorname{Im}(0,2,3,5,6,8,10,11,13) \\
& e=\operatorname{Im}(0,2,6,8,10,14) \\
& f=\operatorname{Im}(0,4,5,6,8,9,10,11,12,13,14,15) \\
& g=\operatorname{Im}(2,3,4,5,6,8,9,10,11,12,13,14,15)
\end{aligned}
\]
tach maxterm is a sum of variables. It is derived by solving a \(n\)-map for the 0 -terms instead of the 1 -terms. Maxterms are used in a Product of Sums solution.

\section*{Example 4.3}

Rework the first two K-maps from Example 4.1 to get a maxterm solution.

\(l a=X^{*} / Z+/ W^{*} X^{*} / Y^{*} Z\)
\(a=(/ X+Z)^{*}(W+X+Y+/ Z)\)
\(a=Z M(1,4,6,12,14)\)
\(/ \mathbf{b}=\mathbf{X} * / \mathbf{Y}+\mathbf{X}^{*} / \mathbf{Z}\)
\(b=(/ X+Y)^{*}(/ X+Z)\)
\(b=\Sigma M(5,6,13,14)\)

Given either algebraic form, it is a simple matter of converting to the other form, or the inverse of either form.
\begin{tabular}{|l|l|l|l|l|}
\hline \multirow{2}{*}{ GIVEN FORM } & \multicolumn{3}{|c|}{ DESIRED FORM } \\
\cline { 2 - 5 } & Minterm expansion of \(F\) & Maxterm expansion of \(F\) & Minterm expansion of \(F\) & Maxterm expansion of \(F\) \\
\hline \begin{tabular}{l} 
Minterm \\
expansion of \(F\)
\end{tabular} & - & \begin{tabular}{l} 
Maxterm numbers \\
are those numbers \\
not on the minterm \\
list for \(F\)
\end{tabular} & \begin{tabular}{l} 
List minterms not \\
present in \(F\)
\end{tabular} & \begin{tabular}{l} 
Maxterm numbers \\
are the same as \\
minterm numbers \\
of \(F\)
\end{tabular} \\
\hline \begin{tabular}{l} 
Maxterm \\
expansion of \(F\)
\end{tabular} & \begin{tabular}{l} 
Minterm numbers \\
are those numbers \\
not on the maxterm \\
list for \(F\)
\end{tabular} & - & \begin{tabular}{l} 
Minterm numbers \\
are the same as \\
maxterm numbers \\
of \(F\)
\end{tabular} & \begin{tabular}{l} 
List maxterms not \\
present in \(F\)
\end{tabular} \\
\hline
\end{tabular}

Table 4-2. Conversion of Forms Table

\subsection*{4.3 NAND Gates and NOR Gates}

A set of logic operators is said to be functionally complete if any Boolean function can be expressed in terms of this set of operations. The set; AND, OR and NOT, is functionally complete. The NAND and the NOR gates are each functionally complete by themselves. Therefore they are called Universal gates.

Conversion of AND and OR networks to NAND networks is carried out by starting with a minimal sum of products expression and then applying the theorem; \(F=/(/ F)\). This equation should then be solved using De Morgan's theorem.

\section*{NAND}
\begin{tabular}{|c|c|c|}
\hline\(X\) & \(Y\) & \(Z\) \\
\hline 0 & 0 & 1 \\
\hline 0 & 1 & 1 \\
\hline 1 & 0 & 1 \\
\hline 1 & 1 & 0 \\
\hline
\end{tabular}


Table 4-3. Truth Tables

Example 4-3
From the K-map in Figure 4-2, find equations for an AND-OR, NAND-NAND, OR-NAND and NOR-OR networks.


Figure 4-2. Karnaugh Map
\[
\begin{array}{ll}
F=A^{*} B+/ A^{*} / C^{*} / D+A^{*} C^{*} D & \text { eq. } 4-1 \\
F=/\left[/\left(A^{*} B+/ A^{*} / C^{*} / D+A^{*} C^{*} D\right)\right] & \text { eq. } 4-2 \\
F=/\left[/\left(A^{*} B\right)^{*} /\left(/ A^{*} / C^{*} / D\right)^{*} /\left(A^{*} C^{*} D\right)\right] & \text { eq. } 4-3 \\
F=/\left[(/ A+/ B)^{*}(A+C+D)^{*}(/ A+/ C+/ D)\right] & \text { eq. } 4-4 \\
F=/(/ A+/ B)^{*} / /(A+C+D)+(/ A+/ C+/ D) & \text { eq. } 4-5
\end{array}
\]

Equations 4-2 thru 4-5 are AND-OR, NAND-NAND, OR-NAND and NOR-OR networks, respectively.
In order to get a network of NOR gates we must start with the minimum Product of Sums form of F.

\section*{Example 4-4}

From the K-map in Figure 4-2 find equations for OR-AND, NOR-NOR, AND-NOR and NAND-AND networks.
\[
\begin{aligned}
& / F=/ A^{*} / C^{*} D+/ A^{*} C^{*} / D+A^{*} / B \\
& F=A+C+/ D^{*} A+/ C+D^{*} / A+B \text { eq. } 4-6 \\
& F=/\left[/\left(A+C+/ D^{*} A+/ C+D^{*} / A+B\right)\right] \text { eq. } 4-7 \\
&F=/[/(A+C+/ D)+/(A+C+D)+/ / A+B)] \text { eq. } 4-8 \\
& F=/\left(/ A^{*} / C C^{*} D+/ A^{*} C^{*} / D+A^{*} / B\right) \text { eq. } 4-9 \\
&\left.F=/\left(/ A^{*} / C C^{*} D\right)^{*} / / / A^{*} C^{*} / D\right)^{*} /\left(A^{*} / B\right) \text { eq. } 4-10 \\
& \text { eq. } 4-11
\end{aligned}
\]

Equations 4-7, 4-9, 4-10 and 4-11 are OR-AND, NOR-NOR, AND-NOR and NAND-AND networks, respectively.
NAND-NAND and NOR-NOR networks are very common in industry because both the NAND and NOR gates are universal gates. Thus, these gates are made in great quantities, making them more available for designers.
A NAND-NAND network is made from a Sum of Products solution. The AND and OR gates of the SOP solution are replaced by NAND gates with all the interconnections staying the same. Variables that are input directly to the output gate must be inverted.
A NOR-NOR network is made from a Product of Sums solution. The OR and AND gates are replaced by NOR gates with all interconnections staying the same. Any variables that are input directly to the output NOR gate must be inverted.
An easy way of forming either a NAND network from a Sum of Products solution or a NOR network from a Product of Sums solution is to place two inversion bubbles in series between the two levels as demonstrated in Figure 4-3.




Figure 4-3. Network Conversion

\subsection*{4.4 Multiplexers}

Multiplexers are circuits which select one of 2 n input lines using n selector lines. For example, an eight-input multiplexer selects one of \(2^{3}\) input lines using three select lines.

\section*{Example 4.5}

Design an 8:1 multiplexer in SOP form by using a truth table.
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|c|c|}
\hline \multicolumn{2}{|c|}{ SELECT } & \multicolumn{6}{|c|}{ MULTIPLEXER INPUTS } & OUTPUT \\
\hline A & B & C & D0 & D1 & D2 & D3 & D4 & D5 & D6 & D7 & Y \\
\hline 0 & 0 & 0 & 0 & X & X & X & X & X & X & X & 0 \\
\hline 0 & 0 & 0 & 1 & X & X & X & X & X & X & X & 1 \\
\hline 0 & 0 & 1 & X & 0 & X & X & X & X & X & X & 0 \\
\hline 0 & 0 & 1 & X & 1 & X & X & X & X & X & X & 1 \\
\hline 0 & 1 & 0 & X & X & 0 & X & X & X & X & X & 0 \\
\hline 0 & 1 & 0 & X & X & 1 & X & X & X & X & X & 1 \\
\hline 0 & 1 & 1 & X & X & X & 0 & X & X & X & X & 0 \\
\hline 0 & 1 & 1 & X & X & X & 1 & X & X & X & X & 1 \\
\hline 1 & 0 & 0 & X & X & X & X & 0 & X & X & X & 0 \\
\hline 1 & 0 & 0 & X & X & X & X & 1 & X & X & X & 1 \\
\hline 1 & 0 & 1 & X & X & X & X & X & 0 & X & X & 0 \\
\hline 1 & 0 & 1 & X & X & X & X & X & 1 & X & X & 1 \\
\hline 1 & 1 & 0 & X & X & X & X & X & X & 0 & X & 0 \\
\hline 1 & 1 & 0 & X & X & X & X & X & X & 1 & X & 1 \\
\hline 1 & 1 & 1 & X & X & X & X & X & X & X & 0 & 0 \\
\hline 1 & 1 & 1 & X & X & X & X & X & X & X & 1 & 1 \\
\hline
\end{tabular}

Truth Table for 8:1 Multiplexer

As can be seen from the truth table \(A, B\) and \(C\) select one of the eight multiplexer inputs to appear on the output, Y. If \(A, B\) and \(\mathrm{C}=011\), then the D3 AND gate will be enabled while all the other AND gates will be disabled. This allows D3 to be 'ORed' with seven zeros and thus end up on the output Y .


\section*{Example 4.6}

Design a dual 8:1 mux with the appropriate PAL device.
When selecting a PAL device several things must be considered. Will the design need registers, how many inputs and outputs are there, are the outputs active high or active low? For a Dual 8:1 mux the select lines will be shared but the eight data inputs to each mux are independent. Thus, we need nineteen inputs and two outputs for the design. This narrows our choices down to one PAL device, the PAL20L2. The output of the PAL20L2 is active low but this causes no problems because an active high output will result by simply inverting all the data inputs.
Multiplexers have been widely used as logic devices as well as selector circuits. A 4:1 mux can be used to realize any threevariable function. An 8:1 mux can realize any four-variable function.

\section*{Example 4.7}

Solve the K-map in Figure 4-4 and build the circuit with an 8:1 multiplexer.


\section*{Figure 4-4. Eight One-Variable Karnaugh Maps}
\(\mathrm{A}, \mathrm{B}\) and C are used as control inputs to the multiplexer, this leaves \(D\) as the only real variable in the problem. The 16 -square K -map can thus be broken up into eight one-variable K -maps. Each map is solved for one of the eight data inputs to the \(8: 1\) multiplexer.
\begin{tabular}{|c|c|c|c|}
\hline \(\mathbf{A}\) & \(\mathbf{B}\) & \(\mathbf{C}\) & \\
\hline 0 & 0 & 0 & \(10=1 \mathbf{D}\) \\
\hline 0 & 0 & 1 & \(11=1\) \\
\hline 0 & 1 & 0 & \(12=1 \mathbf{D}\) \\
\hline 0 & 1 & 1 & \(13=0\) \\
\hline 1 & 0 & 0 & \(14=1\) \\
\hline 1 & 0 & 1 & \(15=1\) \\
\hline 1 & 1 & 0 & \(16=0\) \\
\hline 1 & 1 & 1 & \(17=1 D\) \\
\hline
\end{tabular}


\subsection*{4.5 Decoders}

On a multiplexer with \(n\) address lines, one of the \(2^{n}\) inputs is selected to be output. On a decoder with \(n\) address lines, one of the \(2^{n}\) output lines is forced either high or low, depending on the design of the decoder. Table 4-4 shows a truth table for a 3-to-8 decoder.
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|c|}
\hline \multicolumn{4}{|c|}{ SELECT LINES } & \multicolumn{8}{|c|}{ OUTPUT LINES } \\
\hline \(\mathbf{A}\) & \(\mathbf{B}\) & \(\mathbf{C}\) & \(\mathbf{f}\) & \(\mathbf{g}\) & \(\mathbf{h}\) & \(\mathbf{i}\) & \(\mathbf{j}\) & \(\mathbf{k}\) & \(\mathbf{l}\) & \(\mathbf{m}\) \\
\hline 0 & 0 & 0 & 1 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\
\hline 0 & 0 & 1 & 0 & 1 & 0 & 0 & 0 & 0 & 0 & 0 \\
\hline 0 & 1 & 0 & 0 & 0 & 1 & 0 & 0 & 0 & 0 & 0 \\
\hline 0 & 1 & 1 & 0 & 0 & 0 & 1 & 0 & 0 & 0 & 0 \\
\hline 1 & 0 & 0 & 0 & 0 & 0 & 0 & 1 & 0 & 0 & 0 \\
\hline 1 & 0 & 1 & 0 & 0 & 0 & 0 & 0 & 1 & 0 & 0 \\
\hline \(\mathbf{1}\) & 1 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 1 & 0 \\
\hline \(\mathbf{1}\) & 1 & 1 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 1 \\
\hline
\end{tabular}

\section*{Table 4-4. Decoder Truth Table}

A decoder will have as many outputs as there are possible binary input combinations. It can be seen from Table 4-4 that only one output can be equal to 1 at any one time. The outputted 1 represents the minterm combination that was input to the decoder. It can also be noticed from Table 4-4 that there is not a combination of inputs that will give all 0 's on the outputs. Many designs need this ability. It can be added simply by putting an enable line in all of the output AND gates. The logic design and block diagram for the 3-bit decoder in Table 4-4 appears in Figure 4-5.


Figure 4-5. (a) Logic Diagram for 3-to-8 Decoder (b) Block Diagram for 3-to-8 Decoder

- "raymiuve cumparatur is a combinational circuit that compares two numbers, then outputs one of three signals;
\(A>B, A=B\) or \(A<B\).

\section*{Example 4.8}

Design a 3-bit magnitude comparator in a Sum of Products form, then fit it into an appropriate PAL device.
\(B 2, B 1, B 0\)
\[
\begin{aligned}
& \text { A2, A1, A0 } \begin{array}{l|l|l|l|l|l|l|l|l|}
\hline 000 & 001 & 011 & 010 & 110 & 111 & 101 & 100 \\
\hline
\end{array} \\
& \begin{array}{c|c|c|c|c|c|c|c|c|}
\hline & 000 & 001 & 011 & 010 & 110 & 111 & 101 & 100 \\
\hline 000 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\
\hline 001 & 1 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\
\hline 011 & 1 & 1 & 0 & 1 & 0 & 0 & 0 & 0 \\
\hline 010 & 1 & 1 & 0 & 0 & 0 & 0 & 0 & 0 \\
\hline 110 & 1 & 1 & 1 & 1 & 0 & 0 & 1 & 1 \\
\hline 111 & 1 & 1 & 1 & 1 & 1 & 0 & 1 & 1 \\
\hline 101 & 1 & 1 & 1 & 1 & 0 & 0 & 0 & 1 \\
\hline 100 & 1 & 1 & 1 & 1 & 0 & 0 & 0 & 0 \\
\hline
\end{array} \\
& A>B=A 2^{*} / B 2 \\
& +A 1^{*} / B 2^{*} / B 1 \\
& +\mathrm{A} 0^{*} / B 2^{*} / B 1^{*} / \mathrm{BO} \\
& +A 2^{*} A 1^{*} / B 1 \\
& +A 2^{*} A 1^{*} A 0^{*} / B 0 \\
& +\mathbf{A} 2^{*} A 0^{*} / B 1^{*} / B 0
\end{aligned}
\]

The six-variable K-maps are used to produce Sum of Product equations for \(A>B\) and \(B>A\). These equations are then used to form the two-level logic diagram of the 3-bit magnitude comparator.


The logic diagram of the 3-bit comparator shows that there are six inputs and two outputs in the circuit. Each output is derived from seven product terms. The PAL16H2 fits the design best. This PAL device has more inputs than are needed, but it is the smallest PAL device with enough product terms to realize the circuit. A NOR gate external to the PAL device can be used to get the result \(A=B\). The outputs of the PAL device will be the inputs to the NOR gate, when both inputs equal ' 0 ', \(A\) equals \(B\).

\subsection*{4.7 Adder}

A binary adder takes two binary inputs, adds them, then outputs the binary sum. A full adder is the basic building block of any adding network. A full adder is a 1-bit adder with a carry-in and a carry-out. The truth table is shown in Table 4-5. The logic design and block diagram appear in Figure 4-6.
\begin{tabular}{|c|c|c|c|c|}
\hline \(\mathbf{A}\) & \(\mathbf{B}\) & \(\mathbf{C}_{\mathbf{I N}}\) & \(\mathbf{Y}\) & \(\mathbf{C}_{\text {OUT }}\) \\
\hline 0 & 0 & 0 & 0 & 0 \\
\hline 0 & 0 & 1 & 1 & 0 \\
\hline 0 & 1 & 0 & 1 & 0 \\
\hline 0 & 1 & 1 & 0 & 1 \\
\hline 1 & 0 & 0 & 1 & 0 \\
\hline 1 & 0 & 1 & 0 & 1 \\
\hline 1 & 1 & 0 & 0 & 1 \\
\hline 1 & 1 & 1 & 1 & 1 \\
\hline
\end{tabular}

Table 4-5. Truth Table for Full Adder


Logic Tutorial

Logic Diagram
PAL16L8


The truth table is used to form K -maps for the outputs Y and \(\mathrm{C}_{\mathrm{in}}\). These simple K-maps are solved to obtain equations for \(Y\) and \(\mathrm{C}_{\mathrm{in}}\). The equations are then used to design a Sum of Products circuit for the \(3: 8\) decoder. The decoder is shown in Figure 4-6.


Figure 4-6. (a) Karnaugh Maps for 3:8 Decoder, (b) Logic Diagram, (c) Block Diagram

A parallel 4-bit adder will now be designed using four full adders.


Figure 4-7. Parallel 4-Bit Adder
To implement this circuit in a PAL device, each carry-out is directly input to the next digit's carry-in. Nine inputs and eight outputs are needed. Three of the outputs (the first three carryouts) are only needed so they can be fed back into the circuit as inputs. A PAL16L8 is the perfect PAL device for this design.

\subsection*{4.8 Hazards}

Even though a digital network is designed correctly, it still may have erroneous outputs at times due to Hazards. Hazards exist because physical circuits do not behave ideally. For example, a D-type flip-flop has two outputs; Q and /Q, which should always be complements of each other. In the real world \(Q\) may be switching from 1 to 0 and \(/ Q\) from 0 to 1. Unless both \(Q\) and /Q switch at exactly the same time \(Q\) will equal / \(Q\) for some finite amount of time. In some cases this could cause the network to malfunction. The change in the flip-flop output may not cause the steady-state output of the network to change, but the transient output may have had a spurious change due to the nonideal flip-flop. If the network's output was the set line of a latch, the latch would set due to the hazard.
There are two types of hazards, Static and Dynamic. Static Hazards occur when the steady-state output of a network does not change due to an input change, but a momentary change does occur in the transition from one state to another. Static Hazards are qualified further as either static 1 hazards or static 0 hazards. Static 1 hazards exist when the steady-state output is 1 , static 0 hazards exist when the steady-state output is 0 .


Figure 4-8. (a) Static 0 Hazard, (b) Static 1 Hazard

Dynamic hazards occur when the steady-state output is supposed to change due to an input change. The hazard occurs when the transient output changes several times before settling down.


\section*{Figure 4-9. Dynamic Hazard}

As previously mentioned hazards are caused by the nonideal physical network. Two classifications of hazards causes do exist; function hazards and logic hazards.
Function hazards can be present when more than one input variable changes. It is easy to see from the K-map in Figure 4-10 why function hazards exist.
\begin{tabular}{|c|c|c|c|c|}
\hline & 00 & 01 & 11 & 10 \\
\hline 00 & 1 & 0 & 1 & 0 \\
\hline 01 & 0 & 1 & 0 & 0 \\
\hline 11 & 0 & 0 & 0 & 1 \\
\hline 10 & 0 & 0 & 1 & 0 \\
\hline
\end{tabular}

Figure 4-10. Karnaugh Maps with Function Hazards

A function static 1 hazard is present when the input variables \(A\), \(B, C\) and \(D\) go from \(\leqslant 0000>\) to \(<0101>\). If both \(B\) and \(D\) changed simultaneously no temporary erroneous pulse would appear on the output; however in the real world either B or D would change first. The transient output would have gone to 0 from being momentarily in state \(<0100>\) or \(\langle 0001\rangle\). Looking at the K-map, it is easy to see function static hazards and function dynamic hazards.
The easiest way to avoid function hazards is by restricting input changes to one variable at a time. This method is not always possible though, because the inputs may not be under your control.
Logic hazards exist because of the way a function is realized. Logic hazards can exist even if input changes are rescticted to one variable at a time.

A K-map is a very good way of locating logic hazards. When trying to locate the static 0 and static 1 logic hazards on a K-map it is only necessary to map the 1 -sets or the 0 -sets.



Figure 4-11. (a) Karnaugh Map with Two Logic Hazards (b) Karnaugh Map with No Logic Hazards

A 1-set is a product expression derived from a grouping of 1's on the K-map. If there are two adjacent input states that produce a 1 on the output, but are not covered by the same 1-term, a static logic hazard exists. Logic hazards may be eliminated by redesigning the circuit so adjacent input states that produce ones are covered by the same 1-term.

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\section*{5.1 introduction}

In the previous chapter, combinational circuits were discussed circuits whose outputs are determined completely by their present input. Outputs of some networks depend not only on their present inputs but also on the sequence of their past inputs. These circuits are called sequential switching networks. Sequential networks must be able to remember the past sequence of their inputs in order to be able to produce new

\section*{outputs.}

\subsection*{5.2 Latches}

In order for a sequential circuit to remember the previous inputs, it must retain those values in some memory elements. The most basic memory element is called a latch. Latches are memory devices with one or more inputs that effect their outputs.
One of the most important properties of the latches is that any change to the input of the latch will appear at the output and the new output will be delayed only by the propagation delay of the gates between inputs and the outputs. All the latches have this transparency property and usually are referred to as transparent latches. A latch constructed of NOR gates is shown in Figure 5-1a.

\subsection*{5.2.1 RS Latch}

The circuit in Figure 5-1a is called a SET-RESET or an RS latch. There are two input lines to an RS latch, which are used to control the state of the latch. The rules for this type of latch are:
1. If SET \(=\) RESET \(=0\), then the latch remains in the same state and output does not change.
2. A ' 1 ' on the SET and ' 0 ' on the RESET line will make the latch SET to ' 1 '.
3. A ' 0 ' on the SET line and a ' 1 ' on the RESET line causes the latch RESET to ' 0 ' state.
4. If SET = RESET \(=1\), then \(Q\) and / \(Q\) will be ' 0 ' at the same time which is meaningless. When designing with an RS latch, we should remember that SET \(=\) RESET \(=1\) is forbidden.
Following an RS latch circuit, its state table, characteristic equation and waveforms are shown.

\[
s_{6}, R_{t} a_{7} \begin{array}{c|c|c|}
\hline & 0 & 1 \\
\hline 00 & 0 & 1 \\
\hline 01 & 0 & 0 \\
\hline 11 & x & x \\
\hline 10 & 1 & 1 \\
\hline
\end{array}
\]
\(a_{t+1}=s_{t}+a_{t}^{*} / R_{t}\)
(where, \(\mathrm{s}_{\mathrm{t}}{ }^{*} \mathrm{R}_{\mathrm{t}}=0\) )
(c)


Figure 5-1. RS Latch (a) Logic Circuit (b) State Table (c) Karnaugh Map (d) Waveforms

Let's examine the RS latch circuit when SET \(=\) RESET \(=1\). In this case the output, \(Q\), will toggle for a long period of time, and it is unpredictable to know when the circuit will be out of this state. The following waveforms examine this case:


Latches can have more than two inputs. In Figure 5-2, we examine a latch circuit that has two SET terms instead of one. The latch circuit and the transition table are shown.

(a)
\begin{tabular}{|c|c|c|c|c|}
\hline \(\mathbf{S 1}\) & \(\mathbf{S 2}\) & \(\mathbf{R}\) & \(\mathbf{Q}_{\mathbf{t}}\) & \(\mathbf{Q}_{\mathbf{t}+\mathbf{1}}\) \\
\hline \hline 0 & 0 & 0 & X & NC \\
\hline 1 & X & 0 & X & 1 \\
\hline X & 1 & 0 & X & 1 \\
\hline 0 & 0 & 1 & X & 0 \\
\hline \(\mathbf{1}\) & X & 1 & X & 0 \\
\hline X & 1 & 1 & X & 0 \\
\hline
\end{tabular}
(b)

Figure 5-2. RS Latch (a) Latch Circuit (b) State Table
The RS latch configuration shown in Figure 5-1a, can be modified considering that an OR gate with an inverted output is equivalent to an AND gate with inverted inputs.

\begin{tabular}{|c|c|c|}
\hline \(\mathbf{A}\) & \(\mathbf{B}\) & \(\mathbf{Q}\) \\
\hline 0 & 0 & 1 \\
\hline 0 & 1 & 0 \\
\hline 1 & 0 & 0 \\
\hline 1 & 1 & 0 \\
\hline
\end{tabular}


The RS latch schematic can be changed, so that it uses the above equivalence:


This configuration for realizing a latch is very useful, because it is in sum-of-product form.
In some applications using latches, it is desired for the input data to be effective only when another signal - usually referred to as a control signal - is active. For these applications, the RS latch could be modified as shown in Figure 5-3.
It is apparent from Figure 5-3 that only when the control signal (C) is active, the values of the SET and RESET are effective. So when \(C=0\), the changes in the SET-RESET terms would not have any effect on the output.
A thorough examination of Figure 5-3b will show that a change in the input of the latch does not effect the output simultaneously, and there is a short delay for this change to appear on the output. This delay is caused because of the propagation delays of the gates between inputs and outputs.

(a)

(b)

Figure 5-3. RS Latch with Control (a) Latch Circuit (b) Waveforms

\subsection*{5.2.2 D Latch}

Other kinds of latches are used in sequential circuits. One of the most popular latches is called a delay latch - D latch. An RS latch is modified to a D -latch by inserting an inverter between S and \(R\), and assigning \(S\) to \(D\) input term. The D latch will take the value of its input and transfer it to the output. The advantage of the D latch over the RS latch is that in the former only one input is needed and there is no forbidden state. The only disadvantage of the D latch is that it does not have a "no change" state. This state could be reached by inserting a control signal, C , as an input to the latch (Figure 5-4).


Figure 5-4. D Latch (a) Logic Circuit (b) State Table (c) Waveforms

\subsection*{5.2.3 JK Latch}

Another useful latch is the JK latch which is shown in Figure 6-5. This latch consists of an RS latch with two AND gates in front of the inputs. This is most useful because JK latches act like RS latches, and it is permissible to apply ' 1 ' to both inputs simultaneously. The state table and characteristic equation for a JK latch is shown in Figure 5-5.

(a)
\begin{tabular}{|c|c|c|c|}
\hline \(\mathbf{S t}\) & \(\mathbf{R t}\) & \(\mathbf{Q}_{\mathbf{t}}\) & \(\mathbf{Q}_{\mathbf{t}+\mathbf{1}}\) \\
\hline \hline 0 & 0 & 0 & 0 \\
\hline 0 & 0 & 1 & 1 \\
\hline 0 & 1 & 0 & 0 \\
\hline 0 & 1 & 1 & 0 \\
\hline 1 & 0 & 0 & 1 \\
\hline 1 & 0 & 1 & 1 \\
\hline 1 & 1 & 0 & 1 \\
\hline 1 & 1 & 1 & 0 \\
\hline
\end{tabular}
(b)

Figure 5-5. JK Latch (a) Logic Circuit (b) State Table and Characteristic Equation

\subsection*{5.2.4 T Latch}

Another type of latch is a triggered latch (T Latch), which has only one input called \(T\). Whenever \(T\) is high, the latch changes state. T latch is realized by connecting both J and K to one input, T .

\[
Q_{t+1}=/ T^{*} Q+T^{*} / Q
\]
(b)
(c)

Figure 5-6. T Latch (a) Logic Circuit (b) State Table and Characteristic Equation

\subsection*{5.3 Flip-Flops}

A flip-flop is also a bistable device - a circuit with only two stable states. There is one main difference between flip-flops and latches. Flip-flops do not have the transparency of the latches. Therefore a change in the input does not effect the output immediately. A change in the flip-flop is a result of a change to the control or an asynchronous input. The main advantage of the flip-flops over the latches is that it is possible to "read in" a new value to the flip-flop and read out an output at the same time. This property is not allowed in the latches because of the latch transparency.
A group of flip-flops form a register. A register is a digital device that is used to hold information. A register may be a combination of flip-flops and gates. The gates would control how and when the data from the flip-flops will be transferred.
In the previous sections, different types of latches were discussed. The same type of flip-flops are available (RS, JK, D and T flip-flops) and the state equations are the same with the difference that the output change in latches is realized on the same clock pulse and in the flip-flops on the next pulse.
Let's take a look at a D-latch and a D flip-flop and discuss the difference between them.


Figure 5-7. Comparison of a D-Latch and a D Flip-Flop

Examining the above waveforms, we could notice that the \(D\) latch and D flip-flop act the same except when the \(D\) input changes while \(C=1\). Because in the flip-flop at the edge of each clock pulse the input is seen and the flip-flop maintains the value till the next clock edge. But in latches the output follows the input while \(\mathrm{C}=1\).

\subsection*{5.3.1 Characteristic Equations}

The characteristic equations for various flip-flops are summarized as follows:
\begin{tabular}{lr}
\(Q_{t+1}=S+/ R^{*} Q_{t}\) & RS flip-flop \\
\(Q_{t+1}=J^{*} / Q_{t}+/ K^{*} Q_{t}\) & JK flip-flop \\
\(Q_{t+1}=T_{t+:} Q_{t}\) & T flip-flop \\
\(Q_{t+1}=Q_{t}\) & D flip-flop
\end{tabular}

In the above equations \(Q_{t+1}\) is the next state and \(Q_{t}\) is the present state. Generally we could convert one flip-flop to the other by inserting some gates in front of the RS flip-flop.

\subsection*{5.4 Designing Sequential Circuits}

As it was stated earlier, the states of a sequential circuit depend not only on the present states of its inputs, but also on the past history of them. A sequential circuit is constructed of flip-flops and gates. The gates construct the combinational part of a sequential circuit, and we could have any number of flip-flops that are needed. A general block diagram of a sequential circuit is shown in Figure 5-8.


Figure 5-8. Sequential Circuit Block Diagram

The combinational section receives external binary inputs and feeds information to the flip-flops. The flip-flops have a feedback path to the combinational circuit. The circuit has external outputs. At the rising edge of each clock pulse the information from the combinational circuit is read into the flip-flops and the new outputs are generated. The outputs do not change until the next clock pulse.
A general block diagram of a sequential circuit has been reviewed. Now let's look at a more specific circuit. In Figure 6-9, an example of a sequential circuit is shown.


Figure 5-9. Example of a Sequential Circuit

This circuit consists of two JK flip-flops, an inverter, an AND gate and an XOR gate. It has an external binary input, \(X\), and an external ouput, \(Z\).
In this section, we try to familiarize ourselves with the analysis and synthesis of sequential circuits. Synthesis will be covered first, because it would make the analysis understanding easier.

\subsection*{5.4.1 Transition Tables}

The states of a sequential circuit are determined by its inputs, the outputs and states of the flip-flops. In order to examine these states, we should determine the input equations to the flip-flops. Let's look at Figure 5-9. Using the characteristic equation for the JK flip-flop, the input equaiton for Figure \(5-9\) will be examined:
\(J_{A}=X:+: B\)
\(J_{B}=X^{*} / A\)
\(Z=A\)
\(K_{\mathrm{A}}=/ \mathrm{X}\)
\(K_{B}=X\)

The next state equations are
\(A_{t+1}=J_{A^{*}} / Q+/ K_{A}{ }^{*} Q=(X:+: B)^{*} / A+X^{*} A\)
\(=\left(X^{*} / B+/ X^{*} B\right)^{*} / A+X^{*} A\)
\(=/ A^{*} / B^{*} X+/ A^{*} B^{*} / X+B^{*} / X\)
\(B_{t+1}=J_{B^{*}} / Q+/ K_{B^{*}} Q=/ A^{*} / B^{*} X+B^{*} X\)
the above are called the state equations. The corresponding K-maps are:

\(A_{t+1}\)


Using these maps, the transition tables for Figure 5-9 are derived. There are only four different combinations that \(A\) and \(B\) could have. The next state values are derived using these four possible combinations.
The present state is the state of the flip-flop before the clock pulse, the next state is the state of flip-flop after the clock pulse has been applied. The present output, \(Z\), is the output of the sequential circuit after the clock pulse. As mentioned before, the circuit can have four states: \(A B=00,01,11\) and 10. At this point, we try to cover transitions for one input state. Suppose the circuit is in the 00 state. If an \(X=0\) input is applied, the next state will be 00 . If an \(X=1\) is applied, the next state will be 11. the output for both cases is \(Z=0\).
\begin{tabular}{|c|c|c|c|}
\hline PRESENT STATE & \multicolumn{2}{|c|}{\begin{tabular}{c} 
NEXT STATE \\
\(\mathbf{A}_{\mathbf{t}+\mathbf{1}} \mathbf{B}_{\mathbf{t}} \mathbf{1}\)
\end{tabular}} & PRESENT OUTPUT \\
\hline \(\mathbf{A B}\) & \(\mathbf{X = 0}\) & \(\mathbf{X}=\mathbf{1}\) & \(\mathbf{Z}\) \\
\hline 00 & 00 & 11 & 0 \\
\hline 01 & 10 & 01 & 0 \\
\hline 11 & 00 & 11 & 1 \\
\hline 10 & 00 & 10 & 1 \\
\hline
\end{tabular}

Figure 5-10. Transition Table for Figure 5-9

\subsection*{5.4.2 State Tables and State Diagrams}

Examining the transition table, we notice that \(A B\) has four combinations. We could assign letters to these four combinations: \(\mathrm{S}_{0}=00, \mathrm{~S}_{1}=01, \mathrm{~S}_{2}=11\) and \(\mathrm{S}_{3}=10\). Using these assignments the transition table could be modified to the state table shown in Figure 5-11.
\begin{tabular}{|c|c|c|c|}
\hline \multirow{2}{*}{ PRESENT STATE } & \multicolumn{2}{|c|}{ NEXT STATE } & PRESENT OUTPUT \(\mathbf{Z}\) \\
\cline { 2 - 4 } & \(\mathbf{x = 0}\) & \(\mathbf{x = 1}\) & \\
\hline \hline S0 & S0 & S 2 & 0 \\
\hline S1 & S 3 & S 1 & 0 \\
\hline S2 & S 0 & S 2 & 1 \\
\hline S3 & S 0 & S 3 & 1 \\
\hline
\end{tabular}

Figure 5-11. State Table for Figure 5-9
A state diagram can be derived using the state table. A state diagram could show transitions between the states when a specific input is applied. Each state is represented by a circle and the transition between the state is shown by arrows.


Figure 5-12. State Diagram for Figure 5-9
The condition under which a transition occurs is represented by \(\mathrm{X} / Z\). Applying an input, X , a transition from one state to the other takes place and a Z output will be produced. The state diagram for the state table in Figure 5-11 is shown in Figure 5-12.
We have gone through a complete analysis procedure for the previous example. This process could be summarized as follows:
1. Using a given network, determine the input equations.
2. Derive the next state equations, using the flip-flop characteristic equations:
\begin{tabular}{lr}
\(Q_{t+1}=D\) & D flip-flop \\
\(Q_{t+1}=T+: Q\) & \(T\) flip-flop \\
\(Q_{t+1}=J^{*} / Q+/ K^{*} Q\) & JK flip-flop \\
\(Q_{t+1}=S+/ R^{*} Q\) & RS flip-flop
\end{tabular}
3. Derive the corresponding K-maps, and transition tables.
4. Assigning states to the variables, make the state table.
5. From the state table, draw the state diagram.

The analysis of a sequential circuit could be easier to understand, because the same steps could be taken in reverse order. A flow chart of the procedure is shown below.


Figure 5-13. Flow Chart of Sequential Circuit Analysis
5.4.3 Design Examples

In this section, the procedure for designing sequential circuits will be shown in more detail by analyzing some design problems. The design steps will follow the flow table shown in the previous section.

\section*{Example 5.1:}

Design a clocked sequential circuit which receives an input, \(X\), and will produce an output, \(Z=1\), after it has received an input sequence of 0010 or 100 .

\section*{Solution:}

The first step is to make a state diagram. The state diagram will start in a state designated by S 0 , if the next input from S 0 state is a 0 , it could be the start for the 0010 sequence. If a 1 is received, the circuit will go to state S4, which could be the start for the 100 sequence.

When in the S1 state one of two inputs could be received \(\mathrm{X}=0\) or \(X=1\). If \(X=0\) then the circuit could still follow the 0010 sequence, because so far it has received the 00 sequence. If \(X=1\) then the input sequence would be 01 so far, which cannot follow the 0010 any more but it could be a start for the 100 sequence, therefore under this condition the circuit would have a transition from state S1 to S4.

While in the S4 state, if an \(X=1\) is received it would stay in the same state, because a sequence of 11 could still follow the 100 pattern. If \(X=0\) is received the 100 pattern could continue, because 10 follows the 100 pattern.

When in the S 2 state if an \(\mathrm{X}=0\) is received, it will stay in the S2 state and if \(X=1\) then it will have a transition from the S2 to S3 state. While in the S3 state, we will have a transition to state S4 if \(X=1\), because the input sequence would be 0011 which cannot follow the 0010 sequence any more, but the 1 at the end could be a beginning for the 100 sequence which is the same state as the S4. If \(X=0\) is received then the 0010 sequence is complete and an output, \(Z=1\), is generated. At the same time in the 0010 sequence, the 10 at the end could be the start of the 100 sequence. Therefore under the \(X=0\) condition \(a Z=1\) is generated and a transition from the S 3 to the S 5 state will happen.

While in the S 5 state an \(X=1\) will transfer the circuit from S 5 to S 4 , and an \(\mathrm{X}=0\) will cause a transition from S5 to S6. Under this condition a \(Z=1\) is generated for the output because the 100 sequence for the inputs has occurred.

From the S 6 state we will see a transition from S 6 to S 2 if \(\mathrm{X}=0\), and a transition to S 3 if \(X=1\). A state diagram of this design is shown in Figure 5-14a.

By analyzing the state diagram, a state table is generated (Figure 5-14b). A careful look at the state table will show that the S2 and the S 6 states are equivalent, because under \(\mathrm{X}=0\) they both have a transition to state S 2 with \(Z=0\), and under \(X=1\) they would transfer to S 3 with \(\mathrm{Z}=0\). So the state table could be summarized to Figure 5-14c. After summarizing the state table, there will be a total of six states left, therefore at least three variables will be needed for the state assignments \(\left(2^{3}=8\right)\). In this case only six assignments will be used. The state variables are designated by \(A, B\) and \(C\). The state assignments are illustrated in Figure 5-14d.

(a)
\begin{tabular}{|c|c|c|}
\hline \multirow{2}{*}{\begin{tabular}{c} 
PRESENT \\
STATE
\end{tabular}} & \multicolumn{2}{c|}{ NEXT STATE} \\
\cline { 2 - 3 } & \(\mathbf{x}=\mathbf{0}\) & \(\mathbf{x}=\mathbf{1}\) \\
\hline S 0 & \(\mathrm{~S} 1,0\) & \(\mathrm{~S} 4,0\) \\
\hline S 1 & \(\mathrm{~S} 2,0\) & \(\mathrm{~S} 4,0\) \\
\hline S 2 & \(\mathrm{~S} 2,0\) & \(\mathrm{~S} 3,0\) \\
\hline S 3 & \(\mathrm{~S} 5,1\) & \(\mathrm{~S} 4,0\) \\
\hline S 4 & \(\mathrm{~S} 5,0\) & \(\mathrm{~S} 4,0\) \\
\hline S 5 & \(\mathrm{~S} 6,1\) & \(\mathrm{~S} 4,0\) \\
\hline S 6 & \(\mathrm{~S} 2,0\) & \(\mathrm{~S} 3,0\) \\
\hline
\end{tabular}
(b)
\begin{tabular}{|c|c|c|}
\hline PRESENT & \multicolumn{2}{|c|}{ NEXT STATE } \\
STATE & \(\mathbf{X}=\mathbf{0}\) & \(\mathbf{X}=\mathbf{1}\) \\
\hline S 0 & \(\mathrm{~S} 1,0\) & \(\mathrm{~S} 4,0\) \\
\hline S 1 & \(\mathrm{~S} 2,0\) & \(\mathrm{~S} 4,0\) \\
\hline S 2 & \(\mathrm{~S} 2,0\) & \(\mathrm{~S} 3,0\) \\
\hline S 3 & \(\mathrm{~S} 5,1\) & \(\mathrm{~S} 4,0\) \\
\hline S 4 & \(\mathrm{~S} 5,0\) & \(\mathrm{~S} 4,0\) \\
\hline S 5 & \(\mathrm{~S} 2,1\) & \(\mathrm{~S} 3,0\) \\
\hline
\end{tabular}
(c)
\begin{tabular}{|c|c|c|c|c|}
\hline \multirow{2}{*}{\((\mathbf{A B C})_{\mathbf{t}}\)} & \multicolumn{2}{|c|}{\((\mathbf{A B C})_{\mathbf{t}+\mathbf{1}}\)} & \multicolumn{2}{c|}{\(\mathbf{Z}\)} \\
\cline { 2 - 5 } & \(\mathbf{X}=\mathbf{0}\) & \(\mathbf{X = 1}\) & \(\mathbf{X}=\mathbf{0}\) & \(\mathbf{X}=\mathbf{1}\) \\
\hline \hline 000 & 001 & 100 & 0 & 0 \\
\hline 001 & 010 & 100 & 0 & 0 \\
\hline 010 & 010 & 011 & 0 & 0 \\
\hline 011 & 101 & 100 & 1 & 0 \\
\hline 100 & 101 & 100 & 0 & 0 \\
\hline 101 & 010 & 100 & 1 & 0 \\
\hline
\end{tabular}
(d)

Figure 5-14. Example 5.1 (a) State Diagram (b, c) State Tables (d) Transition Table

From the Assignment table, the K-maps for each state are derived. In this design the circuit is realized by JK flip-flops, therefore two K-maps are needed for each state variable (shown in Figure 5-15).

\(J_{A}=/ B^{*} X+B^{*} C\)
A, B \begin{tabular}{c|c|c|c|c|}
\(c, x\) \\
00 & 01 & 11 & 10 \\
\hline 00 & \(x\) & \(x\) & \(x\) & \(x\) \\
\hline 01 & \(x\) & \(x\) & \(x\) & \(x\) \\
\hline 11 & \(x\) & \(x\) & \(x\) & \(x\) \\
\hline 10 & 0 & 0 & 0 & 1 \\
\hline
\end{tabular}
\(K_{A}=X^{*} \mathbf{C}\)


\(J_{C}=B^{*} X+/ B^{*} / C^{*} / X\)

\(K_{C}=/ B+X\)
\[
\left.\begin{array}{c}
\text { C, } X \\
A, B \quad 00 \\
\hline 00 \\
\hline 01 \\
\hline 01 \\
\hline 11
\end{array}\right)
\]

Figure 5-15. Karnaugh Maps for Example 5.1
State equations are derived using the K-maps. Using the state equations, the circuit diagram for the design would be obtained as shown in Figure 5-16. The state equations are summarized as follows.
\(J_{A}=/ B^{*} X+B^{*} C\)
\(J_{B}=C^{*} / X\)
\(J_{C}=B^{*} X+A^{*} / X\)
\(K_{A}=/ X^{*} C\)
\(K_{B}=C\)
\(K_{C}=/ B+X\)


Figure 5-16. Circuit Diagram for Example 5.1

\section*{Example 5.2}

Derive the state diagram, state table, and state equations of a sequential circuit which adds five to a binary number in the range of 0000 to 1010. The inputs and outputs should be serial with the least significant bit arriving first. Realize this design with three JK flip-flops.

\section*{Solution:}

In Figure 5-17a, all the possible combinations for the input and the output are shown. The state table starts at state A. At time to the first input is received, if \(X=0\) then we look at the map for all possible combinations and notice that at to whenever \(X=0\), the output is a 1 . Thus, if the present state is \(A\), under \(X=0\) the output is \(Z=1\). On the other hand, if \(X=1\) the map shows that \(Z\) will be a 0 . At time \(t_{1}\) if \(X=0\) and the sequence of the inputs has been 00 then the output would be a 01 . So in this transition \(Z=0\). All the states of the state diagram could be derived by inspection of the table in Figure 5-17a. The state diagram will be completed as in Figure 5-17b.
The state table is drawn using the state diagram. Inspecting the state table will show that some of the states are equal. States H, J and \(L\) will have the same next state under \(X=0\) and \(X=1\), and produce the same outputs, therefore \(H=J=L\), and if they appear anywhere in the state table, they will be replaced by the H state. States I, K, M, N and \(P\) are equivalent for the same reasoning, thus they all will be replaced by 1 in the state table. Because \(\mathrm{H}=\mathrm{J}=\mathrm{L}\) and \(\mathrm{I}=\mathrm{K}=\mathrm{M}\), states D , E and F are equivalent. Therefore, the state table would be summarized to the table shown in Figure \(5-18 \mathrm{~b}\). There are a total of seven states used in the last table, so three state variables will be needed. The state variables are called A, B and C. A complete transition table is shown in Figure 5-18c.
The K-maps are drawn, using the state table. The state equations are calculated using the K-maps.
\begin{tabular}{ll}
\(J A=B^{*} X+B^{*} C\) & \(K A=B\) \\
\(J B=/ A^{*} C+A^{*} / C\) & \(K B=A+/ C^{*} X+C^{*} / X\) \\
\(J C=/ A^{*} / X\) & \(K C=A+B^{*} X\) \\
\(Z=B^{*} / X+A^{*} X+/ A^{*} / C^{*} X+/ B^{*} C^{*} X\)
\end{tabular}

\begin{tabular}{|c|c|c|c|c|c|c|c|}
\hline \multicolumn{5}{|c|}{\begin{tabular}{c} 
XINARY INPUT \\
B
\end{tabular}} & \multicolumn{5}{c|}{ ZUTPUT } \\
\hline \(\mathbf{t}_{\mathbf{3}}\) & \(\mathbf{t}_{\mathbf{2}}\) & \(\mathbf{t}_{\mathbf{1}}\) & \(\mathbf{t}_{\mathbf{0}}\) & \(\mathbf{t}_{\mathbf{3}}\) & \(\mathbf{t}_{\mathbf{2}}\) & \(\mathbf{t}_{\mathbf{1}}\) & \(\mathrm{t}_{\mathbf{0}}\) \\
\hline 0 & 0 & 0 & 0 & 0 & 1 & 0 & 1 \\
\hline 0 & 0 & 0 & 1 & 0 & 1 & 1 & 0 \\
\hline 0 & 0 & 1 & 0 & 0 & 1 & 1 & 1 \\
\hline 0 & 0 & 1 & 1 & 1 & 0 & 0 & 0 \\
\hline 0 & 1 & 0 & 0 & 1 & 0 & 0 & 1 \\
\hline 0 & 1 & 0 & 1 & 1 & 0 & 1 & 0 \\
\hline 0 & 1 & 1 & 0 & 1 & 0 & 1 & 1 \\
\hline 0 & 1 & 1 & 1 & 1 & 1 & 0 & 0 \\
\hline 1 & 0 & 0 & 0 & 1 & 1 & 0 & 1 \\
\hline 1 & 0 & 0 & 1 & 1 & 1 & 1 & 0 \\
\hline 1 & 0 & 1 & 0 & 1 & 1 & 1 & 1 \\
\hline
\end{tabular}

Figure 5-17. Example 5.2 (a) Truth Table (b) State Diagram
\(\square\)
(b)
 sidet molltarmy (b)



 (2) (e)

\begin{tabular}{|c|c|c|c|c|}
\hline \multirow{2}{*}{ PRESENT STATE } & \multicolumn{2}{|c|}{ NEXT STATE } & \multicolumn{2}{c|}{\(\mathbf{Z}\)} \\
\cline { 2 - 5 } & \(\mathbf{X}=\mathbf{0}\) & \(\mathbf{X}-\mathbf{1}\) & \(\mathbf{X}=\mathbf{0}\) & \(\mathbf{X}=\mathbf{1}\) \\
\hline A & B & A & 1 & 0 \\
\hline B & D & E & 0 & 1 \\
\hline C & F & G & 1 & 0 \\
\hline D & H & I & 1 & 0 \\
\hline E & J & K & 1 & 0 \\
\hline F & L & M & 1 & 0 \\
\hline G & N & P & 0 & 1 \\
\hline H & A & A & 0 & 1 \\
\hline I & A & - & 1 & - \\
\hline J & A & A & 0 & 1 \\
\hline K & A & - & 1 & - \\
\hline L & A & A & 0 & 1 \\
\hline M & A & - & 1 & \(-10 \mid\) \\
\hline N & A & - & 1 & - \\
\hline P & A & - & 1 & - \\
\hline
\end{tabular}
(a)
\begin{tabular}{|c|c|c|c|c|}
\hline \multirow{2}{*}{ PRESENT STATE } & \multicolumn{2}{|c|}{ NEXT STATE } & \multicolumn{2}{c|}{\(\mathbf{Z}\)} \\
\cline { 2 - 5 } & \(\mathbf{X}=\mathbf{0}\) & \(\mathbf{x}=\mathbf{1}\) & \(\mathbf{x}=\mathbf{0}\) & \(\mathbf{x}=\mathbf{1}\) \\
\hline \hline A & B & A & 1 & 0 \\
\hline B & D & D & 0 & 1 \\
\hline C & F & G & 1 & 0 \\
\hline D & H & I & 1 & 0 \\
\hline G & I & I & 0 & 1 \\
\hline H & A & A & 0 & 1 \\
\hline I & A & - & 1 & - \\
\hline
\end{tabular}
(b)
\begin{tabular}{|c|c|c|c|c|}
\hline \multirow{2}{*}{ PRESENT STATE } & \multicolumn{2}{|c|}{ NEXT STATE } & \multicolumn{2}{c|}{\(\mathbf{Z}\)} \\
\cline { 2 - 5 } & \(\mathbf{x = 0}\) & \(\mathbf{x}=\mathbf{1}\) & \(\mathbf{x}=\mathbf{0}\) & \(\mathbf{x = 1}\) \\
\hline \hline 000 & 001 & 000 & 1 & 0 \\
\hline 001 & 011 & 011 & 0 & 1 \\
\hline 010 & 011 & 100 & 1 & 0 \\
\hline 011 & 101 & 110 & 1 & 0 \\
\hline 100 & 110 & 110 & 0 & 1 \\
\hline 101 & 000 & 000 & 0 & 1 \\
\hline 110 & 000 & - & 1 & - \\
\hline
\end{tabular}
(c)

Figure 5-18. Example 5.2 (a) State Table (b) Reduced State Table (c) Transition Table
\[
J_{A}=B^{*} X+B^{*} C
\]
\[
K_{A}=B+C
\]
\[
\begin{aligned}
& \\
& \text { A, B }
\end{aligned}
\]
\begin{tabular}{c|c|c|c|c|}
\multicolumn{5}{c}{\(\mathrm{C}, \mathrm{X}\)} \\
\(\mathrm{A}, \mathrm{B}\) & 0 & 00 & 01 & 11 \\
& 10 \\
\hline 00 & 0 & 0 & 1 & 1 \\
\hline 01 & x & x & x & x \\
\hline 11 & x & x & x & x \\
\hline 10 & 1 & 1 & 0 & 0 \\
\hline
\end{tabular}
\(\mathrm{C}_{\mathrm{A}, \mathrm{B}}\)

\(K_{B}=A+C^{*} X+C^{*} / X\)

\[

\]

\[

\]

Figure 5-19. Karnaugh Maps for Example 5.2


Design a sequential pattern detector that receives an input and produces an output, \(Z=1\), if, and only if, there has been only one group of ones in the input sequence. Derive the state diagram, state tables and state equations using three D flip-flops.

\section*{Solution:}

The state diagram is drawn as in Figure 5-21. The state table, transition table, and K-maps can be drawn easily from the state diagram. The state equations are calculated as follows:
\[
\mathrm{D}_{\mathrm{A}}=\mathrm{A}+\mathrm{B}^{*} / \mathrm{X} \quad \mathrm{D}_{\mathrm{B}}=\mathrm{B}^{*} / \mathrm{X}+\mathrm{A}^{*} \mathrm{X} \quad \mathrm{Z}=\mathrm{B}
\]

The state tables are shown in Figure 5-20, and the K-maps are shown in Figure 5-21


Figure 5-20. Example 5.3 (a) State Diagram (b) State Table


Figure 5-21. Karnaugh Maps for Example 5.3

Counters are among the most commonly used sequential circuits. In the following sections, they are covered in detail.
A register that goes through a predetermined state upon receiving an input pulse is called a counter. Counters are one of the simplest sequential circuits, and are found in almost all equipment containing digital logic. According to what sequence of logic a counter follows, we will have different types of counters: BCD, binary, etc.
The binary counter is one of the simplest counters. An n-bit binary counter is a register with \(n\) flip-flops and associated combinational logic that follows the sequence of \(n\)-bits from \(0-2^{n-1}\).

\section*{Example 5.4}

Design a 3-bit up/down binary counter. There are three outputs from the binary counter: DA, DB and DC. The input to the counter is \(X\), the counter will increment if \(X=1\), and decrement if \(X=0\). Design this circuit using three \(D\) flip-flops.

\section*{Solution:}

This circuit would have eight different states, because the 3 -bit counter goes through eight different states. The states are called \(\mathrm{q} 0, \mathrm{q} 1, \mathrm{q} 2, \mathrm{q} 3, \mathrm{q} 4, \mathrm{q} 5, \mathrm{q} 6\) and q 7 . If \(\mathrm{X}=1\) each state will have a transition to its next higher state. For example \(q 0\) will go to \(q 1, q 1\) will go to \(q 2\) and so on. If \(X=0\) then each state will change to its previous state. For example, \(q 7\) will go to \(\mathrm{q} 6, \mathrm{q} 5\) to q 4 and so on.

The state diagram of this design is shown in Figure 5-22a. The state, and transition tables which are derived from the diagram are shown in Figure 5-22b. The K-maps and the state variables are shown in Figure 5-22c. The state equations are calculated using the \(K\)-maps. The equations are summarized as follows:
\(D_{A}=/ A^{*} / B^{*} / C^{*} / X+/ A^{*} B^{*} C^{*} X+A^{*} B^{*} / C^{*} X+A^{*} / B^{*} X+A^{*} C^{*} / X\)
\(D_{B}=/ B^{*} / C^{*} / X+/ B^{*} C^{*} X+B^{*} / C^{*} X+B^{*} C^{*} / X\)
\(D_{C}=/ C\)

slase Dsoubsfi (d) oldeT picie (s) S.a slamex3 .8r-z swagiq uldet moifizner (o) aidaT


Figure 5-23. 5-Bit Counter (a) State Diagram (b) State Tables

Logic Tutorial
Logic Diagram
PAL16R4
\[
\text { CLK } \perp
\]


Figure 5-24. Circuit Diagram for Example 5.5

Logic Tutorial


As you might have noticed, the equations are derived for the low outputs because many PAL devices have only low outputs. The equations derived so far are written just for an up/down counter. To implement the clear function, the signal should be ANDed with the other terms in the equations for \(\mathrm{A}, \mathrm{B}, \mathrm{C}\) and D , and a CLEAR term should be ORed with each equation. The LOAD function should be ORed with all the terms to make them lows and another term should be added to each equation that consists of LOAD* (new value). The modified and final equations are listed below:
\[
\begin{aligned}
& / A=/ \mathrm{LOAD}^{*} / \mathrm{CLR}^{*} / A^{*} / \mathrm{C}^{*} \quad \mathrm{UP} \\
& \text { +/LOAD*/CLR*/A* D*/UP } \\
& +/ \text { LOAD*/CLR*/A*/B* C } \\
& +/ \mathrm{LOAD}^{*} / C L R^{*} / \mathrm{A}^{*} \mathrm{~B}^{*} / \mathrm{D} \\
& \text { + /LOAD*/CLR* } A^{*} / B^{*} / C^{*} / D^{*} / \text { UP } \\
& +/ L O A D^{*} / C L R^{*} A^{*} B^{*} C^{*} D^{*} \text { UP } \\
& \text { + LOAD*/CLR* AI } \\
& + \text { CLR }
\end{aligned}
\]

\[
+/ \text { LOAD }^{*} / \text { CLR }^{*} / \mathrm{B}^{*} / \mathrm{C}^{*}
\]
UP
\[
+/ \text { LOAD*/CLR*/B* } \quad \mathrm{D}^{*} / \mathrm{UP}
\]
\[
\text { + /LOAD*/CLR* B* C* }{ }^{*} \text { UP }
\]
\[
+/ \text { LOAD*/CLR* } \mathrm{B}^{*} / \mathrm{C}^{*} / \mathrm{D}^{*} / \mathrm{UP}
\]
\[
+\operatorname{LOAD*} / C L R^{*} / B I
\]
=
AD/CLR/C DNUP
+ /LOAD*/CLR* C* D* UP
+ LOAD*/CLR*/Cl
+ CLR
\(=/\) LOAD \(^{*} /\) CLR \(^{*} D\)
+ CLR
Using the above equations and PAL16R4, the schematic for the 4 -bit counter could be generated. This design is shown in Figure 5-26.
As we try to design bigger counters, the design of them using the state tables and K-maps gets more diffucult. In the design of the 4 -bit counter, K-maps were used. If we try to design a counter bigger than this summarizing the equations will be very tough to do. Therefore, we try to find a general solution for solving the counter design problems, Let's try to write the equation for the most significant bit (MSB) of an n-bit binary counter ( \(Q_{n}\) ).
Let's look at the case where the counter is counting up. The new value of \(Q_{n}\) will depend on the carry-in from bit \(Q_{n-1}\) into \(Q_{n}\). If all least significant bits (LSBs) are high when we count up, we will have a carry-in from \(Q_{n-1}\) into \(Q_{n}\).
\[
C_{I N}:=Q_{n-1} Q_{n-2} \ldots Q 1^{*} Q 0^{*} U P
\]

Now let's look at the following table:
\begin{tabular}{|c|c|c|c|}
\hline UP & Qn & CARRY INTO Qn & NEW Qn \\
\hline \hline\(H\) & \(L\) & \(L\) & \(L\) \\
\hline\(H\) & \(L\) & \(H\) & \(H\) \\
\hline\(H\) & \(H\) & \(L\) & \(H\) \\
\hline\(H\) & \(H\) & \(H\) & \(L\) \\
\hline
\end{tabular}

Carry-in Table
Examining the above table, it is easily concluded that:
\[
\begin{aligned}
& Q_{n}:=Q_{n}:+: \text { carry-into } Q_{n} \\
& Q_{n}:=Q_{n}: *:\left(Q_{n-1} 1^{*} Q_{\left.n-2^{*} \ldots 0^{*} \cup P\right)}\right.
\end{aligned}
\]

Now that we have calculated the equation for the count-up case, let's look at the count down. Carry-in from \(Q_{n-1}\) into \(Q_{n}\) will be high if all the LSBs are low and we are counting up.
Borrow in Qn := /Qn-1*/Qn-2**.../Q0*/UP
Let's look at the following table:
\begin{tabular}{|c|c|c|c|}
\hline UP & Qn & CARRY INTO Qn & NEW Qn \\
\hline\(L\) & \(L\) & \(L\) & \(L\) \\
\hline\(L\) & \(L\) & \(H\) & \(H\) \\
\hline\(L\) & \(H\) & \(L\) & \(H\) \\
\hline\(L\) & \(H\) & \(H\) & \(L\) \\
\hline
\end{tabular}

Borrow-in Table


So:
\[
\begin{aligned}
& Q_{n}=Q_{n}:+: \text { Carry-into } Q_{n} \\
& \left.Q_{n}=Q_{n}:+: / / Q_{n-1} 1^{*} / Q_{n-2^{*}} \ldots / Q 1^{*} / Q 0^{*} / U P\right)
\end{aligned}
\]

Therefore:
\[
\begin{aligned}
Q_{n} & =Q_{n}:+:\left(Q_{n-1}{ }^{*} Q_{n-2} 2^{*} \ldots Q 1^{*} Q 0^{*} U P\right) \\
& +Q_{n} \cdot+:\left(/ Q_{n-1} * / Q_{n-2} 2^{*} \ldots / Q 1^{*} / Q 0 /^{*} U P\right)
\end{aligned}
\]

Let's try to summarize the above equaiton. For simplicity, let's give shorter names to different parts of the above equation.
\[
\begin{aligned}
& A=Q_{n} \\
& B=Q_{n-1}^{*} Q_{n-2^{*} \ldots} \ldots 1^{*} Q 0^{*} U P \\
& C=/ Q_{n-1} / / Q_{n-2^{*} \ldots / Q 1^{*} / Q 0^{*} / U P}
\end{aligned}
\]

Therefore the equation is expressed as:
\[
\begin{aligned}
A & =A:+: B \\
& +A:+: C
\end{aligned}
\]
\(B\) and \(C\) are exclusive from each other, so the above equation could be summarized to:
\[
A=A:+: B+C
\]
then:
\[
\begin{align*}
& Q_{n}=Q_{n}:+:\left(Q_{n-1}{ }^{*} Q_{n-2^{*}} \ldots Q_{1 *}^{*} Q 0^{*} U P\right) \\
&+\left(/ Q_{n-1^{*} / Q_{n-2}} \ldots / Q 1^{*} / Q 0^{*} / U P\right)
\end{align*}
\]

Using the solution discussed above, let's try to solve a design problem.

\section*{Example 5.7:}

Design an n-bit counter that can count up, count down, SET and LOAD new values into the counter. SET overrides LOAD, count and hold. LOAD overrides count. Count is conditional on carry in, otherwise it holds.

\section*{Solution:}

The above operations are exercised in the function table and summarized in the operations table.
\begin{tabular}{|c|c|c|c|c|c|c|}
\hline SET & LD & CIN & UP & D & Q & OPERATION \\
\hline H & X & X & X & X & X & Set all HIGH \\
\hline L & L & X & X & D & D & Load D \\
\hline L & H & H & X & X & Q & Hold Q \\
\hline L & H & L & L & X & Q plus 1 & Increment \\
\hline L & L & L & H & X & Q minus 1 & Decrement \\
\hline
\end{tabular}

Now using the operations table, we could start writing the equations for our counter. We will try to generate a general equation that can be used for any bit in the counter. If we take the nth bit, we have \(D_{n}\) as input and \(Q_{n}\) as output. There are four operations that can happen for any given bit: LOAD, HOLD, SET and count up or count down. We load the new value in the counter's register if SET is OFF \((/ S E T=H)\). So \(Q_{n}\) is replaced by new \(D_{n}\) value if \((/ S E T=H, L O A D=H)\), the expression that will allow loading the new value will be /SET*LOAD*/Dn. In order to be able to HOLD the \(Q_{n}\) value, we should have the following conditions: \(\left(S E T=L, L O A D=L, C_{I N}=L\right)\). So the expression for holding the old value is:
\[
/ \mathrm{SET}^{*} / \mathrm{LOAD}^{*} / \mathrm{C}_{\mathrm{IN}}{ }^{*} \mathrm{Q}_{\mathrm{n}}
\]

There are two more functions for the counter: count up and count down. These two functions have been calculated in Eq. 6.1. Using this equation and the calculation for the HOLD and LOAD cases, the final equation for the \(n\)th bit is calculated.
\[
\begin{aligned}
\mathrm{Q}_{\mathrm{n}} & =/ \mathrm{SET}^{*} \mathrm{LOAD}^{*} \mathrm{D}_{\mathrm{n}} \\
& +/ \mathrm{SET}^{*} / \mathrm{LOAD}^{*} / \mathrm{Q}_{\mathrm{n}} \\
& \text { :+: } / \mathrm{SET}^{*} / \mathrm{LOAD}^{*} \mathrm{C}_{\text {IN }} \mathrm{UP}^{*} \mathrm{QO}^{*} \mathrm{Q1}^{*} \ldots \mathrm{Q}_{\mathrm{n}}-1 \\
& +/ \mathrm{SET}^{*} / \mathrm{LOAD}^{*} \mathrm{CIN}^{*} / \mathrm{UP}^{*} / \mathrm{QO} 0^{*} / \mathrm{Q1} 1^{*} \ldots / \mathrm{Q}_{\mathrm{n}-1}
\end{aligned}
\]
\[
\text { Eq. } 5.2
\]

Using the above general equation, any large counter could be designed.



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\section*{Introduction}

PALASM2 software is a high-level language to describe implementation and simulation of logic designs. For every logic application a PAL device Design Specification (PDS) can be created using PALASM2 software syntax. This Pal device Design Specification consists of a set of functional equations and simulation commands. The functional equations describe how the logic is to be implemented on PAL device and the simulation commands describe how the logic should behave after implementation. The detail of the syntax of the language will be described in later sections.

The PAL device Design Specification is processed by the PALASM2 software compiler at the front end and an intermediate file is created. This intermediate file is then processed by various modules at the back end to accomplish various functions. At present MMI has developed an XPLOT generator which can generate the fuse patterns and the standard JEDEC file from PDS which can be downloaded to various programmers to program a PAL device.

Also available is a SIMULATOR package which will exercise each simulation command in the PDS against the functional description to check for the functional validity of the design. The output of the SIMULATOR is a set of vectors which can be physically exercised against the programmed part. (At date of publication the SIMULATOR is an ALPNA version, check with your local FAE for current availability.)


\section*{Key Features:}
-Assembles PAL device Design Specifications.
-Simulates and verifies the logic behavior.
-Generates PAL device fuse patterns in JEDEC format.
-Reports errors in syntax, assembly and simulation.
-New structured logic description syntax models more complex PAL devices and permits compaction of logic descriptions.
-String substitution allows concise mnemonic names for long frequently used logic expressions.
-Powerful functional simulator accurately models asynchronous and mixed PAL architectures.
-Structured high level language for describing test procedures, instead of long truth tables.

PALASM2 software supports PAL device assembly and simulation using these PAL devices:
20-pin Devices:


NOTE: PALASM2 software does NOT support 16A4 and 16X4 PAL devices.

\section*{Functional differences from PALASM1 software}

PALASM2 software is implemented quite differently than PALASM1 software. It is composed of several interacting programs coupled by disk files. The menu system (currently IBM-PC only) attempts to mask this somewhat, but floppy based files slow interaction. RAM or hard disks are prefered for production use. The principle benefit of the reorganization is the freedom from fixed limits within the design file.

As mentioned, in the feature section, the syntax of PALASM2 software is significantly different from PALASM1 sofstware. It allows description of asynchronous devices like the 20RA1 and devices of much higher complexity, like the MegaPAL devices. The syntax will be enhanced to include description capability for state machines and bus oriented logic elements.

The logic simulator is a true event driven simulator, modeling both synchronous and asynchronous events accurately. Cross-coupled logic functions, asynchronous set and reset terms, and tri-state devices are all simulated correctly. The user need not be initially concerned with predicting all device outputs each timing cycle the simulator may be operated as a logic analyzer, capturing and displaying output behavior. Once the design is understood, specific output values may be sampled selectively, instead of viewing each output cycle.

PALASM2 software also omits several features provided within PALASM1 software. They are fault coverage prediction for test vectors, documentation command, device signal/pinout display, support of security fuse and printing of logic equations for each product term in fuse plot. Some of these represent a change in philosophy, others will be provide in later versions of the program.

\section*{}

\footnotetext{

 . Ronubelinava ian bexim bras auonontoryas elebom plajensase 10 tafumia lenoitonul futuewot-

}

\section*{Structure of PAL Device Design Specifications mandmatsoci if molfoo3}

This section gives an overview of the PAL device Design Specification (PDS). It explains the three sections of the PDS with regard to the layout of each section, the information to be provided in each section, and what function it serves in the design process. The detailed syntax and contents of each section will be discussed in the succeeding sections. Examples will be used to illustrate correct syntax along with common misconceptions.


Xartive natiomotri siftor9 tonosewo



This section is used to record information about the customer necessary for documentation and future reference the type of PAL device used, the signal names given to each pin of the device, and some predefined states and strings to be used in the design. This section must come before all the other sections of the PDS. Any signal name that is going to be used in the equations has to be declared first in this section. There is a customer profile information section for documentation and future reference purposes.

Comments may be inserted freely, and begin with a semi-colon character-";". Any of the items described may be in lower or upper case all items are case-folded before processing. Line length maximum is 13 characters all beyond that are ignored. All control characters (including tabs) are treated as a single space. The maximum length of any legal statement or logic equation is 100 tokens (a token is either a pin name, a simulation command, a keyword or a logical operator).

The declaration section has two parts. They are:

-Customer Profile Information.
-Pin list information.

\section*{Example}
\begin{tabular}{|c|c|c|}
\hline & TITLE PATTERN & This is an example to illustrate the syntax ABC1234-MMI \\
\hline \multirow[t]{5}{*}{Customer Profile} & REVISION & 000-ABC1234 \\
\hline & AUTHOR & Imtiyaz Bengali \\
\hline & COMPANY & Monolithic Memories Inc. \\
\hline & DATE & Dec. 5, 1984 \\
\hline & CHIP & example-only 20RS10 \\
\hline \multicolumn{3}{|l|}{Pin} \\
\hline List & CLK ONE & TWO THREE SET RESET NC NC NC WRITE READ GND \\
\hline & /OE & OUT1 OUT2 NC NC NC /ACK /MMI NC NC MEMADR VCC \\
\hline
\end{tabular}

Customer Profile Information SYNTAX
\begin{tabular}{ll} 
keyword & : optional data \\
TITLE & <title of the design> \\
PATTERN & <pattern identification> \\
REVISION & <revision identification> \\
AUTHOR & <designer's name> \\
COMPANY & <company name> \\
DATE & <date of creation>
\end{tabular}

\section*{NOTE:}
-The keywords should appear in the format described in the table above one to a line. You may put optional data on the lines following the keywords it will be retained to annotate your fuseplot and simulation files. Warning messages will be generated if the keywords are omitted you may still generate fuseplot and simulation results.
-Each item can be any alphanumeric text including spaces, tabs and underscores. Only the first 2 characters are used additional characters present are ignored. Do not use any of these special characters:
\[
\left.!@ \# \$ \%^{\wedge} \&^{*}()-=+\{ \}\right]^{\prime \prime} ; ;^{\prime}<>?,
\]
(The software does not specifically check for usage of these characters within these lines.)

CHIP is the keyword which is neccessary to start the pin list information.

\section*{chip name}
<chip name> can be any alphanumeric word (except a reserved word or a PAL type) and is a required identifier. It should follow the same conventions for syntax as a pin name.

The <chip name> name has to be provided before the <PAL type> field is specified.

\section*{PAL type}
\(<\) PAL type \(>\) is the part number of any supported PAL device manufactured by MMI.
All PAL devices with different speed/power options are given the same generic name.
For example PAL16R8, PAL16R8A, PAL16R8A2, PAL16R8A4, and PAL16R8B all have the same generic name PAL16R8.

\section*{Pin list}
<pin list> is a list of signal names to be assigned to the pins of the device.
The length of signal names cannot exceed 14 characters. At least one of these characters must be a letter the remainder may be letters, numbers, or underscores.

For example: \(1,2,3, \ldots\) is an illegal pin list, but \(p 1, p 2, p 3, \ldots\) or \(1 p, 2 p, 3 p, \ldots\) are legal pin lists.
The signal can be specified as active-low or active-high. Active low signals are preceded by (/A is an active-low signal).
Signal names are separated by spaces or commas.
Special pins of the device (like the power and ground pins) are assigned special names. The power pin is assigned VCC and the ground pin is assigned GND. These names should come at the appropriate places in the pin list. For example in PAL20R pin number 2 is VCC and pin number 1 is GND. If any pin is not used, it must be specified as NC (noconnect).

Pins are listed in the order expected for DIP (dual inline package), reguardless of whether the user is planning to eventually program DIP, LCC or Chip Carrier devices. Any pin reording for other packages must be done by the programmer or other special fixture. The PAL64R3 device pinout is specified for 84 pin package.

Symbols not to be used in defining signal names in pin list:
ANY NON ALPHA NUMERIC CHARACTERS ! @ \#\$ \(\%^{\wedge} \&^{*}()-=+\{ \}[]^{\prime}:, ; \gg\) ?, ( \(/\) can be used for active low signals )
Only numbers, letters and the underscore character may be used to create a pin name.
Do not use reserved words or PAL device types as signal name.





\section*{Section 2: Functional Description}

\section*{Xamve noitumahl tall nit}

All the implementation details of an application are given in this part of the PDS using boolean equations. The information provided in this section is used to generate the locations of the fuses to be blown during programming of the part. Depending on the type of outputs, one can use a combinatorial equation identified by ' \(=\) or a registered equation identified by ' \(:=\) '. Also many outputs, such as the PAL20RA10, have special programmable functions associated with them functional equations can be used with these. The following lists different ways of specifying a function:

\section*{SYNTAX}

EQUATIONS ; keyword marking the begining of ; functional description.
<signal> \(\quad=\) Function (<signal>, <operator>)
<signal> \(\quad:=\) Function (<signal>, <operator>)
<signal>.<sfunc> \(=\) Function (<signal>,<operator>)
<signal> is the name of a pin from the pin list
<operator> \(\quad\), *, +, :+:
<sfunc> is a special function associated with the output signal.

Certain PAL devices such as the PAL20RA1 have programmable functions for registers the Clock function (CLKF), the Set function (SETF), the Reset function (RSTF) and the Tristate function (TRST). These functions are represented by special equations using the keyword of the special function to suffex the signal name, for example:
\[
\text { out.CLKF }=A * B
\]

This means that product term A B controls the Clock function of the output OUT.

\section*{Reserved Words}


Note: All PAL types are also reserved words.

\section*{Basic Operators}

The basic operators are defined to perform INVERT, AND, OR, and EXCLUSIVE-OR operations. These basic operators can be used to describe any logic function on the right side of the equation.
-INVERT operator
This operation is used whenever a signal has to be inverted. It preceeds the signal to be inverted.
For example: /A means "not a"
\(\quad\)\begin{tabular}{l}
-AND operator \\
This operation is used when ANDing two or more boolean variables. The operation of ANDing of all \\
the signals result in a product term. For example \(\mathrm{A} / \mathrm{B} \mathrm{C}\) means "A AND (NOT B) AND C"
\end{tabular}
\(+\quad\)-OR operator
This operator is used when ORing two or more product terms and/or signals. For example: A + /C
means "A OR (NOT C)"
\(:+: \quad\)-EXCLUSIVE-OR operator
This operator is used when EXCLUSIVE-ORing two or more product terms and/or signals. For
example: A :+: E means "A EXCLUSIVE-OR E"

With these basic logical operators, one can write logic equations for almost any application. The most useful form of the equations will be in the sum-of-products form it is the only currently supported form. True logic expansion and simplification will be supported in future versions of the PALASM software system. The following sections will illustrate the use of all these operators, except for the XOR. Operator precedence is in the order listed \(/,^{*},+,:+\)

\section*{String Substitution}

In many applications it is possible that a certain expression or part of it is repeated many times. To eliminate repetition of typing the same text again, one can declare that text with a shorter word using string substitution. Then instead of the full text one can use the word used to identify the text. String substitution is textual replacement and the compiler does not try to find any logical meaning to it. Hence the user should be very specific in what he wants to substitute.

STRING <string name> '<text to be substituted>
1entuabir <<
STRING is a keyword and every string substitution should start with the key word STRING.
<string name> is any user defined name of up to I alphanumeric characters. The name has to be unique. This means that the name should not be a reserved word, one of signal names defined in the pin list, or one of the string names used elsewhere.
<text to be substituted> is any legal expression and should be specified within single quotes. The length of the text to be substituted is not limited to one line it may be made up of several lines. There is no fixed length to any single string memory is allocated as necessary to store each. Each part of it must follow the syntax rules of the pin name identifiers and be delimited by blanks or tabs.

The compiler does one to one substitution of the string name with the text to be substituted. It does not try to find the meaning of an expression after substitution.

Currently a maximum of 2 unique strings may be used within any design file.
Ex. 1: STRING LOAD
```

LD */CIN

```
/LD * /SET * /SET * CUP ' STRING CARRY STRING INPUT

A1 + /A2 + A3'
One can also use previously defined string names in the string declaration. For example

\section*{STRING OUTPUT 'LOAD * CARRY'}

The user has to be very careful when using substitution for the final meaning. For example consider Ex I.
If in the equation section there is an occurrence of INPUT then an expression like /AI /A A will result after substitution and not /(AI \(/ A A 3)\) as the user most probably would expect. If the later meaning is what the user wants, the string definition should be:
(This logic expansion is currently not supported in PALASM2)

NOTE:
Once again I want to stress that the user has to be careful of the logical correctness of the final expression after substitution.

Each substitution string should be separated from other characters by at least one blank or tab wherever they are used. For example
\[
A 1:=L O A D * / A 3+A 1
\]


\[
\text { A1 :=LOAD* } \mid A 3+A 1
\]

All substitution strings must be declared after the pin list and before the functional description.
Comments are NOT allowed within the single quotes defining the string.

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<product term> ===>> <signal> *...

identifier \(===\gg\) declared pin name

The combinatorial equation is identified by the operator ' \(=\) '. The signal on the left side of the ' \(=\) sign is the output for which the equation is described. This output signal can be active-high (output) or active-low (/output).

For PAL devices with programmable polarity, the polarity fuse is blown or left intact according to the polarities given to the left side of the equation and those used in the pin list when they are the same, the fuse is blown when they differ the fuse is left intact. For example:

\section*{CHIP POLARITY-EXAMPLE PAL16P8 A B C D /E /F ne nc nc GND}

Y IZ W /V NC NC NC NC NC VCC

\[
\begin{aligned}
& \text { EQUATIONS } \\
& Y=A * B+/ C * D \\
& I Z=E * F+/ F * / E \\
& W=E \\
& V=/ f
\end{aligned}
\]

In this example, equations for outputs for \(Y\) and \(Z\) have the same polarity as they are described in the pin list. In programmable-polarity parts (PAL16P8), the polarity fuse is blown. If this is an active-low part (PAL16L8), then it is an error.

The outputs W and V have polarity reversed from that specified in the pin list. The polarity fuse is left intact.
The programmable-polarity feature allows the user to describe the function in either active-low or active-high state. The user does not have to transform the function using De Morgan's theorem.


This section will discuss the syntax of registered equations. These equations are described for outputs with a a register. For example: Each output of PAL16R8 is a registered output.
```

output := <product term> + <produc term> +
<product term> ===>> <signal> *.
<signal> * . <signal> ===>> /identifier identifier.

```

The registered equation is identified by the operator ' \(:=\) '.
The signal on the left side of the \(':=\) sign is the output for which the equation is described.
The clock to the register is the special clock pin depending on the PAL type, (example PAL16R has pin number as the clock pin), or the clock is generated by a special product term described in a CLKF functional equation on the 20RA10.

The transition at the output of the register takes place on the rising edge of the clock.
This output signal can be active-high (output) or active-low (/output).

\section*{Syntax PALASM2 Software}

For programmable polarity parts, the polarity fuse is blown or left intact according to the polarity given to the left side of the equation and that used in the pin list when they are the same, the fuse is blown, when they differ the fuse is left intact. For example:

CHIP POLARITY-EXAMPLE PAL16RP8
CLK A B C D /E /F nc nc GND
Y IZ W /V NC NC NC NC NC VCC

\section*{EQUATIONS}
\[
\begin{aligned}
Y & =A * B+/ C * D \\
Z & =E * F+/ F * / E \\
M & =E \\
V & =/ f
\end{aligned}
\]

In this example, equations for outputs for \(Y\) and \(Z\) have the same polarity as they are specified in the pin list. In programmable polarity parts (like PAL16RP8), the polarity fuse is blown. If this is an active low part (PAL16R8), then this is an error.

The outputs W and V have polarity reversed from that specified in the pin list. The polarity fuse is left intact.
The programmable polarity feature allows the user to describe the function in either active-low or active-high state. The user does not have to transform the function using De Morgan's theorem.

\section*{Functional Equations}

In some PAL devices, the outputs have special functions which are controlled by a programmable product term. For example in PAL16L8, the tri-state function is controlled by a product term.

In the PAL20RA1 device, every registered output has four programmable functions, which are:
1) programmable clock function
2) programmable set function
3) programmable reset
4) programmable tri-state

In order to describe the functions to be implemented in the PAL device, functional equations are used. Order of appearance in a PAL device design specification is not significant for functional equations. These functional equations have the following syntax.

\section*{output.sfunc \(=<\) product term \(>\)}

The left side of the equation identifies the function for the output defined by the right side of the equation. The following keywords are to be used to identify the functions:
\begin{tabular}{ll} 
CLKF & for programmable clock function. \\
SETF & for programmable set function. \\
RSTF & for programmable reset function. \\
TRST & for programmable tri-state function.
\end{tabular}

The following default conditions apply:
CLKF -the default condition is that all the fuses are left intact i.e. it is connected to GND.
SETF - If the output is defined as combinatorial, default value is VCC.
If the output is defined as registered, default value is GND.
RSTF -If the output is defined as combinatorial, the default value is VCC.
If the output is defined as registered, the default value is GND.
TRST -The default value is VCC.

Here are some details of these functions and their default conditions.

\section*{Default for SETF and RSTF}

In PAL20RA10, it is always possible to bypass the register by having the SET and RESET product terms high. There are two ways of doing this. One way is to be explicit as follows:

OUT \(:=A+/ B+D * E ;\) Output defined as registered OUT.SETF \(=\) VCC OUT.RSTF \(=\) VCC OUT.CLKF \(=\) GND The other way is to be implicit as follows:
\[
\text { OUT }=A+/ B+D^{*} E \quad \text {; Output defined as combinatorial }
\]

In the implicit case, the program XPLOT will take care of the default conditions for SETF, RSTF and CLKF

\section*{Default for registered output}

In some cases, the user might not want to use the SET and RESET functions. Again, he can be explicit as follows:
\[
\text { OUT }:=A+/ B
\]
OUT.SETF = GND
OUT.RSTF = GND
or he can be implicit as follows:
OUT := A + /B
OUT.CLKF \(=\) CLK
The program XPLOT will take care of the default conditions and program the appropriate fuses.

\section*{Default for TRST}

The default for the tri-state function is VCC. This can be specified explicitly as follows:
```

OUT := A + B
OUT.CLKF = CLK
OUT.TRST = VCC

```
or implicity by not specifying the tri-state function, the XPLOT program will blow all the fuses.

\section*{Default for CLKF}

If the clock function is not defined, all the fuses are left intact.
If the output is defined as a registered output, the CLKF MUST BE DEFINED. Otherwise, XPLOT will give an error. You can define it as GND if you do not want to use it but it must be defined.

If the output is defined as combinatorial, then it is redundant to define the CLKF. XPLOT will give an error if it is defined.

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The user must remember that the polarity fuse is located in front of the register and hence effects the inversion of the data path. The data path is the output of the OR gate through polarity fuse and into the register. It does not effect the set or reset function of the output.

If no output equation is defined, the polarity fuse is left intact.
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\section*{Section 3: Simulation}

Simulation is a very important part of any design cycle. After the user has defined the logic in terms of equations, it is neccessary to be able to verify that the equations do implement the required function. The basic feature of any simulation is the ability to give a set of inputs to the design and be able to check the outputs for correctness. This ability to give values to inputs and observe the outputs is crucial to any simulation language.

Logic Simulation can be described using
-SETF, CLOCKF, TRACE-ON, TRACE-OFF, and CHECK commands. ana and and and and
-FOR loop to iterate a set of commands a fixed number of times.
-WHILE <condition> DO loop also to iterate a set of commands till the condition is false.
-IF <condition> THEN ELSE for conditional branching.
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PALASM2 software has an 'Event Driven Simulator supporting all the different PAL device architectures, both asynchronous and synchronous. The program is so designed that internal events generated by asynchronous/synchronous feedbacks and external events generated by the user are simulated in a very realistic way. Oscillatory conditions are also detected and reported to the user. Conflict in the expected and the actual value of any signal is an error which is detected by the simulator and reported to the user. The simulation continues from that point using the actual value of the signal.

The PALASM2 software language has simulation commands which are 'English like words thereby making the simulation specification very natural to read and understand. There are facilities for iterative looping, conditional branching, setting of signals, checking of signal values, and selective observation of signals. All these commands will be explained in the following paragraphs.

All the simulation results are stored in two files, a history file (<filename>.HST) and a trace file (<filename>.TRF). The history file has the values of all the signals from the start of simulation to the end. The trace file has the values of the signals mentioned in the TRACE-ON statement and only up to the next TRACE-OFF statement.

The simulation results are organized in a horizontal format resembling a timing diagram. Each page contains 4 vectors. a maximum of 51 vectors are allowed with this release of the simulator. Corresponding to each SETF and CLOCKF statement in the simulation a 'g or 'c appears on the horizontal axis in the result files. A CLOCKF statement causes the clock to go \(L\) to \(H\) to \(L\). The 'c appears over the final \(L\). This helps the user to identify the vector corresponding to SETF or CLOCKF statement.

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The basic philosophy of the simulaton tanguage is to makent easy tor the aesigner to aescrive the funcuun in a natural way so that it is easy to comprehend the behavior of the design from the simulation specification. PALASM simulation language is divided into two sections Directives and Structured Control. The simulation directives provide commands to establish circuit inputs, clock waveforms, check for circuit outputs and capture time response waveforms as desired by the user.

The simulation section is introduced by the keyword SIMULATION.

\begin{tabular}{ll} 
SETF & <signal list> \\
CLOCKF & <clock signals> \\
CHECK & <signal list> \\
TRACE-ON & <signal list> \\
TRACE-OFF &
\end{tabular}

Structured Control constructs-Syntax:


The structured control constructs are used to build up sequences of operations that repeat or are modified as a result of particular logic values or conditions. They provide the basic looping and decision branching of structured high-level programming languages. <condition> is a boolean expression or a mathematical equality. The condition is true if the boolean expression is asserted or the mathematical equality is satisfied.

\section*{Details of the Simulation Syntax: \(\quad\) 保}

Each of the individual statements will be described, along with some related items necessary for their proper usage.

\section*{SETF statement}
```

SETF <signal list>
Ex. SETF A /OE B /RESET /D0 D1 D2

```

The signal is set high \((\mathrm{H})\) if it is not preceded by otherwise it is set low \((\mathrm{L})\). In the above example A B D and D are all set to \(H\) and OE, RESET, and \(D\) are all set to \(L\).

The signal should only be set if a change is wanted from the previous value. The simulator always remembers the last value of all the signals. At the start of simulation all signals are assumed to have don't care value (X).

Every time a SETF statement is executed, a vector is generated and all the equations that are effected are evaluated. Any internally generated events are also detected and evaluated. Depending upon the activity, many more vectors can be generated by a single SETF statement because of feedbacks and asynchronous events. The simulator continues this till the system stabilizes, that is, until there are no more changes in the output signals or no events are generated. If the system fails to stabilise after 1 iterations, then an oscillatory condition is detected and the simulation halts.

\section*{CLOCKF statement}

\section*{gnol \(80^{7}\)}

Ex. CLOCKF CLK1 CLK2
velas
The CLOCKF statement has the list of clock signals (dedicated clock pins) to which a clock pulse is to be applied. Only the clock pins of the device can be used in the CLOCKF statement, any other pin is an illegal signal for CLOCKF statement.

Each CLOCKF statement corresponds to a pulse going from low to high to low. Thus two vectors are generated in the proccess and during the positive edge transition, the new value of the registers which are clocked is transfered to the output. No action takes place for the registers that are not clocked.

At every CLOCKF statement, internally generated events and asynchronous events are detected and if present, more vectors are generated. The operation of CLOCKF is similair to that of SETF statement except that it goes through a pulse rather than a level.

CHECK < signal list>
EX. CHECK Q /Q /Q
This is a facility provided to the user to keep track of the simulation results. The signals in the check statement are the output signals which the user wants to check. In the above example, the user wants to check if \(Q\) is high and \(Q\) and \(Q\) are low. Again a signal without is to be checked high and the signal with is to be checked for low.

Whenever a CHECK statement is executed, the simulator compares the actual value and the expected value of a particular signal. If they are equal then no action is taken. Otherwise, an error is reported and the simulator continues assuming the actual value. The error is reported by . in the vector at the place of the error and also the vector number. The history and trace files will contain the . at the particular location.

This is a powerful statement that should be used at important points in your simulation for debugging your design.

TRACE-ON <signal list>
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Ex. TRACE-ON /OE SET RESET D0 D1 D2 D3 /Q0 /Q1 /Q2
This statement contains the list of signals which have to be listed in the trace file. The signals will be listed in the same order and with the same polarity as present in the TRACE-ON statement. This list of signals will be active until the next TRACE-OFF statement or untill the end of the simulation specification. New signals can be traced on after the TRACE-OFF statement.

This statement helps the user to group the signals more naturally for debugging purposes. For example, all control signals can be grouped together, then all the data signals can be grouped together, and then all the output signals can be grouped together. This makes the observation of the results in the trace file very easy.

\section*{TRACE-OFF statement}

TRACE-OFF

This statement traces off all the signals mentioned in the latest TRACE-ON statement. After this statement, no more results are added to the trace file until the next TRACE-ON statement is executed. Thus all the results between the current TRACE-OFF statement and the next TRACE-ON statement are not displayed in the trace file.

This feature helps to break up the results in different time frames which are critical for debugging purposes, rather than having unwanted results. It should be remembered that the history file contains all the information from the start of the simulation to the end of simulation. The signals are in the same order and of the same polarity as mentioned in the pin list of the CHIP statement.

\section*{FOR loop}
FOR <index var> := <lower limit> TO <upper limit> DO
BEGIN
<statements>
END
Ex. FOR J: = 3 to 8 DO BEGIN
SETF A /B CLOCKF cIk
IF J=5 THEN BEGIN CHECK QO END
ELSE BEGIN CHECK /QO END

The FOR loop provides a repetitive execution of statements which is very powerful. Many statements can be embedded in a FOR loop even another FOR statement with a different indexing variable. Using this statement one can generate many vectors by just increasing the limits of the for loop.

The <lower limit> should be less than or equal to the upper limit. All the limit values should be greater than or equal to zero. You can not use negative values for the limits. The loop is not executed if the conditions expressed in the limits are equal.
ail lengiss >03+10
IF THEN ELSE
IF <Cond> THEN or
BEGIN
\(<\) Statements>
END

There are two variations of this statement. In the first usage, there is an ELSE clause and in the second usage there is no ELSE clause. If the <condition> is true the THEN clause is exectuted otherwise the ELSE clause is executed. If there is no ELSE clause, then the simulation executes the next statement after the IF statement. Condition expressions can not contain nested parenthesis.

The <condition> can be any mathematical equality;
( \(=,>,<,>=,<=,<>\) ), for example:
 CAF \((\mathrm{I}<2)\) THEN

The <condition> also be any boolean expression, for example:

In the first example the condition of I less than is checked and in the second example the expression (DRDY /CLR) is evaluated and if it is true then the condition is true.
mamolsia 7.

\section*{WHILE loop:}

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WHILE <condition> DO


The WHILE loop provides a repetetive execution of statements which may be controled by evaluation of logic conditions present within the PAL device. Many statements can be embedded in a WHILE loop including even other looping constructs. The WHILE loop is used to itterate a set of commands until the condition is false.

The <condition> can be any boolean expression of logic signals.
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\section*{Contents Section 6}

An Introduction to Programmable Logic Elements .................................... 6-3


\title{
An Introduction to Programmable Logic Elements
}

A logic function, whether combinatorial or sequential, may be represented in Sum of Product (SOP) form by using De Morgan's law and Boolean Algebra. Any complex multi-level logic function can easily be reduced to a two-level AND-OR configuration. This property of logic functions lends a very regular character, making it possible to implement them in a structured methodical
way. The uniform AND-OR array-like architecture of Programmable Logic Devices was conceived for a clean and efficient implementation of these functions, as shown in Figure 1.

Either or both of the arrays can be programmable, constituting three distinct families of devices as shown in Figure 2.


Figure 1. Structure of Programmable Logic Devices



Figure 2. Structural Differences Between PLE, PAL and PLA Devices

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\section*{PLE Device Architecture}

The array like structure of a PROM lends itself naturally to being viewed as a two-level AND-OR logic circuit. The inputs to the PROM are fully decoded into all possible combinations in the fixed AND plane. Each combination (product term) is fuse connected to each output in the programmable OR plane.

For a PLE device, a product term is equivalent to an AND gate equal in size to the number of inputs. Each output is equivalent to an OR gate connected to all the AND gates. Programming a fuse

then implies breaking a connection between an AND gate and OR gate.
Thus a PROM has a convenient structure for implementing combinatorial logic when a large number of input combinations are required, or a large number of product terms per output is desired. Registered PROMs are ideally suited for implementing complex sequential machines which contain a large number of variables in the state equations.
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Figure 3. General Block Diagram of a \(\mathbf{2 K x 8} \mathbf{P R O M}\)


Figure 4. Block Diagram of a PROM Viewed as a PLE Device

In terms of a Karnaugh map, each minterm in the map corresponds to one product term in the PLE array. Two or more adjacent minterms cannot be be combined to generate a prime implicant, or eliminate a logic hazard. For example, the following Karnaugh map will generate the function \(f=a b+a b\). The minimized function \(f=a\) as indicated by the dotted prime implicant can not be implemented. The PLE device does not contain a product term with fewer than all its inputs present.
The absence of prime implicants in a PLE array may cause logic
hazards which may be unavoidable in asynchronous control systems. However these hazards are masked out in sychronous control systems by the registers, and are largely irrelevant in data path applications where only the final steady state results are looked at. Indeed, most applications of PLE devices are in synchronous control systems to replace random logic. In the data paths, they are used to generate complex functions like ALU operations, high-speed multiplication, Pseudo Random Number sequences, Error Detection codes, etc.


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Figure 6. An Arbitrary Two-Variable Karnaugh Map for a PLE Device
A.

PLAs have the most general architecture with both arrays programmable. For N inputs, M outputs, and P product terms in a PLA, the AND array contains \(2 \times N \times P\) programmable crosspoint connections. All possible combinations of the inputs, taken together, or in groups, or even a single input, can have a product term in the AND array. The inputs not desired in a product term are disconnected, by removing the corresponding crosspoint connection. In field programmable PLAs, this corresponds to electrically blowing a fusible link connection. These PLAs also usually contain less product terms than the maximum possible \(2^{\text {n }}\), to conserve chip area.
outputs, but may be disconnected by blowing that fuse connection. This architecture is used for implementing logic functions with a large number of product terms of varying sizes, or a large number of product terms per output.
Field-programmable PLAs are generally not very-high performance. They are slower in speed compared to PAL and PLE devices. A given signal must pass through two large programmable arrays, which increases the capacitance on the signal, and increases the delay. For most applications, a large number of crosspoints in one or another array are usually left intact, making the architectural flexibility redundant.

X = FUSIBLE
CROSSPOINT CONNECTION


Figure 7. Structure of FPLA

\section*{PAL® Architecture}

PAL devices are the most useful and efficient of the fuse programmable logic family. First developed and patented by Monolithic Memories in 1976, the PAL devices have become well known for their friendliness in system configurations. The programmable AND array and fixed OR array eliminate most of the redundancies associated with PLAs. The PAL AND array is logically identical to a PLA AND array, with the only difference that PAL devices have fewer product terms. In the fixed OR array, each product term is connected to only one output or OR
gate, which eliminates product term sharing of PLAs. The PAL device configuration has permitted several architectural innovations, making the PAL circuit family of devices extremely useful for implementing all kinds of logic functions. PAL device features include outputs with/without registers that are internally fed back to the AND array, special XOR gates in the OR array, arithmetic carry generate gates in the feedback path in the AND array, programmable I/O pins, and programmable output polarity. New generation PAL devices also have the feature of product term sharing where a product term can be attached to one of two adjacent sum terms.

PAL
4 IN-4 OUT-16 PRODUCTS


\footnotetext{
\(\mathrm{X}=\) Fusible crosspoint connection.
- = Fixed connection.
}

Figure 8. Structure of PAL Device

As the PAL AND array is programmable, logic functions can be minimized and logic hazards removed, by combining adjacent minterms in a Karnaugh map. This group of minterms or implicants is implemented as a product term. Thus PAL device outputs can be designed to be glitch-free, and ideal for implementing control logic. Figure 10 illustrates the absence of hazards and race conditions in a PAL device.

The limitation of PAL device is that they have a restricted number of product terms per output, and fewer product terms in general. Certain logic functions containing a large number of product terms would require a large number of PAL devices to implement them, which increases the propagation delay and the chip count. For these applications, PLE devices are ideal.


Figure 10. An Arbitrary Two-Variable Karnaugh Map for a PAL Device
\(\qquad\)

\section*{PLE and PAL Devices}

PLE devices bridge the gap between the flexibility of PLAs, and the product term restrictions in PAL devices. Those applications for which PAL devices are not suitable, PLE devices take over. Where a PAL device typically has a large number of inputs, and a small number of product terms, the PLE devices have a restricted number of inputs and a large number of product terms. Also, it has a large number of product terms per output with full product term sharing, whereas PAL devices have a restricted number of product terms per output with no product term sharing. Thus PAL and PLE devices complement each other both structurally and functionally.

\section*{PLE Device Features}
- \(2^{n}\) product terms per output are available with \(n\) inputs each.
- Programmable output polarity.
- Programmable initialization in registered PLE devices.
- High-level functional specification of PLE systems in terms of logic equations.
- Input-to-output delays comparable to discrete logic gates (typically less than 15 ns ).
- PNP inputs provide high impedance.
- Monolithic Memories' TiW fusible-link technology and advanced self-aligned washed-emitter bipolar process guarantees a programming yield greater than \(98 \%\).

\section*{PLE Circuit Family}

The PLE circuit family of devices is an extension of Monolithic Memories' TiW PROM family. The entire line of TiW PROMs including the Registered parts are available in PLE circuit configurations. High speed and diagnostic versions in military and commercial temperature ranges are available.

\section*{CAD Tool for PLE Designs}

PLEASM software is a PLE Assembler written in FORTRAN 77 and available on most mini- and microcomputer systems. It enables specifying PLE Circuit data in terms of logic equations (like those in Figure 14), which are assembled into a fuse-pattern format compatible with commercially available PROM programmers. PLEASM software also generates a truth table from the logic equations which is later used as test vectors for logic simulation and verification. PLEASM allows complete design customization and documentation of PLE systems in a simple high-level functional language.


\section*{Control Path Example}

A common application of PLE devices in the control path of a synchronous system, is to replace random logic, or customize logic functions. An n-input exclusive OR function is quite
commonly required in comparator and adder circuits. It contains \(2^{n-1}\) product terms, which increases exponentially with \(n\). Therefore, it is very efficient to implement large XOR functions in PLE devices. Figure 11 shows the implementation of a 4-input XOR in a PLE circuit.


Figure 11. Four-Input XOR Function Implemented in a PLE Device. Maximum Delay is 15 nsec


\section*{An Introduction to Programmable Logic Elements}

\section*{Data Path Example}

In the data path, a registered PLE device can be used to implement complex functions, like a Pseudo Random Number (PRN) Generator. RPN sequences are useful in encoding and decoding of information in signal processing and communication systems. They are used for data encryption in secure communication links, and error detection and correction codes in data communication systems. PRN sequences are also utilized as test vectors for circuit simulation, as signal modulators in radar range-finding systems, and as reference white noise in many
signal processing applications. Figure 12 illustrates a typical mechanism for generating PRN sequences.

The advantage of using PLE devices for implementing PRN sequences is that any polynomial can be quickly customized in it. In data encryption systems where the code is frequently changed for protection from unauthorized access, PLE devices can be used to generate a new code each time, or several codes can be implemented in the same device. An example of a PRN generator implemented in a Registered PLE device is shown in Figure 13.



\section*{Parallel CRC in Registered PLE Devices}

Implementing a high－speed M－bit Parallel Cyclic Redundancy Check（CRC）code in a registered PLE circuit is almost trivial． Once the \(M\)－bit carry look－ahead equations are determined， PLEASM software is used to assemble these equations into a fuse pattern for the Registered PLE device．
The speed of operation of parallel CRC implemented in regis－ tered PLE devices will remain the same for any generator poly－ nomial and M．Increasing complexity of the carry look－ahead equations only increases the number of devices required to implement them．It does not decrease the speed of operation．

To illustrate with a practical example，Figure 14 shows the 8 －bit carry look－ahead equations for an 8－bit Parallel implementation of the following generator polynomial：
\[
G(X)=x^{16}+x^{12}+x^{5}+1
\]
also called the CRC－CCITT standard．These equations are derived in Application Note AN－125，where an implementation in four PAL devices is also shown with a maximum delay of 90 nsec ． Figure 16 shows an implementation in three 24－pin registered PLE devices and one SSI part．The maximum delay is 50 nsec ．

where Xi \((n+1)\) is the next state value of the corresponding
register \(i, \quad i=0, \ldots, 15\)
8A牛洔过
Xi \((\mathrm{n})\) is the present value of the corresponding
register \(\mathrm{i}, \quad \mathrm{i}=0, \ldots, 15\)
\(D(n)\) is the parallel input data bits，where \(n=0, \ldots, 7\)

Figure 14．Carry Look－Ahead Equations for 8－Bit Parallel CRC with \(\mathbf{G}(\mathbf{X})\) ．The Equations
are Paritioned into Three Parts for Efficient Implementation in Three Chips．



Figure 15．Block Diagram of 8 －bit Parallel CRC


Figure 16. Diagram Showing How to Connect Three Registered PLE Devices to Implement 8-Bit Parallel CRC. The Error Flag is Valid on the Next Clock Pulse After All the Data Has Been Clocked In.
Error Flag \(=X_{0}+X_{1}+X_{2}+x_{3}+x_{4}+x_{5}+X_{6}+x_{7}+x_{8}+x_{9}+X_{10}+x_{11}+x_{12}+x_{13}+x_{14}+x_{15}\)



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PLE Device Family

PLE Device to PROM Cross Reference
\begin{tabular}{|c|c|c|c|c|c|c|}
\hline TEMPERATURE RANGE & \begin{tabular}{l}
PLE \\
NUMBER
\end{tabular} & INPUTS & OUTPUTS & \begin{tabular}{l}
OUTPUT \\
TYPE
\end{tabular} & \[
\begin{aligned}
& \text { ARRAY } \\
& \text { SIZE }
\end{aligned}
\] & PROM NUMBER \\
\hline & PLE5P8C & 5 & 8 & Three-State & \(32 \times 8\) & 635081 \\
\hline & PLE5P8AC & 5 & 8 & Three-State & \(32 \times 8\) & 63S081A \\
\hline & PLE8P4C & 11-80939 & 4 & Three-State & \(256 \times 4\) & 63S141A \({ }^{\text {a }}\) \\
\hline & PLE8P8C & 8 & 8 digol & Three-State & 1 \(256 \times 8\) & 635281 A \\
\hline & PLE9P4C & 9 & 4 lot & Three-State & 212x4 & 635241 A \\
\hline \[
\begin{aligned}
& \text { axdopg iunoms } \\
& \text { kilithilhe }=99 k
\end{aligned}
\] & PLE9P8C & 9 & 8 & Three-State & \(512 \times 8\) & 635481 A \\
\hline tab-bie-list = aceaz & PLE10P4C & -10 & 4 & Three-State & \(1024 \times 4\) & 63S441A \\
\hline Commercial & PLE10P8C & 10 & 8 & Three-State & \(1024 \times 8\) & 63S881A \\
\hline & PLE11P4C & 11 & 4 & Three-State & \(2048 \times 4\) & 635841A \\
\hline  & PLE11P8C & -11 & 8 & Three-State & 2048x8 & 63S1681A \\
\hline \[
\begin{aligned}
& \text { intinged }=6 \\
& \text { cian }
\end{aligned}
\] & PLE12P4C & -12 & 4 & Three-State & \(4096 \times 4\) & 63S1641A \\
\hline ifo patalasa: & PLE12P8C & 12 & 8 & Three-State & 4096x8 & 63S3281A \\
\hline  & PLE9R8C & 9 & 8 & Register & \(512 \times 8\) & 63RA481A \\
\hline & PLE10R8C & ¢ 10 & 8 & Register & \(1024 \times 8\) & 63RS881A \\
\hline \begin{tabular}{l}
\(3 \mathrm{ct}-\mathrm{dara}=3\) \\

\end{tabular} & PLE11RA8C & 11 & 8 & Register & 2048×8 & 63RA1681A \\
\hline & PLE11RS8C & 11 & 8 & Register & \(2048 \times 8\) & 63RS1681A \\
\hline & PLE5P8M & 5 & 8 & Three-State & \(32 \times 8\) & 535081 \\
\hline & PLE8P4M & 8 & 4 & Three-State & \(256 \times 4\) & 53S141A \\
\hline \[
\begin{aligned}
& \text { (en) get } \\
& x \text { kision }
\end{aligned}
\] & PLE8P8M & 8 & 8 \% & Three-State & 256x8 & 53S281A \\
\hline & PLE9P4M & 9 & 4 & Three-State & \(512 \times 4\) & 53S241A \\
\hline & PLE9P8M & 9 & 8 & Three-State & \(512 \times 8\) & 53S481A \\
\hline & PLE10P4M & 10 & 4 & Three-State & \(1024 \times 4\) & 53S441A \\
\hline Military & PLE10P8M & 10 & 8 & Three-State & 1024×8 & 53S881A \\
\hline & PLE11P4M & 11 & 4 & Three-State & \(2048 \times 4\) & 53S841A \\
\hline 04 & PLE11P8M & 11 & 8 & Three-State & 2048x8 & 53S1681A \\
\hline an & PLE12P4M & 12 & 4 & Three-State & \(4096 \times 4\) & 53S1641A \\
\hline ¢ & PLE12P8M & 12 & 8 & Three-State & \(4096 \times 4\) & 53S3281A \\
\hline वह-1 & PLE9R8M & 9 & 8 & Register & \(512 \times 8\) & 53RA481A \\
\hline & PLE10R8M & 10 & 8 & Register & 1024×8 & 53RS881A \\
\hline as & PLE11RA8M & 11 & 8 & Register & 2048×8 & 53RA1681A \\
\hline 0 & PLE11RS8M & 11 & 8 & Register & 2048×8 & 53RS1681A \\
\hline
\end{tabular}

\section*{Features/Benefits}
- Programmable replacement for conventional TTL logic
- Reduces IC inventories and simplifies their control
- Expedites and simplifies prototyping and board layout
- Saves space with 0.3 inch SKINNYDIP® packages
- Programmed on standard PROM programmers
- Test and simulation made simple with PLEASM software
- Low-current PNP inputs
- Three-state outputs
- Reliable TiW fuses guarantee \(>98 \%\) programming yield

\section*{Ordering Information}


\section*{PLE Device Selection Guide}
\begin{tabular}{|c|c|c|c|c|c|}
\hline PART NUMBER & 8RETS & OUTPUTS & PRODUCT TERMS & OUTPUT REGISTERS & \[
t_{P D}(\mathrm{~ns})
\]
MAX* \\
\hline PLE5P8 & 5 & 8 & 32 & & 25 \\
\hline PLE5P8A & 5 & 8 & 32 & & 15 \\
\hline PLE8P4 & 8 & 4 & 256 & & 30 \\
\hline PLE8P8 & 8 & 8 & 256 & & 28 \\
\hline PLE9P4 & 9 & 4 & 512 & & 35 \\
\hline PLE9P8 & 8 & 8 & 512 & 10.80 & 30 \\
\hline PLE10P4 & 10 & 4 & 1024 & Mimsisum & 35 \\
\hline PLE10P8 & 10 & 8 & 1024 & M6-3tim & 35 \\
\hline PLE11P4 & - 11 & 4 & 2048 &  & 35 \\
\hline PLE11P8 & Bxasor 11 & 8 & 2048 & 4 & 35 \\
\hline PLE12P4 & -x8mor 12 & 4 & 4096 & MSATM31 & 35 \\
\hline PLE12P8 & - 12 & 8 & 4096 & M683:19319 & 40 \\
\hline PLE9R8 & 9 & 8 & 512 & 8 & 15 \\
\hline PLE10R8 & 10 & 8 & 1024 & 8 & 15 \\
\hline PLE11RA8 & 11 & 8 & 2048 & 8 & 15 \\
\hline PLE11RS8 & 11 & 8 & 2048 & 8 & 15 \\
\hline
\end{tabular}
* Clock to output time for registered outputs.

Note: Commercial limits specified.

\section*{PLE Device Means Programmable Logic Element}

Joining the world of IdeaLogic \({ }^{\text {Tw }}\) is a new generation of highspeed PROMs which the designer can use as logic elements. The combination of PLE devices with PAL devices can greatly enhance system speed while providing almost unlimited design freedom.
Basically, a PLE circuit is ideal when a large number of product terms is required; on the other hand, a PAL circuit is best suited for situations when many inputs are needed.
The PLE circuit transfer function is the familiar OR of products. Like PAL circuits, a PLE circuit has a single array of fusible links. Unlike PAL circuits, PLE circuits have a programmable OR array driven by a fixed AND array (a PAL device is a programmed AND array driving a fixed OR array).


The PLE device family features common electrical parameters and programming algorithms, low-current PNP inputs, full Schottky clamping and three-state outputs.
The entire PLE device family is programmed on conventional PROM programmers with the appropriate personality cards and socket adapters.

\section*{Registered PLE Devices}

The registered PLE devices have on-chip "D" type registers, versatile output enable control through synchronous and asynchronous enable inputs and flexible start-up sequencing through programmable initialization.
Data is transferred into the output registers on the rising edge of the clock. Provided that the asynchronous ( \(\bar{E}\) ) and synchronous (ES) enables are Low, the data will appear at the outputs. Prior to the positive clock edge, register data are not affected by changes in addressing or synchronous enable inputs.
Data control is made flexible with synchronous and asynchronous enable inputs. Outputs may be set to the high-impedance state at any time by setting \(\bar{E}\) to a High or if \(\overline{\mathrm{ES}}\) is High when the rising clock edge occurs. When \(V_{C C}\) power is first applied the synchronous enable flip-flop will be in the set condition causing the outputs to be in the high-impedance state.
A flexible initialization feature allows start-up and time-out sequencing with 1:16 programmable words to be loaded into the output registers. With the synchronous INITALIZE (IS) pin Low, one of the 16 initialize words, addressed through pins 5, 6, 7 and 8 will be set in the output registers independent of all other input pins. The unprogrammed state of \(\overline{\mathrm{IS}}\) words are Low, presenting a CLEAR with \(\overline{\mathrm{S}}\) pin Low. With all \(\overline{\mathrm{I}}\) column words (A3-A0) programmed to the same pattern, the \(\overline{\mathrm{S}}\) function will be independent of both row and column addressing and may be used as a single pin control. With all \(\overline{\bar{s}}\) words programmed High a PRESET function is performed.

PLE9R8 has asynchronous PRESET and CLEAR functions. With the chip enabled, a Low on the \(\overline{P R}\) input will cause all outputs to be set to the High state. When the \(\overline{C L R}\) input is set Low the output registers are reset and all outputs will be set to the Low state. The \(\overline{\mathrm{PR}}\) and \(\overline{\mathrm{CLR}}\) functions are common to all output registers and independent of all other data input states.

\section*{PLEASM Software}

\section*{Software that makes programmable logic easy.}

Monolithic Memories has developed a software tool to assist in designing and programming PROMs as PLE devices. This package called "PLEASM" software (PLEAssembler) is available for several computers including the VAX/VMS and IBM PC/DOS. PLEASM software converts design equations (Boolean and


\section*{Logic Symbols}


7

\section*{Logic Symbols}

\begin{tabular}{|c|c|c|}
\hline Absolute Maximum Ratings & & \\
\hline Supply voltage \(\mathrm{V}_{\mathrm{CC}}\) & -0.5 V to 7 & ..... 12 V \\
\hline Input voltage & -1.5 V to 7 V & \\
\hline Off-state output voltage & -0.5 V to 5.5 V & \\
\hline Storage temperature & \(-65^{\circ}\) to \(+150^{\circ} \mathrm{C}\) & \\
\hline
\end{tabular}

Operating Conditions
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|}
\hline \multirow[b]{2}{*}{SYMBOL} & \multirow[b]{2}{*}{PARAMETER} & & \multicolumn{3}{|l|}{COMMERCIAL} & \multicolumn{3}{|c|}{MILITARY} & \multirow[b]{2}{*}{UNIT} \\
\hline & & OK & MIN & TYP* & MAX & MIN & TYP* & MAX & \\
\hline \(\mathrm{V}_{\mathrm{CC}}\) & Supply voltage & & 4.75 & 5 & 5.25 & 4.5 & 5 & 5.5 & V \\
\hline \(\mathrm{T}_{\mathrm{A}}\) & Operating free-air temperature & & 0 & 25 & 75 & -55 & 25 & 125 & \({ }^{\circ} \mathrm{C}\) \\
\hline
\end{tabular}

\section*{Electrical Characteristics Over Operating Conditions}

\(\dagger\) Vertical at \(5.0 \mathrm{~V} \mathrm{~V}_{\mathrm{CC}}\) and \(25^{\circ} \mathrm{C} \mathrm{T}_{\mathrm{A}}\)
* Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.
** VIL and VIM limits are absolute with respect to the device ground pin(s) and include all overshoots due to test equipment noise.

PLE Device Family

Switching Characteristics Over Military Operating Conditions
agnilan mutnimsill obluloadA
\begin{tabular}{|c|c|c|c|c|c|}
\hline St & \multicolumn{2}{|l|}{DEVICE TYPE} & \[
\begin{aligned}
& \text { tpD }_{\text {PR }}(\mathrm{ns}) \\
& \text { PROPAGATION DELAY } \\
& \text { MAX }
\end{aligned}
\] & \({ }^{\text {t }}\) PZX AND tpXZ INPUT TO OUTPU ENABLE/DISABLE MAX &  \\
\hline & \multicolumn{2}{|l|}{5P8M} & 35 & amolati 305 & 0 \\
\hline & \multicolumn{2}{|l|}{8P4M} & 40 & 30 & \\
\hline TII & - 8P8M & xatas ray & 408 40 & [4 30 & गणषातार \\
\hline & 2ᄅ 9P4M & ¢ & 45 & sostlo 30 -que & \(2{ }^{\text {V }}\) \\
\hline & ast 9P8M & 5 & \(0 \square 40\) & Crastimeat 30 & \\
\hline \multicolumn{3}{|c|}{10P4M} & 50 & 30 & \\
\hline \multicolumn{3}{|c|}{10P8M} & an 45 as matana 20 & askeknesoch 30 /in la & 109? \\
\hline \multicolumn{3}{|c|}{11P4M} & uncriavonte 50 & gatamasak 30 & logmye \\
\hline \multicolumn{3}{|c|}{11P8M} & 50 & und & \\
\hline \multicolumn{2}{|r|}{12 P 4 M} & ** & 50 & Hovil 30 & V \\
\hline \multicolumn{3}{|c|}{12P8M} & 50 & 35 & \\
\hline
\end{tabular}

Switching Characteristics Over Commercial Operating Conditions


\section*{Operating Conditions}
\begin{tabular}{|c|c|c|c|c|c|c|}
\hline SYMBOL & PARAMETER & \multicolumn{2}{|l|}{COMMERCIAL MIN TYP* MAX} & \multicolumn{2}{|l|}{MILITARY} & UNIT \\
\hline \({ }_{\text {t }}\) w & Width of clock (High or Low) & 20 & 10 & 20 & 10 & ns \\
\hline \({ }_{\text {tprw }}\) & \multirow[t]{2}{*}{Width of preset or clear (Low) to Output (High or Low)} & 20 & 10 & 20 & 10 & ns \\
\hline \({ }_{\text {t }}^{\text {clrw }}\) w & & & & & & \\
\hline tprr & \multirow[t]{2}{*}{Recovery from preset or clear (Low) to clock High} & \multirow[t]{2}{*}{20} & \multirow[t]{2}{*}{11} & \multirow[t]{2}{*}{25} & \multirow[t]{2}{*}{11} & \multirow[t]{2}{*}{ns} \\
\hline \(\mathrm{t}_{\mathrm{clrr}}\) & & & & & & \\
\hline \(\mathrm{t}_{\text {su }}\) & Setup time from input to clock & 30 & 22 & 35 & 22 & ns \\
\hline \(\mathrm{t}_{\mathrm{s}}(\overline{\mathrm{ES}})\) & Setup time from \(\overline{E S}\) to clock & 10 & 7 & 15 & 7 & ns \\
\hline \(t_{h}\) & Hold time from input to clock & 0 & -5 & 0 & -5 & ns \\
\hline \(t_{h} \overline{(E S)}\) & Hold time from ES to clock & 5 & -3 & 5 & -3 & ns \\
\hline
\end{tabular}

Switching Characteristics Over Operating Conditions and using Standard Test Load
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|}
\hline & \multirow[b]{2}{*}{PARAMETER} & & \multicolumn{3}{|l|}{COMMERCIAL} & \multicolumn{3}{|l|}{MILITARY} & \multirow[b]{2}{*}{UNIT} \\
\hline SYMBOL & & & MIN & TYP* & MAX & MIN & TYP* & MAX & \\
\hline \({ }^{\text {t CLK }}\) & Clock to output delay & V20-140 & & 11 & 15 & & 11 & 20 & ns \\
\hline \(\mathrm{t}_{\mathrm{PR}}\) & Preset to output delay & & & 15 & 25 & & 15 & 25 & ns \\
\hline \({ }^{\text {t CLR }}\) & Clear to output delay & & & 18 & 25 & & 18 & 35 & ns \\
\hline tPZX (CLK) & Clock to output enable time & & & 14 & 25 & & 14 & 30 & ns \\
\hline tPXZ (CLK) & Clock to output disable time & & & 14 & 25 & & 14 & 30 & ns \\
\hline \({ }^{\text {t P Z }}\) ( \({ }^{\text {P }}\) & Input to output enable time & 3 mm & \(\square\) & 10 & 20 & & 10 & 25 & ns \\
\hline \({ }^{\text {tP PXZ }}\) & Input to output disable time & 8 & & 10 & 20 & & 10 & 25 & ns \\
\hline
\end{tabular}
* Typical at \(5.0 \mathrm{~V} \mathrm{~V}_{\mathrm{CC}}\) and \(25^{\circ} \mathrm{C} \mathrm{T}_{\mathrm{A}}\).

\section*{Definition of Waveforms}


NOTES: 1. Input pulse amplitude 0 V to 3.0 V .
2. Input rise and fall times \(2-5 \mathrm{~ns}\) from 0.8 V to 2.0 V
3. Input access measured at the 1.5 V level.
4. Switch \(\mathrm{S}_{1}\) is closed. \(\mathrm{C}_{\mathrm{L}}=30 \mathrm{pF}\) and outputs measured at 1.5 V level for all tests except \(\mathrm{t}_{\mathrm{PXZ}}\) and \({ }^{t_{P Z X}}\)
5. tPZX and tPZX(CLK) are measured at the 1.5 V output level with \(\mathrm{C}_{\mathrm{L}}=30 \mathrm{pF} . \mathrm{S}_{1}\) is open for high impedance to " 1 " test and closed for high impedance to " 0 " test.
\({ }^{\text {t PXZ }}\) and \(t_{P X Z}(C L K)\) are tested with \(\mathrm{C}_{\mathrm{L}}=5 \mathrm{pF} . \mathrm{S}_{1}\) is open for " 1 " to high impedance test, measured at \(\mathrm{VOH}_{\mathrm{OH}^{-}} 0.5 \mathrm{~V}\) output level; \(\mathrm{S}_{1}\) is closed for " 0 " to high impedance test measured at \(\mathrm{V}_{\mathrm{OL}}+0.5 \mathrm{~V}\) output level.

\section*{Operating Conditions}
\begin{tabular}{|c|c|c|c|c|c|c|}
\hline \multirow[b]{2}{*}{SYMBOL} & \multirow[b]{2}{*}{PARAMETER} & \multicolumn{2}{|l|}{COMMERCIAL} & \multicolumn{2}{|r|}{MILITARY} & \multirow[b]{2}{*}{UNIT} \\
\hline & & MIN & TYP* MAX & MIN & TYP* MAX & \\
\hline \(t_{w}\) & Width of clock (High or Low) & 20 & 10 & 20 & 10 & ns \\
\hline \(\mathrm{t}_{\text {su }}\) & Setup time from input to clock (10R8) & 30 & 25 & 40 & 25 & ns \\
\hline \(\mathrm{t}_{\text {su }}\) & Setup time from input to clock (11RA8, 11RS8) & 35 & 28 & 40 & 28 & ns \\
\hline \(\mathrm{t}_{\mathrm{s}}(\overline{\mathrm{ES}})\) & Setup time from \(\overline{\mathrm{ES}}\) to clock & 15 & 7 & 15 & 7 & ns \\
\hline \(\mathrm{t}_{\mathrm{S}}\) (İS) & Setup time from \(\overline{\mathrm{I}}\) to clock & 25 & 20 & 30 & 20 & ns \\
\hline \(t_{h}\) & Hold time input to clock & 0 & -5 & 0 & -5 & ns \\
\hline \(t_{h}(\overline{E S})\) & Hold time ( \(\overline{E S}\) ) & 5 & -3 & & -3 & ns \\
\hline \(t_{h}\) ( \(\overline{\text { I }}\) ) & Hold time ( \(\overline{\mathrm{IS}}\) ) & 0 & -5 & 0 & -5 & ns \\
\hline
\end{tabular}

Switching Characteristics Over Operating Conditions and using Standard Test Load
\begin{tabular}{|c|c|c|c|c|c|c|c|}
\hline \multirow[t]{2}{*}{SYMBOL} & \multirow[t]{2}{*}{PARAMETER} & \multicolumn{2}{|l|}{COMMERCIAL} & \multicolumn{3}{|c|}{MILITARY} & \multirow[t]{2}{*}{UNIT} \\
\hline & & MIN TYP* & MAX & & & MAX & \\
\hline \({ }^{\text {t CLK }}\) & Clock to output delay & 10 & 15 & & 10 & 20 & ns \\
\hline \({ }^{\text {tPZX }}\) (CLK) & Clock to output enable time & 17 & 25 & & 17 & 30 & ns \\
\hline \({ }^{\text {t PXZ }}\) (CLK) & Clock to output disable time & 17 & 25 & & 17 & 30 & ns \\
\hline \({ }_{\text {tPZX }}\) & Input to output enable time & 17 & 25 & & 17 & 30 & ns \\
\hline \({ }_{\text {tPXZ }}\) & Input to output disable time & 17 & 25 & & 17 & 30 & ns \\
\hline
\end{tabular}
* Typical at \(5.0 \vee \mathrm{~V}_{\mathrm{CC}}\) and \(25^{\circ} \mathrm{C} \mathrm{T}_{\mathrm{A}}\).

Definition of Waveforms


NOTES: 1. Input pulse amplitude 0 V to 3.0 V .
2. Input rise and fall times \(2-5 \mathrm{~ns}\) from 0.8 V to 2.0 V .
3. Input access measured at the 1.5 V level.
4. Switch \(\mathrm{S}_{1}\) is closed. \(\mathrm{C}_{\mathrm{L}}=30 \mathrm{pF}\) and outputs measured at 1.5 V level for all tests except \(\mathrm{tp}_{\mathrm{L}} \mathrm{Cx}\) and tpxz .
5. \(\mathrm{IPRXX}^{\text {and }}\) IPZXICLK) are measured at the 1.5 V output level with \(\mathrm{C}_{\mathrm{L}}=30 \mathrm{pF} . \mathrm{S}_{1}\) is open for high impedance to " 1 " test and closed for high impedance to " 0 " test.
\({ }^{\mathrm{t} p \times Z}\) and \(\mathrm{t}_{\mathrm{P} \times \mathrm{Z}}\) (CLK) are tested with \(\mathrm{C}_{\mathrm{L}}=5 \mathrm{pF} . \mathrm{S}_{1}\) is open for "1" to high impedance test. measured at \(\mathrm{V}_{\mathrm{OH}}-0.5 \mathrm{~V}\) output level \(\mathrm{S}_{1}\) is closed for " 0 " to high impedance test measured at \(\mathrm{VOL}^{\circ}+0.5 \mathrm{~V}\) output level.

Switching Test Load
Definition of Timing Diagram


\section*{PLE \({ }^{\text {TM }}\) Device Family \\ Programming Instructions}

\section*{Device Description}

All of the members of the PLE device family are manufactured with all outputs LOW in all storage locations. To produce a HIGH as a particular word, a Titanium-Tungsten Fusible-Link must be changed from a low resistance to a high resistance. This procedure is called programming.

\section*{Programming Description}

To program a particular bit normal TTL levels are applied to all inputs. Programming occurs when:
1. \(\mathrm{V}_{\mathrm{CC}}\) is raised to an elevated level.
2. The output to be programmed is raised to an elevated level.
3. The device is enabled.

In order to avoid misprogramming the PLE device only one output at a time is to be programmed. Outputs not being programmed should be connected to \(\mathrm{V}_{\mathrm{CC}}\) via \(5 \mathrm{~K} \Omega\) resistors.
Unless specified, Inputs should be at VIL.

\section*{Programming Sequence}

The sequence of programming conditions is critical and must occur in the following order:
1. Select the appropriate address with chip disabled
2. Increase \(\mathrm{V}_{\mathrm{CC}}\) to programming voltage
3. Increase appropriate output voltage to programming voltage
4. Enable chip for programming pulse width
5. Decrease \(\mathrm{V}_{\text {OUT }}\) and \(\mathrm{V}_{\mathrm{CC}}\) to normal levels

\section*{Programming Timing}

In order to insure the proper sequence, a delay of 100 ns or greater must be allowed between steps. The enabling pulse must not occur less than 100 ns after the output voltage reaches programming level. The rise time of the voltage on \(\mathrm{V}_{\mathrm{CC}}\) and the output must be between 1 and \(10 \mathrm{~V} / \mu \mathrm{s}\).

\section*{Verification}

After each programming pulse verification of the programmed bit should be made with both low and high \(\mathrm{V}_{\mathrm{CC}}\). The loading of the output is not critical and any loading within the DC specifications of the part is satisfactory.

\section*{Additional Pulses}

Up to 10 programming pulses should be applied until verification indicates that the bit has programmed. Following verification, apply five additional programming pulses to the bit being programmed.

Programming Parameters Do not test these parameters or you may program the device
\begin{tabular}{|c|c|c|c|c|c|}
\hline \multirow[b]{2}{*}{SYMBOL} & \multirow[t]{2}{*}{PARAMETER} & \multicolumn{3}{|c|}{RECOMMENDED} & \multirow[t]{2}{*}{UNIT} \\
\hline & & MIN & VALUE & MAX & \\
\hline \(\mathrm{V}_{\text {CCP }}\) & Required \(\mathrm{V}_{\mathrm{CC}}\) for programming & 11.5 & 11.75 & 12.0 & V \\
\hline \(\mathrm{V}_{\mathrm{OP}}\) & Required output voltage for programming & 10.5 & 11.0 & . 11.5 & \({ }_{31} \mathrm{~V}\) \\
\hline \({ }^{t_{R}}\) & Rise time of \(\mathrm{V}_{\text {CC }}\) or \(\mathrm{V}_{\text {OUT }}\) & 1.0 & 5.0 & 10.0 & \(\mathrm{V} / \mu \mathrm{S}\) \\
\hline \({ }^{1} \mathrm{CCP}\) & Current limit of \(\mathrm{V}_{\mathrm{CCP}}\) supply & 800 & 1200 & & mA \\
\hline \({ }^{\prime} \mathrm{OP}\) & Current limit of \(\mathrm{V}_{\text {OP }}\) supply & 15 & 20 & \%rtoal3 & mA \\
\hline \({ }^{\text {tPW }}\) & Programming pulse width (enabled) & 9 & 10 & 11 & \(\mu \mathrm{S}\) \\
\hline \(\mathrm{V}_{\mathrm{CC}}\) & Low \(\mathrm{V}_{\mathrm{CC}}\) for verification & 4.2 & 4.3 & - 4.4 & V \\
\hline \(\mathrm{V}_{\mathrm{CC}}\) & High \(\mathrm{V}_{\mathrm{CC}}\) for verification & 5.8 & 6.0 & 6.2 & V \\
\hline MDC & Maximum duty cycle of \(\mathrm{V}_{\mathrm{CCP}}\) & & 25 & 25 & \% \\
\hline \({ }^{\text {D }}\) D & Delay time between programming steps & 100 & 120 & & ns \\
\hline \(V_{\text {IL }}\) & Input low level & 0 & 0 & 0.5 & V \\
\hline \(\mathrm{V}_{\text {IH }}\) & Input high level & 2.4 & 3.0 & 5.5 & V \\
\hline
\end{tabular}


\section*{Programming Equipment and Software Suppliers}

Monolithic Memories' PLE devices are designed and tested to give a programming yield greater than \(98 \%\). If your programming yield is lower, check your programmer. It may not be properly calibrated.

Programming is final manufacturing - it must be qualitycontrolled. Equipment must be calibrated as a regular
routine, ideally under the actual conditions of use. Each time a new board or a new programming module is inserted, the whole system should be checked. Both timing and voltages must meet published specifications for the device.

Remember - The best PLE devices available can be made unreliable by improper programming techniques.

\section*{PROGRAMMERS}

Data I/O Corp.
10525 Willows Rd. N.E.
Redmond, WA 98073-9746
(800) 426-1045

Kontron Electronics, Inc.
©̂ingeléc Înč.
586 Weddell Dr.
Suite 1,
Sunnyvale, CA 94089
(408) 745-0722

\section*{Stag Microsystems Inc.}

528-5 Weddell Dr.
Sunnyvale, CA 94089
(408) 745-1991

Varix Corp.
1210 F Camnhell Rd No. 100

\section*{SOFTWARE}

PLEASM
Monolithic Memories
IdeaLogic Exchange
2175 Mission College Blvd. M/S 09-07
Santa Clara, CA 95054
(408) 970-9700 x. 6085

Redmond, WA 98073-9746
(800) 426-1045

CUPL
Assisted Technology
2381 Zanker Rd. No. 150
San Jose, CA 95131
(408) 942-8787

\section*{Block Diagrams}


\section*{Block Diagrams}


PLE12P4

PLE12P8
BAMr13.19
7


\section*{Block Diagrams}

-IS selects 1:16 programmable initialization words.

Monolithic Memories PLE Device Programmer Reference Chart
\(\left.\begin{array}{|l|l|l|l|l|l|l|}\hline \begin{array}{l}\text { Source and } \\ \text { Location }\end{array} & \begin{array}{l}\text { Data I/O } \\ \text { 10525 Willow Rd. N.E. } \\ \text { Redmond, WA 98073 }\end{array} & \begin{array}{l}\text { Kontron Electronics } \\ \text { 630 Price Ave. } \\ \text { Redwood City, CA 94063 }\end{array} & \begin{array}{l}\text { Stag Microsystems } \\ \text { 528 Weddell Dr., Suite 1 } \\ \text { Sunnyvale, CA 94089 }\end{array} & \begin{array}{l}\text { Digelec } \\ \text { 586-1 Weddell Dr. } \\ \text { Sunnyvale, CA 94089 }\end{array} & \begin{array}{l}\text { Varix - Suite 100 } \\ \text { 1210 E. Campbell Rd. } \\ \text { Richardson, TX 75081 }\end{array} \\ \hline \begin{array}{l}\text { Programmer } \\ \text { Model(s) }\end{array} & \begin{array}{l}\text { Model 19/29 } \\ \text { Model 22 }\end{array} & \text { Model MPP-80S }\end{array} \quad \begin{array}{l}\text { Model PPX } \\ \text { Model PP17 }\end{array}\right)\)

\footnotetext{
\(\dagger\) - Contact manufacturer for availability and programming information
}



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\section*{Random Logic Replacement}

\section*{Random Logic Replacement}

PROMs, as logic elements, have been providing solutions as replacements of random logic. This is the concept of PROM as a Programmable Logic Element (PLE) device.

The usages of PLE devices include simple multiplexer/demultiplexer/encoder/decoder, control signal generators, data communications support like CRC, and arithmetic elements like ALUs, multipliers, sine and inverse look-up tables, and applications in signal processing
The advantages of PLE devices over SSI/MSI logic devices are the flexibility of design and the fast turnaround time which nonprogrammable devices cannot offer. For example, if a decoder is used to select between memory pages and I/O ports, once a design is done, it will be fixed - it not easy to find a part to be put just in the same place without modification of PC board layout in case the designer wants to expand the memory or to increase the I/O. For a PLE device, what is needed is to program another PLE device and place it in the same socket where the old part was placed. In addition, it can allow designers to define their logic functions in a component.
The AND-OR planar structure of the PLE circuit array lends itself naturally to being viewed as a two-level logic circuit. The fixed AND plane contains all possible combinations of the literals of its inputs. Each combination (product term) is fuse-connected to each output in the programmable OR plane.
A common PLE device application in the control path is to customize logic functions. An \(n\) input exclusive OR function is quite commonly required in comparator and adder circuits. It contains \(2^{n-1}\) product terms, which becomes quite large for large values of n . Therefore, it is very convenient to implement large XOR functions in PLE devices.
The PLE logic circuit implementation of a 4-input XOR is shown below.

Although it seems that XOR functions may be replaced by SSIs, in most applications, the XOR functions will not be alone by themselves, PLE circuits can provide the flexibility of adding in additional functions without using additional packages.
In the data path, a PLE device can be used to implement complex functions such as a Pseudo Random Number (PRN) Generator Random number sequences are useful in encoding and decoding of information in signal processing and communications systems. They are used for data encryption, image quantization, waveform synchronization, and white noise generation, etc.
There are many techniques for generating PRN sequences. The most common technique, however, is to use ' \(n\) ' stages of linear shift registers with feedback through a logic function. The function \(f\) is an arbitrary function chosen for a specific application. A most general linear function is an ' \(m\) ' input XOR ( \(m \leq n\) ).


There are a number of examples in the following session which shows how a PLE device can be used to replace SSI/MSI logic devices using PLEASM software.


\section*{BASIC GATES (cont'd)}

FUNCTION TABLE
\begin{tabular}{llllllllllllll} 
IO I1 I2 & I3 & I4 & O1 & 02 & 03 & 04 & 05 & 06 & 07 & 08 & & & \\
; INPUT & - & - & OUTPUTS & FROM & BASIC & GATES & - & - & \\
; 01234 & BUF & INV & AND & OR & NAND & NOR & XOR & XNOR & COMMENTS \\
\hdashline LLLLL & L & H & L & L & H & H & L & L & ALL ZEROS \\
HHHHH & H & L & H & H & L & L & H & H & ALL ONES \\
HLHLH & H & L & L & H & H & L & H & H & ODD CHECKERBOARD \\
LHLHL & L & H & L & H & H & L & L & L & EVEN CHECKERBOARD
\end{tabular}

\section*{DESCRIPTION}

THIS EXAMPLE ILLUSTRATES THE USE OF PLE DEVICES TO IMPLEMENT THE BASIC GATES: BUFFER, INVERTER, AND GATE, OR GATE, NAND GATE, NOR GATE, EXCLUSIVE OR GATE, AND EXCLUSIVE NOR GATE.

NOTE ALSO THAT THREE-STATE OUTPUTS ARE PROVIDED WITH ONE ACTIVE LOW OUTPUT ENABLE CONTROL (/E).

PLEASM SOFTWARE GENERATES THE PROM TRUTH TABLE FROM THE LOGIC EQUATIONS AND SIMULATES THE FUNCTION TABLE IN THE LOGIC EQUATIONS.

BASIC
GATES
PLE5P8

; SELECTS ADDRESS RANGE \(0 \mathrm{~K}-2 \mathrm{~K}\)
; SELECTS ADDRESS RANGE \(2 \mathrm{~K}-4 \mathrm{~K}\)
; SELECTS ADDRESS RANGE \(4 \mathrm{~K}-6 \mathrm{~K}\)
; SELECTS ADDRESS RANGE \(6 \mathrm{~K}-8 \mathrm{~K}\)
; SELECTS ADDRESS RANGE \(8 \mathrm{~K}-10 \mathrm{~K}\)
; SELECTS ADDRESS RANGE \(10 \mathrm{~K}-12 \mathrm{~K}\)
; SELECTS ADDRESS RANGE \(12 \mathrm{~K}-14 \mathrm{~K}\)
; SELECTS ADDRESS RANGE \(14 \mathrm{~K}-16 \mathrm{~K}\)


FUNCTION TABLE
All Al2 Al3 Al4 Al5 /MREQ /CE1 /CE2 /CE3 /CE4 /CE5 /CE6/CE7 /CE8
\begin{tabular}{|c|c|c|c|c|}
\hline \multicolumn{5}{|c|}{ADD LINES} \\
\hline ; & 11111 & & CHIP ENABLES & 840839 \\
\hline ; & 12345 & /MREQ & 12345678 & COMMENTS \\
\hline & LLLLL & L & LHHHHHHH & SELECT ADDRESS RANGE 0-2K \\
\hline & HLLLL & L & HLHHHHHH & SELECT ADDRESS RANGE 2K-4K \\
\hline & LHLLL & L & HHLHHHHH & SELECT ADDRESS RANGE 4K-6K \\
\hline & HHLLL & L & HHHLHHHH & SELECT ADDRESS RANGE 6K-8K \\
\hline & LLHLL & L & HHHHLHHH & SELECT ADDRESS RANGE 8K-10K \\
\hline & HLHLL & L & HHHHHLHH & SELECT ADDRESS RANGE 10K-12K \\
\hline & LHHLL & L & HHHHHHLH & SELECT ADDRESS RANGE \(12 \mathrm{~K}-14 \mathrm{~K}\) \\
\hline & HHHLL & L & HHHHHHHL & SELECT ADDRESS RANGE 14K-16K \\
\hline & XXXXX & H & HHHHHHHH & NO MEMORY SELECT (/MREQ=H) \\
\hline
\end{tabular}


8-6

\section*{MEMORY ADDRESS DECODER (cont'd)}

\section*{DESCRIPTION}

THIS PLE8P8 PROVIDES A SINGLE CHIP ADDRESS DECODER FOR USE WITH MANY POPULAR 8-BIT MICROPROCESSORS SUCH AS THE Z80 AND 8080. THE FIVE MSB ADDRESS LINES (All-A15) AND THE MEMORY REQUEST LINE (/MREQ) FROM THE 280 MICROPROCESSOR ARE DECODED TO PRODUCE EIGHT ACTIVE LOW CHIP ENABLES (/CE1-/CE8) TO SELECT A RANGE OF 2K BYTES FROM A BANK OF EIGHT 2Kx8 STATIC RAMS. THIS BANK OF STATIC RAMS WILL OCCUPY THE LOWEST 16K BYTES OF ADDRESS SPACE LEAVING THE UPPER 48 K BYTE SPACE AVAILABLE FOR OTHER MEMORIES AND I/O. THE PLE8P8 HAS THREE ADDITIONAL INPUTS WHICH CAN BE RESERVED FOR FUTURE SYSTEM EXPANSION.


Random Logic

PLE8 P4
PLE CIRCUIT DESIGN SPECIFICATION
P5029
VINCENT COLI 10/13/84
6809 ADDRESS DECODER
MMI SANTA CLARA, CALIFORNIA
- ADD A8 A9 Al0 All Al2 A13 Al4 Al5
.DAT /DRAM / IO /SRAM /PROM


IO = A8* A9* Al0* All* Al2* Al3*/Al4* Al5 ; SELECTS ADDRESS RANGE BFO0-BFFF



FUNCTION TABLE

A8 A9 Al0 All Al2 Al3 Al4 Al5 /DRAM /IO /SRAM /PROM

ADDRESS LINES
; 111111
; 89012345 /DRAM /IO /SRAM /PROM COMMENTS
\begin{tabular}{lllllll} 
LLLL LLLL & L & H & H & H & OOXX HEX SELECTS DRAMS \\
LLLL HHLH & L & H & H & H & BOXX HEX SELECTS DRAMS \\
HHHH HHLH & H & L & H & H & BFXX HEX SELECTS I/O PORTS \\
LLLL LLHH & H & H & L & H & COXX HEX SELECTS SRAM \\
LLLL HLHH & H & H & L & H & DOXX HEX SELECTS SRAM \\
LLLL LHHH & H & H & H & L & EOXX HEX SELECTS PROM \\
HHHH HHHH & H & H & H & L & FFXX HEX SELECTS PROM
\end{tabular}

DESCRIPTION
THIS PLE8P4 PROVIDES A SINGLE CHIP ADDRESS DECODER FOR USE WITH MANY POPULAR 8-BIT MICROPROCESSORS SUCH AS THE MOTOROLA 6809. THIS PLE DEVICE DECODES THE EIGHT MSB ADDRESS LINES (A8-A15) FROM THE MICROPROCESSOR TO PROVIDE FOUR ACTIVE LOW CHIP ENABLES (/DRAM,/IO, /SRAM, AND /PROM).

THE 64K MEMORY MAP OF THE SYSTEM IS DIVIDED UP INTO FOUR SECTIONS: DRAM, IO PORTS, SRAM, AND PROM. EACH OF THESE FOUR SECTIONS CAN CONTAIN ONE OR MORE BLOCKS OF MEMORY. EACH OF THESE BLOCKS CAN START AND STOP ON ANY 256 BIT BOUNDARY



TRUE/COMPLEMENT AND CLEAR/SET (cont'd) DESCRI PTION

THIS PLE8P8 IS A 6-BIT TRUE/COMPLEMENT AND CLEAR/SET LOGIC FUNCTIONS. THE CONTROL LINES (II AND I2) SELECT ONE OF FOUR LOGIC FUNCTIONS FOR THE 6-BIT INPUT DATA (Dl-D6) AND THE 6-BIT OUTPUT FUNCTION (Yl-Y6).

WHEN Il IS FALSE (Il=LOW) THE FUNCTION IS INVERT IF I2 IS FALSE (I2=LOW) OR TRUE IF I2 IS TRUE (I2=HIGH).

WHEN Il IS TRUE ( \(\mathrm{I}=\mathrm{HIGH}\) ) THE FUNCTION IS CLEAR IF I2 IS FALSE (I2=LOW) OR SET IF I2 IS TRUE (I2=HIGH).

THE PLE8P8 ALSO FEATURES THREE-STATE OUTPUTS WITH TWO ACTIVE LOW OUTPUT ENABLE CONTROLS (/E1 AND /E2).
\begin{tabular}{lllll} 
I1 & I2 & D1-D6 & Y1-Y6 & FUNCTION \\
\hdashline L & L & D & /D & INVERT \\
L & H & D & D & TRUE \\
H & L & X & H & CLEAR \\
H & H & X & L & SET
\end{tabular}



PLE CIRCUIT DESIGN SPECIFICATION
FRANK LEE \(04 / 15 / 84\)
```

ACTIVE HIGH, SELECT 0
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 4-7
ACTIVE LOW, SELECT 2,3,6,7
ACTIVE LOW, SELECT 1,3,5,7
ACTIVE HIGH, SELECT 1
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 4,5,6,7
ACTIVE LOW, SELECT 2,3,6,7
ACTIVE LOW, SELECT 0,2,4,6
ACTIVE HIGH, SELECT 2
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 4-7
ACTIVE LOW, SELECT 0,1,4,5
ACTIVE LOW, SELECT 1,3,5,7
ACTIVE HIGH, SELECT 3
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 4-7
ACTIVE LOW, SELECT 0,1,4,5
ACTIVE LOW, SELECT 0,2,4,6
ACTIVE HIGH, SELECT 4
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 0-3
ACTIVE LOW, SELECT 2,3,6,7
ACTIVE LOW, SELECT 1,3,5,7
ACTIVE HIGH, SELECT 5
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 0-3
ACTIVE LOW, SELECT 2,3,6,7
ACTIVE LOW, SELECT 0,2,4,6
ACTIVE HIGH, SELECT }
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 0-3
ACTIVE LOW, SELECT 0,1,4,5
ACTIVE LOW, SELECT 1,3,5,7
ACTIVE HIGH, SELECT }
ACTIVE LOW, DI INACTIVE
ACTIVE LOW, SELECT 0-3
ACTIVE LOW, SELECT 0,1,4,5
ACTIVE LOW, SELECT 0,2,4,6

```
\begin{tabular}{|c|c|c|c|c|}
\hline ; PO & DI & \[
\begin{aligned}
& \text { SSS } \\
& 210
\end{aligned}
\] & \[
\begin{aligned}
& \text { YYYYYYYY } \\
& 76543210
\end{aligned}
\] & COMMENTS \\
\hline H & L & XXX & LLLLLLLL & DATA INPUT \(=0\) \\
\hline H & H & LLL & LLLLLLLH & SELECT OUTPUT 0 \\
\hline H & H & LLH & LLLLLLHL & SELECT OUTPUT 1 \\
\hline H & H & LHL & LLLLLHLL & SELECT OUTPUT 2 \\
\hline H & H & LHH & LLLLHLLL & SELECT OUTPUT 3 \\
\hline H & H & HLL & LLLHLLLL & SELECT OUTPUT 4 \\
\hline H & H & HLH & LLHLLLLL & SELECT OUTPUT 5 \\
\hline H & H & HHL & LHLLLLLL & SELECT OUTPUT 6 \\
\hline H & H & HHH & HLLLLLLL & SELECT OUTPUT 7 \\
\hline L & H & XXX & HHHHHHHH & DATA INPUT \(=0\) \\
\hline L & L & LLL & HHHHHHHL & SELECT OUTPUT 0 \\
\hline L & L & LLH & HHHHHHLH & SELECT OUTPUT 1 \\
\hline L & L & LHL & HHHHHLHH & SELECT OUTPUT 2 \\
\hline L & L & LHH & HHHHLHHH & SELECT OUTPUT 3 \\
\hline L & L & HLL & HHHLHHHH & SELECT OUTPUT 4 \\
\hline L & L & HLH & HHLHHHHH & SELECT OUTPUT 5 \\
\hline L & L & HHL & HLHHHHHH & SELECT OUTPUT 6 \\
\hline L & L & HHH & LHHHHHHH & SELECT OUTPUT 7 \\
\hline
\end{tabular}

EXPANDABLE 3-TO-8 DEMULTIPLEXER


DESCRIPTION
THIS PLE5P8 IMPLEMENTS AN EXPANDABLE 3-TO-8 DEMULTIPLEXER. THE DEVICE DEMULTIPLEXES THREE SELECT INPUT SIGNALS (S2-SO) INTO EIGHT OUTPUTS (Y7-Y0) USING THE INPUT DI WITH POLARITY SELECT PO. SINCE THE DEVICE HAS THREE-STATE OUTPUTS, IT CAN BE EXPANDED USING THE ACTIVE LOW ENABLE PIN (/E).

PIN ASSIGNMENTS:
1. PO HIGH INDICATES OUTPUT IS ACTIVE HIGH. LOW INDICATES OUTPUT IS ACTIVE LOW.
2. DI DATA INPUT (DEMULTIPLEXING INPUT). ACTIVE LOW IF PO IS LOW.
3. S2-S0 SELECT PINS. S2 IS THE MOST SIGNIFICANT BIT. ACTIVE HIGH REGARDLESS OF PO.
4. Y7-Y0 OUTPUTS. CAN BE ACTIVE HIGH OR ACTIVE LOW DEPENDING ON PO. ACTIVE LOW IF PO IS LOW.

\section*{OPERATIONS TABLE:}
\begin{tabular}{ccccl} 
PO & DI & S2-S0 & Y7-YO & OPERATION \\
\hdashline L & H & \(X\) & H & OUTPUTS HIGH \\
H & H & S & DEMUX & DEMUX ACTIVE HIGH \\
L & L & S & /DEMUX & DEMUX ACTIVE LOW \\
H & L & \(X\) & L & OUTPUTS LOW
\end{tabular}


MMI SANTA CLARA, CALIFORNIA
. ADD SX SY Al Bl Cl D1 A2 B2 C2 D2 .DAT X1 Y1 X2 Y2


THIS IS AN EXAMPLE OF TWO INDEPENDENT 2-TO-1 MULTIPLEXERS USING A PLEIOP4 THE DEVICE WILL SWITCH BETWEEN TWO PAIRS OF 2-BIT INPUTS (A, B AND C, D), AS DETERMINED BY THE TWO SELECT LINES (SX, SY), FOR OUTPUT THROUGH TWO PAIRS OF 2-BIT OUTPUTS (X AND Y). THREE-STATE OUTPUTS ARE ALSO PROVIDED WITH TWO ACTIVE LOW ENABLE PINS (/El AND /E2). THE FUNCTIONS OF THE DEVICE ARE SUMMARIZED IN THE TABLE BELOW:


DUAL 2:1
MULTIPLEXER


\title{
PLE CIRCUIT DESIGN SPECIFICATION
}

P5005
S. HORIKO \(04 / 29 / 84\)

QUAD 2:1 MULTIPLEXER WITH POLARITY CONTROL
MMI JAPAN
. ADD SEL POL AO A1 A2 A3 B0 B1 B2 B3
. DAT Y0 Y1 Y2 Y3
\begin{tabular}{|c|c|c|c|c|c|}
\hline YO \(=\) /SEL*/POL*/A0 & ; & SELECT & INPUT & /AO & (COMP) \\
\hline +/SEL* POL* A0 & ; & SELECT & INPUT & A0 & (TRUE) \\
\hline + SEL*/POL*/B0 & ; & SELECT & INPUT & /B0 & (COMP) \\
\hline + SEL* POL* B0 & ; & SELECT & INPUT & B0 & (TRUE) \\
\hline \(\mathrm{YI}=/ \mathrm{SEL} * / \mathrm{POL}\) */A1 & ; & SELECT & INPUT & /Al & (COMP) \\
\hline +/SEL* POL* Al & ; & SELECT & INPUT & Al & (TRUE) \\
\hline + SEL*/POL*/B1 & ; & SELECT & INPUT & /Bl & (COMP) \\
\hline + SEL* POL* Bl & ; & SELECT & INPUT & B1 & (TRUE) \\
\hline Y2 \(=/\) SEL*/POL*/A2 & ; & SELECT & INPUT & /A2 & (COMP) \\
\hline +/SEL* POL* A2 & ; & SELECT & INPUT & A2 & (TRUE) \\
\hline + SEL*/POL*/B2 & ; & SELECT & INPUT & /B2 & (COMP) \\
\hline + SEL* POL* B2 & ; & SELECT & INPUT & B2 & (TRUE) \\
\hline Y3 = /SEL*/POL*/A3 & ; & SELECT & INPUT & /A3 & (COMP) \\
\hline +/SEL* POL* A3 & ; & SELECT & INPUT & A3 & (TRUE) \\
\hline + SEL*/POL*/B3 & ; & SELECT & INPUT & /B3 & (COMP) \\
\hline + SEL* POL* B3 & & SELECT & INPUT & B3 & (TRUE) \\
\hline
\end{tabular}
msar3.je
FUNCTION TABLE
SEL POL A0 A1 A2 A3 BO B1 B2 B3 Y0 Y1 Y2 Y3


QUAD 2:1 MULTIPLEXER WITH POLARITY CONTROL (contd) 2IUSR12 318
DESCRIPTION

THIS IS AN EXAMPLE OF A QUAD 2:1 MULTIPLEXER WITH POLARITY CONTROL IMPLEMENTED IN A PLEIOP4. THE DEVICE SELECTS BETWEEN TWO 4-BIT INPUTS (A1-A4 AND B1-B4) WHICH ARE DIRECTED TO ONE 4-BIT OUTPUT (Yl-Y4) AS DETERMINED BY ONE INPUT SELECT LINE (SEL) AND POLARITY CONTROL (POL). WHEN POLARITY IS TRUE (POL=HIGH), THE TRUE OF THE INPUT SIGNAL IS SELECTED. WHEN POLARITY IS FALSE (POL=LOW), THE COMPLEMENT OF THE INPUT SIGNAL IS SELECTED.

THE PLE10P4 ALSO FEATURES THREE-STATE OUTPUTS WITH TWO ACTIVE LOW ENABLE PINS (/EL AND /EZ). THE FUNCTION IS SUMMARIZED BELOW:
\begin{tabular}{llllcccc} 
SEL & POL & Al-A4 & Bl-B4 & Y1-Y4 & & & \\
\hdashline L & H & A & X & A & & & \\
L & L & A & X & /A & & \\
H & H & X & B & B & & \\
H & L & X & B & /B & & \\
\hline
\end{tabular}


8-16
Monolithic MM
Memories
OE = /A* /C ; SEGMENT E
OE = /A* /C ; SEGMENT E
    \(+\quad C * D\)
    \(+/ A^{*} B\)
    \(+A^{*} B^{*} D\)
LT ; IF LT=H MAKE BLANK TEST ON SEGMENT E
\(O F=/ A^{*} / B \quad ;\) SEGMENT \(F\)
    \(+\quad / B^{*} C * / D\)
    \(+\quad / C^{* D}\)
    + B* D
    \(+/ A^{*} B^{*} C\)
    \(+\quad\) LT ; IF LT=H MAKE BLANK TEST ON SEGMENT F
OG \(=\quad \mathrm{B} * / \mathrm{C} \quad\); SEGMENT G
    \(+/ A^{*} B\)
    \(+\quad / C * D\)
    \(+A^{*} D\)
    \(+\quad / B^{*} C * / D\)
\(\mathrm{DP}=\mathrm{LT}\)
; TURNS DP ON ONLY WHEN LT=H

THIS EXAMPLE ILLUSTRATES THE USE OF A PLE5P8 AS A HEXADECIMAL TO SEVEN SEGMENT DECODER．THE DEVICE DECODES A 4－BIT BINARY INPUT（ \(D, C, B, A\) ）INTO THE SEVEN SEGMENT OUTPUTS NEEDED TO DRIVE AN LED DISPLAY．NOTE THAT THIS DESIGN IS AN IMPROVEMENT FROM THE 74 LS 47 SINCE ALL 16 HEXADECIMAL DIGITS（ \(0-F\) ）CAN BE DISPLAYED．A LAMP TEST IS PROVIDED TO ILLUMINATE ALL SEVEN SEGMENTS AND THE DECIMAL POINT（IF DP IS CONNECTED）BY BRINGING LAMP TEST HIGH（LT＝HIGH） REGARDLESS OF THE OTHER BINARY INPUTS．THREE－STATE OUTPUTS ARE ALSO PROVIDED WITH ONE ACTIVE LOW ENABLE PIN（／E）．


\footnotetext{
＊BLANK TEST OF DISPLAY
}

\section*{HEXADECIMAL TO SEVEN－SEGMENT DECODER}


HEXADECIMAL TO SEVEN-SEGMENT DECODER (cont'd)

HEXADECIMAL TO SEVEN-SEGMENT DECODER


PLE5P8
P5007
5-BIT BINARY TO BCD CONVERTER
MMI SANTA CLARA, CALIFORNIA
. ADD BIO BII BI2 BI3 BI4
.DAT B00 B01 B02 B03 Bl0 Bll Bl2 Bl3
\(\mathrm{BOO}=\mathrm{BIO}\)
\(\mathrm{BO1}=/ \mathrm{BI} 4 * / \mathrm{BI} 3 * \quad \mathrm{BII}\)
+/BI4* BI3* BI2*/BIl
+ BI4* BI3*/BI2* BIl
+ BI4*/BI3*/BI2*/BII
+ BI3* BI2* BII
\(\mathrm{B} 02=/ \mathrm{BI} 4 * / \mathrm{BI} 3 * \mathrm{BI} 2\)
+/BI4* BI2* BII
+BI 4* \(^{+} \mathrm{BI} 3 * / \mathrm{BI} 2\)
+ BI4*/BI3*/BI2*/BII
\(\mathrm{B} 03=/ \mathrm{BI} 4^{*} \mathrm{BI} 3 * / \mathrm{BI} 2 * / \mathrm{BI} 1\)
+ BI4* BI3* BI2*/BII
+ BI4*/BI3*/BI2* BII
\(\mathrm{BlO}=/ \mathrm{BI} 4^{*} \mathrm{BI} 3^{*} \quad \mathrm{BII}\)
+/BI4* BI 3* BI2
+ BI3* BI2* BIl
\(+\mathrm{BI} 4 * / \mathrm{BI} 3 * / \mathrm{BI} 2\)
\(\mathrm{Bll}=\mathrm{BI} 4\) * BI 3
BI2
\(\mathrm{Bl2}=\mathrm{BI} 4 * / \mathrm{BI} 4\)

Bl3 \(=\) BI4*/BI4
\(\qquad\)

\section*{PLE CIRCUIT DESIGN SPECIFICATION}

VINCENT COLI 02/03/82
; CONVERT FIRST BIT OF 0 DECIMAL (LSB)
; CONVERT SECOND BIT OF 0 DECIMAL

 ; CONVERT THIRD BIT OF 0 DECIMAL
    CONVERT FOURTH BIT OF 0 DECIMAL
    CONVERT FIRST BIT OF 1 DECIMAL
    CONVERT SECOND BIT OF 1 DECIMAL
    CONVERT THIRD BIT OF 1 DECIMAL
    CONVERT FOURTH BIT OF 1 DECIMAL (MSB)
                                    5-BIT BINARY
                                    TO BCD
                                    CONVERTER


FUNCTION TABLE
BI4 BI3 BI2 BIl BI0 Bl3 Bl2 Bll Bl0 B03 B02 B01 B00


DESCRI PTION

THIS 5-BIT BINARY TO 2-DIGIT BCD CONVERTER IS IMPLEMENTED IN A PLE5P8 LOGIC CIRCUIT. THE DEVICE ACCEPTS A 5-BIT BINARY INPUT (BI) AND CONVERTS THIS INTO TWO 4-BIT BINARY CODED DECIMAL (BCD) OUTPUTS (BI AND BO).

THREE-STATE OUTPUTS ARE ALSO PROVIDED WITH ONE ACTIVE LOW ENABLE PIN (/E).

\section*{PLE5 P8}

PLE CIRCUIT DESIGN SPECIFICATION
P5008 VINCENT COLI 10/16/81
4-BIT BCD TO GRAY CODE CONVERTER
MMI SANTA CLARA, CALIFORNIA
. ADD B0 B1 B2 B3
.DAT GO Gl G2 G3
\(\mathrm{GO}=\mathrm{BO}:+\mathrm{Bl}\)
G1 = B1 : + : B2
G2 \(=\) B2 : + : B3
\(\mathrm{G} 3=\mathrm{B} 3\)
; CONVERT GO (LSB)
; CONVERT G1
; CONVERT G2
; CONVERT G3 (MSB)

DESCRIPTION

THIS PLE5P8 WILL CONVERT A 4-BIT BCD INPUT (B3-B0) INTO A 4-BIT GRAY CODE REPRESENTATION (G3-G0) FOR OUTPUT.


\section*{4-BIT
GRAY GRAY} CODE


PLE5P8 PLE CIRCUIT DESIGN SPECIFICATION
P5009 VINCENT COLI 03/16/84
4-BIT GRAY CODE TO BCD CONVERTER
MMI SANTA CLARA, CALIFORNIA
.ADD G0 G1 G2 G3
. DAT B0 B1 B2 B3
\begin{tabular}{ll} 
B0 \(=\) G0 \(:+:\) G1 \(:+:\) G2 :+: G3 & ; CONVERT B0 (LSB) \\
B1 \(=\) G1 :+: G2 :+: G3 & ; CONVERT B1 \\
B2 \(=\) G2 :+: G3 & ; CONVERT B2 \\
B3 \(=\) G3 &
\end{tabular}

\section*{DESCRIPTION}

THIS PLE5P8 WILL CONVERT A 4-BIT GRAY CODE INPUT (G3-G0) INTO A 4-BIT BINARY REPRESENTATION (B3-BO) FOR OUTPUT.


4-BIT GRAY CODE TO BCD CONVERTER



8-BIT PRIORITY ENCODER
MMI SANTA CLARA, CALIFORNIA
. ADD I0 Il I2 I3 I4 I5 I6 I7
.DAT S0 S1 S2 EN
```

SO = I7
+/I6* I5
+/I6*/I4* I3
+/I6*/I4*/I2* Il
Sl= I7
+ I6
+ /I5*/I4* I3
+/I5*/I4* I2
S2 = I7

```

    \(+I 6 \quad ; I 7-I 0=X 1 X X X X X X\)
    + I5 ; I7-I0 = XXIXXXXX
    + I4 \(\quad\); \(77-I 0=X X X I X X X X\)
EN
    \(=/ I 0^{*} / I 1 * / I 2 * / I 3^{*} / I 4^{*} / I 5^{*} / I 6^{*} / I 7\)
; ALL LOWS ENABLE NEXT PRIORITY ENCODER

FUNCTION TABLE

I7 I6 I5 I4 I3 I2 I1 I0 EN S2 Sl S0


\section*{8-BIT PRIORITY ENCODER (cont'd) \\ DESCRI PTION}

THIS 8-BIT PRIORITY ENCODER SCANS FOR THE FIRST HIGH INPUT LINE (I7-IO) FROM I7 (WHICH HAS THE HIGHEST PRIORITY) TO IO (WHICH HAS THE LOWEST PRIORITY). IT WILL GENERATE A BINARY ENCODED OUTPUT (S2-SO) WHICH WILL POINT TO THE HIGHEST PRIORITY INPUT WHICH IS AT A HIGH STATE.

IF NO INPUT LINES ARE HIGH (I7-IO=LOW), THEN THE BINARY ENCODED OUTPUTS WILL BE ZERO (S2-SO=LOW) AND THE ENABLE OUTPUT WILL BE HIGH (EN=HIGH) INDICATING A CARRY OUT TO THE NEXT PRIORITY ENCODER. THE OUTPUT ENABLE WILL BE LOW (EN=LOW) IF ANY OF THE INPUT LINES ARE HIGH.

THE PLE8P4 ALSO HAS THREE-STATE OUTPUTS WITH TWO ACTIVE-LOW OUTPUT ENABLE CONTROL PINS (/E1 AND /E2).

8-BIT PRIORITY ENCODER

PLE8P4


\section*{PLE8 P4}

PLE CIRCUIT DESIGN SPECIFICATION
P5011
ULRIK MUELLER 04/01/83
4-SIT MAGNITUDE COMPARATOR
MMI SANTA CLARA, CALIFORNIA
. ADD A0 A1 A2 A3 BO B1 B2 B3
- DAT EQ NE LT GT
```

EQ = A3:*:B3 * A2:*:B2 * Al:*:Bl * A0:*:B0 ; A = B

```


```

    + A3:*:B3 */A2 * B2 ; A2 LT B2
    +A3:*:B3 * A2:*:B2 */A1 * B1 ; Al LT B1
    + A3:*:B3 * A2:*:B2 * A1:*:B1 */A0 * B0 ; A0 LT B0
    GT =A3 */B3 ; A3 GT B3
+A3:*:B3 * A2 */B2 ; A2 GT B2
+A3:*:B3 * A2:*:B2 * Al */B1 Al GT B1
+ A3:*:B3 * A2:*:B2 * A1:*:B1 * AO */B0 ; AO GT BO

```

DESCRIPTION
THIS PLE8P4 COMPARES TWO 4-BIT NUMBERS (A3-A0 AND B3-B0) TO ESTABLISH IF THEY ARE EQUAL ( \(A=B\) THEN \(E Q=H\) ), NOT EQUAL ( \(A\) NOT \(=B\) THEN NE=H), LESS THAN (A LT B THEN LT=H), OR GREATER THAN (A GT B THEN GT=H) AND REPORTS THE COMPARISON STATUS ON THE OUTPUTS (EQ, NE, LT, GT) AS ILLUSTRATED IN THE OPERATIONS TABLE BELOW.

THE PLE8P4 ALSO FEATURES THREE-STATE OUTPUTS WITH TWO ACTIVE-LOW OUTPUT ENABLE CONTROL PINS (/E1 AND /E2).


\section*{4-BIT MAGNITUDE COMPARATOR}


Random Logic

\section*{PLE12 P4}

PLE CIRCUIT DESIGN SPECIFICATION
P5012 VINCENT COLI 10/16/83
6-BIT MAGNITUDE COMPARATOR
MMI SANTA CLARA, CALIFORNIA
. ADD A0 A1 A2 A3 A4 A5 B0 B1 B2 B3 B4 B5
. DAT EQ NE LT GT
\(E Q=A 5: *: B 5 * A 4: *: B 4 * A 3: *: B 3 * A 2: *: B 2 * A 1: *: B 1 * A 0: *: B 0 ; A=B\)
\(N E=A 5:+: B 5+A 4:+: B 4+A 3:+: B 3+A 2:+: B 2+A 1:+: B 1+A 0:+: B 0 ; A N O T=B\)


DESCRIPTION
THIS PLEL2P4 COMPARES TWO 6-BIT NUMBERS (A5-AO AND B5-B0) TO ESTABLISH IF THEY ARE EQUAL ( \(A=B\) THEN \(E Q=H\) ), NOT EQUAL (A NOT \(=B\) THEN NE=H), LESS THAN (A LT B THEN LT=H), OR GREATER THAN (A GT B THEN GT=H) AND REPORTS THE COMPARISON STATUS ON THE OUTPUTS (EQ, NE, LT, GT) AS ILLUSTRATED IN THE OPERATIONS TABLE BELOW.

THE PLEL2P4 ALSO FEATURES THREE-STATE OUTPUTS WITH TWO ACTIVE-LOW OUTPUT ENABLE CONTROL PINS (/E1 AND /E2).


4-BIT MAGNITUDE COMPARATOR WITH POLARITY CONTROL
MMI SANTA CLARA, CALIFORNIA
- ADD A0 A1 A2 A3 B0 B1 B2 B3 POL
. DAT EQ NE LT GT


\section*{DESCRIPTION}

THIS PLE9P4 COMPARES TWO 4-BIT NUMBERS (A3-A0 AND B3-B0) TO ESTABLISH IF THEY ARE EQUAL (A EQ B), NOT EQUAL (A NE B), LESS THAN (A LT B), OR GREATER THAN (A GT B). THE COMPARISON STATUS IS REPORTED WITH ACTIVE-HIGH POLARITY (EQ, NE, LT, GT) WHEN THE POLARITY CONTROL INPUT IS TRUE (POL=H) AND WITH ACTIVE-LOW POLARITY (/EQ, /NE, /LT, /GT) WHEN THE POLARITY CONTROL INPUT IS FALSE (POL=L).

THE PLE8P4 ALSO FEATURES THREE-STATE OUTPUTS WITH ONE ACTIVE-LOW OUTPUT ENABLE CONTROL PIN (/E).

OPERATIONS TABLE:


\footnotetext{
* COMPARISON STATUS WILL BE ACTIVE-LOW (I.E., /EQ, /NE, /LT,/GT) WHEN POL=L.
}


\section*{Block Diagram}


-bit barra shifter
.ADD D0 D1 D2 D3 D4 D5 D6 D7 S0 S1 S2
.DAT OO O1 O2 O3 O4 O5 O6 O7
mulmbat uis98밈
 2 manesici sookial


\(\square\)

\footnotetext{
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} -

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Memorles

\section*{8-BIT BARREL SHIFTER (cont'd)}

DESCRI PTTON

THE 8-BIT BARREL SHIFTER, IMPLEMENTED IN A PLEIIP8, ROTATES EIGHT BITS OF DATA (D7-D0) A NUMBER OF LOCATIONS INTO THE OUTPUTS (07-O0) AS SPECIFIED BY THE 3-BIT BINARY ENCODED SHIFT CONTROL LINE (S2-SO). THE THREE-STATE OUTPUTS ARE IN A HIGH-Z STATE WHEN ANY ONE OF THE TWO OUTPUT ENABLE PINS (/El OR /El) ARE HIGH.

A POSSIBLE UPGRADE VERSION OF THIS DESIGN IMPLEMENTED IN A PLE12P8 COULD INCLUDE A DIRECTION CONTROL LINE. THIS CONTROL LINE PERMITS THE 8-BIT BARREL SHIFTER TO ROTATE DATA IN EITHER DIRECTION (LEFT OR RIGHT).

8-BIT BARREL SHIFTER



```

PLEllP4
P5014
4-BIT RIGHT SHIFTER WITH PROGRAMMABLE OUTPUT POLARITY
MMI LTD., FARNBOROUGH, U.K.
.ADD S0 S1 INV D0 D1 D2 D3 D4 D5 D6 /EN
.DAT OO O1 O2 O3
OO = DO*/SO*/SI*/INV* EN
+/DO*/SO*/S1* INV* EN
+ Dl* SO*/Sl*/INV* EN
+/Dl* SO*/S1* INV* EN
+ D2*/SO* S1*/INV* EN
+/D2*/S0* S1* INV* EN
+ D3* SO* SI*/INV* EN
+/D3* S0* Sl* INV* EN
O1 = Dl*/S0*/S1*/INV* EN
+/D1*/SO*/S1* INV* EN
+ D2* SO*/S1*/INV* EN
+ /D2* SO*/Sl* INV* EN
+ D3*/S0* Sl*/INV* EN
+ /D3*/SO* Sl* INV* EN
+ D4* SO* Sl*/INV* EN
+/D4* S0* SI* INV* EN
O2 = D2*/S0*/S1*/INV* EN
+/D2*/S0*/Sl* INV* EN
+ D3* SO*/SI*/INV* EN
+ /D3* S0*/Sl* INV* EN
+ D4*/SO* Sl*/INV* EN
+ /D4*/SO* Sl* INV* EN
+ D5* S0* S1*/INV* EN
+ /D5* SO* Sl* INV* EN
O3 = D3*/SO*/Sl*/INV* EN
+/D3*/S0*/Sl* INV* EN
+ D4* S0*/Sl*/INV* EN
+/D4* S0*/Sl* INV* EN
+ D5*/S0* Sl*/INV* EN
+/D5*/S0* Sl* INV* EN
+ D6* SO* Sl*/INV* EN
+ /D6* SO* Sl* INV* EN
SELECT INPUT DO
SELECT INPUT /DO
; SELECT INPUT DI
; SELECT INPUT /D1
; SELECT INPUT D2
SELECT INPUT /D2
SELECT INPUT D3
SELECT INPUT /D3
SELECT INPUT DI
SELECT INPUT /DI
SELECT INPUT D2
; SELECT INPUT DO

```
    PLE CIRCUIT DESIGN SPECIFICATION
CHRIS JAY 05/30/84

\section*{4-BIT RIGHT SHIFTER WITH PROGRAMMABLE OUTPUT POLARITY (cont'd)}



\section*{4-BIT RIGHT SHIFTER WITH PROGRAMMABLE OUTPUT POLARITY (cont'd)}

DESCRIPTION

THIS PLEIIP4 IMPLEMENTS A 4-BIT RIGHT SHIFTER WITH PROGRAMMABLE OUTPUT POLARITY. THE SHIFTER CAN RIGHT SHIFT SEVEN BITS OF DATA, FOUR BITS AT A TIME. THE SEVEN DATA INPUTS (D6-DO) ARE SHIFTED 0, 1, 2 , OR 3 LOCATIONS AS DETERMINED BY THE 2-BIT SHIFT CONTROL LINE (Sl-SO). THE SHIFTED DATA IS THEN DIRECTED TO THE FOUR OUTPUTS (O3-OO).

THE OUTPUT DATA IS NONINVERTED ( \(O=D\) ) WHEN INV=L AND INVERTED ( \(O=/ D\) ) WHEN INV=H. THE OUTPUTS ARE FORCED LOW ( \(O=L\) ) WHEN /EN=H REGARDLESS OF OTHER INPUTS. THE PLELIP4 ALSO FEATURES THREE-STATE OUTPUTS WITH ONE ACTIVE LOW OUTPUT ENABLE (/E).

A POSSIBLE UPGRADE VERSION OF THIS DESIGN IMPLEMENTED IN A PLE12P4 COULD INCLUDE A DIRECTION CONTROL LINE. THIS CONTROL LINE PERMITS THE 4-BIT RIGHT SHIFTER TO SHIFT DATA IN EITHER DIRECTION (LEFT OR RIGHT).

OPERATIONS TABLE:
\begin{tabular}{llllllll} 
/EN & INV & Sl-S0 & D6-D0 & O3-OD & OPERATION & \\
\hdashline\(H\) & \(X\) & \(X\) & \(X\) & \(L\) & DISABLE OUTPUTS LOW & & \\
L & L & N & D & SHIFT(D) & SHIFT NONINVERTED DATA "N" PLACES \\
L & \(H\) & N & D & SHIFT(/D) & SHIFT & INVERTED DATA "N" PLACES
\end{tabular}

PLE8P8
P5015
8-BIT TWO'S COMPLEMENT CONVERSION
MMI BREA, CALIFORNIA
•ADD D0 D1 D2 D3 D4 D5 D6 D7
•DAT Y0 Y1 Y2 Y3 Y4 Y5 Y6 Y7

FUNCTION TABLE
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|}
\hline 1 & L & L & L & L & L & L & L & L & L & L & L & L & L & L & L & & 0 \\
\hline \(L\) & L & L & L & L & \(L\) & L & H & H & H & H & H & H & H & H & H & & 1 \\
\hline 1 & \(L\) & L & L & L & L & H & H & H & H & H & H & H & H & L & H & & 3 \\
\hline \(L\) & L & L & L & L & H & H & H & H & H & H & H & H & L & L & H & & 7 \\
\hline L & L & L & L & H & H & H & H & H & H & H & H & L & L & \(L\) & H & & 15 \\
\hline L & L & L & H & H & H & H & H & H & H & H & L & L & L & L & H & & 31 \\
\hline \(L\) & L & H & H & H & H & H & H & H & H & L & L & L & L & L & H & & 63 \\
\hline L & H & H & H & H & H & H & H & H & L & \(L\) & L & L & L & L & H & & 127 \\
\hline H & H & H & H & H & H & H & H & L & L & L & L & L & L & L & L & & 255 \\
\hline H & H & H & H & H & H & H & L & L & L & L & L & L & L & H & L & & 254 \\
\hline H & H & H & H & H & H & \(L\) & L & L & \(L\) & L & L & L & H & \(L\) & L & & 252 \\
\hline H & H & H & H & H & L & L & L & L & L & L & L & H & L & L & L & & 248 \\
\hline H & H & H & H & \(L\) & L & L & L & L & \(L\) & L & H & L & L & \(L\) & L & & 240 \\
\hline H & H & H & \(L\) & \(L\) & L & \(L\) & \(L\) & \(L\) & L & H & L & L & \(L\) & L & L & & 224 \\
\hline H & H & L & L & L & L & L & L & L & H & L & L & L & \(L\) & L & L & & 192 \\
\hline H & L & L & L & L & L & L & L & H & L & L & L & L & L & L & L & & 128 \\
\hline
\end{tabular}


\section*{8-BIT TWO'S COMPLEMENT CONVERSION (cont'd)}

DESCRIPTION

THIS PLE8P8 CONVERTS AN 8-BIT BINARY NUMBER (D7-DO) INTO TWO'S COMPLEMENT REPRESENTATION (Y7-Y0) WHERE D7 AND Y7 ARE THE MSB AND DO AND YO ARE THE LSB. TWO'S COMPLEMENT REPRESENTATION IS USED IN SIGNED ARITHMETIC SYSTEMS.



TIMING GENERATOR FOR PAL PROGRAMMING (cont'd)

FUNCTION TABLE

\section*{A4 A3 A2 A1 A0 NA4 NA3 NA2 NA1 NAO TIALR TVCC TO}



TIMING GENERATOR FOR PAL PROGRAMMING (cont'd)
DESCRIPTION

THIS LOGIC SPECIFICATION IS A TIMING SIGNAL GENERATOR TO BE USED FOR ARRAY PROGRAMMING OF PAL DEVICES. A PLE5P8 FOLLOWED BY AN 8-BIT REGISTER ARE USED TO IMPLEMENT THIS FUNCTION.

THE PLE CONTAINS BOTH 5-BIT NEXT ADDRESS AND 3-BIT WAVEFORMS. TIALR OUTPUT IS A TIMING WAVEFORM FOR I, A, AND L/R SIGNALS, AND TVCC AND TO OUTPUTS ARE USED FOR VCC AND O SIGNALS, RESPECTIVELY.

THE SCHEMATIC IS AS FOLLOWS:


APPLYING 200 KHz CLOCK SIGNAL TO THE CLK INPUT OF THE REGISTER GENERATES THE FOLLOWING TIMINGS:
1. \(I, A, A N D L / R\) WIDTH
2. tD2

50 usec
3. \(t D\)

20 usec
4. tVCCP
: 5 usec
30 usec
5. TP
: 20 usec
BECAUSE THE TIMING PATTERNS ARE STORED IN THE PROM, WE CAN EASILY CALIBRATE THE RELATIONS AND THE PERIOD AMONG THOSE SIGNALS TO MAKE AN OPTIMUM CONDITION.

A PORTION OF A
TIMING GENERATOR FOR
PAL LOGIC CIRCUIT ARRAY PROGRAMMING
PLE5P8

\begin{tabular}{lll}
\hline PLESP8 & & \\
P5028 \\
TIMING GENERATOR FOR PAL
\end{tabular}


THIS LOGIC SPECIFICATION IS A TIMING SIGNAL GENERATOR TO BE USED FOR SECURITY FUSE PROGRAMMING OF PAL DEVICES. A PLE5P8 FOLLOWED BY AN 8-BIT REGISTER ARE USED TO IMPLEMENT THIS FUNCTION.

THE PLE LOGIC CIRCUIT CONTAINS TWO FUNCTIONS IN THE SINGLE CHIP. THE FIRST FUNCTION IS A UNIQUE COUNTER USED FOR NEXT ADDRESS GENERATION. THE COUNTER INCREMENTS UP TO COUNT-21 AND THEN LOCKS UP THE INCREMENTAL OPERATION AT COUNT-22. THE SECOND FUNCTION IS A TIMING GENERATOR USED FOR DEFINING TIMING RELATIONSHIP AMOUNG VCC, PO1, AND Pll SIGNALS.

THE SCHEMATIC IS AS FOLLOWS:


THIS LOGIC OUTPUTS A SEQUENCE OF TIMING PATTERNS DURING THE INCREMENTAL OPERATION AND THEN HOLDS ALL OUTPUTS LOW UNTIL A RESET SIGNAL FOR THE 8-BIT REGISTER IS APPLIED.

APPLYING 200 KHz CLOCK SIGNAL TO THE CLK INPUT OF THE REGISTER, THE FOLLOWING TIMINGS ARE GENERATED:
\begin{tabular}{ll} 
1. VCC WIDTH & : 95 usec \\
2. TPP & : 40 usec \\
3. tD & \(: 5\) usec
\end{tabular}

BY APPLYING THIS DESIGN METHOD, WE CAN EASILY GENERATE A SEQUENCE OF UNIQUELY DEFINED PATTERNS EACH TIME THE RESET PULSE IS APPLIED.

\section*{TIMING GENERATOR FOR PAL} SECURITY FUSE PROGRAMMING


\section*{Fast Arithmetic Look-up}

In performing arithmetic operations like trigonometric functions, multiplications and division, in order to reduce the delay, look-up tables are often used.

\section*{Sine Look-up}

For trigonometric functions like sine function, it is very timeconsuming to generate the function using the polynomial which represents the function. PLE devices can provide a very good alternative for sine look-up. An example is to use a 2 Kx 8 PLE device to do a sine look-up of an 11-bit input to 8 -bit sine outputs.
Since sine function has the following property: \(\sin (x)=\sin (\pi-x)\) \(=-\sin (\pi+x)=-\sin (2 \pi-x)=\sin (2 \pi+x)\), what is needed is just the sine function for \(0<x<\pi / 2\); the rest can be easily calculated using the above relations. In order to fully utilize the dynamic range, the inputs of the sine look-up PLE device should be normalized to \((\pi / 2) /\left(2^{n}\right)=\pi /\left[2^{n+1}\right]\) where \(n\) is the number of address lines to the device.

Since \(n\) is fixed for the PLE device chosen, and \(\pi\) is a constant, for the look-up table \(\pi /\left[2^{n+1}\right]\) is a constant. Therefore, if the sine function of a given \(x\) is to be found, \(x\) will first be multiplied by the constant \(\left[2^{n+1}\right] / \pi\) and sent to the address of the PLE device to get the final result.
\(\operatorname{Cos}(x)\) is related to sine function as \(\sin (\pi / 2-x)\). Thus the cosine function can also be found in the same manner by using \(\pi / 2-x\) instead of just \(x\). Other functions like tangent, secant etc., can also be found as a function of sine.
To increase the dynamic range of outputs, we can just use another PLE device to generate the less-significant bits of the sine function.

If a larger dynamic range is needed for the inputs, the result may be approximated using the Taylor series:
\[
f(X)=f(X 0)+f^{\prime}(X 0)(X-X 0)+1 / 2 f^{\prime \prime}(X 0)(X-X 0)^{2}+\ldots
\]
where \(f^{\prime}\) and \(f^{\prime \prime}\) are the first and second derivations of \(f\). Since \(X 0\) by itself represents a resolution of \(2^{-n}\), and X is XO concatenated with the rest of the bits, \(X-X 0\) must lie between 0 and \(1 / 2^{-n}\). For \(f(X)=\sin (X)\),
\(f(X 0)=\sin (X 0)\)
\(\mathrm{f}^{\prime}(\mathrm{XO})=\cos (\mathrm{XO})\)
and \(\mathrm{f}^{\prime \prime}(\mathrm{XO})=-\sin (\mathrm{XO})\)
So \(f^{\prime \prime}(X O)\) is between -1 and 0 for \(X 0\) lies between 0 and \(\pi / 2\) and \(X-X 0<2^{-n}\). Therefore, the last term will be between \(1 / 2^{n}\) and 0 , and as long as we do not want to expand the dynamic range of \(X\) beyond \(2 n\)-bits, it should be sufficient to approximate \(\sin (X)\) in the first two terms:
\(\sin (X)+\sin \left(X_{0}\right)+\cos (X 0)(X-X 0)\)

Since \(X-X 0\) is represented by only the bits after the more significant \(n\)-bits, and \(\cos (X 0)=\sin (\pi / 2-X 0)\), the implementation will be very simple.

\section*{Division}

Division will normally be much slower than multiplication. There are several ways to perform division. Bit-by-bit division restoring and nonrestoring algorithms are generally very slow. Another way is to use several bits at a time division which is faster than the previous methods. A third way is to multiply the dividend by the inverse of the divisor. The inverse of the divisor can be found by getting an approximation followed by iterations.

The approximation is again given by the Taylor series:
```

$f(X)=f(X 0)+f^{\prime}(X 0)(X-X 0)+1 / 2 f^{\prime \prime}(X 0)(X-X 0)^{2}+.$.
and $f(X 0)=1 / X 0$
$f^{\prime}(X 0)=-1 / X 0^{2}$
$f^{\prime \prime}(X 0)=2 / X 0^{3}$

```

Say \(\mathrm{X0}\) is 8 -bits long and the first approximation of the inverse is found using a \(256 \times 8\) PLE device. The first approximation can be obtained by subtracting \((X-X 0) /\left(X O^{2}\right)\). Since the first approximation is limited by an error of approximately \((X-X 0)^{2} / X 0^{2}\), and if \(X 0\) at least 1 , the error is limited by approximately \((X-X 0)^{2}\) Since XO has an 8 -bit resolution, \(\mathrm{X}-\mathrm{XO}\) is represented by the rest of the bits. The resolution of the second approximation will be about 16 bits. The third approximation is similarly deduced and has a resolution of about 32 bits, and the fourth has a resolution of about 64 bits.
The inverse thus obtained is then multiplied by the dividend to give the quotient.

\section*{Scaling}

In arithmetic operations, scaling is sometimes needed. Scaling normally involves multiplication or division by a constant. If this constant can be expressed in \(2^{n}\) where n is an integer, then scaling is simply shifting. Scaling with other constants may need a multiplier. A multiplier is more expensive and has a higher pin count than using a PLE device because the constant that the operand is to be scaled by is not required as an input as in the case of a multiplier. This will tremendously reduce the overhead for data scaling.

\section*{Other Applications}

Arithmetic look-up are also very useful for arithmetic operations where conventional binary integral arithmetic is not applicable -like residue arithmetic, and distributed arithmetic.

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```

PLE8P8 PLE CIRCUIT DESIGN SPECIFICATION

```
P5018
VINCENT COLI 12/08/82
4-BIT MULTIPLIER LOOR-UP TABLE
MMI SANTA CLARA, CALIFORNIA
. ADD X0 X1 X2 X3 Y0 Y1 Y2 Y3
.DAT S0 S1 S2 S3 S4 S5 S6 S7
\(\mathrm{S} 7, \mathrm{~S} 6, \mathrm{~S} 5, \mathrm{~S} 4, \mathrm{~S} 3, \mathrm{~S} 2, \mathrm{~S} 1, \mathrm{~S} 0=\mathrm{X} 3, \mathrm{X} 2, \mathrm{X} 1, \mathrm{X} 0\).*. \(\mathrm{Y} 3, \mathrm{Y} 2, \mathrm{Y} 1, \mathrm{Y} 0 \quad ; \mathrm{S}=\mathrm{X} * \mathrm{Y}\)
FUNCTION TABLE
X3 X2 X1 X0 Y3 Y2 Y1 Y0 S7 S6 S5 S4 S3 S2 S1 S0
\begin{tabular}{|c|c|c|c|c|}
\hline \multicolumn{2}{|l|}{;-OPERANDS-} & \multirow[t]{2}{*}{PRODUCTS} & \multicolumn{2}{|l|}{\multirow[b]{2}{*}{COMMENTS}} \\
\hline ; XXXX & YYYY & & & \\
\hline ; 3210 & 3210 & 76543210 & & \\
\hline LLLL & LLLL & LLLLLLLL & 0 * 0 & 0 \\
\hline LLLH & सHHH & LLLLHHHH & 1 * 15 & \(=15\) \\
\hline HHHH & LLLH & LLLLHHHH & 15 * 1 & \(=15\) \\
\hline HHHH & HHHH & HHHLLLLH & 15 * 15 & \(=225\) \\
\hline
\end{tabular}

DESCRI PTION
THIS PLE8P8 PERFORMS 4-BIT LOOK-UP TABLE MULTIPLICATION. THE DEVICE ACCEPTS TWO 4-BIT OPERANDS (X3-X0 AND Y3-Y0) TO PRODUCE THE 8-BIT PRODUCT (S7-S0). THE PLE8P8 ALSO HAS THREE-STATE OUTPUTS WITH TWO ACTIVE-LOW OUTPUT ENABLE CONTROL PINS (/E1 AND /E2).



FUNCTION TABLE



DESCRIPTION
THIS APPLICATION ILLUSTRATES THE CALCULATION OF THE ARC TANGENT FUNCTION USING A PLE5P8 AS A LOOK-UP TABLE. OTHER TRIGONOMETRIC FUNCTIONS (SUCH AS SINE, COSINE, COTANGENT, SECANT, COSECANT AND THEIR ARC INVERSE EQUIVALENT FUNCTIONS) OR HYPERBOLIC FUNCTIONS CAN ALSO BE CONSTRUCTED USING PLE DEVICES AS LOOK-UP TABLES.
\(F=\operatorname{ARCTAN}(A) \quad\) WHERE \(F=\) ARC TANGENT OF A
\(A=\) ANGLE IN RADIANS
EXAMPLE: FOR \(A=5, F=\operatorname{ARCTAN}(5)=1.3672\)
A PLE JEVICE WITH MORE INPUTS, SUCH AS THE PLEIIP8, SHOULD BE USED TO CONSTRUCT A LOOK-UP TABLE WHEN ADDITIONAL ACCURACY IS REQUIRED.


ARC TANGENT LOOK-UP TABLE PLE5P8


HYPOTENUSE OF A RIGHT TRIANGLE LOOK-UP TABLE MMI GMBH MUNICH
. ADD AO Al BO B1 B2
.DAT C0 C1 C2 C3 C4 C5 C6 C7 Suveras

```

[ COMPUTE DIGIT FOR 2EXP-5 (0.03125) (LSB)

```
\(C 0=A 0 * / B 2 * B 1\)
    \(+/ A 1 * A 0 * B 2 * / B 1\)
    + A1* \(/ B 2\) * B0
    \(+\mathrm{Al*} / \mathrm{B} 2 * \mathrm{Bl}\)
    \(+A 1 * / A 0 * B 2 * / B 1 * / B 0\)
    \(+\mathrm{Al*} A 0^{*} \mathrm{Bl} * \mathrm{BO}\)
    +A 0 */B2* B 0
\(\mathrm{Cl}=\mathrm{A} 0^{*} \quad \mathrm{Bl} * / \mathrm{BO}\)
; COMPUTE DIGIT FOR 2EXP-4
(0.0625)
    \(+/ A 1 * A 0\) * \(B 2\)
    \(+A 1 * / A 0^{*} / B 2\) * \(B 0\)
    \(+\mathrm{Al*} / \mathrm{A} 0 * \mathrm{~B} 2 * / \mathrm{B} 0\)
    \(+A 0^{*} B 2\) * \(B 0\)
    +Al * \(\mathrm{A} 0^{*} \mathrm{Bl}\)
\(C 2=A 0 * / B 2 * \quad B 0\)
    ; COMPUTE DIGIT FOR 2EXP-3 (0.125)
    \(+/ A 1 * A 0^{*} / B 2 * B l\)
    \(+A 1 * / A 0^{*} B 2 * / B 1\)
    + A1* A0* B2* Bl
    \(+\mathrm{Al*} / \mathrm{B} 2 * / \mathrm{Bl} * \mathrm{~B} 0\)
\(C 3=/ A 1 * A 0 * / B 2 * / B 1 * B 0\)
    ; COMPUTE DIGIT FOR 2EXP-2 (0.25)
    \(+A 1 * / A 0^{*} \quad B 1 * / B 0\)
    \(+A 1 * / A 0 * B 2\)
    \(+\mathrm{Al*} \mathrm{~B} 2\) * B0
\(C 4=A 1 * / A 0 * / B 2 * B 1\); COMPUTE DIGIT FOR 2EXP-1 (0.5)
    \(+A 1 * A 0^{*} B 2 * / B 1 * B 0\)
    \(+\mathrm{Al*} \mathrm{~A} 0\) * Bl */B0
\(\mathrm{C} 5=/ \mathrm{Al} * \quad \mathrm{BO} \quad\); COMPUTE DIGIT FOR 2EXPO (1)
    \(+A 0 * / B 2 * / B 1\)
B0
    32* B0
    \(+A 1 * A 0 * / B 2 * / B 0\)
    \(+A 1 * A 0^{*} / B 1\)
\(\mathrm{C} 6=/ \mathrm{Al}\) * B1 ; COMPUTE DIGIT FOR 2EXPI (2)


8-48


\section*{}

\section*{HYPOTENUSE OF A RIGHT} TRIANGLE LOOK-UP TABLE

 DESCRI PTION
```

THE GENERATION OF COMPLEX ARITHMETIC FUNCTIONS SUCH AS THE PYTHAGOREAN
THEOREM IS GENERALLY VERY DIFFICULT TO IMPLEMENT DIRECTLY IN HARDWARE.
HOWEVER, IMPLEMENTING THE FUNCTION AS A LOOK-UP TABLE USING A PLE GREATLY
SIMPLIFIES THE PROBLEM.
THIS EXAMPLE ILLUSTRATES HOW TO IMPLEMENT A LOOK-UP TABLE IN A PLE5P8 WHICH CALCULATES THE LENGTH OF THE HYPOTENUSE OF A RIGHT TRIANGLE AS A FUNCTION OF THE LENGTH OF THE TWO REMAINING SIDES OF THE TRIANGLE. THE THEOREM OF PATHAGOREAN STATES THAT THE LENGTH OF THE HYPOTENUSE OF A RIGHT TRIANGLE I EQUAL TO THE SQUARE ROOT OF THE SUM OF THE SQUARE OF THE OTHER TWO SIDES OR $C=\operatorname{SQRT}(A * * 2+B * * 2)$. THE INPUTS, "A" AND "B", CORRESPOND TO THE SIDES ADJACENT TO THE RIGHT ANGLE (I.E. 90 DEGREE ANGLE), WHILE THE OUTPUT, "C", CORRESPONDS TO THE SIDE OPPOSITE TO THE RIGHT ANGLE WHICH IS CALLED THE

``` HYPOTENUSE.
\(C=S Q R T(A * * 2+B * * 2) \quad\) WHERE \(C=\) LENGTH OF SIDE C (THE HYPOTENUSE)
\(A=\) LENGTH OF SIDE A
\(B=\) LENGTH OF SIDE B

EXAMPLE: FOR \(A=2\) AND \(B=4, C=\operatorname{SQRT}(2 * * 2+4 * * 2)=4.47\)




PERIMETER OF A CIRCLE LOOK-UP TABLE (cont'd)


8-52

PERIMETER OF A CIRCLE LOOK-UP TABLE (cont'd)
DESCRIPTION

THIS EXAMPLE ILLUSTRATES HOW TO IMPLEMENT A LOOK-UP TABLE IN A PLE5P8 FOR THE PERIMETER OF A CIRCLE AS A FUNCTION OF THE RADIUS. THE INPUT PINS (R4-RO) WHICH REPRESENT THE RADIUS OF A CIRCLE, ARE MULTIPLIED BY 2 TIMES PI IN ORDER TO CALCULATE THE PERIMETER OF A CIRCLE (P7-PO). THIS LOOK-UP TABLE IS VALID FOR RADII BETWEEN 0 AND 31. A PLE8P8 SHOULD BE USED INSTEAD IF A LARGER RADIUS RANGE (BETWEEN 0 AND 81) IS REQUIRED.
```

WHERE P = PERIMETER OF THE CIRCLE

```
    \(P I=3.1415\)
    \(\mathrm{R}=\) RADIUS OF THE CIRCLE (BETWEEN 0 AND 31)
EXAMPLE: FOR \(R=3, \mathrm{P}=2 * \mathrm{PI} * 3=19\)




PERIOD OF OSCILLATION FOR A MATHEMATICAL PENDULUM LOOK-UP TABLE MMI GMBH MUNICH
. ADD L0 Ll L2 L3 L4 . DAT TO T1 T2 T3 T4 T5 T6 T7

TO = /L4* /L2*/Ll* LO ; COMPUTE DIGIT FOR 2EXP-5 (0.03125) (LSB)
\(+\quad / \mathrm{L} 3 * / \mathrm{L} 2 * \mathrm{Ll} * / \mathrm{L} 0\)
\(+\quad \mathrm{L} 3 * / \mathrm{L} 2 * \mathrm{~L} 0\)
+/L4* L2*/Ll*/LO
+ L4* L3* LO
\(+\mathrm{L} 4 * / \mathrm{L} 3 * \mathrm{Ll}\)
\(+\mathrm{L} 4 * / \mathrm{L} 3 * \mathrm{~L} 2 * / \mathrm{LO}\)
Tl \(=\) /L2* L1*/LO ; COMPUTE DIGIT FOR 2EXP-4 (0.0625)
+ /L4*/L3* L2* LO
+/L4* L3*/L2* Ll
+/L4* L2*/L1*/LO
+ L4*/L3*/L2* Ll
\(+\quad / \mathrm{L} 3 *\) L2*/L1
+ L4* L3* /L1* L0
\(+\mathrm{L} 4 * \mathrm{~L} 3 * \mathrm{Ll}\) */LO
\(T 2=/ L 4 * / L 3 * \quad L 1 * / L 0\)
; COMPUTE DIGIT FOR 2EXP-3 (0.125)
+ /L4* L3*/L2* LO
+ L4*/L3*/L2*/L1*/LO
+ L4*/L3* Ll* LO
\(+\mathrm{L} 4 * \mathrm{~L} 3 * / \mathrm{L} 2 * \mathrm{Ll}\) */LO
+ L4* L3* L2*/L1
\(+\mathrm{L4*} \mathrm{~L} 2\) * L0
+ /L4*/L3* /L1* L0
+/L4*/L3* L2* /LO
\(T 3=/ L 4 *\) L3* L1* LO
; COMPUTE DIGIT FOR 2EXP-2 (0.25)
L4*/L3* L1
+ L4* L3* L2*/L1
\(+\quad / \mathrm{L} 3 * / \mathrm{L} 2 * / \mathrm{L} 1 *\) L0
\(+\quad / \mathrm{L} 3 * \mathrm{~L} 2 * \mathrm{Ll}\) * L0
\(+\quad \mathrm{L} 3 * / \mathrm{L} 2 * \mathrm{Ll} * \mathrm{LO}\)
\(+\quad \mathrm{L} 3 * \mathrm{~L} 2 * / \mathrm{L} 1 * \mathrm{~L} 0\)
+ /L4* L2*/L1* L0
T4 = /L4*/L3* Ll*/LO ; COMPUTE DIGIT FOR 2EXP-1 (0.5)
+ /L3* L2* Ll
+ /L4* L3* L2*/L1
+ L4*/L3* L2
+ L4* L2* Ll
\(+\quad \mathrm{L2}\) * L1*/LO
```

        +/L4* LL*/L2*/Ll}/\textrm{LO
        L3*/L2 LLI
    L4* L3
    T6 = /L4* /L2* Ll* L0
COMPUTE DIGIT FOR 2EXPI
(2)
/LO
+/L4* L3*
+/L4*/L3* L2
+/L4*/L3* /Ll
T7 = L3* L2* Ll* LO
; COMPUTE DIGIT FOR 2EXP2
(4) (MSB)

```

\section*{FUNCTION TABLE}
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|c|}
\hline \multicolumn{5}{|l|}{\[
\begin{aligned}
& \text {;--AMPLITUDE-- } \\
& \text {; INTEGER }
\end{aligned}
\]} & \multicolumn{11}{|l|}{--PERIOD OF OSCILLATION--} \\
\hline L4 & L3 & L2 & Ll & L0 & T7 & T6 & T5 & T4 & T3 & T2 & T1 & T0 & LI' & LOOK-UP & CALCULATED \\
\hline L & L & L & L & L & L & L & H & L & L & L & L & L & 1 & 2.0000 & 2.0050 \\
\hline L & L & L & L & H & L & L & H & L & H & H & L & H & 2 & 2.8125 & 2.8356 \\
\hline L & L & L & H & L & L & L & H & H & L & H & H & H & 3 & 3.4375 & 3.4728 \\
\hline L & L & H & L & L & L & H & L & L & L & H & H & H & 5 & 4.4375 & 4.4834 \\
\hline L & H & L & L & L & L & H & H & L & L & L & \(L\) & L & 9 & 6.0000 & 6.0151 \\
\hline H & L & L & L & L & H & L & L & L & L & H & \(L\) & L & 17 & 8.2500 & 8.2670 \\
\hline H & H & H & H & H & H & L & H & H & L & H & L & H & 32 & 11.3125 & 11.3423 \\
\hline
\end{tabular}

 DESCRIPTION

THIS PLE5P8 IS USED TO IMPLEMENT A LOOK-UP TABLE FOR THE PERIOD OF OSCILLATION OF A MATHEMATICAL PENDULUM. THE PERIOD OF OSCILLATION FOR MATHEMATICAL PENDULUM (T) IS DEPENDENT UPON ITS AMPLITUDE OF SWING (L) AND THE ACCELERATION DUE TO GRAVITY (G). THE PERIOD OF OSCILLATION IS CALCULATED USING THE FOLLOWING EQUATION:
\(T=2 * P I * S Q R T(L / G) \quad\) WHERE \(T=\) PERIOD OF OSCILLATION IN SECONDS
\(P I=3.14\)
L = AMPLITUDE OF SWING IN METERS
\(\mathrm{G}=\) ACCELERATION DUE TO GRAVITY IN M/S/S ( \(9.81 \mathrm{M} / \mathrm{S} / \mathrm{S}\) )

EXAMPLE: FOR L \(=5, \mathrm{~T}=2 * \mathrm{PI} * \operatorname{SQRT}(5 / \mathrm{G})=4.4375\)
A PLE DEVICE WITH 5 INPUTS CAN BE USED TO CALCULATE THE PERIOD OF OSCILLATION FOR AMPLITUDES UP TO \(L=32\) METERS. PLE DEVICE WITH MORE INPUTS SHOULD BE USED TO CALCULATE LARGER PERIODS OF OSCILLATION.

THIS EXAMPLE DEMONSTRATES HOW EASY IT IS TO CONSTRUCT LOOK-UP TABLES FOR COMPLEX ARITHMETIC FUNCTIONS USING PLE DEVICES


PLE12 P8
P5017
ARITHMEIIC LOGIC UNIT
MMI SANTA CLARA, CALIFORNIA
. ADD A3 A2 Al A0 B3 B2 B1 B0 CIN I2 Il I0
- DAT C3 C2 Cl CO Z V C
```

;************************************************
;* THIS DESIGN IS NOT YET SUPPORTED BY PLEASM *
;************************************************
C,C3,C2,Cl,C0 =/S2*/S1* S0*/A3,/A2,/A1,/A0
.+. B3, B2, B1, BO.+. CIN
+/S2*S1*/S0* A3, A2, A1, A0
.+./B3,/B2,/B1,/BO.+. CIN
+/S2* S1* S0* A3, A2, A1, A0
.+. B3, B2, B1, BO.+. CIN
+ S2*/S1*/SO*/A3,/A2,/A1,/A0
:*: B3, B2, B1, B0
+ S2*/S1* S0* A3, A2, Al, A0
+ S2*/S1* S0* B3, B2, B1, BO
+ S2* S1*/S0* A3, A2, Al, A0
* B3, B2, B1, B0
+ S2* S1* S0
V = C:+: C3 ;OVERFLOW
Z =/ C3*/C2*/C1*/C0
;B-A - 1 + CIN
;A - B - 1 + CIN
;A+B+CIN
;A XOR B
;A + B
;A * B
; PRESET
; ZERO

```
PLE CIRCUIT DESIGN SPECIFICATION
                                    FRANK LEE 10/14/83

DESCRI PTION

THIS ALU CAN PERFORM 8 FUNCTIONS ON TWO 4-BIT OPERANDS A (A3-AO) AND B (B3-B0) WITH CARRYIN (CIN) AND GIVES A 4-BIT RESULT C (C3-C0) WITH CARRYOUT ( \(C\) ). IT WILL ALSO GIVE STATUS AS OVERFLOW ( \(V\) ) AND ZERO ( \(Z\) ).
THE FUNCTION IS DETERMINED BY A 3-BIT FUNCTION SELECT CODE (S2-SO):
\begin{tabular}{l|llll} 
MODE & S2 S1 SO FUNCTION \\
\hline 0 & 0 & 0 & 0 & CLEAR \\
1 & 0 & 0 & 1 & B \(-A-1+\) CIN \\
2 & 0 & 1 & 0 & A \(-\mathrm{B}-1+\) CIN \\
3 & 0 & 1 & 1 & A + B + CIN \\
4 & 1 & 0 & 0 & A XOR B \\
5 & 1 & 0 & 1 & A + B \\
6 & 1 & 1 & 0 & A \(*\) B \\
7 & 1 & 1 & 1 & PRESET \\
\hline
\end{tabular}

ARITHMETIC LOGIC UNIT


\title{
をavanoor sal ymas:
}

\section*{Wallace Tree Compression}

In performing arithmetic calculations, it may happen that more than two numbers are to be added together. Adding two numbers can be achieved by using a simple adder. If there are more than two numbers to be summed, several levels of adders may be needed. This often causes too much delay.
An alternative is to use Wallace Tree Compression. Suppose there are m numbers each of \(n\)-bits wide. Summation over these numbers will range from 0 to \(m \times\left(2^{n}-1\right)\) which will take \(\log _{2}\left[m\left(2^{n}-1\right)+1\right]\) bits (rounded UP to the nearest integer). For example, if there are five 2-bit numbers, i.e., \(m=5\), and \(n=2\), the sum will be bounded by \(5 \times\left(2^{2}-1\right)=15\) which will need a total of 4 bits.
One Wallace Tree Compression by itself will not be very useful. But consider if five 8-bit integers are added together. This technique enables vertical compression of these numbers in four groups. This type of vertical compression also eliminates the need of carry propagation. The five numbers are represented by:
\[
\begin{aligned}
& A=(a 7, a 6, a 5, a 4, a 3, a 2, a 1, a 0) \\
& B=(b 7, b 6, b 5, b 4, b 3, b 2, b 1, b 0) \\
& C=(c 7, c 6, c 5, c 4, c 3, c 2, c 1, c 0) \\
& D=(d 7, d 6, d 5, d 4, d 3, d 2, d 1, d 0) \\
& E=(e 7, e 6, e 5, e 4, e 3, e 2, e 1, e 0)
\end{aligned}
\]

The groups are assigned as follows:
G1 : (a0, a1, b0, b1, c0, c1, d0, d1, e0, e1)
G2 : (a2, a3, b2, b3, c2, c3, d2, d3, e2, e3)
G3 : (a4, a5, b4, b5, c4, c5, d4, d5, e4, e5)
G4: ( \(a 6, a 7, b 6, b 7, c 6, c 7, d 6, d 7, e 6, e 7)\)
The above groups of bits can be compressed to:
\(H 1:\left(h 1_{3}, h 1_{2}, h 1_{1}, h 1_{0}\right)\)
H 2 : \(\left(\mathrm{h} 2_{3}, \mathrm{~h} 2_{2}, \mathrm{~h} 2_{1}, \mathrm{~h} 2_{0}\right)\)
H3 : (h3 \(\left.{ }_{3}, h 3_{2}, h 3_{1}, h 3_{0}\right)\)
\(H 4:\left(h 4_{3}, h 4_{2}, h 4_{1}, h 4_{0}\right)\)
where the \(7^{\text {th }}\) bits are the most significant; the calculation is as follows:


S 1 and S 0 are just h 11 and \(\mathrm{h} 10 . \mathrm{S} 10-\mathrm{S} 2\) can be obtained through addition of other bits. The hardware implementation is a follows:

It needs four PLE10P4 devices, two 74S381 ALUs and one 74S182. An alternative is using ten 74S381 ALUs and four 74S182 Carry Lookahead Generators.




A comparison between the two architectures gives the following data:
\begin{tabular}{|l|c|c|}
\hline & \begin{tabular}{c} 
USING WALLACE \\
TREE COMPRESSION
\end{tabular} & \begin{tabular}{c} 
USING CONVENTIONAL \\
ARITHMETIC LOGIC
\end{tabular} \\
\hline \hline Delay (ns) & 79 & 115 \\
\hline Number of components & 7 & 14 \\
\hline Total number pins on the parts & 128 & 264 \\
\hline
\end{tabular}

Since Wallace tree compression can be of any configuration, there is no predefined part available. A PLE device provides an excellent solution. The designer may define his own configuration as long as it can be put in a commercially available PLE device.

SEVEN I-BIT INTEGER ROW PARTIAL PRODUCTS ADDER MMI SANTA CLARA, CALIFORNIA


DESCRI PTION
THIS PLE8P4 PERFORMS PARTIAL PRODUCTS REDUCTION FOR WALLACE TREE COMPRESSION. SEVEN ROWS OF l-BIT NUMBERS (A, B, C, D, E, F, AND G) ARE NUMERICALLY SUMMED TO PRODUCE A 3-BIT RESULT (P2-PO).


FIVE 2-BIT INTEGER ROW PARTIAL PRODUCTS ADDER
MMI SANTA CLARA, CALIFORNIA
. ADD AO A1 BO Bl CO Cl DO Dl EO El
.DAT P0 P1 P2 P3
\(P 3, P 2, P 1, P 0=A 1, A 0\). +. \(B 1, B 0\). +. \(C 1, C 0\). +. \(D 1, D 0\). +. \(E 1, E 0 ; P=A+B+C+D+E\)

\section*{FUNCTION TABLE}

A1 A0 Bl BO Cl CO D1 DO El EO P3 P2 P1 P0
\begin{tabular}{l|lllllll}
;AA & BB & CC & DD & EE & PPPP & COMMENTS \\
\(; 10\) & 10 & 10 & 10 & 10 & 3210 & \(A+B+C+D+E=P\) \\
\hdashline\(L L\) & LL & LL & LL & LL & LLLL & \(0+0+0+0+0=0\) \\
LH & LH & LH & LH & LH & LHLH & \(1+1+1+1+1=5\) \\
HL & HL & HL & HL & HL & HLHL & \(2+2+2+2+2=10\) \\
HH & HH & HH & HH & HH & HHHH & \(3+3+3+3+3=15\)
\end{tabular}

\section*{DESCRIPTION}

THIS PLELOP4 PERFORMS PARTIAL PRODUCTS REDUCTION FOR WALLACE TREE
COMPRESSION. FIVE ROWS OF 2-BIT NUMBERS (Al-AO, Bl-BO, Cl-CO, Dl-DO, AND El-EO) ARE NUMERICALLY SUMMED TO PRODUCE A 4-BIT RESULT (P3-P0).



\section*{DESCRIPTION}

THIS PLE12P8 PERFORMS PARTIAL PRODUCTS REDUCTION FOR WALLACE TREE COMPRESSION. FOUR ROWS OF 3-BIT NUMBERS (A2-AO, B2-BO, C2-CO, AND D2-DO) ARE NUMERICALLY SUMMED TO PRODUCE A 5-BIT RESULT (P4-PO).

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PLE12P8
PLE CIRCUIT DESIGN SPECIFICATION
P5022
VINCENT COLI 08/10/83
THREE 4-BIT INTEGER ROW PARTIAL PRODUCTS ADDER
MMI SANTA CLARA, CALIFORNIA
. ADD A0 A1 A2 A3 B0 Bl B2 B3 C0 Cl C2 C3
.DAT P0 P1 P2 P3 P4 P5
P5,P4,P3,P2,P1,P0 = A3,A2,A1,A0 .+. B3,B2,B1,B0..+.C3,C2,C1,C0;P = A P B+C
FUNCTION TABLE

```

```

DESCRIPTION
THIS PLE12P8 PERFORMS PARTIAL PRODUCTS REDUCTION FOR WALLACE TREE COMPRESSION. THREE ROWS OF 4-BIT NUMBERS (A3-AO, B3-B0, AND C3-C0) ARE NUMERICALLY SUMMED TO PRODUCE A 6-BIT RESULT (P5-P0).

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THREE 4-BIT INTEGER ROW PARTIAL PRODUCTS ADDER


\section*{Residue Arithmetic using PLE Devices}

\section*{Residue Arithmetic using PLE Devices}

Conventional binary arithmetic can be replaced by another kind of computational methodology known as the Residue Number System. The use of this system allows integer arithmetic to be performed by arrays of PLE devices. The idea of PLE devices as arithmetic elements is simply to store pre-computed values of the arithmetic operation in the PLE memory cells and to use the input variables to the arithmetic as addresses to the PLE devices Since we are computing the results of the arithmetic operations the same PLE device organization may be used for many different functions. As an example, a \(256 \times 8\)-bit PLE device can be used as a \(4 \times 4\)-bit binary multiplier, or a 4+4-bit binary adder with the output multiplied by any 3 -bit constant. It is this flexibility which holds so much appeal for the use of PLE devices as computational elements.

\section*{Introduction}

Arithmetic operations often involve carry propagation. This propagation causes too much delay for high-speed arithmetic. The Residue Number System (RNS) provides the required separation property needed for high-speed arithmetic. Each digit of the RNS representation is coded into a certain number of bits. In performing the basic operations of addition, subtraction, and multiplication, no information is required to be passed between the digits. Therefore, the number of bits required for representing each digit can be partitioned so that commercially available PLE devices can be used to implement the arithmetic.

\section*{Basics of the Residue Number System}

In this section, the elements of performing arithmetic using the RNS are introduced. The mechanism of coding numbers, the method of performing arithmetic using the RNS, and finally conversion between binary and RNS are presented.

\section*{Coding of Residue Numbers}

In principle, the coding of Residue Numbers is extremely simple. A residue digit is the remainder when the number to be coded is divided by another number (a modulus). As an example, the residue of 15 divided by a modulus 7 which yields 1 as the remainder can be represented by \(|15|_{7}=1\).

If operations are performed on an RNS where only one modulus is used, it will not be advantageous against a simple binary scheme at all since no information is encoded. Only the encoding of the binary numbers will provide the separation property which will speed up the arithmetic operation. The advantage of the RNS accrues when more digits are used

Another example of encoding a number using 3 moduli to give a 3 -digit RNS representation is as follows: let the moduli be \(m 1=3\), \(m 2=4, m 3=5\). The residues of \(X=25\) will be shown as xi where \(i=1,2,3\). Thus,
\[
\begin{aligned}
& X_{1}=|25| \mathrm{m} 1=|25| 3=1 \\
& X_{2}=|25| \mathrm{m} 2=|25| 4=1 \\
& X_{3}=|25| \mathrm{m} 3=|25| 5=0
\end{aligned}
\]

In the RNS using the moduli \(3,4,5\), the number 25 is represented as \((1,1,0)\).

The number of unique representations for a set of moduli is the Least Common Mulitple (LCM) of the moduli. The most efficient set of moduli is one in which all moduli are pairwise relatively prime.

Tables 1 illustrates an example of a set of moduli \((3,4)\) which can represent 12 integers. Note that the representations of 0 and 12 are the same, since the representation repeats itself after 12 integers.
\begin{tabular}{|c|c|c|}
\hline \(\mathbf{x}\) & \begin{tabular}{c}
\(\mathbf{( 3 )}\) \\
\(\mathbf{x 1}\)
\end{tabular} & \begin{tabular}{c}
\(\mathbf{( 4 )}\) \\
\(\mathbf{x}\)
\end{tabular} \\
\hline \hline 0 & 0 & 0 \\
\hline 1 & 1 & 1 \\
\hline 2 & 2 & 2 \\
\hline 3 & 0 & 3 \\
\hline 4 & 1 & 0 \\
\hline 5 & 2 & 1 \\
\hline 6 & 0 & 2 \\
\hline 7 & 1 & 3 \\
\hline 8 & 2 & 0 \\
\hline 9 & 0 & 1 \\
\hline 10 & 1 & 2 \\
\hline 11 & 2 & 3 \\
\hline 12 & 0 & 0 \\
\hline
\end{tabular}

Table 1. Representation of \(\mathbf{0}\) to \(\mathbf{1 2}\) in RNS Using Moduli 3 and 4. The Representation Repeats Itself After 12 Intergers

In table 2, \((4,6)\) is the set of moduli uses. Since 4 and 6 are not relatively prime, the number of integers that can be represented is not the product of 4 and 6 , but instead is the LCM of 4 and 6 which is 12 . The representation again repeats itself once every 12 integers.
\begin{tabular}{|c|c|c|}
\hline \(\mathbf{x}\) & \(\mathbf{( 3 )}\) & \(\mathbf{( 4 )}\) \\
\(\mathbf{x 1}\) & \(\mathbf{x}\) \\
\hline 0 & 0 & 0 \\
\hline 1 & 1 & 1 \\
\hline 2 & 2 & 2 \\
\hline 3 & 3 & 3 \\
\hline 4 & 0 & 4 \\
\hline 5 & 1 & 5 \\
\hline 6 & 2 & 0 \\
\hline 7 & 3 & 1 \\
\hline 8 & 0 & 2 \\
\hline 9 & 1 & 3 \\
\hline 10 & 2 & 4 \\
\hline 11 & 3 & 5 \\
\hline 12 & 0 & 0 \\
\hline 13 & 1 & 1 \\
\hline 14 & 2 & 2 \\
\hline 15 & 3 & 3 \\
\hline 16 & 0 & 4 \\
\hline 17 & 1 & 5 \\
\hline 18 & 2 & 0 \\
\hline 22 & 3 & 1 \\
\hline 23 & 0 & 2 \\
\hline & 19 & 3 \\
\hline & 2 & 4 \\
\hline & 3 & 5 \\
\hline & 0 & 0 \\
\hline
\end{tabular}

Table 2. Representation of \(0 \times 24\) for Moduli 4 and 6. Since 4 and 6 are Not Relatively Prime, and Their LCM is Only 12, the Representation Again Repeats Itself Every 12 Integers



Negative numbers are formed in the same way negative numbers are formed in binary (two's complement) system. To form the two's complement of a number in binary, we subtract the number \(2^{\mathrm{B}}\) where B is the number of bits of the representation. In RNS, we subtract the RNS number from mi to form the negative. Table 1 can be rewritten as in table 3 for encoding of negative numbers.
\begin{tabular}{|c|c|c|}
\hline \(\mathbf{x}\) & \begin{tabular}{c}
\((3)\) \\
\(\mathbf{1}\)
\end{tabular} & \begin{tabular}{c}
\(\mathbf{( 4 )}\) \\
\(\mathbf{x 2}\)
\end{tabular} \\
\hline \hline 0 & 0 & 0 \\
\hline 1 & 1 & 1 \\
\hline 2 & 2 & 2 \\
\hline 3 & 0 & 3 \\
\hline 4 & 1 & 0 \\
\hline 5 & 2 & 1 \\
\hline-6 & 0 & 2 \\
\hline-5 & 1 & 3 \\
\hline-4 & 2 & 0 \\
\hline-3 & 0 & 1 \\
\hline-2 & 1 & 2 \\
\hline-1 & 2 & 3 \\
\hline
\end{tabular}

Table 3. Representation of -6 to 5 in RNS using Moduli 3 and 4

\section*{Arithmetic Using the RNS}

For two RNS numbers, X and Y , the result of the addition of the two numbers, \(Z\), in RNS is given by:
\(|x i+y i|_{m i}=z i\) for all of the RNS digits.
The same result is found for subtraction and multiplication. This means that arithmetic can be carried out between the same digits of the two numbers, X and Y , without interaction between adjacent digits. The arithmetic is therefore "carry-free". As an example, let us consider the following computation:
\[
z=(863 \times 3942)+(-862 \times 3942)=3942
\]

We only need sufficient dynamic range to represent the result; intermediate overflows can be ignored. Let us choose the following moduli for the RNS representation:
\[
\begin{aligned}
& m 1=7, m 2=9, m 3=11, m 4=13 \\
& M=9009
\end{aligned}
\]

The above set can represent numbers in the range -4505 to 4504 , and so this number range is sufficient for the calculation of this example. The computation is shown in table 4.
\begin{tabular}{|r|c|c|c|c|c|}
\hline \multicolumn{1}{|c|}{\(\mathbf{X}\)} & \begin{tabular}{l}
\((7)\) \\
\(\mathbf{1}\)
\end{tabular} & \begin{tabular}{c} 
(9) \\
\(\mathbf{x 2}\)
\end{tabular} & \begin{tabular}{c}
\((11)\) \\
\(\mathbf{x 3}\)
\end{tabular} & \begin{tabular}{c}
\((13)\) \\
\(\mathbf{x 4}\)
\end{tabular} & \\
\hline \hline 3942 & 1 & 0 & 4 & 3 & \\
\hline 863 & 2 & 8 & 5 & 5 & \\
\hline 862 & 1 & 7 & 4 & 4 & \\
\hline-862 & 6 & 2 & 7 & 9 & \\
\hline \(863 \times 3942\) & 2 & 0 & 9 & 2 & \\
\hline\(-862 \times 3942\) & 6 & 0 & 6 & 1 & \\
\hline\(Z\) & 1 & 0 & 4 & 3 & \(=3942\) \\
\hline
\end{tabular}

Table 4. Calculating \(Z=863 \times 3942+(-862 \times 3942)=3942\)

Division of residue numbers is more complicated than addition, subtraction, or multiplication. If the dividend is exactly divisible by the divisor, the operation is easier. In this case, a division by a number is the same as a multiplication by the inverse of that number. The multiplication inverse of an integer Xin modulo arithmetic can be found by finding the vector ( \(\mathrm{d} 1, \ldots, \mathrm{dn}\) ) which satisfies the following:
\(|X . d i|_{\mathrm{mi}}=1\)
For example, 95 divided by 5 in moduli 2,7 and 9 can be done by first finding the vectors representing 95 and the inverse of 5 .
\(|95|_{2}=1\)
\(|95|_{7}=4\)
\(|95|_{9}=5\)

So, for the multiplicative inverse of 5 , we have:
\[
\begin{aligned}
& \begin{array}{r}
|1 / 5|_{2}=1 \quad|5 \times 1|_{2}=1 \\
|1 / 5|_{7}=3 \text { since }|5 \times 3|_{7}=1 \\
|1 / 5|_{9}=2 \quad|5 \times 2|_{9}=1 \\
\text { Therefore, } \\
|95 / 5|_{2}=\left||95|_{2} \times|1 / 5|_{2}\right|_{2}=|1 \times 1|_{2}=1 \\
|95 / 5|_{7}=\left||95|_{7} \times|1 / 5|_{7}\right|_{7}=|4 \times 3|_{7}=5 \\
|95 / 5|_{9}=\left||95|_{9} \times|1 / 5|_{9}\right|_{9}=|5 \times 2|_{9}=1
\end{array} \\
& \left.\qquad \begin{array}{l}
15
\end{array}\right)
\end{aligned}
\]
and the answer is 19.
The operation becomes more complicated when the dividend is not exactly divisible by the divisor or one of the moduli of the multiplicative inverse does not exist, say, if the residue of the divisor for that modulus is 0 . In this case, we need to obtain the remainder and then subtract the remainder from the dividend and then perform the division. The problem in finding the remainder seems to be the same as performing the division itself. However, this type of division can be done in a process called scaling, which will not be discussed in detail in this paper.
In spite of the improvements made in implementing scaling algorithms, scaling still represents a major effort in any calculation. It is advisable to use RNS only on systems where many arithmetic operations can be performed for each scaling operation.

\section*{A System Using an RNS}

An RNS is very useful in systems which have predefined operations and dynamic ranges. Moreover, it can only operate on integers, or at most, block floating-point numbers. Since the RNS involves conversions between integers and their RNS representations, and conversions by themselves are already time-consuming, the problem to be solved in the RNS system should be operation intensive.


Figure 1. Architecture of an RNS

\section*{Conversion to RNS Representation}

The conversion of an integer to RNS can be viewed as a mapping process. PLE devices provide a natural implementation for
numbers ranging from 0 to 255 , and the following moduli are arbitrarily chosen for conversion to RNS - 2, 11 and 15 (which can represent 330 integers), 8 bits of address are needed for the integer input and 9 outputs ( 1 for modulus 2, 4 for modulus 11 and 4 for modulus 15 ). In reality, only 8 outputs are needed because that bit of residue for modulus 2 is not required, since the least significant bit of the integer is also the residue of itself in modulus. In fact, a PLE8P8 will be sufficient.


Figure 2. Mapping an 8-Bit Integer, X, to Its Residues on Moduli 2, 11 and 15

Another example is a 14-bit integer which is to be converted to RNS. A 14-bit address needs 16 K address spaces for the mapping. 16 K is too deep for a PLE device. An alternative is to use 4K-deep PLE devices. PLE12P4 and PLE12P8 devices and a selector (e.g., a PLE5P8 to control the PLE devices (See Figure 3)). The PLE5P8 device will decode two of the address bits and will selectively enable one of the four sets of PLE devices as the mapping set, thus deepening the effective address to 16 K .


Figure 3. Mapping a 14 -Bit Integer, X , to Its Residues by Selectively Enabling the Outputs of One of the Four Sets of 12-Input PLE Devices

This method of expansion is not effective with bigger integers. If the integer is N -bit and the PLE address space available is M-bit, then \(2^{N-} \mathrm{M}_{\text {sets }}\) of PLE devices will be needed. Besides, as the dynamic range increases, the width of the outputs will also increase about proportionally. An alternative method is to use two or more levels of PLE devices to generate the residues. The first level generates the remainders from the more significant bits of the integer and the products of some of the moduli. These remainders are in turns concatenated with the rest of the bits to become the inputs to the second level PLE devices.

For example, for a 16-bit integer 43689, and let us use (2, 11, 13, \(15,23)\) as the set of moduli. We may choose 23,30 and 143 as the moduli for the first level. The first level consists of PLE12P4s and PLE12P8s which generate the remainders of the most significant 12 bits of 43689 which is 2730 . We know that \(|2730|_{23}\) will be at most 22 and can therefore be represented by a 5 -bit number; \(|2730|_{15}\) will be at most 14 and can be represented by another 4 -bit number; and \(|2730|_{143}\) will be at most 142 and can be represented by a 6 -bit number. The 5 -bit number represented by \(|2730|_{23}\) will be concatenated with the least significant 4 bits of the integer and gives a 9 -bit number which can perform another division by 23 to give the final \(|43689|_{23}\); the 4 -bit number represented by \(|2730|_{15}\) will be concatenated with the least significant 4 bits of the integer and gives an 8 -bit number which can perform another division by 15 to give the final| \(\left.43689\right|_{15}\); the 6 -bit number represented by \(|2730|_{143}\) will be concatenated with the least siginificant 4 bits of the integer and gives a 10-bit number which can perform another division by 11 and 13 to give the final \(|43689|_{11}\) and \(|43689|_{13}\). As in the first example, \(|43689|_{2}\) is just the least significant bit of the integer.


Figure 4. Mapping a 16-Bit Integer \(X\) to Residues in Modulo 2, 11, 13, 15, and 23 Using Two-Level Mapping. The First Level Gives Remainders from the More Significant Twelve Bits, While the Second Level Finds the Final Residues
In some circumstances, although an N -bit integer only has a dynamic range of \(2^{N}\), the intermediate calculations may overflow. It is sometimes necessary to add some other moduli to boost up the dynamic range for the intermediate calculations.

\section*{Arithmetic Operations In RNS}

The arithmetic operations of the RNS is different from regular arithmetic in that even simple addition must be performed in modulo arithmetic. Simple ALU may not be able to handle this arithmetic. Again, PLE devices are proven to be most useful. A PLE8P4 device can perform addition, subtraction, or multiplication on two 4 -bit residue numbers and give a 4 -bit modulo result.


Figure 5. Calculating \(\mathbf{C}=\mathbf{A}+\mathbf{B}, \mathbf{A}-\mathbf{B}, \mathbf{B}-\mathbf{A}\), or \(\mathbf{A} \times \mathbf{B}\) Using PLE8P4
If the modulus is large, say greater than 64, the combined number of bits for two residues will be greater than the number of address bits for the largest of the commercially available PLE device. Of course, more than one device can be used to deepen the effective address space. In this case, for every additional bit of a modulus, two more bits of address will be needed - one for each operand. In other words, for each additional bit of a modulus the address space of operation will be quadrupled. It is not very effective when the modulus grows too large. Fortunately, for both addition and multiplication, there are more efficient procedures.

\section*{Large Modulus Addition}

Table 5 shows the contents required for the addition operations in modulus 11. There is a lot of redundancy in the table which can be compressed by reducing what should be eight bits of inputs to five bits. What we need is just another level of mapping. There are a total of 121 combinations for a number of modulus 11 operating on another operand of the same modulus. In reality, only numbers ranging from 0 to 10 can be represented in modulus 11. The sum ranges from 0 to 20 (not in modulus 11). This range can be represented by a new set of submoduli \((3,7)\) which is five bits wide. In fact, any new set of submoduli which has a dynamic range of at least twenty-one can be used. The operands in modulus 11 will be converted to their representations in submoduli 3 and 7. The addition is done in the submoduli and the result is reconverted back to modulus 11 RNS (see Table 6).
\begin{tabular}{|c|r|r|r|r|r|r|r|r|r|r|r|r|r|r|r|r|r|r|r|r|r|}
\hline\(x+y\) & 0 & 1 & 2 & 3 & 4 & 5 & 6 & 7 & 8 & 9 & 10 & 11 & 12 & 13 & 14 & 15 & 16 & 17 & 18 & 19 & 20 \\
\hline\(|x+y| 11\) & 0 & 1 & 2 & 3 & 4 & 5 & 6 & 7 & 8 & 9 & 10 & 0 & 1 & 2 & 3 & 4 & 5 & 6 & 7 & 8 & 9 \\
\hline\(|x+y| 7\) & 0 & 1 & 2 & 3 & 4 & 5 & 6 & 0 & 1 & 2 & 3 & 4 & 5 & 6 & 0 & 1 & 2 & 3 & 4 & 5 & 6 \\
\hline\(|x+y| 3\) & 0 & 1 & 2 & 0 & 1 & 2 & 0 & 1 & 2 & 0 & 1 & 2 & 0 & 1 & 2 & 0 & 1 & 2 & 0 & 1 & 2 \\
\hline
\end{tabular}

Table 6. Conversion Table Between Modulo 11 Arithmetic and Modulo 3 and 7 Arithmetic


Figure 6. Calulating Addition of Two Numbers in Modulo 11 Using Submoduli Operations

\section*{Large Modulus Multiplication}

The solution to this problem in multiplication is similar. For example, if two RNS digits in modulus 91 is to be multiplied, \((7,13)\) may be chosen as a set of submoduli. The representation of an RNS digit in modulus 91 needs 7-bits. These 7-bits are first mapped to two RNS digits - in modulo 7 which needs 3 -bits; and in modulo 13 which needs 4 -bits. The representations of the two operands in the two moduli can then be multiplied and give the result in modulo 7 and modulo 13. The result is then converted back to modulo 91. Unfortunately, this scheme can be used only when the modulus can be expressed as a product to two integers which are relatively prime. But, in this case, the RNS digit may simply be represented as the residue of the two smaller integers instead of using them as submoduli.


Figure 7. Calculating Multiplication of Two Numbers in Modulo 91 Using Submoduli Operations

Suppose another modulus 101 is used. 101 is a prime number and RNS in modulus 101 ranges from 0 to 100. The real dynamic range of the product of two numbers in modulus 101 is 0 to 10000, which is already too large for a PLE address space. For this modulus, we may use three 4 K -deep PLE devices to deepen the address space. For a modulus like 1001, it may not be too efficient to use this scheme. Instead, since:
\[
\begin{aligned}
x y & =\left[(x+y)^{2}-(x-y)^{2}\right] / 4 \\
\text { or } \quad & \left.=[x+y)^{2}\right] / 4-\left[(x-y)^{2}\right] / 4
\end{aligned}
\]
we may do \(x+y\) and \(x-y\) first and then do the squaring of the sum and the difference scaled by a factor of 4 . Since the final product of two integers must be an integer, the squaring and scaling may be performed in one operation with the fractional part discarded. The way to obtain \(x+y\) and \(x-y\) is the same as what was discussed earlier in the "Large Modulo Addition" session.
In any event, operations on residues of large moduli are slower and involve more hardware and are not recommended.


Figure 8. Performing Modulo 1001 Multiplication
The Reverse Conversion
The reverse mapping from RNS to integer is not as straightforward as the other way. For an RNS system which has a total of twelve bits for all the residues, we can still use 12-input PLE devices to convert. We may also use several sets of 12 -input PLE devices to reverse map the RNS if the integer is not much longer. But for very long integers, we may need to use the general algorithm for the reverse map:
1. Find \(M=m 1 \times m 2 x \ldots x m_{n-1}\) (where \(n\) is the number of moduli)
2. Find \(\mathrm{ti}=\mathrm{M} / \mathrm{mi}\)
3. Find \(X=|x 1 t 1+x 2 t 2+\ldots+x n-1 t n-1| M\)

In hardware implementation, ti's are all known beforehand, We can map xi's to get the xiti's. Then we may perform Wallace Tree Compression (see the session on this subject in this handbook for more information) on the xiti's to give two-level operands which add to the final sum and divide it by \(M\) to get \(X\). Again, PLE devices provide the best solution for Wallace Tree Compression.


Figure 9a. Reverse Mapping to Get \(\mathrm{X}_{\mathrm{i}} \mathrm{t}_{\mathrm{i}}\)

Figure 9b. Modulo M Wallace Tree Compression to Reduce the Number of Levels for Summation to 2 Followed by an Addition and Division to get \(X=\left|x_{1} t_{1}+\ldots+x_{n} t_{n}\right| M\)

\section*{Residue Arithmetic Using PLE Circuits}

\section*{Conclusion}

Memory elements provide excellent solutions to mapping functions - for control purposes, for arithmetic operations and general logic replacements. This paper investigates the possibility of using PLE devices as arithmetic units. In fact, for logic like residue number arithmetic, there is no better solution than to use these devices.




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\section*{Acknowledgement}

Portions of this article were extracted from "Integer Arithmetic Using PROMs" by Dr. G. A. Jullien of the University of Windsor, Canada.
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\title{
Distributed Arithmetic Using PLE \({ }^{T M}\) Devices
}

\section*{Distributed Arithmetic Using PLE Devices}

In digital signal processing, sum-of-product type of operations are often necessary. These operations take the form of:
\[
y=\sum_{i=1}^{M} a_{i} x_{i} \quad \text { where } a_{i} \text { 's are some constants }
\]

If real multiplications are to be performed on every product term, it will need a total of M multiplications and \(\mathrm{M}-1\) additions. Multiplication operations normally take much longer than simple addition. An alternative to calculate equations of the above form is by using distributed arithmetic.

Suppose there is an \(N\)-bit integer \(X\) given by
\[
x=[x(N-1), x(N-2), \ldots, x(1), x(0)]
\]
or equivalently:
\[
x=\sum_{j=0}^{N-1} x(j) 2^{j}
\]
where \(\times(N-1)\) is the most significant bit. The equation:
\[
y=\sum_{i=0}^{M} a_{i} x_{i}
\]
can be expressed as:
\[
\begin{aligned}
y & =\sum_{i=1}^{M} a_{i}\left(\begin{array}{ll}
\sum-1 & x_{i}(j) 2 j \\
j-1 & \sum_{j=0}^{j} \\
& =\sum_{i=1}^{M}
\end{array} a_{i} x_{i}(j)\right)
\end{aligned}
\]

Now, let:
\[
H(j)=\sum_{i=1}^{M} a_{i} x_{i}(j)
\]

Since \(H\) ( j ) is independent of i and since \(\mathrm{a}_{1}\) 's are all constants, we precompute for every \(\times(\mathrm{j})=\left[\mathrm{x}_{1}(\mathrm{j}), \mathrm{x}_{2}(\mathrm{j}), \ldots, \mathrm{x}_{\mathrm{M}}(\mathrm{j})\right]\) the values of H (j). Then x (j) can be used as the address of PLE devices whose outputs are the precomputed result H (j).


Figure 1. Mapping the \(j^{\text {th }}\) Bit from Each of the \(x_{i}\) 's to An L-bit Result

If there are \(M\) bits of data and the result is \(L\)-bit wide, and if \(M\) is very large, say 20 , and \(L\) is 8 , then we need 20 bits of address lines if we want to use only PLE mapping. Since 20 bits of address translate to 1 M words, and there is no available 1 M -deep PLE device on the market, it is not realistic to use PLE mapping. Instead, H (j) can be partitioned as follows:
\[
\begin{aligned}
H(j) & =\sum_{i=1}^{20} a_{i} x_{i}(j) \quad \text { for } M=20 \\
& =\sum_{i=1}^{10} a_{i} x_{i}(j)+\sum_{i=11}^{20} \quad a_{i} x_{i}(j)
\end{aligned}
\]
the 20-bit address can be separated to two 10-bit addresses and each of them is individually mapped. The two outputs will then be added together to give \(\mathrm{H}(\mathrm{J})\). An implementation of this mapping is shown in figure 2.


Figure 2. Mapping the \(j^{\text {th }}\) Bit of Each of \(x_{j}\) 's to an L-bit Result When There Are Too Many x's (20 in This Case)

There is another alternative for implementing a sum-of-product operation: by using a multiplier accumulator (MAC).
The main constraint on distributed arithmetic is that one set of the multiplicands must be fixed, i.e. ai's in this case, for the sum-of-product mapping while a MAC will allow flexibility.

There are normally some constraints on the width for the data bus from which the operands are loaded. If all the operands are new, it will need M cycles to load in the operands anyway, distributed arithmetic offers no advantages over MAC since distributed arithmetic needs to wait for all the operands to be loaded in before any operation can start while MAC can perform a multiplication and an addition every cycle. M cycles will be needed anyway for the complete operation using a MAC while distributed arithmetic may take even longer.

On the other hand, for operations like convolutions where one set of operands are fixed and only one new variable operand is needed for every result, distributed arithmetic will be a better solution since it can give a result in every clock-cycle while a MAC will need M-cycles (because recalculations of all the product terms are necessary). An implementation for convolution is shown in Figure 3.


Figure 3. An Implementation of a Distributed Arithmetic System for Convolution

There is another way to implement distributed arithmetic through bit-serialization:
From \(H\) (j), the sum-of-product of \(y\) can be obtained as:
\[
y=\sum_{j=0}^{N-1} \quad 2^{j} H(j)
\]

To implement this equation, consider that the least significant bit of the result is to be used only for rounding purposes only. Only the more significant bits will be retained. The computation can be performed in the following way:
1) For \(j=0\),
\(y_{0}=2^{0} H(0)=H(0)\)
2) For \(\mathrm{j}=1\) to \(\mathrm{N}-1\)
\[
y_{j}=H(j)+1 / 2 H(j-1)
\]

Note that the second term of the last equation means that the previous result \(\left(y_{j-1}\right)\) is shifted right one-bit; the last bit of \(y_{j-1}\) is truncated.

The implementation of such a system is shown in Figure 3. The system consists of a shift register, a mapper (PLE circuits, or PLE circuits with adders), an accumulator, and an ALU.


Figure 4. A Bit-Serialization Implementation for a Distributed Arithmetic System

The operations are as follows:
1) Load \(x_{i}\) onto the load and shift register at clock 0 .
2) Load H(0) onto accumulator and shift all registers at clock 1
3) From clockk (between clock 2 to clock \(\mathrm{N}-1\) ), the content of the accumulator will be replaced by the sum of \(\mathrm{H}(\mathrm{k}-1)\) and the more significant \(\mathrm{N}-1\) bits of the current accumulator value.
4) For clock \(N\), the following are performed:
a) Repeat step 3. At the end of the operation, the accumulator contains the value of the result (scaled by the number of shifts).
b) \(x_{i}+1\) is loaded onto the load and shift register.

The shifting frequency is equal to N times the basic rate.
Due to the fact that there are a number of shift operations necessary for each data load, this method is recommended for the following conditions:
1) This design is under cost, power dissipation, and board space constraints.
2) This design is for high M-to-N-ratio array multiplications.



\section*{Registered PLE Devices in Pipelined Arithmetic}

PLE devices are useful as logic elements, and registered PLEs are excellent media for pipelined arithmetic. Monolithic Memories supplies a number of registered PLE devices which provide effective solutions to pipelined systems

A data processing system may have fall-through architecture. Since many of these operations may take a long time, it happens that the devices are not often tied up in operations. For example, in a system as in figure 1, the operations can be divided into three functional blocks. When the operands are loaded in, block 1 will operate first, followed by block 2 and then by block 3 . When the data is in block 2, block 1 is not doing anything. We cannot at this time put in the next set of operands because changes in operands may disturb the operation in block 2.


Figure 1. An Example of the Fall-Through Approach to Arithmetic Operation

A solution to this is by registering the operands and signal paths when the operations is switched to block 2 ; and by registering the operands and signal paths again when the operations is carried out in block 3. The result is stated in figure 2. This architecture is called the pipelined structure. It makes the loading of the second set of operands possible even before the first result is out, thus increasing the throughput.
\begin{tabular}{|c|}
\hline BLOCK 1 \\
\hline REGISTER \\
\hline BLOCK 2 \\
\hline REGISTER \\
\hline BLOCK 3 \\
\hline
\end{tabular}

Figure 2. Pipelined Arithmetic Operation

The introduction of the registers for the pipeline increases the operation time of every block due to the addition of the setup times and the clock to output delays. The result is as follows:
1) Overall delay. The architecture in Figure 2 will need at least an additional 2 setup time and 2 clock to output delays of a register. In real, it will be more, because the minimum clock period will be determined by the sum of (i) the maximum of the operation times of individual blocks, and (ii) the setup time of the pipelined registers and (iii) the clock to output delay of the pipelined registers. Symbolically, the overall delays for the architectures in Figures 1 and 2 are:
\[
\begin{aligned}
t_{\text {pd }}(\text { Fig. 1) } & =t_{\text {pd }}(\text { blk } 1)+t_{\text {pd }}(\text { blk } 2)+t_{\text {pd }}(\text { blk } 3) \\
t_{\text {pd }}(\text { Fig. } 2) & =2 \times\left\{\operatorname { m a x } \left[t _ { \text { pd } } \left(\text { blk 1), } t _ { \text { pd } } \left(\text { blk 2), } t_{\text {pd }}\right.\right.\right.\right. \text { (blk 3)] } \\
& \left.+t_{\text {su }}+t_{\text {clk }}\right\}+t_{\text {pd }}(\text { blk } 3)
\end{aligned}
\]

Where \(\mathrm{t}_{\text {pd }}\) (Fig. 1) and \(\mathrm{t}_{\text {pd }}\) (Fig. 2) are the propagation delays of the architectures in figure 1 and figure 2 respectively; \(\mathrm{t}_{\text {pd }}\) (blk 1) \(t_{\text {pd }}\) (blk 2), \(t_{\text {pd }}\) (blk 3) are the propagation delays of block 1 , block 2 , and block 3 respectively; and \(\mathrm{t}_{\mathrm{su}}\) and \(\mathrm{t}_{\text {clk }}\) are the setup time and clock-to-output delay of the registers respectively.
2) Throughputs of clock rate. The architecture in figure 1 has a throughput period of \(\left(t_{\text {pd }}\left(\right.\right.\) blk 1) \(+t_{\text {pd }}(\) blk 2 \()+t_{\text {pd }}(\) blk 3) + \(\mathrm{t}_{\text {su }}+\mathrm{t}_{\mathrm{clk}}\) ), assuming that the operands are coming from and the result is going to some registers; the architecture in Figure 2 has a throughput period of ( \(\max \left[\mathrm{t}_{\mathrm{pd}}(\mathrm{blk} 1), \mathrm{t}_{\mathrm{pd}}\right.\) (blk 2), \(\left.\left.t_{\text {pd }}(b l k 3)\right]+t_{\text {su }}+t_{c l k}\right)\) which is faster.

PLE devices are useful as logic elements, and registered PLE devices are excellent media for pipelined arithmetic. Monolithic Memories supplies a number of registered PLE devices which provide effective solutions to pipelined systems.

Applications for pipeline arithmetic include array and digital signal processing.


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\section*{Contents Section 9}


\section*{Testing Your PAL Devices}

\section*{Manouchehr Vafai}

\section*{Introduction}

The advantage of Programmable Array Logic（PAL®）circuits as a basic building block of digital system is now well established．
PAL circuits are a unified group of devices which combine programmable flexibility with high speed and extensive selec－ tion of interface options．
The architecture of PAL circuits consists of programmable－ AND－OR gate arrays，output－registers and I／O feedback as shown in Figure 1.


\section*{Figure 1．PAL Circuit Architecture}

The increased system speed，reduced chip count and availability of a CAD tool called PALASM \({ }^{\text {4 }}\) software should leave no doubt for design engineers that they have made a right choice in choosing PAL circuits．
The HAL circuit family is the masked program version of a PAL circuit．HAL® circuits will provide the users a cost－effective solution for large quantities and is unique in that it is a gate array with a programmable prototype．
The following steps are required when designing with PAL circuits．
－Familiarity with Demorgan＇s law．
－Familiarity with the Karnaugh maps．
－Ability to express logic equation in Sum－of－Product form．
－Ability to write simple seed vector for function table．
－Familiarity with different PAL circuits．

\section*{Programming PAL Circuits}

PAL circuits will be programmed using PALASM software．
PALASM software is the CAD tool developed by Monolithic Memories to facilitate the process of programming．PALASM software is a Fortran IV program which assembles and sim－ ulates PAL circuits design specifications．It generates PAL cir－ cuit fuse patterns in formats compatible with PAL circuits or PROM programmers．
Besides generating PAL circuit fuse pattern in different pro－
gramming formats，PALASM software does the following：
－Assembles PAL circuit design specification and reports error messages．
－Simulates the Function Table．
－Tests each product term for Stuck at zero（SAO）and stuck at one（SA1）faults．

The purpose of writing vectors is to prove that a device is capa－ ble of performing it＇s function before it is put in a system． PALASM software will exercise the vectors and will report any discrepancy．Writing vectors will raise confidence that a device will function properly at least in the design level．The simulator also transfers the function table vectors to a set of universal test vectors which may be used for functional testing after the device is programmed．
When a new system is transferred to production，the system designer hands over the responsibility for the system to the test engineering department，who now determines how and what test should be performed to ensure proper operation of the system．At this point the system designer transmits the neces－ sary information for understanding the system operation． Unfortunately，much information is lost at this point．Test engi－ neers usually have a hard time understanding how the system works with insufficient information．It is the design engineer who best knows the operation of his PAL circuit design，and it is the design engineer who can quickly specify a few seed vectors to give the test a starting point in solving the future problem．

\section*{Design for Testability}

In short the only way to control a digital circuit is to apply a known value to it＇s input．Fault simulation has been the best technique of yielding a quantitive measure of test effectiveness． Fault simulation will test stuck－at－0（SA0）and stuck－at－1（SA1） of input and output lines．By generating test vectors that will test for each product term for（SAO）and（SA1）faults，then by observing the corresponding output and comparing it with the fault－free output，one can conclude whether a fault can be detected or not．
Consider the following example：


Figure 2 Logic Diagram and It＇s PAL Circuit Implementation

\section*{ABCDEFZ \\ \(1110 \times \times 1\)}

The (vector-1) selects a product term P1. Under a fault-free condition, the output (2) will be high (we can observe this); however, under a fault condition the output will be low. In other words, one can conclude that either product term (P1) is (SAO) or outputs \(Z\) (Figure 2.) are (SAO).
Now consider vector 2.

\section*{ABCDEFG}

0000000
latusl (1AB) eno to woule
ais alosoov (vector-2)
alabonil
(vector-1)

As it can be seen that both of the product terms are low, if the observed output is high, one can conclude that either product terms or outputs are Stuck-at-one.
Fault simulation grading is used by Monolithic Memories to evaluate candidates design for transfering from a PAL circuit to a HAL circuit.
In designing with PAL circuits, four different cases should be considered
1. A purely combinational circuit where output is function of input.
2. A purely combinational circuit where output is function of input and feedback from output.
3. A purely sequential logic where output is function of input and feedback from output.
4. A combinational-sequential logic where output is function of input, feedback from combinational output and feedback from sequential output.
In cases 1 and 2 we can define a structured way of writing function table. Cases 3 and 4, on the other hand, because of dependency of the device on the previous state of the device, impose a relatively more sophisticated scheme of testing strategy.
In the following examples the various techniques which might be helpful in testability of PALs, will be discussed.

\section*{Example 1: Glitch-free and Testable}

Suppose we want to implement (EQ-1) using any of the combinational PAL.
\[
F=X^{*} A+\bar{X}^{*} B
\]
\[
(e q-1)
\]

The K-MAP and logic diagram are shown in (Figure 3.)


Figure 3. Logic Diagram and It's K-Map

The above logic is testable because we have full control over each node for (SA0) and (SA1) test.

The implementation using PAL circuits is as follows:


Figure 4. PAL Circuit Implementation of the Logic

Ideally the output should always be high if both inputs are high. The circuit is not glitch-free, the output might momentarily drop to low if we change the state of \(X\), due to propagation delay between X and \(\overline{\mathrm{X}}\).
The problem will be solved by including a redundant (AB) term to (eq-2).
The equation will look like this.
\[
F=X A+\bar{X} B+A B
\]
(eq-2)
The output is glitch-free, but untestable!


Figure 5. A Glitch-free Circuit
Node (2) is not Observable for (SAO). One can not force node (2) to one and keep node (1) and (3) in the low state. So the redundant product term is untestable.
This circuit can be made testable by the addition of control signal \((\mathrm{Y})\) as follows:


Figure 6. Glitch-free and Testable Logic
Now the logic is glitch-free and testable.

\section*{Example 2: Untestable Logic - A Simple Example}

The logic \(F:=\bar{F}\) is untestable


Figure 7. Implementation of \(\mathbf{F}:=\overline{\mathbf{F}}\)

The initial state of the oscillator is unknown; this system can be made testable as follows:


Figure 8. Implementation of \(F:=\bar{F}\) with SET and RESET
It has been done by addition of two control signals (RESET and SET) and one extra product term.

\section*{Illegal States}

Upon power-up the initial state of output registers are unknown; this might force the device into one of the "illegal states".
The design engineer should be worried about the illegal state at design time. For example let's look at modulo-6 state machine


Figure 9. State Transition Diagram for a Modulo-6 Counter
The design engineer might ignore the other possible state \((6,7)\) but his ignorance might be costly at test time. If upon power-up the machine starts at either of (6) or (7) state, there is no way to control the state-machine. The best solution is to force both of the illegal states into one of the known states.


Figure 10. A Modulo 5 Counter with No Illegal State
Example 3: Design "pitfall" Case One
Consider the implementation of the following example
\[
\text { Q1 := } 11 \text { * Q1 }
\]


Figure 11. Implementation of Q1:= 11 * Q1 Using a PAL
If Q1 falls to zero, it will stay there forever. The logic needs a control signal for output reset.

Example 4: Design "Pitfall" Case Two
Consider the implementation of the following equation:
\[
\overline{\mathrm{QO}}=\overline{\mathrm{A}} \overline{\mathrm{Q}}^{*} \overline{\mathrm{Q} 0}+\mathrm{A}^{*} \mathrm{Q} 1^{*} \overline{\mathrm{Q} 0}+\overline{\mathrm{Q0}}
\]


Figure 12. Implementation of \(\overline{\mathbf{Q 0}}=\overline{\mathbf{A}^{*}} \overline{\mathbf{Q} 1^{*} \mathbf{Q} 0}+\mathbf{A}^{*} \mathbf{Q} 1^{*} \overline{\mathbf{Q 0}}+\overline{\mathbf{Q 0}}\)

If \(\overline{\mathrm{Q} 0}\) goes to one it will stay there forever, the logic needs a control signal to clear it's output.

\section*{Hard Array Logic (HAL) Devices}

The HAL device is the Hard Array version of a PAL device.
HAL logic circuits are the best choice for designs that are firm and volumes are large enough to justify the initial cost. Besides having Boolean equation in PAL DESIGN SPECIFICATION format the user should provide the following.
1. A FUNCTION TABLE which gives enough information about the operation of the device. Normally this FUNCTION TABLE shall test a minimum of \(50 \%\) "Stuck at fault" grading using PALASM or TEGAS fault grading test.
2. The FUNCTION TABLE shall be constructed such that the device may be initilized to a known state within a specified number of steps (or clocks).

The HAL CIRCUIT SPECIFICATION is the input file used with PALASM software for the HAL's. The input format as shown in example 5 is as follow:
- Line 1 HAL circuit part number
- Line 2 user's part number followed by originator's name and the date
- Line 3 device application name
- Line 4 user's company name, city, state
- Line 5 pin list which is a sequence of symbolic names separated by one or more spaces. All pins including VCC and GND must be named
- Line \(M\) the logic equation which are used to generate metal masks from the provided equations
 A zaosge va betmagear vilampifqo bis eman nig toas vol


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}


\section*{EXAMPLE 5}
- Line N the function table which begins with the key word "FUNCTION TABLE." It's followed by a pin list which may be in a different order and polarity from the pin list in line 5 . VCC and GND cannot be listed. The pin list is followed by dashed line; e.g.; _-_ which in turn is followed by a list of vectors, one vector per line. One state must be specified for each pin name and optionally separated by spaces. A vector is a sequence of states listed in the same order as the pin list and followed by an optional comment.

The allowable states are H (HIGH LEVEL), L (LOW LEVEL), X (IRRELEVENT), C (TRANSITION FROM HIGH TO LOW OR CLOCK PULSE) and Z (HIGH IMPEDENCE). After preparing the PAL DESIGN SPECIFICATION in the above format, PALASM software can be used to simulate and perform fault testing.


The following information is reported to the user
- Total number of SA1 Faults. (8 in example 5)
- Total number of detected SAO faults. (9 in example 5)

SA1 faults + SA0 faults
- \(2^{*}\) total number of product terms
\(* 100 \% \quad\left(\frac{8+9}{2^{*} 10} \quad * 100 \%=85 \%\right.\) ex- 5 )
- One vector may detect more than one SAO OR SA1 FAULTS (vector \# 11 in example 5)
- The user is reported with a message which tells him the product term for which it was not tested. (PRODUCT TERM 1 \& 2EQ 6, in example 5)
The following vectors can be added to the function table in example 5 in order to achieve 100\% fault coverage.
\begin{tabular}{ll}
\(A B\) & CDE FGH IJKL MNO PQR
\end{tabular}

PALASM \({ }^{\text {™ }}\) software has tested the above function table for example 5 , the result is as follows:

\section*{BASIC GATES}

2 XXXXXXXXXXXXXXXXXI 11 \(311 \times x \times x \times x \times x \times x \times x \times \times \mathrm{Hx} \times 1\)
 \(400 \times \times \times \times x \times x \times 0 \times x \times x I \times 1\)







12 x \(00 \times 000 \times 000000 \times 8 \times 00 \times 1\)




PASS SIMULATIGN
NUMBER OF STUCR AT ONE (SAl) FAULTS ARE \(=10\)
NIMBER OF STUCK AT ZERO (SAO) FAULTS ARE \(=10\)
PRODUCT TERM COVERAGE \(\quad=100 \%\) PALASM \({ }^{\text {T }}\) is a trademark of Monolithic Memories.

\title{
PAL®20RA10 Design for Testability
}

\author{
Edwin Young
}

This article is written to help customers of the PAL20RA1 recognize some fundamental design-for-testability issues which may arise due to the part's unique architecture. Customers should understand that these issues represent design criteria which Monolithic Memories will use to accept PAL20RA10 patterns for test generation/fault grading and for estimating the resource cost to test engineering if accepted. This article does not address the BUSINESS REQUIREMENTS such as the need for acceptable test vectors and the acceptability of a particular pattern for processing as a HAL® device.
The designer who wishes to use a 20RA10 in his/her design must bear in mind that although the part has preloadability, certain designs could diminish the effectiveness of this feature. The following rules are presented to help establish Test Engineering acceptance standards for the 20RA10. Additional general guidelines applicable are available in the PAL Handbook article reprint "Testing Your PAL Devices" by M. Vafai.

\section*{Avoid False Latching Situations}

The equation \(D=\left(A^{*} B\right)+(C+D)\) and its variants are susceptible to latching hazards since ATE may have considerable input skew. Of course, from a testing viewpoint, such implementations should be avoided. But if they must be implemented, care must be exercised in developing the function table so as to account for the possibility of latching. The designer must adopt and stick to some guideline such as "no more than one input undergoes a change in logic value per vector" when specifying the function table.


Assume A, B and C are primary inputs while D is a fed-back output. The waveforms to the left show two possible outcomes for output D depending on the skew of inputs \(A\) and \(B\), which is a function of tester calibration.

The latch problem described is not unique to the 20RA10 but is clearly applicable to any PAL with asynchronous outputs with feedback (e.g., 16R4). The designer should realize, however. that false latching may occur on a 20RA10 even if all outputs are registered. Consider the equation set \(\mathrm{D}:=\mathrm{C}\) and \(\mathrm{D} . C L K F=A^{*} B\) for a simple registered 20RA10 output. The resulting waveforms would look similar to those of the previous asynchronous example. The important distinction here is that a 20RA10 has programmable asynchronous clocks rather than a single 'master clock' pin which can cause difficulties in testing.

\section*{Allow Data to Setup Prior to Clocking}

The previous two pitfalls were examples of flaky latching due to glitches during testing. Consider the equation set \(C:=B\) and C.CLKF \(=\mathrm{A}\) for a registered output. The following example shows a definite positive latching ...but of flaky (skewed) data.


\section*{Avoid Unreachable States}

The 20RA10 may be preloaded to any state desired for testing purposes. Unfortunately, the desired state may not exist long enough for the simulator or ATE to use it. With all other preloadable PALs, any arbitrary state may be preloaded into the registers on a given test vector and the state will persist into the next vector providing the required conditions to detect some fault/s. This means all stuck-at-type faults possibly detectable can be detected. With the 20RA10, the preloaded state may feed back to assert state dependent resets or presets on one or more
registers. Consequently, the desired state may last only a few nanoseconds after the preload vector is complete before changing to some new state. Since the desired state is not stable going into the vector immediately following the preload vector, the faults expected to be detected become non-detectable.
Another problem arises whenever output control logic is a function of state. In this case, assume the desired state for detecting faults is preload and is stable in the next vector. If this state provides the conditions necessary to detect faults and also disables the outputs, then the faults will be effectivley masked from detection.

\section*{Caution on Individual Register Bypass Mode}

The 20RA10 allows the designer to permanently and independently bypass any register. Those registers not permanently bypassed may be bypassed under program control by setting both SET and RESET nodes to logic high. In this 'bypass mode', the register's D node is multiplexed to the output rather than its \(Q\) node. There is generally no test problem in going into bypass mode. The pitfall is in returning to 'register mode' operation, which only the 20RA10 can do. Consider the equation set C.RSTF \(=A\) and C.SETF \(=B\) of a simple registered output and


An indeterminate state on the output can occur if both primary inputs \(A\) and \(B\) go to logic low on the same vector.
the following possible waveforms. A race condition will occur to see whether set or reset operation prevails in going from bypass to register mode. There are two methods by which to get known states for testing purposes:
1) Clock a known value into the register on the next vector or;
2) Set RESET to logic low on one vector and then SET to low on the next or vice versa.










\title{
PAL® Design Function and Test Vectors
}

\section*{E. Young}

\section*{Introduction}

This article was written to help customers understand the purpose of seed vectors and provide some general guidelines as to what elements are important in developing them. It is assumed that the reader has read the "PALASM \({ }^{\text {™ }}\) Manual" and the "PAL® Handbook" article reprint Testing Your PAL Devices.
in general, PAL®/HAL® devices are required to provide a function table or "Seed Vectors" to Monolithic Memories in order to ensure that parts shipped have a high degree of reliability for the application intended. Ideally, these vectors should accomplish three objectives:
1) Initialize the PAL device preferably in the same way as in the actual system;
2) Exercise the customer's functions thoroughly, emulating actual system operation as closely as possible;
3) Provide a high degree of fault coverage.

\section*{Initialization}

Seed vectors which initialize the PAL logic circuit consist of one or more vectors placed at the very beginning which will bring both combinatorial and registered outputs to a stable and known logic state ( 1 or 0 ). This is necessary in the system also so that its operation upon power-up is predictable. Furthermore, care should be taken to ensure that the initialization state is a legal state of the state machine for which the PAL device is intended.

\section*{Exercise Functions}

The essential functions for which the PAL device was originally designed must be exercised fully. This will assure that the tested parts work the way they were intended to. In addition to essential "designed-for" functions, it is prudent to include general test exercises such as verifying that outputs don't change in the absence of clock pulses and checking to see that inputs in the "don't care" (X) state don't produce adverse responses. General test exercises help to reinforce the validity of a design and can uncover overlooked design errors. After a set of exercises has been decided upon, the next step is to write them in a format suitable for simulation purposes.
The designer may have originally defined the functions in terms of equations, state diagrams, truth tables, etc. Truth tables are readily reformatted to PALASM1 syntax "Function Tables" and exercises with the simulation option (code=S). State diagrams can be converted by expressing each state and input edge in binary vector format and sequencing them according to the diagram's flow. The customer should become thoroughly familiar with the syntax of the function table description (see the PALASM Manual for a detailed treatment of syntax) before attempting to translate truth tables, etc.

The following simple example demonstrates how exercising seed vectors might be derived from a designer's state diagram:


Assume the following state and edge definitions accompany the diagram:
\begin{tabular}{|c|c|c|}
\hline STATE \(0=L L\) & & EDGE \(0=L L\) \\
\hline STATE \(1=\mathrm{LH}\) & & EDGE \(1=\mathrm{LH}\) \\
\hline STATE \(2=\mathrm{HL}\) & & EDGE \(2=\mathrm{LL}\) \\
\hline STATE 3 \(=\mathrm{HH}\) & & EDGE \(3=\mathrm{LH}\) \\
\hline & & EDGE \(4=\mathrm{LL}\) \\
\hline & & EDGE \(5=\mathrm{HH}\) \\
\hline & (INITIALIZING) & EDGE \(6=\mathrm{HL}\) \\
\hline & (INITIALIZING) & EDGE \(7=\mathrm{HL}\) \\
\hline & (INITIALIZING) & EDGE \(8=\mathrm{HL}\) \\
\hline & (INITIALIZING) & EDGE \(9=\mathrm{HL}\) \\
\hline
\end{tabular}

From the above information, it is possible to create the truth table for the diagram and then the function table representation:
\begin{tabular}{|c|c|c|}
\hline EDGE & PRESENT STATE & NEXT STATE \\
\hline \(\mathbf{A B}\) & CD & CD \\
\hline \hline HL & XX & LL \\
\hline HH & LL & HL \\
\hline LL & HL & HL \\
\hline LH & HL & LH \\
\hline LH & LH & LL \\
\hline LL & LL & LH \\
\hline LL & LH & HL \\
\hline
\end{tabular}
\begin{tabular}{|c|c|c|}
\hline \multicolumn{3}{|c|}{ FUNCTION TABLE REPRESENTATION } \\
\hline FUNCTION TABLE \\
\hline AB & CD & \\
\hline HL & LL & INITIALIZE DEVICE \\
\hline HH & HL & TEST EDGE 5 \\
\hline LL & HL & TEST EDGE 4 \\
\hline LH & LH & TEST EDGE 3 \\
\hline LH & LL & TEST EDGE 1 \\
\hline LL & LH & TEST EDGE 0 \\
\hline LL & HL & TEST EDGE 2 \\
\hline
\end{tabular}

\section*{Fault Coverage}

Another criterion for seed vector completeness is "fault coverage". Fault coverage is an empirical method and is more quantitative than functional exercising - indeed, no knowledge of the circuit's intended function is necessary or assumed (although it could help) while developing fault coverage vectors.
Fault coverage, being an empirical approach to determining a logic circuit's reliability, uses the concept of "failure models" to grade the effectiveness of a given set of test vectors. This is called "fault grading". In fault grading a set of vectors, a fault coverage value is calculated that is simply the ratio of detected faults to total faults expressed as a percentage.

Test vectors may be graded against one or more failure models. Some well-known models include single stuck-at-1/ stuck-at-0, pattern sensitivities, shorts and opens and multiple stuck-at models. Selection of a failure model (or models) for fault grading fundamentally depends on the model's empirical effectiveness for screening bad parts and will be affected by a number of factors including circuit technology and fault simulator capabilities.
The most common and primary fault coverage failure model considered by "TGEN" at Monolithic Memories is the classic single stuck-at-1/stuck-at-0 failure model. "TGEN" automatically appends test vectors which test for the following additional failure models where applicable: 1) Adjacencies, 2) Clock, 3) Tri-state.
"TGEN" has a specified minimum value of fault coverage for PAL and HAL devices based on the single stuck-at failure model. The minimum values are determined by current "TGEN" policy (see your FAE) and reflect the economic trade-off between acceptable levels of reliability and the cost of test generation for maximum coverage. PAL and HAL devices for which the specified minimum values cannot be attained will require the customer's written waiver for low coverage prior to production release of the pattern.

The fault coverage percentage determined by "TGEN" is different from the percentage determined by selecting the fault testing option (code=F) of PALASM1 software. In PALASM1 software fault coverage is based on product term coverage (PTC). PTC is still the ratio of detected to total faults except that "detected" and "total" fault sums refer to stuck-at faults on product term outputs only. PTC ignores stuck-at faults which occur anywhere else. A more accurate procedure is to calculate the coverage based on all the circuit nodes where a stuck-at condition may occur. When every node (fault site or wire) is considered, the coverage calculated correlates to the design's testability better and will generally be a much lower value than PTC. "TGEN" goes one step further in conservatism by calculating fault coverage on a "collapsed" fault basis. Fault collapsing simply divides all the stuck-at faults into groups such that, within a group, if one fault is detected, then all the others in the group are detected too. The advantage of collapsing it that only one representative fault in a group needs to be selected for test generation and if it is detected, then the other "equivalent" faults are detected by definition. This saves time and effort on test generation for equivalent faults. Calculations on a collapsed fault basis treat each group as one fault.
The following simplified example demonstrates the difference in fault coverage calculations using a collapsed fault list:


Note: This example is a simplified one for illustrative purposes only and does not show the effects of faults normally associated with input or output buffers. Also, some partial collapsing has already been done (i.e , input faults of "OR" gate are collapsed into output faults of "AND" gates).

Assume the above circuit is to be realized as a PAL or HAL device. Suppose some seed vectors are provided also, as shown here:
\begin{tabular}{|c|c|c|c|c|c|c|c|c|c|}
\hline & A & B & C & D & E & F & G & H & I \\
\hline \hline VECTOR 1 & H & H & H & L & L & L & L & L & L \\
\hline VECTOR 2 & L & L & L & H & H & H & L & L & L \\
\hline VECTOR 3 & L & L & L & L & L & L & H & H & H \\
\hline VECTOR 4 & L & L & L & L & L & L & L & L & L \\
\hline
\end{tabular}

The seed vectors on the previous page yield various values for fault coverages corresponding to the method of calculation as shown in the table below.

\begin{tabular}{|l|l|l|l|l|}
\hline & PTC & EVERY NODE & COLLAPSED & \\
\hline \hline SUBSET OF TOTAL & 20 & \(2,4,6,20,26\) & 2 & 8 \\
FAULTS CONSIDERED & 22 & \(8,10,12,22\) & 8 & Vector 1 \\
\cline { 2 - 5 } FOR CALCULATIONS & 22 & \(14,16,18,24\) & 14 & Vector 2 \\
\cline { 2 - 5 } THAT ARE DETECTED & 24 & \(19,21,23,25\) & 19 & Vector 3 \\
BY EACH VECTOR & \(19,21,23\) & \(1,2,3,4,5,6,7,8,9,10,11\), & \(1,2,3,5,7\), & Vector 4 \\
\cline { 2 - 5 } (SHOWN AT FAR RIGHT) & 19,20, & \(8,9,11,13\), & \\
\hline TOTAL FAULTS & 21,22, & \(14,15,17,19\) & \\
CONSIDERED FOR & 23,24 & \(19,20,21,22,16,17,18,24,25,26\) & \(4 / 13=31 \%\) & \\
\hline CALCULATIONS & \(6 / 6=100 \%\) & \(17 / 26=65 \%\) & & \\
\hline PERCENT COVERAGE & & & & \\
\hline
\end{tabular}

As can be seen from the above example, given the same seed vectors, PALASM1 software would show \(100 \%\) coverage whereas "TGEN" would show \(31 \%\) coverage. Notice that the poor coverage by "TGEN" is due to none of the input nodes being tested for stuck-at-1. In most instances, a better set of test vectors
can improve the coverage significantly. For the above example, the reader can verify that the following slight modification of the seed vectors would yield \(100 \%\) coverage for all calculation methods:
\begin{tabular}{|l|c|c|c|c|c|c|c|c|c|}
\hline & A & B & C & D & E & F & G & H & I \\
\hline \hline VECTOR 1 & H & H & H & L & L & L & L & L & L \\
\hline VECTOR 2 & L & L & L & H & H & H & L & L & L \\
\hline VECTOR 3 & L & L & L & L & L & L & H & H & H \\
\hline VECTOR 4 & L & H & H & L & H & H & L & H & H \\
\hline VECTOR 5 & H & L & H & H & L & H & H & L & H \\
\hline VECTOR 6 & H & H & L & H & H & L & H & H & L \\
\hline
\end{tabular}

\section*{Testability}

The previous sections described some essentials for comprehensive seed vector set. Variations on how fault coverage is calculated was covered also. However, no matter how it is calculated, fault coverage is only as good as the testability of the circuit permits. Using the stuck-at failure model, the customer must consider both absolute and practical fault coverages achievable for his PAL/HAL logic circuit design. Certain testa-
bility factors, such as redundancy, number of test points (outputs) or reconvergence, affect absolute (i.e., theoretical maximum) coverage. Other factors, including preloadable state machines, the amount of feedback and overall controllability, will affect practical coverage since many faults may be potentially detectable but uneconomical to detect due to excessive vectors or difficult to reach states. As testability is improved, absolute and practical fault coverage will usually increase.

\section*{A Study of the anomalous behavior of synchronizer circuits}

\section*{Danesh M. Tavana}


\section*{INTRODUCTION}

This article will summarize the results of the studies performed on synchronizer circuits. The information presented may be used by system designers to gain insight into the anomalous behavior of edge riggered flip-flops. Understanding flip-flop behavior and applying some simple design practices can result in an increased reliability of any system.

\section*{METASTABILITY}

In the digital world a bit represents the fundamental unit of measure The output state of any digital device is either "HIGH" (a voltage level above VIH) or "LOW" (a voltage level below VIL) as shown in figure 2 Under the proper operating conditions the register in figure 1 outputs a HIGH or a LOW on the rising edge of the clock within a nominal delay called the "clock to out" delay If the setup and hold times are violated the register has a small probability of entering a third region of operation called the "metastable" state. Metastable is a Greek word meaning "in between" and it is a state between HIGH and LOW. Even though most synchronizers snap out of metastability in a short period of time, theoretically this state can persist indefinitely. Some of the registers built from older technologies had metastable states which lasted as long as a few microseconds. When the output of a device goes into metastability the clock to out delay will be grossly affected. This may alter the system's worst case propagation delay and potentially lead to a system crash


\section*{SYNCHRONIZERS}

The design of a synchronous digital system is based on the assumption that the maximum propagation delay of a flip-flop and any other gates are known. A digital system is free of hazardous race conditions and timing anomalies if the maximum propagation delay in the system does not exceed the clock's period. In systems where an asynchronous input is intertaced with a clocked device such as a flip-flop, the maximum specified propagation delay of this device may no longer be valid if certain electrical parameters are violated Computer peripherals, an operator's keyboard, or two independently clocked subsystems are instances where there is a possibility of interfacing an asynchronous input which will violate the synchronizer's electrical parameters

A popular device typically used in synchronized systems is the edge-triggered register shown in figure 1. The edge-triggered register will properly synchronize the incoming data to the system's clock as long as its operating conditions are satistied. Table I summarizes these specifications for Monolithic Memories Inc's (MMI) 74ILS374 register. It is difficult to guarantee setup and hold time requirements when the data is asynchronously interfaced to a register The violation of setup or hold time in a register has a probability of initiating a misbehavior termed "Metastability"
\begin{tabular}{c|l|ccc|c}
\hline SYMBOL & \multicolumn{1}{|c|}{ PARAMETER } & \multicolumn{3}{|c|}{ COMMERCIAL } & UNIT \\
& & MIN. & TYP. & MAX. & \\
\hline \(\mathrm{V}_{\text {CC }}\) & Supply Voltage & 4.5 & 5 & 5.5 & V \\
\hline \(\mathrm{~T}_{\mathrm{A}}\) & Operating free air temp & 0 & & 75 & \({ }^{\circ} \mathrm{C}\) \\
\hline \(\mathrm{t}_{\mathrm{w}}\) & Width of clock & 15 & & ns \\
\hline \(\mathrm{t}_{\mathrm{su}}\) & Setup time & 20 & & ns \\
\hline \(\mathrm{t}_{\mathrm{h}}\) & Hold time & 0 & & ns \\
\hline
\end{tabular}


NS
Figure 2
The diagrams in figure 3 illustrate some examples of waveforms in the metastable condition. From the waveforms it is evident that the outputs are distorted under metastable conditions. Figure 3d shows the output of a typical 74LS374 register manufactured by Monolithic Memories. Monolithic Memories family of bipolar devices exhibit superior metastable hardened pertormance due to their high speed bipolar technology and advance Schottky TTL circuit design techniques Most of these devices typically snap out of metastability in a flashing 15 nanoseconds

\section*{WHY THE SYNCHRONIZER FAILS}

Before attempting to explain how the synchronizer's internal circuity fails let's take a look at an interesting problem
PROBLEM: In the SR type latch shown in figure 4 what happens if the set ( \(S\) ) and the reset ( R ) inputs are simultaneously raised from a LOW voltage level to a HIGH level?
transition and will quickly oschllate to a nnai steaay state on enter finun or LOW (see fioure 3a). To demonstrate this result the reader is encouraged to do this excercise either mentally or to actually build the circuit and view the output on the oscilloscope.
riggered flip-flop with an asynchronous data interface. If the setup and hold times of the flip-flop are satisfied the output behaves properly (figure 6a). One of the four possible events below can take place if the flip-flop goes metastable:

(a) CROSS-TIED NAND GATES
(b) REGISTER WITH NORMAL BEHAVIOR

(c) MONOLITHIC MEMORIES INC'S PAL16R4A


(d) MONOLITHIC MEMORIESINC:S Figure 3

Clock driven master-slave flip-flops contain the same type of cross tied RS latch within their internal circuitry. The NAND gate equivalent of the master-slave D type flip-flop is shown in figure 5. The gates circled in this figure can potentially behave similar to the above problem. If the clock and data are triggered within a specific window of one another the output may have an oscillatory behavior before settling down.


Cross tied RS latch structure is seen in the master-slarve edge triggered flip-flop.

Figure 5
1) The output starts to make a transition but snaps back to its origina state (figure 6b).
2) The output makes a complete transition but the maximum propagation delay of the device is exceeded (figure 6c).
3) The output starts oscillating and retains its present state (figure 6d).
4) The output oscillates to a new state (figure 6e).


Figure 6

The circuit shown in figure 7 is used to obtain experimental results of a metastable device. The circuit can detect and count the number of events of metastability. The device under test (DUT) is forced into metastability by repeatedly sweeping the edges of the data past the rising edges of the clock. The modulation of the data is possible by using a comparator device (Ul) along with an external sawtooth waveform Thousands of transitions are created within the setup and hold time window of the DUT. Sweeping the data edges past the low to high clock transitions simulates an asynchonous input and increases the probability of getting a metastable failure on the output ( \(Q\) ) of the DUT.

(1) PROPER OUTPUT WAVEFORM
(1) \(\triangle\) CLOCK SAMPLES THE OUTPUT (®) AFTER A DELAY \(\triangle\)

\section*{Figure 7}

If the output of the device goes into metastability it will be detected by the comparator pair (U2) and (U3). The comparators will have complementary outputs if the output ( \(Q\) ) of DUT is anywhere between VIH and VIL. The outputs of the comparators are latched by a delayed version of the clock ( \(\triangle\) Clock). The EXCLUSIVE-NOR gate followed by the register signal the event of metastability to an external counter.
The variable delay \((\Delta)\) between the two clocks will sample the output at various locations on the time axis. As this delay is varied the event of metastability is sampled and counted at these locations by our circuit. Therefore the output of our circuit measures the rate of metastability versus time delay. The real behavior of a metastable output can thus be effectively characterized with this scheme, that is, we can determine the length of time a metastable condition will persist and the density distribution of the metastable event.
Three 74374 devices and four PAL devices are used in this experiment. The plots of metastable failure versus time are shown in figures \(8 a . b\). The next section will discuss in detail the characteristics of these plots.

\section*{EXPERIMENTAL RESULTS}

Various graphs of metastability failure rate versus delay time are illustrated in figure 8 . We can conclude from these graphs that the rate of metastability failure decreases as the sample clock ( \(\triangle C L O C K\) ) moves farther and farther away from the DUT clock. The pictures shown in figure 9 have captured repeated events of metastability on the oscilloscope

Let's take a closer look at one of the graphs to examine the behavior of the device. The PAL16R4A-4 device exhibits one count per second if the delay \((\Delta)\) is 60 nanoseconds. As the delay \((\Delta)\) is decreased. the rate increases exponentially until the delay equals 32 ns at which point the rate flattens out and remains fixed. The 32 ns forms the knee of our graph and will be relerred to as \(\Delta 0\). The rate will remain constant if the delay \((\Delta)\) is decreased past the knee of our graph. Further reduction in the delay will place the sampling clock's rising edge prior to data transitions and thius the error rale vanishes to zero. The time at which the rate goes to zero is marked with an (X) on the graphs. By using this time \((X)\), and another location on the graph such as the time where only one error per second occurs, we can associate an approximate range of metastability for different devices. This range of metastability is referred to as the "mean time to snap out of metastability". From the graph it is evident that the mean time to snap out of metastability for the PAL16R4A\(4 \operatorname{logic}\) circuit is the difference between 60 ns and 25 ns which is 35 ns .



All of the graphs illustrated can be quantified by an equation of the form:
\[
\log \text { FAILURE }=\log \mathrm{MAX}-\mathrm{b}(\Delta-\triangle 0)
\]

Since a natural logarithm is a constant multiple of base 10 logarithm we can rewrite the above equation as:
\[
a \cdot \ln \text { FAILURE }=a \cdot \ln M A X-b(\Delta-\Delta 0)
\]

In the above equation the MAX value is representative of the maximum metastability failure rate in our device. This MAX value is closely related to the frequency at which a metastable condition may occur in our device. The frequency at which metastability occurs is simply a constant multiple of the product of CLOCK and DATA frequency
\(\mathrm{MAX}=\mathrm{Kl} \cdot \mathrm{I}_{\mathrm{CLOCK}} \cdot \mathrm{I}_{\text {DATA }}\)

Substituting this in our original equation we get:
\[
\begin{gathered}
\mathrm{a} \cdot \ln \text { FAILURE }=\mathrm{a} \cdot \ln \left(\mathrm{Kl} \cdot \mathrm{f}_{\mathrm{CLOCK}} \cdot \mathrm{f}_{\mathrm{DATA}}\right)-\mathrm{b}(\triangle-\triangle \mathrm{O}) \\
\ln \text { FAILURE }=\ln \left(\mathrm{Kl} \cdot \mathrm{f}_{\mathrm{CLOCK}} \cdot \mathrm{f}_{\mathrm{DATA}}\right)-\mathrm{b} / \mathrm{a}(\Delta-\triangle \mathrm{O}) \\
\text { FAILURE }=\left(\mathrm{Kl} \cdot \mathrm{f}_{\mathrm{CLOCK}} \cdot \mathrm{f}_{\mathrm{DATA}}\right) \mathrm{e}^{-\mathrm{k} 2(\Delta-\Delta \mathrm{O})}
\end{gathered}
\]

Metastability


Table 2 gives the three important parameters which can be used by system designers to fully characterize the metastable behavior of the mentioned devices. These parameters can be obtained for different devices by duplicating this experiment. An example is given below to show how the information on table 2 may help the designer in the design of asynchronous systems
\begin{tabular}{c|l|c|c|c}
\hline \multirow{5}{*}{ MANUFACTURER } & DEVICE & \(\mathrm{K}_{1}(\mathrm{Sec})\) & \(\mathrm{K}_{2}\left(\mathrm{~ns}^{-2}\right)\) & \(\triangle \mathrm{O}(\mathrm{ns})\) \\
\hline \multirow{5}{*}{ MMI } & PAL16R4 & \(1 \times 10^{-7}\) & 4.3 & 37 \\
\cline { 2 - 5 } & PAL16R4A & \(1 \times 10^{-7}\) & 4.3 & 34.5 \\
\cline { 2 - 5 } & PAL16R4A-2 & \(1 \times 10^{-7}\) & .64 & 25 \\
\cline { 2 - 5 } & PAL16R4A-4 & \(1 \times 10^{-7}\) & 5 & 31 \\
\cline { 2 - 5 } & 74 LS 374 & \(2 \times 10^{-7}\) & 1.8 & 27.5 \\
\hline AMD & 74 LS 374 & \(2 \times 10^{-7}\) & 2.0 & 34.5 \\
\hline FAIRCHILD & \(74 \mathrm{~F}_{3} 74\) & \(2 \times 10^{-7}\) & 11.5 & 17.5 \\
\hline
\end{tabular}

Table 2

EXAMPLE
For the hardware implementation in figure 10 determine the maximum clock frequency to give a typical error rate of one failure per year We must choose the minimum period to give an error rate of less than

one failure per year. From this result we can determine the maximum clock frequency. The time \(\Delta\) in the equation below will determine the distance between clock edges. We must determine \(\Delta\) from the equation by numerical extrapolation. The system clock's period can be represented as ( \(\triangle+\) Tcc + setup). or plugging in the numbers it is \(\triangle+75\).
\[
\text { FAILURE }=\left(\mathrm{K} 1 \cdot \mathrm{f}_{\mathrm{CLOCK}} \cdot \mathrm{f}_{\text {DATA }}\right) \mathrm{e}^{-\mathrm{K} 2(\Delta-\Delta 0)}
\]
and plugging in the appropriate values we have:
\[
3.2 \mathrm{EE}-8=[(1 \mathrm{EE}-7)(1 /(\Delta+75 \mathrm{~ns}))(9600)] \mathrm{e}^{-[(4.3)(\Delta-37)]}
\]

Solving for \(\Delta\), we see that it is approximately 43 nanoseconds. The system period is thus seen to be the sum of 43 ns and 75 ns or 118 ns . The maximum clock frequency is the inverse of the period or approximately 8 MHz .

\section*{CONCLUSION}

Synchronization of two independent pulse trains is possible through the use of edge triggered registers. The electrical characteristics of the flip-flop are affected when the setup and hold times of the device are violated. This misbehavior is termed "metastability" and its probability of occurrence can be derived for a given system. The factors which affect this probability and the length of time which a metastable condition persists are influenced by the technology of the device as well as by the circuit design techniques.

An important fact which needs to be stressed is that even if a register's output goes metastable, the system may not necessarily fail if the register snaps out in time to satisty the system's worst case timing requirement. The following design practices are suggested when using synchronizers:
Try to minimize the number of locations where asynchronous signals enter your system.
Clocking the asynchronous inputs through two pipelined registers can greatly reduce the error rate.
Use a single clock within your local system environment. For multiple system clocks, derive all the clock signals from a single source to assure synchronization between different devices within the system.

When analyzing the worst case timing of your system, add the time to snap out of metastability to any register in an asynchronous data path.
A single PAL " with registers can be your best choice for state machine analysis of asynchronous events. As the registers have virtually identical setup times, the simultaneous observation of a metastable event by different register states are likely to be the same. Contrasted to a distributed system of observing register states with different setup times. the PAL system of register states with identical setup times is a superior synchronizer.
Avoid edge sensitive devices on the output paths of the registers which have asynchronous inputs. The glitch created when the synchronizer goes metastable is enough to trigger the edge sensitive device. The use of level sensitive devices is generally a better design practice.
PAL devices can be effective synchronizers where various registering schemes are easily implemented.

\title{
Fast 64x64 Multiplication Using 16x16 Flow-Through Multiplier and Wallace Trees*
}

\author{
Marvin Fox, Chuck Hastings and Suneel Rajpal
}

The Monolithic Memories SN54/74S556 is a high-speed fullyparallel \(16 \times 16\) multiplier and it provides the entire 32 -bit product on a flowthrough basis from a single part. It is available in an 84-pin Leadless Chip Carrier (LCC) and 88-pin, pin-grid array packages. 8x8 40-pin array-multipliers such as the SN54/74S557/8 have been available for several years, however there is a large parts count for implementing longer wordlengths.
This paper describes the design philosophy and internal architecture of the 'S556 and appiications for larger wordlength mul-
tiplications such as 32,48 , and 64 bits using these multipliers and high-speed PROMs and ALUs also available from Monolithic Memories.

The system advantages for using the 'S556 over the MPY-16Hclass multipliers is also discussed; the main advantages being the availability of the entire product each cycle and the space savings on the board.

* This paper is a slightly updated version of the paper by the same name which appeared in the Northcon/83 Professional Program Session Record, Session 24 reprint, paper 24/2, 10-12 May 1983. A modified version subsequently also appeared in the Mini Micro West/83 Professional Program Session Record, Session 14, paper 14/2, 8-11 November 1983

\section*{Summary}

Multiplication is one basic digital-computer operation which can readily be speeded up by employing massive parallelism. "Cray multiplication" techniques, first used in large specialpurpose computers a quarter of a century ago, are now commonplace in high-performance systems.
Essentially, in Cray Multiplication a full adder is placed in every position which would be occupied by a partial-product bit in a pencil-and-paper binary multiplication example (r1, r2). This technique may be applied within an LSI integrated circuit, in a system, or in both at once; it may or may not be modified by using "Booth-multiplication" approaches (r3, r4, r5).
\(8 \times 8\) 40-pin Cray-multiplier integrated circuits have been available for several years, with a useful "flow-through" architecture. However the parts count for implementing fullblown Cray multiplication with practical scientific-computation word-lengths has been quite large. There have, of course, been several 16x16 Cray-multiplier 64-pin integrated circuits available; however, these have been unable, because of pin limitations, to furnish an entire 32-bit product in parallel. As a result, long-word-length multiplication cannot be performed economically on a flowthrough basis using these parts; some sort of clocking and multiplexing scheme is necessary to use them whenever the wordlength exceeds 16 bits, or else they must be duplicated outright.

Now there is a \(16 \times 16\) Cray-multiplier part, the Monolithic Memories SN54/74S556, which provides the entire 32-bit product on a flow-through basis from a single part. The 'S556 has been designed to use the new 84-pin leadless-chip-carrier (LCC) and 88-pin pin-grid array packages, rather than compromising the architecture of the part because of the pin limitations (64 at most) of dual-in-line (DIP) packages.
This paper describes the design philosophy and internal architecture of the 'S556. It also shows how long-wordlength multipliers may be built up from arrays of individual

Cray-multiplier integrated circuits and programmable readonly memories (PROMs); the latter are used as "Wallacetree" adders. Part-count and performance comparisons are made, for the representative word length of 64 bits, between implementations based on \(64-\) pin \(16 \times 16\) devices and implementations using 'S556s, in two different architectures; one which aims at lower cost and is a compromise between Cray multiplication and traditional shift-and-add multiplication.


MULTIPLICATION . . . CAN READILY BE SPEEDED UP BY EMPLOYING MASSIVE PARALLELISM . . ."

\section*{'S556 Architecture}

The 'S556, shown in Figure 1, is a \(16 \times 16\) Cray multiplier designed with an ultra-high-speed array of 256 adders, internally organized to the shift-and-add technique for multiplication (r1, r2). In place of the usual ripple-carry adders used in multiplier designs to sum up the final product bits, the 'S556 uses a carry-lookahead adder.


The "flow-through" architecture of the 'S556 works equally well in synchronous or asynchronous pipelined systems. Latches are available to hold the input operands and the resulting double-length product, to increase the throughput rate in pipelined systems. If the designer does not wish to use these latches, they may be disabled, and the 'S556 then operates as a pure memoryless arithmetic network.

The 'S556 accepts operands in either unsigned or signed twos-complement form. When used in pipelined architectures, the S556 is capable of supplying 32-bit products at a 12.5 MHz repetitive throughput rate. The 'S556 has threestate outputs, controlled by the TRIL and TRIM control inputs.

Rounding-control input pins are provided on the 'S556 for rounding either unsigned or signed operands. Rounding is allowed in either of two binary positions, to support either "fractional-arithmetic" or "integer-arithmetic" positioning of a single-length rounded result.
The more traditional shift-and-add technique was chosen for the internal design of the 'S556 adder network because of the compactness, simplicity, and lower power requirement of this implementation. The Booth-algorithm approach, which groups the multiplier bits to effectively reduce the number of rows in the array, was considered (r3, r4, r5). However this approach also has penalties, in that it increases the width of each row from 16 to 18 bits, and the width of the final adder from 18 to 24 bits. Intrinsically, both the shift-and-add technique and the Booth-algorithm technique require 31 logic delays in the multiplier array using a ripple-carry final adder. At this point, the use of a carry-lookahead adder structure results in major speed improvements.


Here again there are tradeoffs. In MSI bipolar circuits, carry-lookahead parts are reasonable to construct with scanning widths of up to 4 bits, with a carry-out available (r5). Beyond that, the circuit gets bulky and power-hungry. Parallel "banking" of 4-bit-adder groups may be used to extend this limit, but here again 4 to 5 banks is as far as this approach can be reasonably pushed. With parallel banking the 24-bit adder required by the Booth-algorithm technique can be implemented using 6 banks of 4 -bit adders; this exceeds the limit of 4 to 5 banks. This shows that the Booth-algorithm
implementation requires fewer horizontal rows of adders, which translates to shorter propagation delays as compared to shift-and-add technique; however the final adder in the Booth-algorithm implementation is slower than the final adder in the shift-and-add technique implementation.
The 'S556 internal design uses an Emitter-Coupled-Logic (ECL) circuit implementation, based on Monolithic Memories new washed-emitter process. ECL was chosen here over TTL and Emitter-Follower Logic, both of which have been used in previous Monolithic Memories Cray-multiplier designs ( \(\mathrm{r} 3, \mathrm{r} 4\) ). Here, ECL also turns out to have the most compact circuit-layout form, requiring 82 square mils of chip surface area per full adder. Emitter Function Logic (EFL) was chosen for one portion of the design, the carry-lookahead tree, because it interfaces easily with single-ended ECL outputs. All latches are implemented in ECL, to interface easily with the TTL/ECL buffers at the inputs and the ECL/TTL buffers at the outputs. The input latches introduce one ECL delay, but there is zero additional delay at the outputs as the output latches are incorporated right into the ECL/TTL translators.
The 'S556 is a universal multiplier aimed at a flow-through-type-processor architecture. Latches are used since registers cannot implement a flow-through architecture directly.
To be sure, the currently-available \(16 \times 16\) multipliers from TRW and AMD, which use 64-pin dual-in-line packages do have a feed-through capability on the output registers. This capability allows latch-like transparency on the output registers, but nowhere else, since the parts are pin-limited and input and output data must in some cases share the same pins. Such an implementation consumes considerably more chip area and power than a purely latch design.

".. THE 'S55G INTERNAL DESIGN USES
MONOLITHIC MEMORIES' NEW WASHED-EMITTER PROCESS...

Many users who wish to use registers to achieve pipelined operation can find ways to do so using the 'S556s' internal latches. Usually pipelining can be achieved by choosing the proper phasing and pulse width of the latch gate-control signals without resorting to using external registers. Of course, external registers may be used when absolutely necessary.
The 'S556 will be supplied in an 84 -pin Leadless Chip Carrier (LCC), and also in an 88-pin pin-grid-array package, with an integral heat sink. Both Commercial and Military grade parts will be available. The pinout is shown in Figure 2a. A photograph of the 84 -pin LCC package is shown in Figure 2b.


Figure 2a. The 'S556 Pinout Diagram


Figure 2b. The 'S556 84-pin LCC package

\section*{Expansion for Longer Wordlengths}

A major advantage of the 'S556 is the availability of all 32 product bits in 100 nsec from the very beginning of a multiply operation, or every 80 nsec on a repetitive pipelined basis. (These times, and others quoted in this paper, are worst-case rather than typical.) Thus, the 'S556 is especially suited for longer-wordlength arithmetic units.
Other commercially-available multipliers, of the TRW MPY-16H class, are packaged in 64-pin 900-mil DIPs, which require a circuit board area of approximately \(1^{\prime \prime} \times 3.25\)." Moreover, these parts operate more slowly in expanded configurations, as the most-significant half and the leastsignificant half of the 32 -bit double-length product must be obtained on two successive clock cycles.

\section*{Totally-Parallel 32-bit Multiplier}

The 'S556, together with PROMs organized in a "WallaceTree" configuration, can sail along at the rate of four \(56 \times 56\) multiplications every microsecond. An unsigned 32-bit multiplication can be performed using 4 'S556 multipliers, 11 63S481A PROMs used as "Wallace-Tree adders" (r1), and 16 'S381 and 5 'S182 used to form a 64-bit adder. The multipliers supply the partial products which are positioned as shown

in Figure 3. The difference is that only unsigned operands are used, and only positive partial products are added. The three rows of partial products which overlap are added by using PROMs which "compress" these three rows to 2 rows, which are then added in the 64-bit adder. The compression technique is discussed in greater detail in the description, later on, of the 64 -bit multiply operation. Using the above configuration, an unsigned \(32 \times 32\) multiply operation can be performed in less than 175 nsec worst-case allowing for a 75 -nsec 'S556 multiplier delay, a 30-nsec 63S481A PROM delay and a 64-nsec 64-bit adder delay.


Alternatively, a twos-complement \(32 \times 32\) multiplication can be performed within 228 nsec using 4 'S556s, 18 'S381s, and 7 'S182s. This \(32 \times 32\) multiply operation involves the adding up of four partial products as shown in Figure 3. These four partial products are generated in four multipliers; the outputs are \(X A * Y A, X A * Y B, X B * Y A, X B * Y B\), where \(X 31-16=X B\), \(\mathrm{X} 15-0=\mathrm{XA}, \mathrm{Y} 31-16=\mathrm{XB}, \mathrm{Y} 15-0=\mathrm{XA}\).
The implementation of this twos-complement \(32 \times 32\) multiplier is shown in Figure 4. The outputs of the \(16 \times 16\) multipliers are connected to two levels of adders to give a 64-bit product. The first level of adders is needed to add the two central partial products of Figure 2, \(X A * Y B\) and \(X B * Y A\). Notice the technique which is used to generate the "sign extension" or the most-significant sum bit of the first level of adders. The ' S 556 provides as a direct output the complement of the most-significant product bit; having this signal immediately speeds up the sign-extension computation, and reduces the external parts count.


Figure 4. Implementation of the \(32 \times 32\) Multiplier

For example, the inputs to the adder in the most significant position are the \(\overline{\$ 31}\) outputs from the two central multipliers. The sign extension of the addition of \(X A^{*} Y B\) and \(X B^{*} Y A\) is defined as

\section*{SIGN EXT \(=\overline{\bar{A}} \cdot \bar{B} \cdot+\overline{\mathrm{A}} \cdot \mathrm{C}+\overline{\mathrm{B}} \cdot \mathrm{C}\), where}
\(A\) is the most-significant bit of the term \(X A * Y B\);
\(B\) is the most-significant bit of the term \(X B * Y A\); and
\(C\) is the carry-in to the most-significant bits of \(X A * Y B\) and \(X B * Y A\), in the adder.
The sign extension can be computed as the negation of the carry-out term of three terms, A, B, and C. This term corresponds to the negative of the carry-out of the bit position just one place to the right of the most-significant bit position of the first level of adders. The negative of the carry-out can be generated by presenting a carry-out and a binary "one" to the most significant bit of the adder. The generated sum bit then corresponds to the negation of the carry-out of the previous stage, which is the sign extension required to be added to the 16 most-significant bits of the XB*YB partial product term.
The second level of adders, which performs a 40-bit add function, is fairly straightforward. These adders can be implemented using 'S381 four-bit ALUs and 'S182 carry-bypasses ("carry-lookahead generators") which are available from Monolithic Memories, Inc. and from other vendors.
Other configurations such as \(48 \times 48\) multipliers can be designed using the same methodology. Figure 5 shows the alignment of the partial products from 9 ' 5556 s for the \(48 \times 48\) case.

\section*{Serial-Parallel Multiplier}

In applications where speed can be sacrificed, it is possible


Figure 5. Partial Products for a \(48 \times 48\) Multiplication
to implement an alternative solution using fewer multipliers, at some penalty in speed, but still with a very significant speed gain over other methods of multiplication. Figure 6 shows a plausible method of performing a \(64 \times 64\) multiply operation, in four cycles. Each cycle generates four partial products, each of which is 32 bits wide; these must be added in at the appropriately-aligned bit positions to generate an 80-bit partial product, in logic external to the multipliers. On the next cycle another 80 -bit partial product is generated, and is added to the previous 80 -bit partial product at the appropriate alignment offset. Figure 7 shows the 16 32-bit partial products aligned appropriately to their binary weighting, for the entire time-sequenced multiply process. The final 128-bit product can be obtained from the addition of the four 80 -bit partial products on successive clock cycles.


THE \(Y_{1}\) - PARTIAL 16 -BIT OPERANDS \(Y_{D}, Y_{C}, Y_{B}, Y_{A}\) ARE LOADED AND MULTIPLIED BY THE ENTIRE 64-BIT X OPERAND IN FOUR STEPS TO OBTAIN A 128-BIT PRODUCT AS SHOWN IN FIGURE 7.

Figure 6. A Serial-Parallel Multiplier Architecture

\section*{Totally-Parallel 64-Bit Multiplier}

A speed-oriented hardware configuration takes the approach of using whatever external logic is needed for the very fastest possible \(64 \times 64\) multiply operation. Figure 7 may be applied in this case also; it shows 16 32-bit partial products. (For simplicity, will assume that the configuration described here deals strictly with unsigned integers, so that the 16 partial products are unsigned.) Since 16 ' 5556 s are being used, then the 32-bit partial products corresponding to all of the combinations of the partitioned multiplier and the partitioned multiplicand are all available at the same time. Now comes the crucial aspect of the design, which involves adding all of these bits in at the appropriate binary positions!

Figure 8 shows the aligned configuration of the partial products for a \(64 \times 64\) multiply operation. Each dot represents an output bit of the 'S556, shown at the topmost part of Figure 8. To generate the final product, these partial products must be "compressed." This compression can be achieved by grouping product bits in a logical manner, so
that "deep and short" vectors are compressed to "shallower and longer" vectors. What is really being accomplished is the addition of several (here 3,5 or 7) bits having the same weight into a simple binary sum; and then the adding up of all of these (overlapping) sums, which is normally much easier. This two-step summation is performed by a "Wallace-treeadder" arrangement ( \(r 1, r 2, r 3\) ) in which 7 vectors of varying lengths are compressed to 2 vectors, and these are in turn presented as 2 operands to a single carry-lookahead adder. The dots shown in the inverted pyramidal array in the middle of Figure 8 represent compressed outputs generated from the first level of dots. The lowermost array of dots represent the inputs to the adder; these are "compressed" outputs from the Wallace-Tree array.

For example, group A shown in Figure 8 consists of a \(3 \times 3\) column of bits. If all of these bits were binary "ones" then the result when they were added would be \(3+(3.2)+(3.4)=\) 21 , which is representable in 5 binary positions. This is precisely what "A1" signifies; a compression of a \(3 \times 3\) block, \(A\), to a 5 -bit vector, A1. The compression can easily be achieved by using a PROM, with the 9 bits of A as address lines, and the outputs as A1. The PROM used in this example is the Monolithic Memories 63S481A 30-nsec 512x8 PROM; only five of the eight output bits are used. Designers may prefer to group the bits in a different configuration from the one suggested in Figure 8; many other arrangements are possible. For example, one may group another column of three bits and thereby reduce a \(4 \times 3\) block to a 6 -bit vector, using 63S3281s, which are ( \(40-\mathrm{nsec} 4 \mathrm{Kx8}\) PROMs); this approach would give a different pattern than the one in the middle of Figure 8.

Similar compressions for Group B to B1 can be performed using 63S441/1A \(1 \mathrm{~K} \times 4\) PROMs. This configuration compresses five 2 -bit vectors to a 4 -bit vector, which fits the 10 -bit input address and 4-bit output word of the \(1 \mathrm{Kx4}\) PROM.


Figure 7. Partial Product Alignment for a Serial-Parallel Multiplier


Other compressions shown are C and D groups to C 1 and D1 respectively. The C group is handled by compressing five 1 -bit vectors to a 3 -bit vector. The D group is handled by compressing seven 1 -bit vectors to a 3 -bit vector. The C and D groups can be compressed using 'S141/1A 256x4 PROMs. Similarly, groups E, F, G, and H are compressed to E1, F1, G1 and H 1 respectively. All the above mentioned PROMs are available from Monolithic Memories.

The second level of dots has some groups of four columns These four-column groups contain 3 bits in the leastsignificant bit position, and 2 bits in the remaining columns. These 9 inputs can be compressed using a 63S481A 30nsec \(512 \times 8\) PROM, to a vector 5 bits wide. For parts-counting purposes, the same 63S481A PROM type is used for all the compressions in the middle of Figure 8.

To aid users in the programming of PROMs for these and other Wallace-tree applications, or in fact any other applications exploiting PROMs as logic elements, Monolithic Memories provides Programmable Logic Element ASseMbler (PLEASM), a portable computer program written in FORTRAN. PLEASM provides a simple method for generating a PROM truth table. The user has only to supply equations which define the arithmetic/Boolean function needed within the PROM; PLEASM does all the drudgery of figuring out the code values which are needed in each PROM location.

Sample PLEASM source codes are shown at the end of this paper. For example, the entire 1 Kx 4 PROM which reduces the five 2-bit vectors to a 4-bit vector can be specified, using PLEASM, in 15 or fewer lines of code. Without PLEASM or its equivalent, the user would have had to specify the contents of 1024 PROM locations, after computing the corresponding code values for those locations.

\section*{Performance Comparisons}

The bottom line for any hardware-architecture analysis is how fast the system runs, and what it costs in circuit-board
real estate and dollars. With this understanding, a performance table is derived, based on three configurations.
The first is the configuration of Figure 7, using 4 'S556 multipliers; the entire multiplication takes four clock cycles. In addition to the multiplier ICs, a 64-bit adder is needed for the four partial products, which effectively furnishes a 80-bit partial product on every cycle. A 64-bit adder can be used to do the addition, since the least-significant partial-product bits are available directly. The 80-bit partial product has to be shifted 16 bits and then added to the second 80-bit partial product, which implies a need for a 64-bit register and an 80 -bit ALU, which together serve as an accumulator.
The second configuration is the totally-parallel design using 16 'S556 multipliers plus PROMs and ALUs, shown in Figure 8.

The third configuration uses TRW-MPY16H-class 64-pin \(16 \times 16\) multipliers. The entire 32-bit product of an MPY-16H is available on two successive clock cycles, as the product lines are shared with the incoming data. An additional 145 nsec is added to the MPY-16H time to allow for the necessary clocking and multiplexing steps to occur: effectively, the operands cannot be pipelined at one clock cycle as may be done in the ' S 556 architecture. Even if the pin-compatible Am29516 multiplier is used, a cycle is still wasted, as two cycles are needed to clock the entire multiplier.
There is one way around this problem, when using the Am29516 multiplier; twice as many multipliers are used, and a pair of adjacent multipliers receive the same input operands. One multiplier of the pair then outputs the leastsignificant half of the product, and the other multiplier of the pair outputs the most-significant half of the product; thus, the two paired Am29516 64-pin DIPs are functionally a quasiequivalent of the 84 -pin 'S556, albeit they require many times the circuit board area.
The analysis in the Table 1 assumes the use of 16 MPY16 HJ multipliers. 1616 -bit registers are needed to hold the 16 halves of the various different partial products. After the

1632 -bit products are available, then the Figure 8 configuration is applicable to this case as well. In terms of speed, it is assumed that the MPY-16HJ multiplier configuration takes a clock cycle ( 145 nsec ), more than the computed delay. The computed delay in this case is that of the MPY-16HJ in its feedthrough mode, followed by that of the compressor array of Figure 8.
\begin{tabular}{|c|c|c|}
\hline Multiply Configuration & Speed & Components Used \\
\hline \(64 \times 64\) Multiply Serial-Parallel & \(4 \times 215\) nsec & \[
\begin{array}{r}
4 \text { 'S556s } \\
36 \text { 'S381s } \\
11 \text { 'S182s } \\
8 \text { 'S374s }
\end{array}
\] \\
\hline 64×64 Multiply Totally-Parallel Using 'S556s (84-pin packages) & 226 nsec & \begin{tabular}{l}
16 'S556s \\
27 63S481As (512x8) \\
16 63S441s ( \(1 \mathrm{Kx4}\) ) \\
33 63S141s ( \(256 \times 4\) ) \\
32 'S381s \\
11 'S382s
\end{tabular} \\
\hline \(64 \times 64\) Multiply Clocked Parallel Using MPY-16HJ (64-pin packages) & 481 nsec & \begin{tabular}{l}
16 MPY-16HJ \\
32 'S374s \\
27 63S481s (512×8) \\
16 63S441s ( 1 Kx 4 ) \\
33 63S141s ( \(256 \times 4\) ) \\
32 'S381s \\
11 S382s
\end{tabular} \\
\hline
\end{tabular}

Table 1. Performance Comparisons

\section*{Conclusion}

The 'S556 \(16 \times 16\) multiplier is an excellent building block for longer-wordlength multipliers. It is useful in graphics systems, array processors, minicomputers, and large mainframe computers. It surpasses the currently-available 64-pinDIP multipliers in that the entire 32-bit product is available on every clock cycle.

Some configurations which use 'S558-type \(8 \times 8\) multipliers as building blocks for a \(56 \times 56\) multiplier are discussed in r1 and r2.

\section*{References}

All of the following references are available from Monolithic Memories, Inc.
r1. "Big, Fast, and Simple-Algorithms Architecture, and Components for High-End Superminis," Ehud Gordon and Chuck Hastings, Monolithic Memories Application Note AN-111.
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r3. "Real-Time Processing Gains Ground with Fast Digital Multiplier,', Shlomo Waser, Electronics, 9/29/77.
r4. "State-of-the-Art in High Speed Arithmetic Integrated Circuits,' Shlomo Waser, Computer Design, 6/1978.
r5. "Doing Your Own Thing in High-Speed Arithmetic," Chuck Hastings, Conference Proceedings of the 6th West Coast Computer Faire, pages 492-510, 4/5/81. Also Monolithic Memories Conference Proceedings reprint CP-102.


\section*{Appendix-Sample PLEASM Source Listing-To Reduce Group B In Figure 8}
```

PLE10P4
PLE DESIGN SPECIFICATION
P5020
FIVE 2-BIT INTEGER ROW PARTIAL PRODUCTS ADDER
MMI SANTA CLARA, CALIFORNIA
. ADD AO Al BO Bl CO Cl DO Dl EO El
.DAT PO P1 P2 P3
VINCENT COLI 08/22/83
P3,P2,P1,PO = A1,A0 .+. B1,B0 .+. C1,C0 .t. D1,D0 .t. E1,E0 ; P = A+B+C+D+E

```

FUNCTION TABLE

A1 A0 B1 BO Cl CO D1 DO E1 E0 P3 P2 P1 P0
\begin{tabular}{llllllll}
; AA & BB & CC & DD & EE & PPPP & COMMENTS \\
\(; 10\) & 10 & 10 & 10 & 10 & 3210 & \(A+B+C+D+E=P\) \\
\hdashline LL & LL & LL & LL & LL & LLLL & \(0+0+0+0+0=\) & 0 \\
LH & LH & LH & LH & LH & LHLH & \(1+1+1+1+1=\) & 5 \\
HL & HL & HL & HL & HL & HLHL & \(2+2+2+2+2=10\) \\
HH & HH & HH & HH & HH & HHHH & \(3+3+3+3+3=\) & 15
\end{tabular}

\section*{DESCRI PTION}

THIS PLEIOP4 PERFORMS PARTIAL PRODUCTS REDUCTION FOR WALLACE TREE COMPRESSION. FIVE ROWS OF 2-BIT NUMBERS (Al-A0, Bl-BO, Cl-C0, Dl-DO, AND El-EO) ARE NUMERICALLY SUMMED TO PRODUCE A 4-BIT RESULT (P3-P0).



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Cascade Chapter, ERA
Portland and Seattle Sections IEEE Portland and Seattle Chapters, NWPCA


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\section*{PROMs yield delayed pulses}

\section*{Rick Wegner}

Storage Tech Corp, Louisville, CO

If you need a highly accurate, delayed pulse with adjustable width, the circuit shown in the figure will do the job. The circuit can operate at repetition rates as high as 20 MHz , a limitation set by the bipolar PROMs' access time (in this case, 50 to 60 nsec ) and the counters'
maximum clock rate ( 32 MHz for the example's 74LS193). To generate a delayed pulse from the original input pulse, program the PROMs to yield a logic Low upon reaching the desired delay count and a logic High at the end of the delayed pulse's period.

The delay count equals the desired delay divided by the clock period. In the schematic shown, you need an OR gate because PROM A goes through several intermediate counts before both counters attain the final delay count. To set up your desired pulse width,


\footnotetext{
EDN FEBRUARY 23, 1984
}
generate anotner puise tnat represents tne adaed delay (equal to the desired delay plus the pulse width).

These two pulses then serve to set and reset a flip flop that generates a delayed pulse with the programmed width. You can obtain additional pulses by using the PROMs' other two outputs. The feedback resets the circuit so that the next input pulse can start the delay counting again. A specific program example is shown in (b).

The design has several modification possibilities. If you need a longer delay (without sacrificing accuracy), you can add more counters and PROMs. Moreover, an 8 -output PROM allows the generation of more delayed pulses. If you need smaller pulse widths or more accurate delays, you can disconnect PROM A's \(\mathrm{A}_{0}\)
lett in the scnematic. This action allows the determination of a new set of delay counts, effectively doubling the input clock-rate capability.

What are the limitations of this circuit? First, because all address inputs must change simultaneously, the circuit demands synchronous counters. Second, you shouldn't use large-capacity EPROMs, because their increased access time reduces the maximum clock rate, thus reducing the accuracy of both the delay and the pulse width.

EDN



\title{
High-Speed PROMs with On-Chip Registers and Diagnostics
}

\author{
Vincent J. Coli, Stephen M. Donovan and Frank Lee
}

A family of High-Speed Registered and Diagnostic PROMs offers new savings for system designers. The Registered PROM family features on-chip D-type output registers which are useful in pipelined systems and state machines. In addition to
output registers, the Diagnostic PROMs feature a Shadow Register which makes it easier for system designers to include diagnostics in microprogrammed systems. Architectures and applications for these devices are discussed in this paper.


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\section*{Architectures}

In digital systems, it is natural to have a PROM followed by a register. This structure is particularly useful in microprogramming and state machine design. The Registered PROM family includes an on-chip Output Register as illustrated in Figure 1. By integrating these two building blocks into one chip, the following benefits are realized:
1. 2-to-1 chip count reduction
2. PC-Board space saving
3. Reduced power consumption
4. Eliminate the PROM output buffer and register input buffer and their associated delays.


Figure 1. Registered PROM Block Diagram with Synchronous Initialization

In addition to the on-chip Output register, the Diagnostic PROMs include extra circuitry to perform system level diagnostics, DOC (On-Chip). Specifically, a buried Shadow Register with shifting capability and a \(2: 1\) multiplexer are provided. A block diagram illustrating the Diagnostic PROM architecture is given in Figure 2.
Shadow register diagnostics allows observation and control of all points in a digital system by scanning through the Shadow Register. As a result, test vector generation is greatly simplified and a high degree of fault coverage can be easily obtained. A standalone 8-Bit Diagnostic Register (SN54/74S818 shown in Figure 3 b ) is also available. Several references are listed at the end of this paper which provide a detailed description of diagnostic architecture and how to use it, including Session 16 of this conference (see r4).


Figure 2. Diagnostic PROM Block Diagram

\section*{Product Families} Registered PROMs

The Registered PROMs are configured in 8-bit wide organizations with densities of \(4 \mathrm{~K}, 8 \mathrm{~K}\), and 16 K . The following Registered PROMs are available:
53/63RA481
- 512 words \(\times 8\)-bit memory with both synchronous and asynchronous three-state enables and preset and clear functions
53/63RS881
- 1024 words \(\times 8\)-bit memory with both synchronous and asynchronous three-state enables and 16 synchronous initialization words
53/63RA1681

53/63RS1681
- 2048 words \(\times 8\)-bit memory with asynchronous three-state enable and 16 synchronous initialization words
- 2048 words \(\times 8\)-bit memory with synchronous three-state enable and 16 synchronous initialization words


Figure 3a. Logic Symbols for the Registered PROM Family

\section*{Diagnostic PROMs}

The Diagnostic PROMs are configured in 4-bit wide organizations with densities of \(4 \mathrm{~K}, 8 \mathrm{~K}\) and 16 K . The following Diagnostic PROMs are available:
\begin{tabular}{|c|c|}
\hline 441 & - 1024 words \(\times 4\)-bit memory with asynchronous initialization and two asynchronous three-state enables \\
\hline 53/63DA442 & - 1024 words x 4-bit memory with both asynchronous and synchronous threestate enables \\
\hline 53/63DA841 & - 2048 words \(\times 4\)-bit memory with asynchronous initialization and asynchronous three-state enable \\
\hline 53/63D1641 & - 4096 words \(\times 4\)-bit memory with asynchronous three-state enable \\
\hline 53/63DA1643 & 4096 words x 4-bit memory with asynchronous initialization and totem-pole outputs \\
\hline
\end{tabular}

Both the Registered PROMs and Diagnostic PROMs are available in space-saving 24-pin SKINNYDIP® (0.3- inch wide) packages and are specified over both commercial and military temperature ranges.

\section*{Features}

\section*{Edge Triggered Registers}

Data from the PROM is loaded into the Output Register on the
rising edge of the clock. The use of the term "register" is to be distinguished from the term "latch." in that a register contains master-slave flip-flops while a latch contains gated flip-flops. In other words a register is edge-triggered while a latch is level-sensitive. The output of a register will change only on the rising edge of the clock. A latch holds whatever input data is piesent on the falling edge of the clock. The distinguishing advantage of a register is that its output will only change on the rising edge of the clock, while a latch becomes transparent (output follows input) when the clock is HIGH. As a result, system timing is simplified and faster microcycle times can be obtained.

\section*{Asynchronous Programmable Initialization}

The Output Register can be loaded with a user-programmable initialization word. Each flip-flop in the Output Register may be individually programmed to either a HIGH state or a LOW state so that when the Initialize pin (1) is active (LOW), the Output Register will now contain this initialization word. Note that the initialization operation will occur independent of a clock pulse. Also, this feature is a superset of a preset and clear function. Therefore programmable initialization can be used to generate any arbitrary microinstruction for system reset or interrupt. This feature if offered in several of the Diagnostic PROMs


Figure 3b. Logic Symbols for the Diagnostic PROM Family

\section*{Synchronous Programmable Initialization}

This feature provides sixteen user-programmable synchronous initialization words. As illustrated in the Block Diagram (Figure 4), with the synchronous initialize pin (IS) LOW, one of sixteen column words (A3-AO) will be loaded into the Output Register following the clock pulse and independent of the row addresses (A9-A4). This is useful for implementing a small ( \(\leq 16\) word) reset or interrupt routine. With all \(\overline{\mathrm{I}}\) column words (A3-AO) programmed to the same pattern, the IS function will be independent of both row and column addressing and may be used as a single pin control. This feature is offered in several of the Registered PROMs.

\section*{Three-State Drivers}

The output of the register is buffered by three-state drivers which are compatible with low-power Schottky three-state bus standards. Thus VOL is 0.5 volts at IOL of \(24 \mathrm{~mA}, \mathrm{VOH}\) is 2.4 volts at IOH of -3.2 mA , and IOS minimum is guaranteed to be -20 mA . These hefty standards provide ample drive to meet the requirements of many bus standards.

\section*{Synchronous and Asynchronous Enables}

Both synchronous and asynchronous output enable options are available. The synchronous output enable ( \(\overline{\mathrm{ES}}\), see figure 5 a ), which is sampled on the rising edge of the clock, is used when more than one PROM is bused together to increase word length. In this case the enables effectively become the most significant address bits and, as such, must be registered just as data. Stated another way, when the clock goes high, the address is free to change, requiring enable information to be remembered somewhere. It is most appropriate to store the enable information. When the enable is not used, or when the outputs are to be gated onto some type of bus, the registered enable tends to get in the way. For this reason, the asynchronous output enable option ( \(\overline{\mathbf{E}}\), see Figure 5b) is offered to allow direct control of the enable independent of the clock. For parts which have both synchronous and asynchronous output enables (see Figure 5c), outputs are enabled if, and only if, \(\overline{\mathrm{ES}}\) is LOW during the last rising edge of the clock and \(\overline{\mathrm{E}}\) is LOW.


Figure 4. Block Diagram of 24-pin 53/63RA1681 Registered PROM. The 2Kx8 Registered PROM Contains Sixteen Programmable Initialization Words


Figure 5a. Synchronous Output Enable ( \(\overline{\mathrm{ES}}\) )


Figure 5b. Asynchronous Output Enable ( \(\overline{\mathrm{E}}\) )


Figure 5c. Enabling of Outputs for Both Synchronous ( \(\overline{\mathrm{ES}}\) ) and Asynchronous ( \(\bar{E}\) ) Output Enables

\section*{Application Areas Microprogram Control Store}

Microprogramming is the technique of using control programs stored in high-speed memory, such as bipolar PROMs, to instruct a digital system to perform various functions. A typical microprogram control store architecture is given in Figure 6.

The Microprogram Sequencer generates the addresses for the Microprogram Memory which stores the control program. The Microprogram register assures that all bits change simultaneously after the clock pulse and allows for pipelining instruction fetch and instruction execution. Some bits from the register are fed back to the sequencer while others are used for system control. This field of bits is called a Microword.



Figure 6. Typical Microprogram Control Store

\section*{Pipelined Systems}

Pipelining is the art of designing digital systems such that delays associated with causal operations occur in parallel. A complex operation is divided into several smaller stages which are performed during clock cycles. Just as a widget traveling down an assembly line, each stage is operating on a piece of information which the previous stage operated on during the previous clock cycle. Maximum utilization of the hardware, which translates into maximum system performance, is achieved when the pipeline is full. The fall-through time for any piece of data through the system is the same (or even longer), but the number of pieces of data processed per unit time is greatly increased.
Clearly the benefit in pipelining microprogrammed systems is that instruction fetch and instruction execution times can be overlapped. Therefore the microcycle time is defined as the longer of either fetch or execution times, rather than the sum of both fetch and execution times, as illustrated in Figure 7.
Pipelining can also be used to obtain higher performance in dataintensive systems such as array processors where a large amount of data is coming in for processing without passing through the CPU. It is very inefficient to hold the next set of data until the previous data has propagated through all of the logic blocks in the system (Figure 8a). It is more efficient to pipeline the system and load new data after the previous data has been passed to the next block (Figure 8b).


Figure 7. Length of Microcycle for Pipelined and Non-Pipelined Systems. Note that Delays are Overlapped in the Pipelined System, While Delays are Summed in the Non-Pipelined System

Figure 8b. Pipelined Arithmetic Operation. Note That tPD \(=\) MAX [tPD (blk 1), tPD (blk 2), tPD (blk 3)] + tPD (reg)

\section*{Programmable Logic Elements (PLE) Devices}

Since the inputs of PROMs are fully decoded and the outputs are definable for all possible input combinations, PROMs can be used as logic elements, replacing several levels of logic gates. PROMs are particularly useful for this application since the PROM provides a vast number of product terms \(\left(2^{n}\right.\), where \(n\) is the number of inputs) so that any transfer function can be implemented in a PROM with a sufficient number of inputs. The Ouput Register can be used to eliminate static hazards (glitches) which are normally unavoidable in PROMs. The Monolithic Memories trade name for high-speed PROMs used for logic is "PLE" (acronym for Programmable Logic Element). Monolithic Memories has developed a software tool called "PLEASM" software (PLE Assembler) to assist in designing and programming PROMs as PLEs. PLEASM is available for many computers and may be requested through the Monolithic Memories IdeaLogic Exchange. References r6, r7 and r8 offer an in-depth discussion of programmable logic applications for PROMs.

\section*{State Machines}

A natural extension of using PROMs as logic elements is to use Registered PROMs as single-chip State Machines. In a classic state machine, the present state (or output) is a function of both the present inputs and the previous state. The combinatorial logic is implemented in the PROM array and the Output Register is used to store the state. One or more of the Registered PROM outputs are connected to address inputs in order to provide the state of the machine. The abundance of product terms in a PROM used to implement combinatorial logic translates into an unlimited combination of states. For example, a \(2 \mathrm{~K} \times 8\) Registered PROM can implement a 4 -input, 8 -output machine with any combination of 128 states. States and inputs can be traded off to provide a wide range of possible state machines. The programmable initialization feature is convenient to initialize the state machine.

\section*{Some Application Examples 64 -Bit Microcontroller}

A 4096-word by 64-bit wide microcontroller can be constructed using sixteen 4096x4 Diagnostic PROMs (53/63D1641) and one Programmable Array Logic (PAL®) chip. This controller supplies thirty-six control signals, four status select bits, and two addresses of twelve bits each (Figure 9) - one for the Next address and one for the Jump address.

In this design, three PROMs are used to store the Next address while an additional three PROMs are used to store the Jump address. Note that three 4-bit wide PROMs provide sufficient inputs to address the full 4096 words of Microprogram memory. One PROM is used to store four status select inputs to the PAL device which is used as a multiplexer for test conditions. A PAL16C1 logic circuit or PAL20C1 device is ideal for this Test Mux since these parts provide many inputs ( 16 and 20 respectively) and complementary output (both true and inverted) polarities. The remaining nine PROMs are used to store the 36 -bit Microcontrol word. Note that a Microprogram sequencer is not used in this architecture.

The Microcontrol signals control various parts of the CPU and other external blocks such as memory and I/O. For certain microinstructions, some operations may involve a Jump. The 4 -bit status select PROM will select a status bit from the test conditions to a pair of complementary outputs which will enable either the Next address or the Jump address. The address enabled will point to the Next microinstruction in the bank of PROMs. If no conditional Jump is needed, both the Next address and the Jump address will be the same.
For example, a Jump will be performed if bit 11 of the test conditions is set; the status select bits will be 1011 (which represent 11) and the status to be tested and its complement will appear on the outputs of the PAL device. Noting that the output enables of the Diagnostic PROMs are active LOW, the true PAL device output controls the NEXT address PROMs, while the inverted PAL device output controls the Jump address PROMs. If the test status is TRUE, the PAL device output disables the Next address PROMs while the inverted PAL device output enables the Jump address PROMs. The reverse will occur when the test status is FALSE. This Next/Jump decision is illustrated in Figure 10.


Figure 9. 64-bit Microcontroller Using Sixteen 4Kx4 Diagnostic PROMs and One PAL Device


Figure 10. Microprogram Memory Map Illustrating the Next Address/Jump Address Decision Made by the Test Multiplexer

The decision cycle time is computed by the following equation:
where
\(f_{M A X}=\frac{1}{t_{S U}+t_{C L K}+t_{P D}+t_{P X Z}}\)
\(t_{\text {su }}=\) address setup time for the diagnostic PROM
\({ }^{\text {t }}\) CLK \(=\) clock to output delay of the PROM
\({ }^{\text {t }}\) PD \(=\) propagation delay in the outside logic
\({ }^{\text {t }}\) PXZ \(=\) output enable/disable delay for the diagnostic PROM.


Note that the decision time can be decreased if the Next/Jump decision is made one clock cycle ahead and stored using a synchronous enable. This scheme will reduce the decision time by an amount equal to the propagation delay through the PAL Test Mux, but microcoding this system will become much more complex.
Fewer PROMs would be required if an even/odd Jump address scheme were used (such as only allowing Jumps to certain paragraphs), however this decreases the flexibility of PROM addressing.

\section*{Pseudo Random Number Generator}

In the data path, a Registered PROM can be used to implement complex functions such as a Pseudo Random Number (PRN) Generator. PRN sequences are useful in encoding and decoding of information in signal processing and communication systems. They are used for data encryption in secure communication links, and error detection and correction codes in data communication systems. PRN sequences are also utilized as test vectors for testing digital systems and as reference white noise in many signal processing applications.

There are many techniques for generating PRN sequences. The most common technique is to use " \(n\) " stages of linear shift registers with feedback paths to determine a polynomial which characterizes a PRN sequence. Figure 11 illustrates a typical mechanism for generating PRN sequences.

The advantage of using a PROM (or PLE) device for implementing PRN sequences is that any polynomial can be quickly customized in it. In data encryption systems where the code is frequently changed for protection from mischievous eavesdroppers, a PROM can be used to generate a new code each time or several codes can be implemented in the same PROM.


Figure 12. A Three-Stage Pseudo Random Number Generator Implemented in a Registered PROM (PLE)

An example of a PRN generator implemented in a Registered PROM is shown in Figure 12. A linear 2-input XOR function is used to generate a PRN sequence characterized by a polynomial of degree 3. The PRN sequence is of maximum length with period 7 .
Cyclical Redundancy Check (CRC) is widely used for Error Detection in data communication. Both serial and parallel CRC can be performed depending on the nature of application. In serial data transfer on Local Area Networks, or between peripheral and main memory, serial CRC is the preferred and perhaps the most efficient technique. However, systems em ploying wide data buses for high-speed short-distance data transfer require a high-speed mechanism of ensuring data integrity. In these applications, parallel CRC might be the better alternative.

The implementation of an M-bit parallel CRC is more complex than its serial counterpart. Although both use Linear Feedback Shift Register (LFSR) configurations, the paratlel implementation requires \(M\)-bit carry look-ahead circuitry to process the \(M\) data bits simultaneously (see reference r9). The equations fo this carry look-ahead represent the output of each stage in the LFSR after every shift of an M-bit string of data. These equations contain a large number of XOR operations which make it very efficient to implement in a Registered PROM.

To illustrate with a practical example, Figure 14 shows the serial implementation of the CRC generator polynomial
\[
G(X)=x^{16}+x^{12}+x^{5}+1
\]
also called the CRC-CCITT standard. Figure 16 shows the 8 -bit carry look-ahead equations for an 8-bit parallel CRC implementation of the same polynomial. These equations are derived in reference r9, where an implementation in four PAL devices is also shown with a maximum delay of 90 ns . Figure 15 shows an implementation in only three Registered PROMs and one SSI chip. The maximum delay is 50 ns .
The speed of operation of parallel CRC implemented in Registered PROMs will remain the same for any generator polynomial and M. Increasing the complexity of the carry look-ahead equations only increases the number of devices required to implement them. It does not increase the delay.


Figure 13. Block Diagram of an 8-Bit Parallel CRC


Figure 14. A 16-Bit Linear Feedback Shift Register (LFSR) Implementing a Serial CRC Generator


Figure 15. Diagram Showing How to Connect Three Registered PROM (or PLE) Devices Together to Implement 8-Bit Parallel CRC. The Error Flag is Valid on the Next Clock Pulse After All the Data Has Been Clocked In
\begin{tabular}{|c|c|}
\hline \(X 0(n+1):=X 8(n) \oplus X 12(n) \oplus D(3) \oplus D(7)\) & 1 \\
\hline \(X 1(n+1):=X 9(n) \oplus X 13(n) \oplus D(2) \oplus D(6)\) & chip2 \\
\hline \(X 2(n+1):=X 10(n) \oplus X 14(n) \oplus D(1) \oplus D(5)\) & chip3 \\
\hline \(X 3(n+1):=X 11(n) \oplus X 15(n) \oplus D(0) \oplus D(4)\) & chip3 \\
\hline \(\mathrm{X} 4(\mathrm{n}+1):=\mathrm{X} 12(\mathrm{n}) \oplus \mathrm{D} 3\) & chip1 \\
\hline \(X 5(n+1):=X 8(n) \oplus X 12(n) \oplus X 13(n) \oplus D(2) \oplus D(3) \oplus D(7)\) & hip1 \\
\hline \(X 6(n+1):=X 9(n) \oplus X 13(n) \oplus X 14(n) \oplus D(1) \oplus D(2) \oplus D(6)\) & chip2 \\
\hline \(X 7(n+1):=X 10(n) \oplus X 14(n) \oplus X 15(n) \oplus D(0) \oplus D(1) \oplus D(5)\) & chip3 \\
\hline \(X 8(n+1):=X 0(n) \oplus X 11(n) \oplus X 15(n) \oplus D(0) \oplus D(4)\) & chip3 \\
\hline \(X 9(n+1):=X 1(n) \oplus X 12(n) \oplus D(3)\) & hip1 \\
\hline \(X 10(n+1):=X 2(n) \oplus X 13(n) \oplus D(2)\) & chip2 \\
\hline \(X 11(n+1):=X 3(n) \oplus X 14(n) \oplus D(1)\) & hip2 \\
\hline \(X 12(n+1):=X 4(n) \oplus X 8(n) \oplus X 12(n) \oplus X 15(n) \oplus D(0) \oplus D(3)\) & chip1 \\
\hline \(\mathrm{X} 13(\mathrm{n}+1):=\mathrm{X} 5(\mathrm{n}) \oplus \mathrm{X} 9(\mathrm{n}) \oplus \mathrm{X} 13(\mathrm{n}) \oplus \mathrm{D}(2) \oplus D(6)\) & chip2 \\
\hline \(X 14(n+1):=X 6(n) \oplus X 10(n) \oplus X 14(n) \oplus D(1) \oplus D(5)\) & chip3 \\
\hline \(X 15(n+1):=X 7(n) \oplus X 11(n) \oplus X 15(n) \oplus D(0) \oplus D(4)\) & chip3 \\
\hline
\end{tabular}
where \(\mathrm{Xi}(\mathrm{n}+1)\) is the next state value of the corresponding
register \(\mathrm{i}, \quad \mathrm{i}=0, \ldots, 15\)
\(\mathrm{Xi}(\mathrm{n})\) is the present value of the corresponding
register \(\mathrm{i}, \quad \mathrm{i}=0, \ldots, 15\)
\(D(n)\) is the parallel input data bits, where \(n=0, \ldots, 7\)

Figure 16. Carry Look-Ahead Equations for 8-Bit Parallel CRC with \(G(X)\). The Equations are Partitioned into Parts for Efficient Implementation in Three Chips

\section*{Summary}

There are many interesting applications for high-speed Registered and Diagnostic PROMs. The integration of a Shadow Register in the Diagnostic PROM greatly simplifies system level diagnostics.

\section*{Acknowledgements}

The Pseudo Random Number Generator and the Parallel CRC application design examples originated from Zahir Ebrahim and Vivian Kong, colleagues of ours at Monolithic Memories. These two applications are reprinted from Monolithic Memories Application Note AN-126 (see reference r6).


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\title{
Diagnostic Devices and Algorithms for Testing Digital Systems*
}

\author{
Imtiyaz M. Bengali, Vincent J. Coli and Frank Lee
}

A new concept called Diagnostics-On-Chip (DOC) was introduced in the industry recently. A series of new products with shadow register diagnostic capability is coming. These new
products use this new concept and will provide a cost-effective solution to the issue of testability for digital systems.

\footnotetext{
* This paper is a slightly modified version of the paper by the same name which appeared in the Electro 84 Professional Program Session Record, Session 16 reprint. paper 16 1: 15-17 May 1984.
}

\title{
Testing Digītal Systems
}

\author{
Imtiyaz M. Bengali, Vincent J. Coli and Frank Lee/Electro 84
}

A new concept called Diagnostics On-Chip (DOC) was introduced in the industry recently. A series of new products with shadow register diagnostic capability is coming. These new products use this new concept and will provide a cost effective solution to the issue of testability for digital systems.

\section*{Introduction}

In developing a digital system, cost is a very sensitive issue. For the OEMs, cost itself can be categorized as R \& D, manufacturing, marketing, testing and maintenance costs, etc. The strategy is to reduce the overall cost for a system. Since marketing cost is about the same for all systems of a certain type and R \& D cost is a one-time expense, it will be beneficial to put in diagnostic features to reduce the future expense in testing and maintenance.
If a large system goes down, it will not be practical to test all the chips individually. An alternative is to have built-in test circuits. If an error occurs, it can be located by running a test sequence through the system. It will definitely save a lot of time and expense compared to using tens or hundreds of man hours to debug the system manually.

\section*{Basics of Diagnostics}

The test problem has two major facets:
1. Test generation
2. Test verification

Test generation is the process of determining the test sequence for a circuit which will demonstrate its correct operation. Test verification is to prove that the circuit works with the test vectors. Fault simulation has been the best technique of yielding a quantitative measure of test effectiveness. Test sequences are automatically generated and verified in the circuit after simulating a single "stuck-at-type" of fault in it. By observing the circuit outputs, faults can be detected and a quantitative measure of test effectiveness can be evaluated.

This technique is efficient for testing combinatorial circuits, especially smaller circuits where the test sequence is trivial. For a more complex circuit, many techniques are available, such as D-Algorithm, Compiled Code Boolean Simulation and Adaptive Random Test Generation.

The techniques for combinatorial circuits are inefficient and ineffective for sequential circuits. As a first approximation, one can treat a sequential circuit as being purely combinatorial within each clock cycle and test it with the above techniques for a particular state. Every time the machine makes a transition to a new state, the test sequence is different. This is a very costly way of testing the circuit, especially if it has many states. Moreover, one should have the knowledge of initial state, illegal states, and
sequences to bring the machine out from an illegal state into a known state. All these problems pertaining to testing of sequential circuits have given rise to the concept of "design for testability".

The key concepts are CONTROLLABILITY and OBSERVABILITY. Control and observation of a network are essential to implement its test procedure. Various designs for testability methods have evolved in the last five to six years. All of these methods have the same objective-to be able to control and observe critical points in a network. These techniques allow test generation problems to be completely reduced to the generation of test vectors for combinatorial logic.

For example, consider the case of the AND gate:

dow ator
Figure 1. A Simple 2-Input AND Gate
In order to test for a stuck-at-1 (sa1) fault, it is necessary to put ' \(A\) ' to ' 0 ', ' \(B\) ' to ' 1 ', and observe output ' \(C\) ' for ' 0 ' or ' 1 '. If ' 0 ' is observed at C , then the AND gate is good for sa1 fault; otherwise there is a fault. In order to fully test the AND gate, the following test vectors are to be exercised:
\(\left.\begin{array}{lll}\left.\begin{array}{lll}\text { A } & \text { B } & \text { C } \\
0 & 1 & 0 \\
1 & 0 & 0 \\
1 & 1 & 1\end{array}\right\}\end{array}\right\}\)\begin{tabular}{l} 
Detect sa1 \\
Detect sa0
\end{tabular}

Table 1. A Set of Test Vectors Fully Covering all Stuck-At-Faults of the AND Gate in Figure 1

As the circuit becomes more complex, it is more difficult to control and observe every signal path. Thus, it becomes essential to give serious thought to the testability of the circuit through the design phase. One approach is to adopt structured design methodology. Ideally, this means that the design is totally synchronous with the system clock.

Most structured design practices are built upon the concept that if the values in all of the registers can be controlled to any specific value, and if they can be observed with a straightforward operation, then the test generation, and possibly the fault simulation task, can be reduced to doing test generation and fault simulation for a combinatorial network. A control signal can switch the memory elements from their normal mode of operation to a mode that makes them controllable and observable.

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A simple but effective way to convert a sequential network to a combinatorial one is by breaking the feedback loop and inserting the test data in place of the sequential data in the feedback registers.


Figure 2a. A Simplified Representation of a Sequential Network


Figure 2b. The Feedback Path on the Sequential Network is Broken in Order to Reduce the Network to a Pseudo-Combinatorial One

There are many methods of design for testability practiced in the industry, like LSSD, ScanPath, Scan/Set, Random Access, and BILBO. All of these techniques require additional hardware, mostly shift registers, in order to input test sequences and to observe critical points in the circuit. It appears that additional cost in terms of special hardware has to be incurred for designing testability and structured design. But since the cost of hardware is declining, the trade-off is advantageous in the reduction of testing cost of bigger circuits.

Moreover, the circuit is well monitored and documented. Thus when the boards are in the field, and if there is a fault in a particular board, each block of the circuit can be monitored efficiently and the fault can be easily diagnosed, thus reducing maintenance cost in the future.

\section*{Previous Diagnostic Schemes}

There are two basic methods to load in test vectors: parallel loading, and serial scanning.
Parallel loading of data in and out requires very wide input and output buses and is not worthwhile. Besides, it would not be effective to store and analyze the results. Built-in digital circuit observer (BIDCO) is a modified example of parallel loading of diagnostic data using a pseudorandom number generator to generate test vectors.
Serial scanning needs several clock cycles to load in or shift out the test results. It may take several minutes to run all the diagnostic vectors through the system. Considering the time needed to analyze the results and repair, the time taken to run the diagnostic vectors is insignificant. Examples of serial scan diagnostics techniques are level-sensitive scan design (LSSD) and Diagnostic-On-Chip (DOC). LSSD involves shifting of
diagnostic data into latches, testing the system with that data and then shifting out the test result. DOC uses a buried register, called a shadow register, through which diagnostic data is shifted in and out.

\section*{Shadow Register-Why?}

For the LSSD, outputs from the microcontrol store will contain some intermediate data when diagnostic microinstructions are shifted in and test results are shifted out. If several control signals are used to drive several ports on the same bus, it is possible that more than one port may be enabled at the same time by the intermediate data (as shown in Figure 4), thus creating a bus fight. The result may be hazardous to your system. Other hazards such as disk crashes are also possible. Designing with LSSD forced compromises in system design.


Figure 3. Serial Scanning Techniques Simplify Testing by Serially Shifting in Test Data and Shifting Out Test Result


Figure 4. Potential Bus Fight May Appear as Port A and Port B may Both be Enabled when Test Data or Result is Shifted Through the Register Bits (Also Called Three-State Overlap)
If the diagnostic data is shifted into some buried registers which are not directly tied to the control lines, the above problem can be avoided. This is the concept of Diagnostic-On-Chip (DOC) which uses shadow register diagnostics.

An additional feature for a shadow register is to permit test vectors to be shifted in during normal execution, which means it is not necessary to hold up the system too long in order to perform diagnosis.

A shadow register is basically a buried register with shift capability (Figure 5). There is also an output register whose
outputs appear to the rest of the system. Each output flip-flop has an associated flip-flop in the shadow register. An output flip-flop drives a three-state buffer before going to the output pin. If the output is disabled, the output pin may be converted to an input pin. This feature is very important if the output is driving a bus and sampling of data on the bus desired.


Figure 5. A Typical Diagnostic IC Using DOC

The input to any bit of the output register is multiplexed from one of two sources:
1) The less significant bit location in the shadow register (or SDI for the least significant bit). This operation is just a simple shift register. 2) The same bit location in the shadow register.
3) Data on the output pin at the same bit position. This data may be the output of the corresponding bit of the output register if there is no output enable pin or if the output is enabled, or the input to that pin if there is an output enable pin and the output is disabled.

The input to a bit of the shadow register is multiplexed from one of three sources:
1) The corresponding input bit from the memory array.
2) The corresponding bit location in the shadow register.

Since the data shifted in during the diagnostic mode does not appear on the output bus, the system will never see the intermediate results of the serial shift. Therefore, all control signals will be valid and the hazards associated with LSSD are eliminated.

With this concept in mind, a new standard for upcoming system diagnostics can now be presented.

\section*{Cascadability of the Diagnostic ICs}

One very significant feature of the diagnostic parts is their cascadability. Diagnostics is not done very frequently. Therefore, it is very costly to put many data and control lines and ICs on a board just for testing. One way to minimize the cost is by having one input line and one output line and shift in all the bits serially. This means that the SDO of a diagnostic chip must be able to connect to the SDI of another diagnostic chip. Noting that SDI can be both the data input or the control input, SDO must contain the most significant bit of the shadow register if SDI is the data input, and must pass the content of SDI if SDI is used as a control signal.
There is only one data input and one data output to the diagnostic parts. When serial data is shifted in or shifted out, data has to be passed from one diagnostic chip to another. Since SDI must be passed from chip to chip (if it is used for control), it is necessary for logic designers to make sure the fall-through time of SCI to the last chip and the setup time from SDI to DCLK are satisfied.

\section*{The Diagnostic IC Family}

A family comprised of \(4 \mathrm{~K}, 8 \mathrm{~K}\) and 16 K Diagnostic PROMs (DPROM) with 4-bit output organizations and 8-bit Diagnostic Register is available from Monolithic Memories. These devices are packaged in industry standard 24-pin SKINNYDIP® (0.30inch wide) packages and are specified over both commercial and military temperature ranges.

Function Table
\begin{tabular}{|c|c|c|c|c|c|c|c|}
\hline \multicolumn{4}{|c|}{INPUTS} & \multicolumn{3}{|c|}{OUTPUTS} & \multirow[b]{2}{*}{OPERATION} \\
\hline MODE & SDI & CLK & DCLK & Q3-Q0 & S3-s0 & SDO & \\
\hline L & x & 1 & * & \(\mathrm{Qn} \leftarrow \mathrm{PROM}\) & HOLD & S3 & Load output register from PROM array \\
\hline L & X & * & 1 & HOLD & \[
\begin{aligned}
& S n \leftarrow S n-1 \\
& S 0 \leftarrow S D I
\end{aligned}
\] & S3 & Shift shadow register data \\
\hline L & X & \(\dagger\) & \(\dagger\) & Qn -PROM & \[
\begin{aligned}
& S n \leftarrow S n-1 \\
& S 0 \leftarrow S D I
\end{aligned}
\] & S3 & Load output register from PROM array while shifting shadow register data \\
\hline H & X & \(\dagger\) & * & \(\mathrm{Qn}-\mathrm{Sn}\) & HOLD & SDI & Load output register from shadow register \\
\hline H & L & * & \(\dagger\) & HOLD & \(\mathrm{Sn} \leftarrow \mathrm{Q}\) & SDI & Load shadow register from output bus \\
\hline H & H & * & \(\dagger\) & HOLD & HOLD & SDI & No operation \(\dagger\) \\
\hline
\end{tabular}

\footnotetext{
- Clock must be steady or falling. + Write back from shadow register to input bus (SN54/74S818 Diagnostic Register only).
}

Table 2. Operation of the Diagnostic ICs in a Digital System

The Diagnostic component series consists of the following products (see Figure 6 below for the Logic Symbols)

53/63DA441 - 1024 words \(\times 4\)-bit memory with asynchronous initialization and two asynchronous three-state enables
53/63DA442 - 1024 words \(\times 4\)-bit memory with asynchronous initialization and both asynchronous and synchronous threestate enables

53/63DA841 - 2048 words \(\times 4\)-bit memory with asynchronous initialization and asynchronous three-state enable
53/63DA1641 - 4096 words x 4-bit memory with asynchronous three-state enable
53/63DA1643-4096 words \(\times 4\)-bit memory with asynchronous initialization and totem-pole outputs

SN54/74S818 - 8-bit register with asynchonous three-state enable and write-back capability to the inputs, basically for loading of writeable control store (WCS). Even in the case of non-writeable control store, diagnostic registers should also be used in breaking the loops of the sequential system
in a new standard for diagnostics. Noting that the diagnostic in a new standard for diagnostics. Noting that the diagnostic devices need controls over two independent registers and a multiplexer, a number of overhead pins are necessary. These overhead pins must be defined in a way that the diagnostic parts can be cascadable.

The diagnostic ICs need the following pins in addition to those used in a similar part without the diagnostic features:
1) Diagnostic Clock (DCLK)-The diagnostic clock is used to clock the shadow register.
2) MODE-This pin is used in selecting the data to the registers. For the output register, MODE = LOW indicates that the output register is being used as a normal register; MODE = HIGH indicates that the next state of the output register will be obtained from the shadow register. For the shadow register, MODE = LOW indicates serial data from SDI (see below) is shifted in every diagnostic clock; MODE \(=\) HIGH switches SDI from a data input to a control input. See below for details.

3) Serial Data In (SDI)-When MODE = LOW, this pin is used for shifting serial data in. When MODE \(=\) HIGH, SDI serves as a control pin. If MODE \(=\) HIGH and SDI \(=\) LOW, data from the output pins will be loaded to the shadow register on the next DCLK. MODE \(=\) HIGH and SDI \(=\) HIGH indicate a reserved operation for diagnostic PROMs, and is used for write-back for the diagnostic register.
4) Serial Data Out (SDO)-When MODE = LOW, this pin carries the shift-out bit of the shadow register. When MODE \(=\) HIGH, the SDI becomes a control pin and the control signal should be passed along if several diagnostic parts are connected together serially. So SDO should carry SDI along in this case
This standard is being used in designing all current and future diagnostic devices.

\section*{Some Applications Examples}

A simple controller can be constructed using Diagnostic PROMs together with other functional blocks such as the arithmetic logic block and peripheral control. The Diagnostic PROMs serve two purposes-sequencing the address of the microinstruction and controlling the rest of the system.

The sequencing field of the control store contains two addresses for sequential and jump addressing modes. The selection of the next address depends on the current status of the CPU. The arithmetic logic block and I/O control will give certain status bits which will be selected by the status multiplexer. The status multiplexer is controlled by certain bits of the microprogram control word. It should have complementary outputs so that one and only one of the addresses will be selected at any time of operation of the controller. A PAL® device with complementary outputs will normally provide a cost-effective solution to this multiplexer.


Figure 7. A Simple Controller

PAL® is a registered trademark of Monolithic Memories.

A continue statement can be implemented by having both addresses programmed to the next sequential address while an unconditional jump can be done by programming both addresses to the Jump address.

The control PROMs provide signals to control various functional blocks of the controller and other external blocks such as memory and I/O.

Since the other functional blocks such as the arithmetic logic and I/O control of the system also have sequential logic, it may be necessary to break the loops in those blocks so that diagnosis can be done on the whole system. The diagnostic registers can be incorporated in those blocks in places such as the registers (say, memory address registers, memory data registers, and instruction registers, etc.) The diagnostic data and result shifted into and out of the CPU can also be shifted through the diagnostic registers.

Another more detailed example of how the diagnostic parts can be built into a system begins in Figure 8. The system consists of blocks like CPU, main memory, auxiliary memory, and I/O ports. These functional blocks are normally independent of each other as far as testability is concerned.


Figure 8. A Typical Digital System

An example of a CPU is given in Figure 9a. The diagnostic parts are used to substitute the instruction register, memory data registers, status register, memory address registers, and the microprogram control store. The only additional block to a typical system without diagnostic features is the diagnostic controller. The diagnostic controller should be able to supply the system with signals like MODE, SDI, DCLK, and the register clock (CLK). In other words, the diagnostic controller in itself is a supercontroller of the processing unit. It should also be noted that all feedback paths, except those for the register files, are broken.


Figure 9a. A CPU Using DPROMs and Diagnostic Registers


Figure 9b. Data Flow During Normal CPU Operation


Figure 9c. Shifting on of Test Vector. Dotted Lines Represent Data Flow in the CPU if the Loading of Test Vector is Hidden in Normal CPU Operations


Figure 9d. After the Last Bit of the Test Data is Shifted In, the Output Registers Will be Loaded With the Test Vector Which Will be Used to Test the System (Control the System)


Figure 9e. The Test Result is Then Loaded Back Into the Output Register (Observe the System)


Figure 91. The Test Result is Shifted Out at the Same Time the Next Test Vector is Shifted In. Again Dotted Lines Represent Data Flow in the CPU if the Loading of Test Vector is Hidden in Normal CPU Operations

In normal operation, the diagnostic controller will inactivate the diagnostic feature by setting MODE = LOW and disabling DCLK and have the CLK free running.

When diagnostics is needed, the following sequence is performed:

\section*{Function Table}
\begin{tabular}{|c|c|c|c|c|}
\hline MODE & SDI & DCLK & CLK & OPERATION \\
\hline L & X & X & \(\dagger\) & Normal operation \\
\hline L & B1, 1 & \(\dagger\) & ** & Shift-in bit 1 of first test vector \\
\hline \(\vdots\) & \(\vdots\) &  &  &  \\
\hline L & B1, \(n\) & + & ** & Shift-in bit n of first test vector \\
\hline H & L & * & \(\dagger\) & Load first test vector to output \\
\hline L & X & X & \(\dagger\) & Load test result to output register \\
\hline H & L & 1 & * & Load test result to shadow register \\
\hline L & B2, 1 & 1 & ** & Shift-in bit 1 of second test vector and shift-out test result \\
\hline : & \(\vdots\) & \(\vdots\) & : & \\
\hline L & B2, n & 1 & ** & Shift-in bit n of second test vector and shift-out test result \\
\hline H & L & * & \(\dagger\) & Load second test vector to output \\
\hline L & X & X & \(\dagger\) & Load test result to output register \\
\hline H & L & 1 & * & Load test result to shadow register \\
\hline \(\vdots\) &  &  &  & AF) \\
\hline L & Bm, 1 & 1 & ** & Shift-in bit 1 of last (mth) test vector and shift-out test result \\
\hline : & \(\vdots\) &  &  &  \\
\hline L & Bm, n & 1 & ** & Shift-in bit n of last (mth) test vector and shift-out test result \\
\hline H & L & * & \(\dagger\) & Load last test vector to output \\
\hline L & X & X & 1 & Load test result to output register \\
\hline H & L & 1 & * & Load test result to shadow register \\
\hline L & X & 1 & x & Shift-out test result \\
\hline : & \(\vdots\) &  &  &  \\
\hline L & X & 1 & X & Shift-out test result \\
\hline
\end{tabular}

\footnotetext{
\(\dagger\) Indicates a rising edge of the corresponding clock.
* Clock must be steady or falling
* * If diagnosis is to be performed embedded in regular CPU cycle, CLK should also be clocked. If not, CLK should be steady or falling
}

Table 3. Operation of Diagnostic ICs in a Digital System


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A block diagram of a simple diagnostic controller is shown in Figure 10. The central control unit of this controller may be a disk-based unit or even another PROM. Since in normal operation MODE remains LOW and only CLK is active, it is possible to include a switch in Figure 10 so that the diagnostic controller will be inactive (see Figure 11).


Figure 10. A Block Diagram of a Diagnostic Controller


Figure 11. Including a Switch to Disconnect the Diagnostic Controller from the CPU

\section*{Some Final Thoughts}

More complicated systems may have co-processors, DMA, I/O ports, etc., in addition to the CPU. A top-down approach will be very efficient in testing such systems by first locating the defective board, followed by the locating of the defective part in that board.

The diagnostic PROMs and registers can also be used in minicomputers, data storage devices, and peripherals.

Besides being used for diagnostics, the serial shifting feature present in a diagnostic component can also be applied to serial character generators, other serial to parallel and parallel to serial converters, serial code generators, etc.

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\title{
A Compiler for Programmable Logic in FORTH*
}

\author{
Michael Stolowitz \\ This paper describes the implementation of a very compact compiler, written in the FORTH language, which is used as a design aid in the generation of digital systems using Programmable Array Logic elements (PAL®) devices. The compiler \\ produces a fuse map for generation of a target part from an algebraic description of the input/output relationships. Many of the techniques used are applicable to other areas.
}
\(\qquad\)
* This paper is a slightly modified version of the paper by the same name which appeared in the 1982 FORML Conference Proceedings, pages 257-265, 6-8 October 1982; available from the FORTH Interest Group, P.O. Box 1105, San Carlos, CA 94070. (FORML stands for FORTH Modification Laboratory.)
PAL* is a registered trademark of Monolithic Memories

\title{
A Compiler for Programmable Logic in FORTH
}

Michael Stolowitz

\section*{Background}

The schematic diagram of a typical PAL device is shown in Figure 1. Note that this part contains multiple logic device elements and outputs from gates or flip-flops. Each intersection in the matrix on the left represents a connection made by a fuse. These fuses may be blown (one time only) to customize the part for a particular application. The digital-system designer writes a set of Boolean equations for the outputs as functions of the inputs. This is most conveniently done using signal names from the application as shown in Figure 2. These expressions must be translated into a hexadecimal data file for transmission to a "programmer" test instrument, capable of blowing the undesired fuses to produce the target part.
It is not impossible to encode this data manually, but the process is tedious and provides considerable opportunity for error. A FORTRAN program (PALASM \({ }^{\text {u }}\) ) is available, but FORTRAN is not usually available on microprocessor-based development systems, and the used of remote systems is not convenient. For the above application and for the reasons stated, the program PAL device was implemented in FORTH.

\section*{Implementation}

The PALs device program uses the same concept as many of the FORTH-based assemblers: namely, an environment is created which allows the source data to be interpreted directly. As in the case of the assemblers, this approach led to a surprisingly short program.
In a FORTH-style assembler, a single pass is made of the source data. The interpreter must be able to process each element of the input stream as it is encountered. In an assembler, each of the operation-code mnemonics is an executable word, whose function is to generate a particular machine-language instruction. In PALs, when the logical expressions are interpreted, each of the signal names is an executable FORTH word. The function of an output signal name is to make the row of fuses associated with its first term current, and to set all of the fuses in this row to be blown. The function of an input signal name is to cause the fuse to be spared which is at the intersection of the current row and the column associated with the named input. The output of the PALs program is the fuse map, which is created in its final format by the interpretation of the logical expressions. The fuse map for the application of Figure 2 is shown in Figure 3.
All of the signal names must be defined before the logical expressions are encountered by the interpreter. Since the rows and columns of the matrix are associated with specific pins of the PAL device, the signal names are created by the declarations which associate signal names with pins. When the declarations are interpreted, the pin numbers (i.e., the words \(1 .-20\). and not the integers \(1-20\) ) have already been defined. Pin numbers are defining words whose function it is to create signal names.

The various types of PAL logic circuits differ in number of inputs and outputs. For this reason, the various PAL type are executable words. The function of a PAL type is to cause the appropriate set of definitions for pin numbers to be placed in the dictionary. For this reason, the PAL type is executed before any of the pin/signal declarations.
The only word which precedes the PAL type in the input is the word PALs. While this happens to be the name of the program, it is also an executable word whose function it is to make PAL the current and context vocabulary. A PAL logic circuit contains definitions for all of the PAL type, and for Boolean operators in the FORTH vocabulary.

\section*{Details}

The 16R4 was selected as an example (Figure 1) because it contains most of the features found in the PAL device family, including: input signals which are available in both true and inverted forms, gate outputs which may have individual threestate controls, and clocked outputs. As shown in the example, the output signals are connected to columns in the fuse matrix, and may therefore be used as inputs. Many of these features require some consideration by the program.

Negation - Inputs may be used in expressions in either their true or complemented forms. The operator " \(/\) " sets a flag called INVERT, which causes the column number of the next input executed to be incremented. The column number of the complemented signal is always one greater than the column number of the corresponding true signal.

Logical "OR" - Execution of the Boolean " + " increments the current row number, selecting the next term of the current output.
Feedback - The use of internal feedback means that an output signal name may appear as a factor in a term, i.e., outputs may sometimes be inputs depending on the context. The question of which function an output signal name is to perform is resolved with a flag called IN/OUT, which indicates which type of signal is expected. IN/OUT is set by outputs, and cleared by inputs. The Boolean " \(\star\) " is used to set the flag again between consecutive inputs.

Ouptut Inversion - PALS requires that all expressions be written as the sum of a group of terms. For logical consistency, the designer must indicate an inverted output by defining the expression for the complement of the output, which he indicates with a "/" (the inversion operator) in front of the output signal name.

Logical vs. Electrical Expression - The use of a negation operator as described above results in electrical expressions rather than logical expressions. The operator indicates that the input must be LOW, and ignores the fact that the signal might be assertive-HIGH or assertive-LOW. A naming convention was developed which allows the expressions to be interpreted logically. The convention is to begin the names of all assertiveLOW signals with the symbol: "/". When reading expressions, the " \(/\) " is pronounced "NOT" whether it is part of the name or an independent operator. Double negatives are not pronounced.*

The Code - The complete code for PALS may be found in Figures 4 and 5 . The compiler itself is on four FORTH screens. The two additional screens show examples of PAL device-type definitions for six of the most common types. The six screens are usually printed on a single page.
The FORTRAN program PALASM \({ }^{\text {w }}\) ( 1981 version) appears on pages 3-58 through 3-63 of the second edition of the PAL® Programmable Array Logic Handbook. Subsequent updates of the source code have not been published, but are available (subject to a charge and an agreement) from the Monolithic Memories Inc. IdeaLogic Exchange.

\section*{A partial glossary of the PALS code follows:}

MAP is the structure in which the output is generated.
PWR2 is used to make a bit mask.
ADDR converts column and row to byte and bit within the map.

FUSE is used to toggle a bit in the map.
(INPUT) is what input signals do
INPUT creates pins which create input signals.
NEXT-TERM is used by output signals and " + " to select a row, and to clear its fuses.

OUTPUT creates pins which create output signals.
PAL. prints the symbolic map as in Figure 3.
PAL-TYPE is the defining word for PAL types.
* Editor's note: in this respect, Mike Stolowitz's program allows a syntax convention (double negative) which isn't supported by PALASM.

\section*{Summary}

One of the objectives of the PALS compiler was that the source data and documentation for the resultant part should be one and the same. This insures that the documentation is always up to date, since it must have been created first. It also eliminates the possibility of documentation errors occurring when documentation is produced after-the-fact by an independent process.

This application program is in use by people who have little or no knowledge of FORTH. A FORTH system with the compiler has been modified to load and run as a CP/M .COM file. The program accepts the name of a text file, which it interprets a line at a time.
The techniques described above have also been adapted to the compilation of other forms of programmable logic, including Field-Programmable Logic Arrays (FPLAs) and Field-Programmable Logic Sequencers (FPLSs).
Why is the PALs program so simple in FORTH? In FORTH, it is rarely necessary to write code for the entire application. It is only necessary to extend what already exists to include the application.

The author. Michael Stolowitz, is a digital hardware/software systems consultant specializing is personal computer systems and peripheral devices. sultant specializing is personal computer systems and peripheral devices. the PALS program from what is described here; in particular, PALS can now produce JEDEC-format files. Questions may be addressed to Mr. Stolowitz at (415) 837-3887, 335 Merrilee Place, Danville, CA 94526.

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A Compiler for Programmable Logic in FORTH


Figure 3. Fuse Map for PAL16R4 Application
```

SCR 499 (63H)
\ \ f u s e ~ a d d r ~ p w r , ~ m a p ~ i n / o u t ~ i n v e r t ~ l a s t - o u t ~ r o w ~ h / l ~ 1 5 S e p 8 2 m c s
CREATE MAP }512\mathrm{ ALLOT
VARIABLE IN/OUT VARIABLE INVER'T
VARIABLE LAST-OUT VARIABLE H/L
VARIABLE RON
: PWR2 (S n -- 2**n) l SWAP ? DUP IF }\varnothing\mathrm{ DO DUP + LOOP THEN ;
: ADDR (col -- addr bit) (addr = r5 r2 rl rø c4 c3 c2 cl c| )
ROW @ 8/MOD SWAP 32* ROT + SWAP (bit = r4 r3)
4/MOD 256 * ROT + MAP + SWAP PWR2 ;
: FUSE (S col -- )
INVERT @ + Ø INVERT ! ADDR TOGCLE ;
\#1ø% (64H)
\ (input) input next-term 15Sep82mcs
: (INPUT) (S 'col -- )
@ FUSE Ø IN/OUT ! ;
: INPUT (scol - ) (pin's dot name)
CREATE , DOES>
(S -- ) (pin's signal name)
@ CREATE , DOES>
IN/OUT @ }\varnothing= ABORT" Output Required!" (INPUT) ;
: NEXT-TERM (S -- )
LAST-OUT @ DUP @ }\varnothing=ABORT" No More Terms!"
-1 OVER +! 2+ DUP @ ROW ! 1 SWAP +!
32 Ø DO I FUSE LOOP 1 IN/OUT ! ;
\#101 (65H)
\ output twk pal. 15Sep82mcs
: OUTPUT (S row \#rows col -- ) ( pin's dot name )
CREATE , , , DOES>
(S -- ) ( pin's signal name)
CREATE , DOES>
@ IN/OUT @ IF (input expected )
DUP@ @ 31 ABORT" No Internal Feedback!" (INPUT)
ELSE ( output expected )
INVERT@ @ E/L @ + 1 - ABORT" Invert Output Equation!"
2+ LAST-OUT ! D INVERT ! NEXT-TERM THEN ;
: TWK ( col -- ) ROW @ SWAP ADDR OVER C@ OR SWAP C! ;
:PAL.CR 64 Ø DO I ROW ! I 3 .R 2 SPACES
32 DO I 3 AND }|=IF SPACE THEN
I ADDR SWAP C@ AND IF ." -" ELSE ." X" THEN LOOP
CR I 8 MOD 7 = IF CR THEN ?KEY IF LEAVE THEN LOOP
Figure 4. The PALS FORTH Program (Screens 1-3)

```
```

SCR \#l\emptyset2 (66H)
\ pal-type pal pals +/ * = HI NC 30Sep82mes
: PAL-TYPE (S +scr h/l)
CREATE, , DOES> 2@ H/L ! [ BLK @ ] IITERAL + LOAD
MAP 512 ERASE Ø INVERT ! ;
: SKIP ( -- ) BL WORD DROP ;
VOCABULARY PAL IMMEDIATE PAL DEFINITIONS
: NC (S -- ) BL WORD DROP ;
: + (S -- ) NEXT-TERM ;
:/ (S - ) 1 INVERT ! ;
: * (S -- ) IN/OUT @ ABORT" Input Expected!" 1 IN/OUT ! ;
:HI (S - ) Ø IN/OUT 1;
: = (S -- ) ;
1 Ø PAL-TYPE 1ØL8 1 1 PAL-TYPE 1णH8 2 Ø PAL-TYPE 16R4
2 \emptyset ~ Ø A L - T Y P E ~ 1 6 R 6 ~ 2 ~ Ø ~ P A L - T Y P E ~ 1 6 R 8 ~ 2 ~ Ø ~ P A L - T Y P E ~ 1 6 L 8 ~
FORTH DEFINITIONS
: PALS (S -- ) [COMPILE] PAL DEFINITIONS ;
SCR \#1Ø3 (67H)
10L8 1ØH8
12 INPUT 5. 16 INPUT 6. 20 INPUT 7. 2. 24 INPUT 3.
28 INPUT 9. : 1\varnothing. SKIP ; 3\varnothing INPUT 11. : 2\emptyset. SKIP ;
5 6 2 ~ B L ~ O U T P U T ~ 1 2 . ~ 4 8 ~ 2 ~ B L ~ O U T P U T ~ 1 3 . ~
4\emptyset2 BL OUTPUT 14. }322\mathrm{ BL OUTPUT 15.
24 BL OUTPUT 16. 16 2 BL OUTPUT 17.
8 BL OUTPUT 18. Ø 2 BL OUTPUT 19.
: TWEEK (S -- )
FORTH 8 Ø DO 2 Ø DO J 8 * I + ROW !
6 TWK }7\mathrm{ TWK 11 TWK 14 TWK 15 TWK 18 TWK
1 9 TWK 22 TWK 23 TWK 26 TWK 27 TWK LOOP LOOP PAL ;
\#1Ø4 (68H)
\16R4 16R6 16R8 16L8 30Sep82mcs
:1.SKIP ; Ø INPUT 2. 4 INPUT 3.
12 INPUT 5. . 16 INPUT 6. 20 INPUT 7. 2, 24 INPUT 8.
28 INPUT 9. : 1\varnothing.SKIP ; : 11.SKIP ; SKIP ;
56 8 30 OUTPUT 12. 48 8 26 OUTPUT 13.
40}822\mathrm{ OUTPUT 14.
24 8 14 OUTPUT 16. 16 8 10 OUTPUT 17.
8 6 OUTPUT 18. Ø 8 2 OUTPUT }19
: TWEEK (S -- ) ;

```

Figure 5. The PALS FORTH Program (Screen 4) and Definitions (Screens 5-6)

\title{
High-Speed Bipolar PROMs Find New Applications As Programmable Logic Elements*
}

\author{
Vincent J. Coli and Frank Lee
}

Classic applications for bipolar PROMs include instruction storage for microprogram control store and software for microprocessor programs. However, due to a new design methodology and state-of-the-art performance, PROMs are finding increasing
numbers of applications as Programmable Logic Element (or PLE) devices. This paper will cover the architecture, applications, and software support for PLE devices.


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\section*{Fuse-Programmable Logic Families}

A typical combinatorial Boolean equation can be written in sum-of-product form, which consists of several AND gates summed at an OR gate. In general, a set of combinatorial Boolean equations with \(n\) inputs ( \(10,11, \ldots, I n-1\) ) and moutputs (O0, O1, . . , Om-1) can be generated through one level of AND gates followed by one level of OR gates. Custom logic functions can be defined using programmable logic.


Figure 1. Structure of Programmable Logic Devices

Fuse-programmable devices normally consist of two levels of logic - AND-array and OR-array - as suggested above. There are three basic types of fuse-programmable devices - PROM (Programmable Read Only Memory), PLA (Programmable Logic Array), and PAL® (Programmable Array Logic) devices. Which arrays are fuse-programmable distinguish these three types of devices.

PLAs offer the greatest flexibility since both the AND and OR arrays are programmable. This flexibility comes with the cost of lower performance, higher power dissipation, and generally higher price.

A PAL device has only the AND-array programmable; the ORarray is fixed. Each output has an OR gate associated with it which sums a fixed number of product terms (AND combinations). Statistically there is only a limited number of product terms in any equation. So the flexibility of a PLA is normally not needed. This is a compromise between flexibility and cost and performance.
The OR-array is programmable in a PROM, but the fixed ANDarray consists of all combinations of literals for each of the input variables. For example, there are 32 product terms available in a PROM with 5 inputs a,b,c,d,e (corresponding to words 0 through 31 in the PROM memory):
\begin{tabular}{ll}
\(/ a^{*} / b^{*} / c^{*} / d^{*} / e\) & (Word \\
\(/ a^{*} / b^{*} / c^{*} / d^{*} e\) & (Word 1) \\
\(/ a^{*} / b^{*} / c^{*} d^{*} / e\) & (Word 2)
\end{tabular}
\begin{tabular}{ll}
\(a^{*} b^{*} c^{*} / d^{*} e\) & (Word 29) \\
\(a^{*} b^{*} c^{*} d^{*} / e\) & (Word 30) \\
\(a^{*} b^{*} c^{*} d^{*} e\) & (Word 31)
\end{tabular}
where '*' represents the Boolean AND operator and '/' represents the Boolean NOT or inverter operator. The fuses in the OR-array are programmed to select the desired AND combinations.

PROGRAMMABLE LOGIC ELEMENT PROGRAMMABLE LOGIC ARRAY PROGRAMMABLE ARRAY LOGIC


FIXED AND ARRAY PROGRAMMABLE OR ARRAY BOTH ARRAYS PROGRAMMABLE
PROGRAMMABLE AND ARRAY FIXED OR ARRAY

Figure 2. Structural Difference Between PLE (PROM), PLA and PAL Devices. Note that the PAL and PLE Logic Circuits Complement Each Other. The PAL Device has Many Input Terms While the PLE Device is Rich in Product Terms

The existence of all combinations of literals for all inputs makes it possible to define functions which cannot be implemented in a PLA or a PAL device. For example, a 5 -input Exclusive-OR (XOR) function can be implemented using sixteen product terms. This may exceed the number of product terms available in a PAL device and will consume too many product terms in a PLA, but can be constructed quite efficiently in a PROM. It is important to realize that any combination of inputs can be decoded in a PROM as long as sufficient input pins are provided since a PROM provides \(2^{n}\) product terms (where \(n\) is the number of inputs). Another way of looking at this is that PROMs store the logic transfer function in a memory. The fixed AND-array (or AND-plane) consists fo the row and column decoders while the fuses in the OR-array (or OR-plane) are the bits in the memory. In a memory, a fuse blown versus a fuse intact distinguishes a HIGH from a LOW.


Figure 3. Block Diagram of a PROM Viewed as PLE Device. Notice that the PLE Provides Many ( \(2^{n}\), Where n is the Number of Inputs) Product Terms. A By-Product of this is Programmable Output Polarity: Either Active-High or Active-Low Output Polarities are Available

Due to this special characteristic of abundant product terms, PROMs are also often used as logic devices. In this paper, PROMs are referred to as PLE (Programmable Logic Element) devices.

\section*{Advantages of PLE Devices}

PLE devices provide a cost-effective solution for many applications. Here are just some of the advantages of PLE devices:
1) Customizable Logic - The designeer is limited to standard functions if SSI/MSI devices are used. The designer can create his own logic chips using PLE devices.
2) Design Flexibility - Modification of design is possible even without redesigning the PC board. For example, the address space of a microprocessor-based system can be reconfigured by merely programming a new device if the decoding is implemented in a PLE device. This feature comes in handy if you want to upgrade a system which originally used 64-K Dynamic RAMs to now use state-of-the-art 256-K Dynamic RAMs.
3) Reduce Errors - Errors are sometimes unavoidable and oftentimes quite expensive. Programmable devices make it easier and less expensive to correct errors.
4) Reduction of Printed Circuit Board Space-PLE devices save PC board space since several SSI/MSI functions can be integrated into a single package.
5) Fast Turnaround Time - With existing commercial programmers and development software support, a prototype of the custom tailored PLE device will be ready in just a few minutes.

\section*{A Great Performer!}


\section*{PLE Applications}

PLE applications include random logic replacement, decoder/ encoders, code converters, custom ALUs, error detection and correction, look-up tables (both trigonometric and arithmetic), data scaling, compression arithmetic like Wallace Tree adders, distributed arithmetic, and residue arithmetic

Several levels of random logic chips can be replaced by one PLE logic circuit. As discussed earlier, PLE devices can implement logic in sum of products form.


Despite the existence of dedicated encoders and decoders, many of these functions are application dependent. A standard 3 -to-8 decoder/demultiplexer ( 74 S 138 ) can be used in decoding applications. But the decoding scheme may require several 3 -to- 8 decoder/demultiplexers and additional SSI OR-gates. On the other hand, a PLE device can be customized to perform the required decoding function with no additional gates. Simple decoders, such as those used for decoding memory chip selects from address lines, can be implemented in a PLE device with five to ten inputs. More complex decoding may require eight to twelve inputs.


Figure 4. PLE Address Decoding Application. The PLE Device Selects One of Eight 2Kx8 Static RAMs by Decoding Several Microprocessor Address Lines

PLE devices also offer a very flexible solution for code conversion applications. Translations of codes such as from ASCII to EBCIDIC, Binary to BCD (Binary Coded Decimal), or BCD to Gray code can be implemented in PLEs. The 74S184 Binary-to\(B C D\) Converter is actually a \(32 \times 8 \mathrm{PROM}\).


Figure 5. Two Examples of PLE Code Converters. The Second Example Illustrates How to Use Two Inputs as Code Select Lines so that Four Converters can be Provided in One PLE Device

Standard ALUs (such as the 74S181) may not provide a very specailized function which a particular system requires, such as BCD arithmetic. In this case a PLE device is again a good alternative. Although the PLE device may be slower than a dedicated ALU, the presence of this specialized function is critical. For example, a 4-bit ALU can be constructed in a PLE device with twelve inputs (A3-A0, B3-B0, I2-10, Cin) and eight outputs (F3FO,/G,/P, Cout, \(A=B\) ). Any eight functions can be implemented.


Figure 6. Block Diagram for a 4-Bit ALU which can be Implemented in a PLE Device

Data scaling is another PLE device application. A dedicated multiplier is not required if the scaling factor is a constant; the prescaled result can be stored in a PLE device. Fixed-bit multipliers are typically implemented in PLE devices.

Column compression technique (also called Wallace Tree Compression) is used when expanding an array of several smaller parallel multipliers to perform large wordlength multiplication. These smaller multipliers will generate partial products (intermediate results) which must be numerically summed according to bit significance in order to calculate the final wordlength multiplication. Many levels of 2-input bus adders can be used to add these partial products, but the carry propagation delays may be too long. However, partial product adders implemented in PLE devices can do compression of many levels without passing carries. Thus, the summmation will be much faster.


THE 'S556, TOGETHER WITH PLES ORGANIZED IN A WALLACE-TREE CONFIGURATION, CAN SAIL RIGHT ALONG AT THE RATE OF FOUR \(56 \times 56\) MULTIPLICATIONS EVERY MICROSECOND

Group Code Recorder (GCR) is an encoding/decoding scheme used for error detection on tape. During a WRITE operation, each 8-bit word is divided into two 4-bit nibbles. Both nibbles are then encoded into 5 -bit codes before being recorded onto tape. Both 5-bit codes are decoded back to the original 4-bit nibbles and then combined during a READ operation. PLE circuits are exceptionally useful in mapping the 4 -bit data to the 5 -bit code and back.


Figure 7. GCR Encoder/Decoder Block Diagram
Exclusive-OR gates, being half adders, are very prevalent in Error Detection and Correction (EDC) schemes. Many SSI chips are required to implement this function while PLA and PAL devices may not provide sufficient product terms. PLE devices are again an ideal solution.


Figure 8. Exclusive-OR Gates can be Implemented in PLE Very Efficiently. A 4-Input XOR Gate (a) Maps into a Checkerboard Pattern in a Karnaugh Map (b) and Requires Eight Product Terms (c). The PLE Implementation is Shown in (d). An 8 -input XOR Gate Requires Sixteen Product Terms

In many applications, the speed of the converging series used to generate the trigonometric functions is too slow and the accuracy obtained by direct table look-up requires too much hardware. A good compromise between speed and hardware is to store an approximation to the function in a PLE device. Then use this approximation as a starting point for an iterative algorithm (such as Newton-Raphson) to obtain additional accuracy. High-Speed division, multiplication, and square-root calculations can be performed in a similar manner.


Figure 9. PLE Look-Up Tables and Iteration Loops can be Used to Generate Very Accurate Trigonometric and Arithmetic Functions. An Approximation to the Function is Stored and Additional Accuracy is Gained Using Iteration Operations


Distributed arithmetic is used for performing convolution operations without using multiplier/accumulators. If the coefficients are constant, a look-up table for convolution can be stored in a PLE device, thus replacing the multiplier.

Residue arithmetic (also called Carry-Independant arithmetic) is a technique used to perform very fast integer arithmetic. High speed is achieved by using numbers in residue representation so that the sequential delay of carries on digits of higher significance is eliminated. A Residue Numbering System (RNS) is determined using an optimum moduli when designing the system. Conversion to and from residue representation are basic mapping functions which can be conveniently done in a PLE device. Also, since operations in residue arithmetic are performed using modulo addition and multiplication without carries, these operations can also be done using PLE devices. In general, residue arithmetic should only be used for integer arithmetic which requires intensive operations.


Figure 10. Architecture of a System Based on RNS. An Integer Number is Converted to RNS Representation Using PLE Devices, Then the RNS Arithmetic is Performed Using Some Other PLE Devices, and Finally the RNS Result is Converted Back to Integer Representation Again Using PLE Devices


\section*{Restrictions}

The basic restrictions for using PLE devices to replace SSI/MSI parts are:
1) Since a memory element has a product term for every combination of literals of all the input terms, static hazard is normally unavoidable. For example, there are 5 inputs available in a \(32 \times 8\) PROM. In order to generate a function like:
\[
f=a^{*} b^{*} c^{*} d
\]

The actual implementation inside the PROM will be:
\[
f=a^{*} b^{*} c^{*} d^{*} / e+a^{*} b^{*} c^{*} d^{*} e
\]

If \(a=b=c=d=\) HIGH, according to the first equation, we shall expect \(f\) to remain HIGH independent of e changing. In the actual PROM implementaton, there will be no hazard if e stays either HIGH or LOW. But if e changes, depending on whether e or /e will occur first, there exists the possibility that both product terms in the second equation will be LOW momentarily, which may cause a static logic hazard (HIGH to LOW to HIGH) for f. This hazard is commonly called a "glitch". Static hazards are not a problem for many applications, like those offered in this paper. but extreme care must be taken if the output of a PLE device is used to strobe another device.


Figure 11. This Truth Table Graphically Illustrates the Possible Glitch (HIGH to LOW to HIGH Hazard) for the Function \(f=a^{*} b^{*} c^{*}\) d Implemented in a \(32 \times 8\) PROM. Address 0F and 1F Contain a 1 while All Other Locations Contain a 0 for Output f. If Address Inpute Should Change, the PROM Decoders Could Momentarily Selct a Location Containing a 0
2) Although PROMs are available with registered outputs, internal feedback from the outputs and buried registers are not yet available in PROMs. External connections from sóme outputs to inputs must be made for applications which require feedback (such as in state machines). However, Registered PROMs without feedback are useful for pipelining (overlap instruction fetch and execution) in order to increase system throughput


Monolithic Memories has developed a software tool to assist in designing and programming PROMs as PLE devices. This package, called "PLEASM" (PLE Assembler), is available for several computers including the VAX/VMS and IBM PC/DOS PLEASM converts design equations (Boolean and arithmetic) into truth tables and formats compatible with PROM programmers. A simulator is also provided to test a design using a Function Table before actually programming the PLE device. The PLEASM operators are listed below and the PLEASM catalog of operations is given on the next page. A sample PLE Design Specification (source code for PLEASM software) with PLEASM outputs is given in Figure 12. PLEASM software may be requested through the Monolithic Memories IdeaLogic Exchange.

Operators (in hierarchy of evaluation)
\begin{tabular}{cl}
; & Comment follows \\
ADD & Dot operator (pin list or arithmetic operator follows) \\
DAT & Data pins (Outputs) \\
\(=\) & Delimiter, separates binary bits (MSB first) \\
\(=\) & Equality (combinatorial)
\end{tabular}

\section*{BOOLEAN OPERATORS}
/ Complement, prefix to a pin name
* AND (product)
+ OR (sum)
+: XOR (exclusive or)
* : XNOR (exclusive nor)

\section*{ARITHMETIC OPERATORS}
*. Multiply (numeric multiplication)
. . . Plus (numeric addition)
Monolithic Memories PLEASM version 1.2D © copyright 1984 Monolithic Memories

PLEASM - PLE Assembler - provides the following options:
C Catalog - Prints the PLEASM catalog of operations
E Echo Input - Prints the PLE design specifications
T Truth Table - Prints the entire truth table
B Brief Table - Prints only used addresses in the truth table
H Hex Table - Prints the truth table in HEX form
\(S\) Simulate - Exercises the function table in the logic equations

I Intel Hex - Generates INTEL HEX programming format

A ASCII Hex
- Generates ASCII HEX programming format

Q Quit - Exits PLEASM


Figure 12a. PLE Design Specification. This is the Source Code for PLEASM Software. PLEASM Software Generates the Truth Table and Programming Formats from the Equations. PLEASM Software Also Exercises the Function Table in the Equation and Reports Errors


Figure 12b. Truth Table. PLEASM Software Generates This Truth Table which can be Used for Verifying Your Design

Figure 12c. Hex Table. PLEASM Software Generates This Truth Table in Hexadecimal Form for Verification of Locations in the PLE

00F3C

Figure 12d. ASCII Hex Programming Format. PLEASM Software Generates this ASCII Hex Programming Format with Hex Check Sum. Control Characters are Included so that the Information can be DownLoaded Directly to a PROM Programmer
: 1000000032D9DA19DA191AD9DA191AD91AD9DA1940 :10001000DA191AD91AD9DA191AD9DA19DA191ACD54 : 00000001FF

Figure 12e. Intel Hex Programming Format. PLEASM Software Generates this Intel Hex Programming Format with a Hex Check Sum Following Every 16 Bytes of Data

\section*{PLE Family}

Monolithic Memories carries a family of fast PROMs which can be used as Memory or PLE devices. Since the critical parameter for logic applications is speed, our series of fast PROMs have
worst-case memory access times (or propagation delays) rang ing from 15 ns for small PROMs to 40 ns for large PROMs. The Logic Symbols for four of the PLE devices are given in Figure 13 and a summary of the PLE family is given below:

\section*{PLE Selection Guide}

*Clock to output time for registered outputs
\(\dagger\) Preliminary data.
NOTE: Commercial limits specified

\section*{Acknowledgements}

Several of the designs discussed in this paper were proposed by our good friend and colleague Ulrik Mueller, who is now studying Computer Science in his native country, Denmark, and our Monolithic Memories Pal Zahir Ebrahim. Special thanks also go to Ranjit Padmanabhan for writing the PLEASM simulator.

\section*{Summary}

There are many interesting applications for high-speed PROMs used as PLE devices. A software package called "PLEASM" software is available as a development tool.

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Figure 13. Four Sample PLE Logic Symbols

\title{
ABEL \({ }^{\text {TM }}\), A Complete Design Tool For Programmable Logic
}

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As the use of PAL® and PLE devices (PROMs) increases, the need for high-level design tools becomes necessary. Designers need easier, faster, and more efficient ways to design with such programmable devices. With the more complex devices currently being introduced to the market, this need is even greater. Additionally, a designer should be able to specify logic designs in a way that makes sense in engineering terms; he or she should not have to learn a new way of thinking about designs.

ABEL \({ }^{\text {m }}\), a complete logic design tool for PAL devices, PLE devices and FPLA devices meets these requirements. ABEL \({ }^{\text {m }}\) incorporates a high-level design language and a set of software programs that process logic designs to give correct and efficient designs.

The \(A B E L^{\text {TM }}\) design language offers structures familiar to designers: state diagrams, truth tables, and Boolean equations. The designer can choose any of these structures or combine them to describe a design. Macros and directives are also available to simplify complex designs.

The \(A B E L^{\text {TM }}\) software programs process designs described with the high-level language. Processing includes syntax checking, automatic logic reduction, automatic design simulation, verification that a given design can be implemented in a chosen device, and automatic generation of design documentation.

To use \(A B E L^{\text {TM }}\), the designer uses an editor to create a source file containing an ABEL \({ }^{\text {TM }}\) design description. He then processes the source file with the ABEL \({ }^{\text {TM }}\) software programs to produce a programmer load file. The programmer load file is used by logic and PLE programmers to program devices. Several programmer load file formats are supported by \(A B E L^{T M}\) so that different programmers may be used.

The source file created by the designer must contain test vectors if simulation is to be performed. Test vectors describe the desired (expected) input-to-output function of the design in a truth table format. The ABEL \({ }^{\text {TM }}\) simulator applies the inputs contained in the test vectors to the design and checks the obtained outputs against the expected outputs in the vectors. If the outputs obtained during simulation do not match those specified in the test vectors, an error is reported.

Following are two designs described in the \(A B E L^{\text {rm }}\) design language. These designs would be processed to verify their correctness and to reduce the number of terms required to implement them. The first design is for a PAL device, the second for a PLE logic circuit.
ABEL** is a trademark of DATA I/O.

\section*{6809 MEMORY ADDRESS DECODER}

Address decoding is a typical application of programmable logic devices, and the following describes the \(A B E L^{\text {TM }}\) implementation of such a design.


Figure 1. Block Diagram: 6809 Memory Address Decoder

\section*{Design Specification}

Figure 1 shows a block diagram for the design and a continuous block of memory divided into sections containing dynamic RAM (DRAM), I/O (IO), and two sections of ROM (ROM1 and ROM2). The purpose of this decoder is to monitor the six high-order bits (A15-A10) of a sixteen-bit address bus and select the correct section of memory based on the value of these address bits. To perform this function, a simple decoder with six inputs and four outputs is designed with a 14L4 PAL device.
Table 1 shows the address ranges associated with each section of memory. These address ranges can also be seen in figure 1.


Figure 2. Simplified Block Diagram: 6809 Memory Address Decoder

\section*{Design Method}

Figure 2 shows a simplified block diagram for the address decoder. The address decoder is implemented with simple
 a set named Address. The lower-order ten address bits that are not used for the address decode are given "don't care" values in the address set. In this way, the designer indicates that the address in the overall design (that beyond the decoder) contains sixteen bits, but that bits 0-9 do not affect the decode of that address. This is opposed to simply defining the set as, Address \(=\) [A15,A14,A13,A12,A11,A10] which ignores the existence of the lower-order bits Specifying all 16 address lines as members of the address set also allows full 16 -bit comparisons of the address value against the ranges shown in table 1.

\section*{Test Vectors}

In this design, the test vectors are a straightforward listing of the values that must appear on the output lines for specific address values. The address values are specified in hexadecimal notation on the left side of the " \(->\) " " symbol. Input to a design always appear on the left side
\begin{tabular}{cc}
- & \(0000-\) DFFF \\
DRAM & E000-E7FF \\
IO & F000-F7FF \\
ROM2 & \\
ROM1 &
\end{tabular}

Table 1. Address Ranges for 6809 Controller


of the test vectors. The expected outputs are specified to the right of the " \(->\) " symbol. The designer chose in this case to use the symbols \(H\) and \(L\) instead of the binary values 1 and 0 to describe the outputs. The correspondence between the symbols and the binary values was defined in the constant declaration section of the source file, just above the section labeled equations.

Figure 3. Source File: \(\mathbf{6 8 0 9}\) Memory Address Decoder

\section*{Seven-Segment Display Decoder}

This display decoder decodes a four-bit binary number to display the decimal equivalent on a seven-segment LED display. The design incorporates the \(A B E L^{T M}\) truth table format and is implemented on a RA5P8 PLE.


Figure 4. Block Diagram: Seven-Segment Display Decoder

\section*{Design Specification}

Figure 4 shows a block diagram for the decoder design and a drawing of the display with each of the seven segments labeled to correspond to the decoder outputs. To light up any one of the segments, the corresponding line must be driven low. Four input lines DO-D3 are decoded to drive the correct output lines. The outputs are named \(a, b, c, d, e\), \(f\), and \(g\) corresponding to the display segments. All outputs are active low. An enable, ena, is provided. When ena is low, the decoder is enabled; when ena is high, all outputs are driven to high impedance.


Figure 5. Simplified Block Diagram: Seven-Segment Display Decoder

\section*{Design Method}

Figures 5 and 6 show the simplified block diagram and the source file for the ABEL \({ }^{\text {TM }}\) implementation of the display decoder. The FLAG statement is used to make sure that the programmer load file is in the Motorola Exorciser format. The binary inputs and the decoded outputs are grouped into the sets bcd and led to simplify notation. The constants \(O N\)
and OFF are declared so that the design can be described in terms of turning a segment on or off. To turn a segment on, the appropriate line must be driven low, thus \(O N\) is declared as 0 and \(O F F\) as 1 .
The design is described in two sections: an equations section and a truth table section. The decoding function is described with a truth table that specifies the outputs required for each combination of inputs. The first line of the truth table (the truth table header) names the inputs and outputs. In this example, the inputs are contained in the set named bcd and the outputs are in led. The body of the truth table defines the input-to-output function. Because the design decodes a number to a seven-segment display, values for bcd are expressed as decimal numbers, and values for led are expressed with the constants ON and OFF that were defined in the declarations section of the source file. This makes the truth table easy to read and understand; the incoming value is a number and the outputs are on and off signals to the LED.
The input and output values could have just as easily been described in another form. Take for example the line in the truth table:

\section*{\(5->\) [ON,OFF,ON,ON,OFF,ON,ON]}

This could have been written in the equivalent form:
\[
[0,1,0,1]->36
\]

In this second form, 5 was expressed as a set containing binary values, and the LED set was converted to decimal. (Remember that ONwas defined as 0 and OFF was defined as 1.) Either of the two forms is valid, but the first is more appropriate for this design. The first form can be read as, "the number five turns on the first segment, turns off the second,..." whereas the second form cannot be so easily translated into terms meaningful for this design.

\section*{Test Vectors}

The test vectors for this design test the decoder outputs for the ten valid combinations of input bits. The enable is also tested by setting ena high for the different combinations. All outputs should be at high impedance whenever ena is high. If they are not, an error has occurred.

\section*{Summary}

Two designs described with the \(\mathrm{ABEL}^{\text {u }}\) design language have been shown. The first design shows how Boolean equations with logical and relational operators are used to describe an address decoder. The second design shows how a truth table describes a seven-segment display decoder design for a PLE logic circuit. In both designs, test vectors were written to test the function of the design using \(A B E L^{T w}\) 's simulator. In addition to the Boolean equations and truth table shown in these examples, \(A B E L^{\text {u }}\) features a state diagram structure. The state diagram allows the designer to fully describe state machines in terms of their states and state transitions.

Regardless of the method used to describe logic, \(A B E L^{\text {TM's }}\) s automatic logic reduction and simulation ensure that the design uses as few terms as possible and that it operates as the designer intended. The end results are savings in time, devices, board space, and money.


Figure 6. Source File: Seven-Segment Display Decoder

\section*{The Universal Compiler For Programmable Logic}

CUPL is the first software CAD tool designed especially for the support of all programmable logic devices (PLDs), including PALs and PROMs. It was developed specifically for YOU, the Hardware Design Engineer. Each feature of the CUPL language has been chosen to make using programmable logic easier and faster than conventional TTL logic design.

\section*{MAJOR EEATURES OF CUPL}
1. UNIVERSAL
a. PRODUCT SUPPORT: CUPL supports products from every manufacturer of programmable logic. With CUPL you are free to use not only PALS, but also other programmable logic devices.
b. PALASM CONVERSIONS: CUPL has a PALASM to CUPL language translator which allows for an easy conversion from your previous PALASM designs to CUPL.
c. LOGIC PROGRAMMER COMPATIBILITY: CUPL produces a standard JEDEC download file and is compatible with any logic programmer that uses JEDEC files.

\section*{2. HIGH LEVEL LANGUAGE}

High Level Language means that the software has features that allow you to work in terms that are more like the way you think than like the final PLD programming pattern. Examples of these are:
a. FLEXIBLE INPUT: CUPL gives the engineer complete freedom in entering logic descriptions for their design:
- EQUATIONS
- TRUTH TABLES
- STATE MACHINE SYNTAX
b. EXPRESSION SUBSTITUTION: This allows you to pick a name for an equation and then, rather than write the equation each time it is used, you need only use the name. CUPL will properly substitute the equation during the compile process.


\section*{3. SELF DOCUMENTING}

CUPL provides a template file which provides a standard "fill-in-theblanks" documentation system that is uniform among all CUPL users. Also, CUPL allows for free form comments through out your work so there can be detailed explanations included in each part of the project.

\section*{4. ERROR CHECKING}

CUPL includes a comprehensive error checking capability with detailed error messages designed to lead you to the source of the problem.

\section*{5. LOGIC REDUCTION}

CUPL contains the fastest and most powerful minimizer offered for Programmable Logic equation reduction. The minimizer allows the choice of various levels of minimization ranging from just fitting into the target device to the absolute minimum.
6. SIMULATION

With CSIM, the CUPL Simulator, you can simulate your logic prior to programming an actual device. Not only can this save devices but it can help in debugging a system level problem.

\section*{7. TEST VECTOR GENERATION}

Once the stimulus/response function table information has been entered into the simulator, CSIM will verify the associated test vectors and append them to the JEDEC file for downloading to the logic programmer. The programmer will verify not only the fuse map, but also the functionality of the PLD, giving you added confidence in the operation of your custom part.

\section*{8. EXPANDABILITY}

CUPL is designed for growth so as new PALs and other devices are introduced you will be kept current with updated device libraries and product enhancements.

\section*{DESIGN EXAMPLE USING CUPL}

In the following design example, a single PAL (or PROM) is used to replace four TTL packages on the interface card for an IBM-PC computer. The Prototype I/O Channel Interface Card, as supplied by IBM, uses four SSI packages to decode the ten bit I/O address and control the direction and enable for the bus buffer on the PCB. The PAL approach conserves real estate and also adds flexibility to decode not only the preassigned address, but the ability to change the board address to any location in the I/O map by merely replacing the programmable device.

\section*{1. CIRCUIT OPERATION}

The inputs to the decoding logic are the expansion bus addresses A0 thru A9. The logic compares the address on the expansion bus and asserts the "IO_DECODE" signal when the correct address range of \(3 F 0-3 F F\) is seen. In addition, the "ENABLE" signal is also asserted if either the I/O READ or I/O WRITE signals are active during this time. The READ signal, which controls the direction of the data bus buffer, is asserted whenever I/O READ is active and AEN, the DMA Address enable signal is inactive. The AEN signal is negated when the microprocessor has control of the address bus and is generating an I/O cycle.

First, all device pins are assigned in the logic description file (see figure l) using CUPL's pin declaration statements. Note the use of indexed variables for the address bus allows a simple assignment for pins 1 thru 8. The active polarity for input and output pins are made in these declarations, so the designer need only be concerned with the logic instead of voltage levels.

The address bus is assigned a name using the FIELD statement. This lets the designer then describe the desired address range with the single equation:
```

    range = ioadr:[300..3lF] ;
    ```
instead of the difficult to understand
```

range = a9 \& a8 \& !a7 \& !a6 \& !a5 ;

```

This range expression is then used in the output equation for IO_DECODE and ENABLE. Since ENABLE may be asserted whenever IOR or IOW are true, the intermediate variable IOREQ is created to define this condition. The resultant CUPL equation for ENABLE is simply
```

enable = range \& ioreq ;

```

Finally, the READ signal is created using the active IOR and the inactive AEN signals as follows:
```

read = ior \& !aen ;

```

Note that for a device such as the PALl6L8 which has a fixed inverting buffer on all of its output pins, CuPL will automatically convert the logic equations when an output is desired to be active-level HI, as with the READ output above.
3. CUPL OUTPUT FILES

CUPL will create a standard JEDEC output file which is compatible with most logic programmers. A simple serial download link is all that is usually required to transfer the fuse information to the programmer. In addition, CUPL generates an extensive documentation file which assists the designer in analyzing his/her design. Figure 2 shows a small section of this file, illustrating such features as pin and variable names, product term utilization, and other information.

```

***********************************************************************
/* This device pravides a are-chip I/O iriterface for ar equivalerit */
/* af the IEM-FC prota board. This logic descriptigri may be placed */
/* ir either a FRROM ar FAL withaut alteratiarı */

```

```

/* Allowable Target Device Types : F'AL m- FAGLELG, F'ALIGF'g */
/* FROM-) F'LE1EP44 */

```

```

/** Input5 **/
FIN [1..8] = [a2..9] ; /* CFU Address bits Q thru 9 */
FIN9 = aer ; /* DMA Address Eriable */
FIN 17 = !ior ; /* I/0 Read Strobe (active LO) */
PIN 18 = !iow ; /* I/0 Write Strobe (active LO) */
1** Outputs **/
FIN1E = read ; /* Direction Control For Eus Buffer */
FIN 13 = !erable ; /* Erable For Bus Buffer */
FIN 14 = !ia_decade ; /* Decaded I/O Strabe far Ori Board Use */
/** Declarations ard Intermediate Variable Defiritigrs **/
field joadr = [a9..E] ; /* Name the I/O Address Eus "ioadr" */
ioreq = ior \# icw ; /* Defime I/O Request */
rarge = igadr:[3Q4..31F] \& !aen ; /* Decoded I/0 Acldress Range ard */
1* ruat DMA cycle */
/** Logic Equatiors **/
erable = range \& iorea;
ia_decode = Marge;
read = ior \& !aen;
/* Charge the irtermediate variable "r"arge" for other I/O Locations */

```

Figure 1.


Figure 2.

\section*{CUPL-GTS \\ DRAW LOGIC SCHEMATICS FOR PAL DESIGNS!}

In recent years, programs like CUPL and ABEL have become available to provide high level language support for PAL designs. These languages allow the designer to represent a PAL function in terms of high-level equations, truth tables or state machines. All of these logic description formats are non-graphical in nature and require a good working knowledge of the computer they run on.

Many hardware designers, however, are most comfortable with the traditional logic schematic and have historically had little reason to use computer in the design process. Use of a highlevel PAL design language presents most of us with a variety of simultaneous unknowns:
1. The computer and its operating system.
2. The full screen editor necessary to create the logic description file.
3. The logic compiler or assembler language syntax.
4. Boolean algebra theory.
5. PAL architectures.

Where this combination places an unnecessary burden on the designer, an alternative is now available.

CUPL-GTS is a powerful combination of hardware and software which turns an \(I B M-P C\) type computer into a programmable logic workstation which allows the user to draw logic schematics for the function of a PAL. A basic premise in creating CUPL-GTS was to provide a friendly environment where the user is isolated from the traditional keyboard as much as possible. To this end, virtually all functions can be actuated with one button by way of the mouse and a series of pop-up menus which ease the user's task. An area is provided at the top of the CUPL-GTS screen for prompting the user regarding the next operation in a command sequence. Highlighting of various elements on the screen is coordinated with these prompts to enhance their effectiveness. For the most part, the user need only utilize the conventional keyboard for defining symbolic names for wires, pins, objects, and files.

An on-screen HELP facility is provided to aid the user with CUPLGTS commands. In addition to the basic set of object types which can be easily picked from a pop-up menu, the ability to call up macro-objects is also provided. These macro-objects have been previously drawn using CUPL-GTS and stored away on the disk under their own symbolic name.

After a logic schematic has been entered, the user may quickly check to see if the design fits in a specific PAL. This is done by selecting the "Translate to PLD" command from the main menu which automatically invokes the GTS translation programs. These programs run in an on-screen window which overlays the graphical information, providing feedback in the form of error messages displayed in this window. Following the automatic execution of these programs, the cursor is returned to the user who can then continue to work in the graphics environment without ever having fully left. In this way many errors can be quickly determined and remedied without ever having to let go of the mouse.

When the user wishes a hard copy version of a design, the print command from the main menu may be selected. This causes the GTS print program to execute in an on-screen window according to the printer configuration file (PRINTCAP) which is stored on the disk. The PRINTCAP file allows the user to configure the GTS print function for any dot matrix printer they might have.

Often a logic description not fit in a particular PAL due to a logic capacity (product-term) limitation. When this occurs, the universal capability of CUPL-GTS will easily allow the user to try placing this same logic in a different pal of similar architecture.

Since CUPL-GTS incorporates CUPL the high level language in its internal operation, it also benefits from CUPL's powerful "Quine Procedure" logic minimizer. This is especially advantageous for CUPL-GTS as logic descriptions showing many levels of gates can be very deceptive in their ability to consume the logic capacity of a PAL. The presence of the logic minimizer can eliminate unnecessary and redundant logical functions, and maximizes the probability that a designwillfit in a target PAL.

Also included with CUPL-GTS is the CUPL simulator, CSIM, which allows the user to simulate a logic design prior to physically creating a programmed PAL. Not only can this save devices, but it can help significantly in debugging a system level problem.

CUPL-GTS is desinged for growth and expandability. As new programmable logic devices are introduced users will be kept current with updated device libraries and product enhancements.

Most of us first use PAL devices to replace TTL in order to shrink a design and/or add functionality. The following example shows how the simple I/O decoder design previously discussed would appear on the CUPL-GTS screen prior to translation to a PAL16L8, PAL16P8 or PLE12P4.

```


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[^1]:    I = Military Product Standard.

